Radiation Report
SLOK013 – July 2025

TLV1704-SEP Radiation Tolerant microPower Quad Comparator Plastic Package TID Report

ABSTRACT

This report covers the radiation characterization results of the TLV1704-SEP, 2.2-V to 36-V microPower comparator. The study was done to determine Total Ionizing Dose (TID) effects under low dose rate (LDR) up to 30 krad(Si) and high dose rate (HDR) up to 30 krad(Si). The results show that all samples passed well within the specified limits up to 30 krad(Si).

Contents

List of Figures

List of Tables

Trademarks

All trademarks are the property of their respective owners.

1 Device Information

The TLV1704-SEP (Quad) device offers a wide supply range, rail-to-rail inputs, low quiescent current and low propagation delay. All these features come in industry-standard, extremely-small packages, making these devices the best general-purpose comparators available. The open collector output offers the advantage of allowing the output to be pulled to any voltage rail up to 36 V above the negative power supply, regardless of the TLV1704-SEP supply voltage.

The device is a microPower comparator. Low input offset voltage, low input bias currents, low supply current and open-collector configuration make the TLV1704-SEP device flexible enough to handle almost any application, from simple voltage detection to driving a single relay.

The microPower comparator features of the TLV1704-SEP make it ideally suited for distributed telemetry applications in next-generation spacecraft. The strong immunity to single-event latchup and total ionizing dose, enable the device to be used in a variety of space and radiation environments. It has been RHA qualified to 30 krad(Si) under both LDR and HDR.

1.1 Device Details

Table 1 lists the device information used in the initial TID characterization and qualification for LDR.

Table 1. Device and Exposure Details

TID HDR and LDR Details: up to 30 krad(Si)	
TI Device Number	TLV1704-SEP
Package	14 pin
Technology	BICOM3XHV
Die Lot Number	4057650
A/T Lot Number / Date Code	8598678/85CQSGK
Quantity Tested	84 irradiated devices + 3 control
Lot Accept/Reject	Devices passed 3 krad(Si), 10 krad(Si), 20 krad(Si), 30 krad(Si)
HDR Radiation Facility	Texas Instruments SVA Group, Santa Clara, CA
LDR Radiation Facility	RAD/Aeroflex in Colorado Springs, Colorado
HDR Dose Level	3 krad(Si), 10 krad(Si), 20 krad(Si), 30 krad(Si)
HDR Dose Rate	65 rad(Si)/s
LDR Dose Level	3 krad(Si), 10 krad(Si), 20 krad(Si), 30 krad(Si)
LDR Dose Rate	0.01 rad(Si)/s
HDR Radiation Source	Gammacell 220 Excel (GC-220E) Co-60
LDR Radiation Source	Gammacell JLSA 81-24 Co-60
Irradiation Temperature	Ambient, room temperature

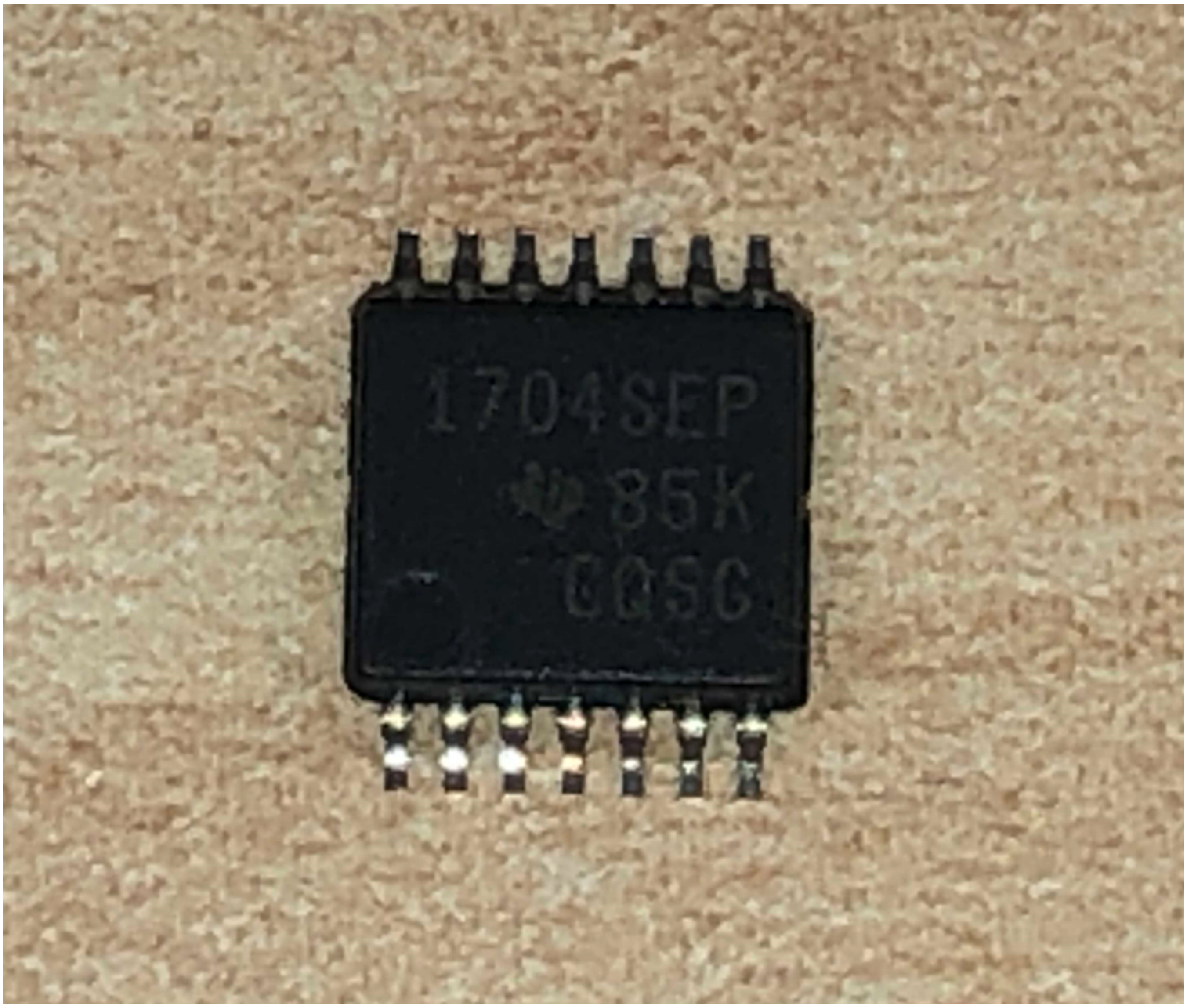


Figure 1. TLV1704-SEP Device Photo

2 Total Dose Test Setup

2.1 Test Overview

The TLV1704-SEP was tested according to MIL-STD-883, Test Method 1019.9, Condition A. The product was irradiated up to 30 krad(Si) and then put through full electrical parametric testing on the production Automated Test Equipment (ATE). The device was functional and passed all electrical parametric tests with readings within guard bands of the data sheet electrical specification limits.

The TLV1704-SEP BICOM3XHV process technology contains Bipolar and CMOS components. Both HDR and LDR tests were performed.

2.2 Test Description and Facilities

The TLV1704-SEP LDR exposure was performed on biased and unbiased devices in a Co60 gamma cell under a 10 mrad(Si)/s exposure rate. The dose rate of the irradiator used in the exposure ranges from < 10 mrad(Si)/s to a maximum of approximately 65 rad(Si)/s, determined by the distance from the source. For the HDR (10 mrad(Si)/s) exposure, the test box was positioned approximately 2 m from the source. The exposure boards are housed in a lead-aluminum box (as specified in MIL-STD-883 TM 1019.9) to harden the gamma spectrum and minimize dose enhancement effects. The irradiator calibration is maintained by Logmire Laboratories using Thermoluminescence Dosimeters (TLDs) traceable to the National Institute of Standards and Technology (NIST) and the dosimetry was verified using TLDs prior to the radiation exposures. After exposure, the devices were packed in dry ice (per MIL-STD-883 Method 1019.9 section 3.10) and returned to TI Dallas for a full post radiation electrical evaluation using Texas Instruments production Automated Test Equipment (ATE). ATE guard band test limits are set within data sheet electrical limits to ensure a minimum Cpk and test error margin based on initial qualification and characterization data. Post radiation measurements were taken within 30 minutes of removal of the devices form the dry ice container. The devices were allowed to reach room temperature prior to electrical post radiation measurements.

The TLV1704-SEP HDR exposure was performed on biased and unbiased devices in a Co60 gamma cell at TI SVA facility in Santa Clara, California. The un-attenuated dose rate of this cell is 65 rad(Si)/s. After exposure, the devices were packed in dry ice (per MIL-STD-883 Method 1019.9 section 3.10) and returned to TI Dallas for a full post radiation electrical evaluation using Texas Instruments ATE. ATE guard band test limits are set within data sheet electrical limits to ensure a minimum Cpk and test error margin based on initial qualification and characterization data. Post radiation measurements were taken within 30 minutes of removal of the devices from the dry ice container. The devices were allowed to reach room temperature prior to electrical post radiation measurements.

2.3 Test Setup Details

The devices under LDR and HDR exposure were tested in both biased and unbiased conditions as described below:

2.3.1 Unbiased

For the unbiased LDR conditions, the exposure was performed with all pins grounded.

2.3.2 Biased

Figure 2 shows the bias conditions for each pin during HDR and LDR exposure.

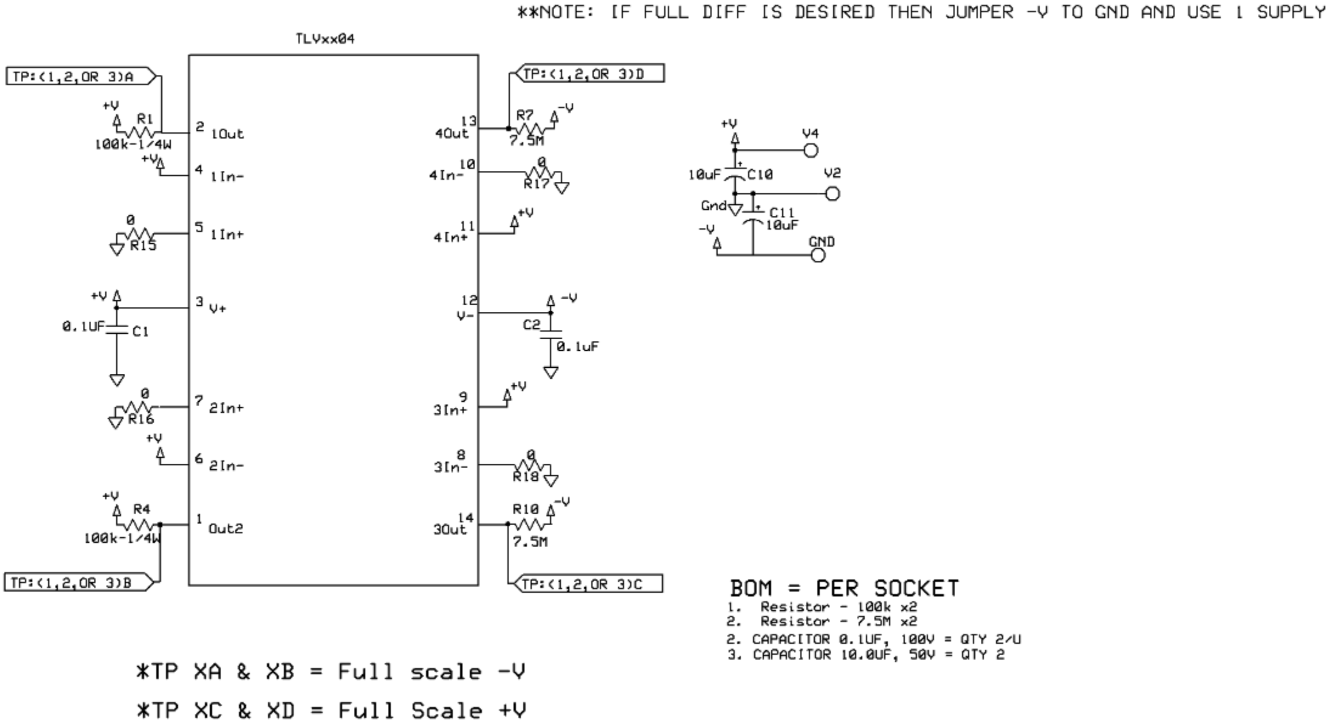


Figure 2. TLV1704-SEP Biased Diagram

2.4 Test Configuration and Condition

A step-stress (3k, 10k, 20k, and 30k) test method was used to determine the TID hardness level. That is, after a predetermined TID level was reached, an electrical test was performed on a given sample of parts to verify that the units are within specified data sheet electrical test limits. MIL-STD-883, Test Method 1019.9, Condition A was used in this case. If this passes, then the wafer lot can be certified as an RHA wafer lot.

Table 2 list the serialized samples that was used during the RHA characterization.

Table 2. LDR = 10-mrad(Si)/s Biased and Unbiased Device Information

LDR = 10 mrad(Si)/s			
Total Samples: 10/dose level (5 biased + 5 unbiased)			
Exposure Levels			
3 krad(Si)	**10 krad(Si)**	**20 krad(Si)**	**30 krad(Si)**
Biased	Biased	Biased	Biased
001, 002, 003, 004, 005 (Wafer 1)	011, 012, 013, 014, 015 (Wafer 1)	021, 022, 023, 024, 025 (Wafer 1)	021, 022, 023, 024, 025 (Wafer 1)
Unbiased	Unbiased	Unbiased	Unbiased
006, 007, 008, 009, 010 (Wafer 1)	016, 017, 018, 019, 020 (Wafer 1)	026, 027, 028, 029, 030 (Wafer 1)	026, 027, 028, 029, 030 (Wafer 1)

Table 3. HDR = 65-rad(Si)/s Biased Device Information

HDR = 65 rad(Si)/s			
Total Samples: 5/dose level (5 biased)			
Exposure Levels			
3 krad(Si)	**10 krad(Si)**	**20 krad(Si)**	**30 krad(Si)**
Biased	Biased	Biased	Biased
001, 002, 003, 004, 005 (Wafer 1)	006, 007, 008, 009, 010 (Wafer 1)	011, 012, 013, 014, 015 (Wafer 1)	016, 017, 018, 019, 020 (Wafer 1)

3 Tested Parameters

Table 4 provides the list of tested parameters.

Table 4. TLV1704-SEP Data Sheet Parameters

PARAMETER	TEST CONDITION	Data sheet Lit# SLOSE29 – November 2018				Test# or Name
		MIN	TYP	MAX	UNIT	
Input offset voltage (Vos)	Tj = 25°C, Vs = 2.2 V		0.5	3.5	mV	190.0__VOS_2p2V_PSRR
Input offset voltage (Vos)	Tj = 25°C, Vs = 36 V		0.3	2.5	mV	210.0__VOS_36V_PSRR
Power-supply rejection ratio (PSRR)	Tj = 25°C		15	100	µV/V	220.0__PSRR
Input bias current (IB)	Tj = 25°C		5	15	nA	440.0__IB_Pos_36V
Input offset current (IOS)	Tj = 25°C		0.5		nA	460.0__IOS_36V
Voltage Output Swing from Rail (Vo)	IO ≤ 4 mA; Input overdrive = 100 mV, Vs = 36 V			1100	mV	510.0__Swing_VOL_4mA_36V
Voltage Output Swing from Rail (Vo)	IO = 0 mA; Input overdrive = 100 mV, Vs = 36 V			700	mV	520.0__Swing_VOL_0mA_36V
Quiescent current (per channel) (IQ)	IO = 0 A		55	75	µA	90.0__IQ_VDD_2p2V

4 Total Ionizing Dose (RHA) Characterization Test Results

4.1 Total Ionizing Dose RHA Characterization Summary Results

The parametric data for the TLV1704-SEP passes up to 30 krad(Si) LDR/HDR per MIL-STD-883, TM1090 Condition A.

The TLV1704-SEP passed post electrical test over all conditions listed below indicating that this lot can be certified as 30 krad(Si) RHA.

- LDR (0.01 rad(Si)/s) unbiased: Post 3 krad(Si), 10 krad(Si), 20 krad(Si), 30 krad(Si)
- LDR (0.01 rad(Si)/s) biased: Post 3 krad(Si), 10 krad(Si), 20 krad(Si), 30 krad(Si)
- HDR (100 rad(Si)/s) biased: Post 3 krad(Si), 10 krad(Si), 20 krad(Si), 30 krad(Si)

Overall radiation performance was very solid. There were no functional or parametric failures at any read point. All data sheet parameters passed at all exposure levels with margin and ELDRS free. Critical Parameters for TLV1704-SEP such as **Input Bias Current (IB)** and **Quiescent Current (IQ)** were still within specifications.

1. **Input Bias Current (IB)**

   Input offset voltage – exhibits a Increase from 10 krad(Si) to 20 krad(Si) and the amount of shift from 10 krad(Si) to 20 krad(Si) was 0.25 nA. The IB 36-V parameter is within the specifications.

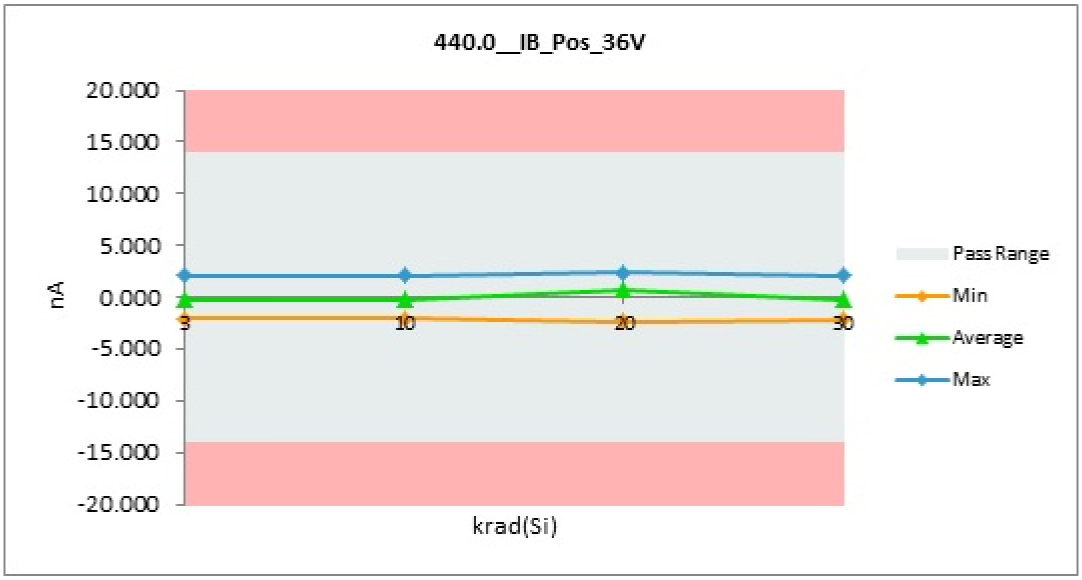


Figure 3. Radiation Exposure Effect on Input Bias Current (IB)

2. **Quiescent Current (IQ) 36 V**

   Input offset voltage – exhibits a decreases from 10 krad(Si) to 20 krad(Si) and the amount of shift from T0 to 20 krad(Si) was ~0.07%. The IQ 36-V parameter is within the specifications.

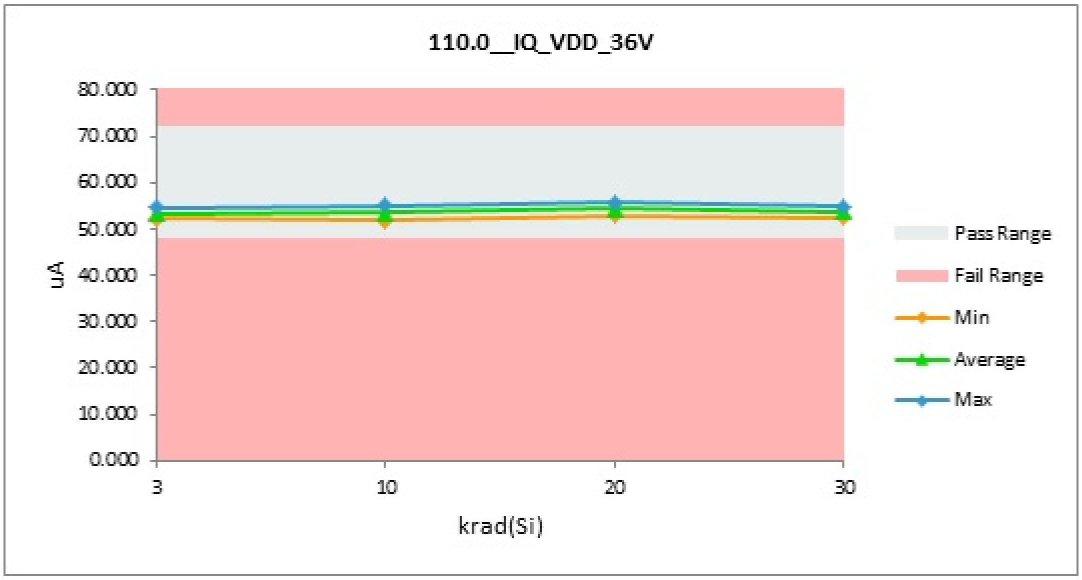


Figure 4. Radiation Exposure Effect on Quiescent Current (IQ) 36 V

Total Ionizing Dose LDR Report

This appendix provides the TLV1704-SEP TID LDR report.

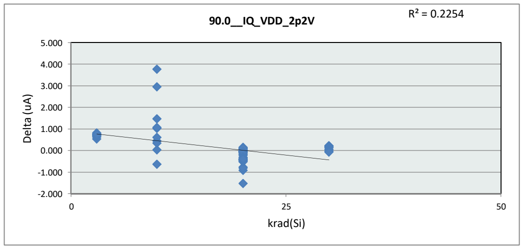
Delta Threshold	10.00%

TID LDR Report
TLV1704-SEP

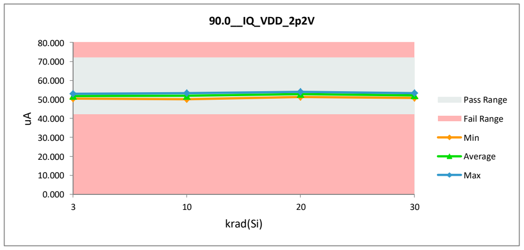
TID LDR Report
TLV1704-SEP

	90.0__IQ_VDD_2p2V	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	uA	uA
Max Limit	72	72
Min Limit	42	42

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	51.005	50.466	0.539
3	2	52.075	51.458	0.617
3	3	51.964	51.294	0.670
3	4	51.977	51.243	0.734
3	5	52.981	52.260	0.722
3	6	52.874	52.097	0.777
3	7	52.794	51.982	0.812
3	8	52.837	52.136	0.701
3	9	53.681	52.949	0.732
3	0	53.227	52.490	0.737
10	1	53.854	50.091	3.762
10	2	54.060	51.113	2.947
10	3	52.595	51.127	1.468
10	4	52.165	51.141	1.024
10	5	51.645	52.277	-0.633
10	6	53.247	52.175	1.073
10	7	52.871	52.422	0.449
10	8	53.112	52.510	0.602
10	9	53.384	53.362	0.022
10	10	53.181	52.845	0.337
20	11	53.854	53.896	-0.042
20	12	54.060	54.048	0.012
20	13	52.595	52.662	-0.068
20	14	52.165	52.093	0.072
20	15	51.645	51.598	0.047
20	16	53.247	53.249	-0.001
20	17	52.871	52.913	-0.042
20	18	53.112	53.135	-0.023
20	19	53.384	53.414	-0.030
20	20	53.181	53.265	-0.083
20	21	52.748	52.969	-0.221
20	22	52.903	53.018	-0.115
20	23	52.943	52.977	-0.034
20	24	52.716	52.798	-0.081
20	25	53.219	53.299	-0.080
20	26	53.182	53.057	0.125
20	27	53.041	52.938	0.102
20	28	52.824	52.682	0.141
20	29	52.589	53.104	-0.515
20	30	52.893	53.090	-0.197
20	31	52.755	52.946	-0.192
20	32	52.788	52.842	-0.054
20	33	52.629	53.405	-0.776
20	34	53.066	52.995	0.071
20	35	52.778	52.766	0.012
20	36	52.990	52.891	0.099
20	37	53.329	53.386	-0.057
20	38	53.324	53.390	-0.067
20	39	53.380	53.507	-0.128
20	40	53.274	53.348	-0.075
20	41	52.333	53.253	-0.920
20	42	51.625	52.442	-0.817
20	43	51.284	52.812	-1.528
20	44	51.961	52.483	-0.522
20	45	52.871	53.344	-0.473
20	46	51.636	52.061	-0.425
20	47	53.023	53.422	-0.399
20	48	53.231	53.656	-0.425
20	49	51.849	52.263	-0.414
20	50	51.554	51.996	-0.443
20	51	51.050	51.506	-0.456
20	52	51.690	52.000	-0.310
20	53	51.623	51.967	-0.344
20	54	51.534	51.950	-0.416
20	55	50.957	51.326	-0.370
20	56	51.412	51.805	-0.394
30	1	51.005	50.797	0.208
30	2	52.075	51.851	0.224
30	3	51.964	51.750	0.215
30	4	51.977	51.815	0.162
30	5	52.981	52.843	0.139
30	62	51.940	51.798	0.142
30	63	53.044	52.979	0.065
30	64	51.995	51.981	0.014
30	65	52.106	52.155	-0.049
30	66	53.245	53.324	-0.079
	Max	54.060	54.048	3.762
	Average	52.592	52.483	0.109
	Min	50.957	50.091	-1.528
	Std Dev	0.763	0.825	0.729



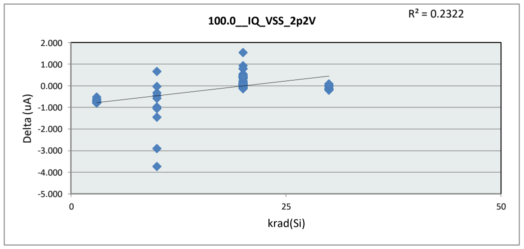
	90.0__IQ_VDD_2p2V			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	72	uA		
Min Limit	42	uA		
krad(Si)	3	10	20	30
LL	42.000	42.000	42.000	42.000
Min	50.466	50.091	51.326	50.797
Average	51.838	51.906	52.825	52.129
Max	52.949	53.362	54.048	53.324
UL	72.000	72.000	72.000	72.000



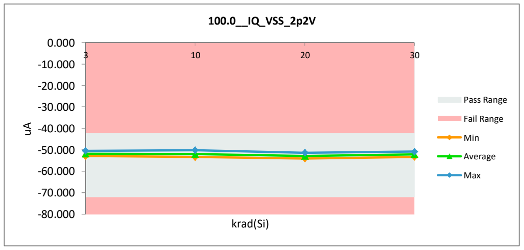
TID LDR Report
TLV1704-SEP

	100.0__IQ_VSS_2p2V	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	uA	uA
Max Limit	-42	-42
Min Limit	-72	-72

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	-51.052	-50.521	-0.530
3	2	-52.110	-51.490	-0.620
3	3	-51.998	-51.332	-0.666
3	4	-52.015	-51.251	-0.764
3	5	-53.032	-52.270	-0.762
3	6	-52.917	-52.135	-0.781
3	7	-52.839	-52.032	-0.807
3	8	-52.875	-52.171	-0.704
3	9	-53.734	-52.974	-0.760
3	0	-53.272	-52.502	-0.770
10	1	-53.903	-50.162	-3.741
10	2	-54.108	-51.191	-2.917
10	3	-52.652	-51.187	-1.465
10	4	-52.208	-51.225	-0.983
10	5	-51.685	-52.339	0.655
10	6	-53.297	-52.240	-1.057
10	7	-52.916	-52.453	-0.463
10	8	-53.155	-52.561	-0.594
10	9	-53.424	-53.391	-0.034
10	10	-53.222	-52.893	-0.330
20	11	-53.903	-53.946	0.043
20	12	-54.108	-54.105	-0.003
20	13	-52.652	-52.712	0.060
20	14	-52.208	-52.151	-0.056
20	15	-51.685	-51.654	-0.031
20	16	-53.297	-53.304	0.007
20	17	-52.916	-52.963	0.047
20	18	-53.155	-53.194	0.039
20	19	-53.424	-53.464	0.039
20	20	-53.222	-53.312	0.090
20	21	-52.792	-53.011	0.219
20	22	-52.943	-53.073	0.131
20	23	-52.980	-53.032	0.052
20	24	-52.760	-52.851	0.090
20	25	-53.261	-53.356	0.095
20	26	-53.252	-53.121	-0.131
20	27	-53.086	-52.987	-0.098
20	28	-52.875	-52.740	-0.135
20	29	-52.635	-53.155	0.520
20	30	-52.940	-53.147	0.207
20	31	-52.809	-53.014	0.205
20	32	-52.832	-52.884	0.052
20	33	-52.669	-53.451	0.782
20	34	-53.114	-53.050	-0.064
20	35	-52.817	-52.815	-0.002
20	36	-53.032	-52.936	-0.096
20	37	-53.383	-53.434	0.051
20	38	-53.368	-53.440	0.072
20	39	-53.425	-53.556	0.132
20	40	-53.319	-53.396	0.076
20	41	-52.377	-53.301	0.924
20	42	-51.692	-52.489	0.797
20	43	-51.341	-52.877	1.536
20	44	-52.004	-52.543	0.539
20	45	-52.926	-53.395	0.468
20	46	-51.676	-52.118	0.442
20	47	-53.076	-53.478	0.402
20	48	-53.282	-53.710	0.428
20	49	-51.894	-52.314	0.421
20	50	-51.622	-52.042	0.421
20	51	-51.096	-51.549	0.453
20	52	-51.731	-52.048	0.317
20	53	-51.664	-52.015	0.352
20	54	-51.581	-51.994	0.413
20	55	-50.995	-51.368	0.374
20	56	-51.449	-51.855	0.406
30	1	-51.052	-50.854	-0.197
30	2	-52.110	-51.905	-0.205
30	3	-51.998	-51.802	-0.196
30	4	-52.015	-51.858	-0.157
30	5	-53.032	-52.895	-0.137
30	62	-51.978	-51.851	-0.127
30	63	-53.078	-53.026	-0.052
30	64	-52.032	-52.036	0.004
30	65	-52.152	-52.210	0.058
30	66	-53.297	-53.371	0.075
	Max	-50.995	-50.162	1.536
	Average	-52.637	-52.533	-0.105
	Min	-54.108	-54.105	-3.741
	Std Dev	0.764	0.824	0.728

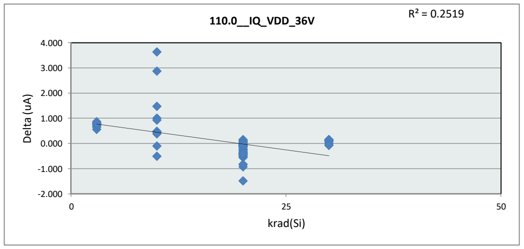


	100.0__IQ_VSS_2p2V			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	-42	uA		
Min Limit	-72	uA		
krad(Si)	3	10	20	30
LL	-72.000	-72.000	-72.000	-72.000
Min	-52.974	-53.391	-54.105	-53.371
Average	-51.868	-51.964	-52.877	-52.181
Max	-50.522	-50.162	-51.369	-50.854
UL	-42.000	-42.000	-42.000	-42.000

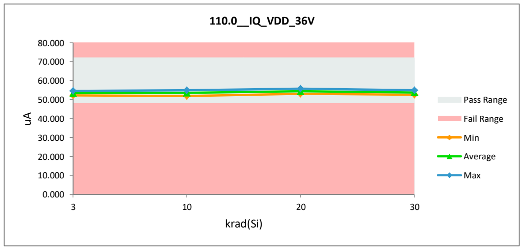


TID LDR Report
TLV1704-SEP

		110.0__IQ_VDD_36V		
	Test Site	MLA	MLA	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	uA	uA	
	Max Limit	72	72	
	Min Limit	48	48	
krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	52.681	52.134	0.547
3	2	53.702	53.061	0.641
3	3	53.590	52.898	0.693
3	4	53.626	52.846	0.780
3	5	54.436	53.683	0.752
3	6	54.450	53.632	0.819
3	7	54.373	53.518	0.855
3	8	54.424	53.685	0.740
3	9	55.279	54.516	0.763
3	0	54.785	54.004	0.781
10	1	55.414	51.789	3.625
10	2	55.638	52.782	2.856
10	3	54.239	52.771	1.468
10	4	53.822	52.830	0.992
10	5	53.241	53.753	-0.512
10	6	54.682	53.760	0.922
10	7	54.470	53.996	0.474
10	8	54.563	54.113	0.450
10	9	54.848	54.954	-0.105
10	10	54.783	54.412	0.370
20	11	55.414	55.501	-0.087
20	12	55.638	55.683	-0.045
20	13	54.239	54.361	-0.122
20	14	53.822	53.810	0.011
20	15	53.241	53.251	-0.009
20	16	54.682	54.727	-0.045
20	17	54.470	54.572	-0.102
20	18	54.563	54.632	-0.069
20	19	54.848	54.925	-0.076
20	20	54.783	54.926	-0.143
20	21	54.325	54.597	-0.272
20	22	54.349	54.501	-0.152
20	23	54.376	54.455	-0.079
20	24	54.139	54.255	-0.116
20	25	54.665	54.796	-0.132
20	26	54.664	54.514	0.149
20	27	54.467	54.409	0.058
20	28	54.253	54.146	0.107
20	29	54.017	54.585	-0.568
20	30	54.330	54.573	-0.243
20	31	54.199	54.418	-0.219
20	32	54.218	54.320	-0.102
20	33	54.073	54.920	-0.847
20	34	54.514	54.439	0.075
20	35	54.194	54.181	0.013
20	36	54.420	54.434	-0.014
20	37	54.797	54.861	-0.064
20	38	54.794	54.864	-0.070
20	39	54.852	54.994	-0.142
20	40	54.778	54.852	-0.074
20	41	53.818	54.747	-0.929
20	42	53.238	54.073	-0.835
20	43	52.911	54.403	-1.492
20	44	53.528	54.058	-0.529
20	45	54.348	54.829	-0.481
20	46	53.218	53.645	-0.427
20	47	54.509	54.908	-0.399
20	48	54.736	55.167	-0.431
20	49	53.453	53.887	-0.434
20	50	53.166	53.612	-0.446
20	51	52.680	53.140	-0.460
20	52	53.313	53.631	-0.318
20	53	53.229	53.589	-0.361
20	54	53.153	53.576	-0.423
20	55	52.591	52.970	-0.379
20	56	53.046	53.461	-0.415
30	1	52.681	52.543	0.138
30	2	53.702	53.554	0.148
30	3	53.590	53.447	0.144
30	4	53.626	53.537	0.089
30	5	54.436	54.339	0.097
30	62	53.528	53.395	0.133
30	63	54.627	54.573	0.054
30	64	53.580	53.582	-0.003
30	65	53.711	53.777	-0.066
30	66	54.749	54.836	-0.088
	Max	55.638	55.683	3.625
	Average	54.136	54.052	0.084
	Min	52.591	51.789	-1.492
	Std Dev	0.718	0.776	0.719



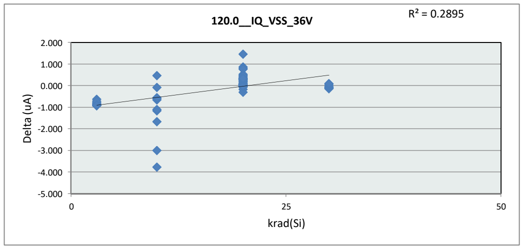
	110.0__IQ_VDD_36V			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	72	uA		
Min Limit	48	uA		
krad(Si)	3	10	20	30
LL	48.000	48.000	48.000	48.000
Min	52.134	51.789	52.970	52.544
Average	53.398	53.516	54.374	53.758
Max	54.516	54.954	55.683	54.836
UL	72.000	72.000	72.000	72.000



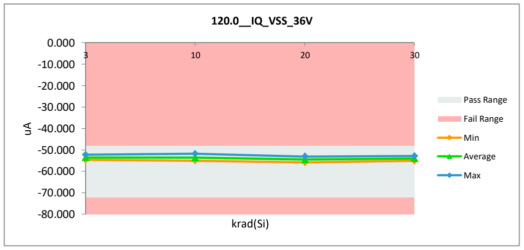
TID LDR Report
TLV1704-SEP

	120.0__IQ_VSS_36V	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	uA	uA
Max Limit	-48	-48
Min Limit	-72	-72

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	-52.942	-52.314	-0.629
3	2	-53.954	-53.171	-0.784
3	3	-53.843	-53.023	-0.820
3	4	-53.868	-52.946	-0.922
3	5	-54.660	-53.812	-0.848
3	6	-54.698	-53.773	-0.925
3	7	-54.556	-53.672	-0.885
3	8	-54.525	-53.806	-0.719
3	9	-55.541	-54.638	-0.903
3	0	-55.027	-54.111	-0.916
10	1	-55.631	-51.860	-3.771
10	2	-55.855	-52.854	-3.001
10	3	-54.547	-52.882	-1.665
10	4	-54.085	-52.918	-1.166
10	5	-53.355	-53.823	0.468
10	6	-54.930	-53.828	-1.102
10	7	-54.722	-54.064	-0.658
10	8	-54.786	-54.180	-0.605
10	9	-55.100	-55.012	-0.088
10	10	-55.038	-54.478	-0.560
20	11	-55.631	-55.719	0.089
20	12	-55.855	-55.903	0.048
20	13	-54.547	-54.563	0.016
20	14	-54.085	-54.085	0.001
20	15	-53.355	-53.439	0.084
20	16	-54.930	-54.900	-0.030
20	17	-54.722	-54.758	0.036
20	18	-54.786	-54.814	0.029
20	19	-55.100	-55.110	0.010
20	20	-55.038	-55.099	0.061
20	21	-54.590	-54.771	0.182
20	22	-54.609	-54.692	0.084
20	23	-54.588	-54.645	0.057
20	24	-54.280	-54.432	0.152
20	25	-54.933	-54.972	0.038
20	26	-54.813	-55.061	0.247
20	27	-54.911	-54.599	-0.312
20	28	-54.509	-54.336	-0.172
20	29	-54.268	-54.755	0.487
20	30	-54.493	-54.755	0.262
20	31	-54.478	-54.674	0.195
20	32	-54.404	-54.496	0.092
20	33	-54.236	-55.098	0.862
20	34	-54.688	-54.654	-0.034
20	35	-54.310	-54.314	0.004
20	36	-54.570	-54.543	-0.026
20	37	-55.069	-54.995	-0.074
20	38	-55.019	-54.985	-0.034
20	39	-55.100	-55.116	0.015
20	40	-55.003	-54.970	-0.032
20	41	-54.069	-54.874	0.805
20	42	-53.445	-54.206	0.761
20	43	-53.156	-54.605	1.450
20	44	-53.673	-54.194	0.521
20	45	-54.541	-54.971	0.431
20	46	-53.448	-53.805	0.357
20	47	-54.673	-55.038	0.365
20	48	-54.964	-55.320	0.356
20	49	-53.714	-54.003	0.289
20	50	-53.436	-53.722	0.286
20	51	-52.931	-53.257	0.326
20	52	-53.438	-53.744	0.306
20	53	-53.460	-53.724	0.265
20	54	-53.281	-53.713	0.432
20	55	-52.764	-53.083	0.319
20	56	-53.274	-53.609	0.334
30	1	-52.942	-52.828	-0.114
30	2	-53.954	-53.810	-0.144
30	3	-53.843	-53.708	-0.135
30	4	-53.868	-53.793	-0.075
30	5	-54.660	-54.602	-0.058
30	62	-53.651	-53.548	-0.103
30	63	-54.763	-54.703	-0.060
30	64	-53.698	-53.725	0.027
30	65	-53.831	-53.909	0.078
30	66	-55.011	-55.101	0.089
	Max	-52.764	-51.860	1.450
	Average	-54.356	-54.211	-0.145
	Min	-55.855	-55.903	-3.771
	Std Dev	0.728	0.794	0.747



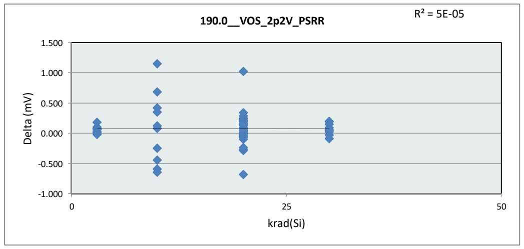
	120.0__IQ_VSS_36V			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	-48	uA		
Min Limit	-72	uA		
krad(Si)	3	10	20	30
LL	-72.000	-72.000	-72.000	-72.000
Min	-54.638	-55.012	-55.903	-55.101
Average	-53.526	-53.590	-54.546	-53.973
Max	-52.314	-51.860	-53.083	-52.828
UL	-48.000	-48.000	-48.000	-48.000



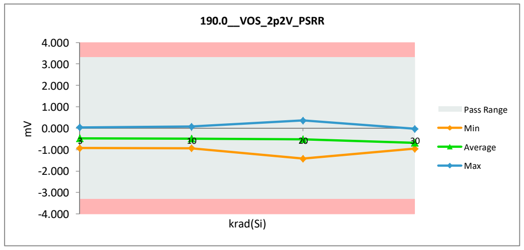
TID LDR Report
TLV1704-SEP

	190.0__VOS_2p2V_PSRR	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	mV	mV
Max Limit	3.3	3.3
Min Limit	-3.3	-3.3

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	-0.842	-0.921	0.079
3	2	-0.485	-0.663	0.178
3	3	-0.228	-0.327	0.099
3	4	-0.802	-0.881	0.079
3	5	-0.168	-0.178	0.010
3	6	0.109	0.040	0.069
3	7	-0.535	-0.515	-0.020
3	8	-0.148	-0.208	0.059
3	9	-0.178	-0.168	-0.010
3	0	-0.832	-0.861	0.030
10	1	-0.584	-0.931	0.346
10	2	-0.317	-0.733	0.416
10	3	0.287	-0.396	0.683
10	4	0.257	-0.891	1.148
10	5	-0.812	-0.218	-0.594
10	6	-0.168	0.079	-0.248
10	7	-1.168	-0.525	-0.644
10	8	-0.129	-0.208	0.079
10	9	-0.614	-0.168	-0.446
10	10	-0.743	-0.861	0.119
20	11	-0.584	-0.832	0.248
20	12	-0.317	-0.535	0.218
20	13	0.287	0.049	0.238
20	14	0.257	0.099	0.158
20	15	-0.812	-1.020	0.208
20	16	-0.168	-0.376	0.208
20	17	-1.168	-1.317	0.148
20	18	-0.129	-0.366	0.238
20	19	-0.614	-0.743	0.129
20	20	-0.743	-0.881	0.139
20	21	-1.129	-1.416	0.287
20	22	-0.238	-0.208	-0.030
20	23	-0.673	-0.832	0.158
20	24	-1.228	-1.366	0.139
20	25	-0.871	-1.059	0.188
20	26	-0.475	-0.416	-0.059
20	27	-0.158	-0.495	0.337
20	28	-0.465	-0.654	0.188
20	29	-0.594	-0.307	-0.287
20	30	-0.228	0.040	-0.267
20	31	0.178	0.049	0.129
20	32	0.168	-0.851	1.020
20	33	-0.693	-0.634	-0.059
20	34	-0.802	-0.871	0.069
20	35	-0.861	-0.762	-0.099
20	36	-0.614	-0.376	-0.238
20	37	-0.010	-0.099	0.089
20	38	-0.663	-0.693	0.030
20	39	0.030	-0.129	0.158
20	40	-0.812	-0.851	0.040
20	41	0.099	0.059	0.040
20	42	0.158	0.079	0.079
20	43	-1.158	-0.475	-0.683
20	44	-0.654	-0.703	0.049
20	45	-0.990	-1.030	0.040
20	46	-0.248	-0.277	0.030
20	47	-0.148	-0.198	0.050
20	48	-0.485	-0.574	0.089
20	49	0.297	0.366	-0.069
20	50	-0.386	-0.376	-0.010
20	51	-0.178	-0.327	0.148
20	52	-0.584	-0.624	0.040
20	53	0.277	0.307	-0.030
20	54	-0.634	-0.644	0.010
20	55	-0.960	-0.951	-0.010
20	56	-0.208	-0.257	0.050
30	1	-0.842	-0.931	0.089
30	2	-0.485	-0.673	0.188
30	3	-0.228	-0.426	0.198
30	4	-0.802	-0.851	0.049
30	5	-0.168	-0.317	0.148
30	62	-0.861	-0.881	0.020
30	63	-0.861	-0.911	0.049
30	64	-0.980	-0.951	-0.030
30	65	0.030	-0.030	0.059
30	66	-0.901	-0.812	-0.089
	Max	0.297	0.366	1.148
	Average	-0.449	-0.524	0.075
	Min	-1.228	-1.416	-0.683
	Std Dev	0.416	0.397	0.269

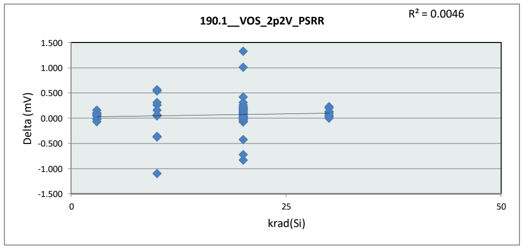


	190.0__VOS_2p2V_PSRR			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	3.3	mV		
Min Limit	-3.3	mV		
krad(Si)	3	10	20	30
LL	-3.300	-3.300	-3.300	-3.300
Min	-0.921	-0.931	-1.416	-0.951
Average	-0.468	-0.485	-0.510	-0.678
Max	0.040	0.079	0.366	-0.030
UL	3.300	3.300	3.300	3.300

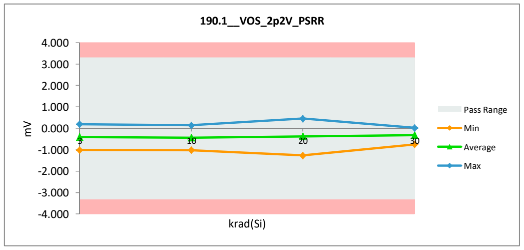


TID LDR Report
TLV1704-SEP

		190.1__VOS_2p2V_PSRR		
	Test Site	MLA	MLA	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	mV	mV	
	Max Limit	3.3	3.3	
	Min Limit	-3.3	-3.3	
krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	-0.129	-0.208	0.079
3	2	0.059	0.069	-0.010
3	3	-0.297	-0.356	0.059
3	4	0.208	0.109	0.099
3	5	-0.525	-0.683	0.158
3	6	-0.901	-1.000	0.099
3	7	-0.426	-0.475	0.049
3	8	-0.693	-0.663	-0.030
3	9	0.119	0.188	-0.069
3	0	-0.970	-1.010	0.040
10	1	0.010	-0.248	0.257
10	2	-0.386	-0.020	-0.366
10	3	-0.366	-0.406	0.040
10	4	-1.040	0.059	-1.099
10	5	-0.594	-0.752	0.158
10	6	-0.475	-1.010	0.535
10	7	-0.376	-0.436	0.059
10	8	-0.089	-0.654	0.564
10	9	-0.238	0.139	-0.376
10	10	-0.713	-1.020	0.307
20	11	0.010	-0.119	0.129
20	12	-0.386	-0.465	0.079
20	13	-0.366	-0.535	0.168
20	14	-1.040	-1.267	0.228
20	15	-0.594	-0.762	0.168
20	16	-0.475	-0.644	0.168
20	17	-0.376	-0.584	0.208
20	18	-0.089	-0.188	0.099
20	19	-0.238	-0.396	0.158
20	20	-0.713	-0.881	0.168
20	21	-0.010	-0.198	0.188
20	22	-0.228	-0.347	0.119
20	23	0.089	-0.099	0.188
20	24	-0.535	-0.693	0.158
20	25	-0.287	-0.376	0.089
20	26	-0.683	0.148	-0.832
20	27	0.455	-0.554	1.010
20	28	-0.475	-0.733	0.257
20	29	-0.574	0.148	-0.723
20	30	0.148	-0.267	0.416
20	31	-0.129	-0.079	-0.050
20	32	0.030	0.455	-0.426
20	33	0.475	-0.851	1.327
20	34	0.158	0.228	-0.069
20	35	-0.970	-0.891	-0.079
20	36	-0.228	-0.307	0.079
20	37	0.168	0.158	0.010
20	38	-0.574	-0.515	-0.059
20	39	0.040	0.069	-0.030
20	40	-0.089	-0.119	0.030
20	41	0.168	0.148	0.020
20	42	-1.129	-1.139	0.010
20	43	-0.099	-0.406	0.307
20	44	-0.445	-0.455	0.010
20	45	-0.960	-1.049	0.089
20	46	-0.040	-0.020	-0.020
20	47	-0.634	-0.614	-0.020
20	48	-0.594	-0.614	0.020
20	49	-0.426	-0.445	0.020
20	50	0.198	0.198	0.000
20	51	-0.663	-0.683	0.020
20	52	-0.198	-0.188	-0.010
20	53	-0.248	-0.297	0.049
20	54	-0.327	-0.356	0.030
20	55	-0.644	-0.683	0.040
20	56	0.099	0.079	0.020
30	1	-0.129	-0.218	0.089
30	2	0.059	0.020	0.040
30	3	-0.297	-0.426	0.129
30	4	0.208	0.010	0.198
30	5	-0.525	-0.752	0.228
30	62	-0.495	-0.535	0.040
30	63	-0.455	-0.455	0.000
30	64	-0.139	-0.257	0.119
30	65	-0.416	-0.445	0.030
30	66	-0.089	-0.139	0.050
	Max	0.475	0.455	1.327
	Average	-0.310	-0.378	0.069
	Min	-1.129	-1.267	-1.099
	Std Dev	0.361	0.381	0.307



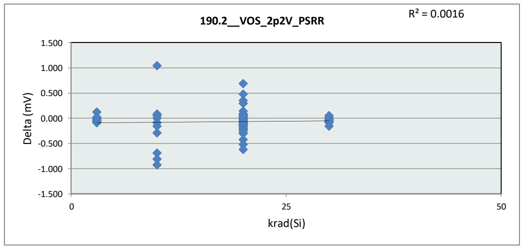
	190.1__VOS_2p2V_PSRR			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	3.3	mV		
Min Limit	-3.3	mV		
krad(Si)	3	10	20	30
LL	-3.300	-3.300	-3.300	-3.300
Min	-1.010	-1.020	-1.267	-0.753
Average	-0.403	-0.435	-0.374	-0.320
Max	0.188	0.139	0.455	0.020
UL	3.300	3.300	3.300	3.300



TID LDR Report
TLV1704-SEP

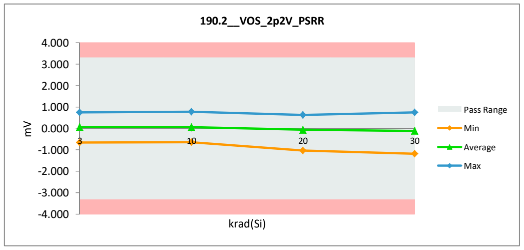
	190.2__VOS_2p2V_PSRR	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	mV	mV
Max Limit	3.3	3.3
Min Limit	-3.3	-3.3

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	-0.139	-0.059	-0.079
3	2	0.683	0.743	-0.059
3	3	0.040	0.129	-0.089
3	4	-0.139	-0.049	-0.089
3	5	0.624	0.663	-0.040
3	6	-0.644	-0.663	0.020
3	7	0.099	-0.020	0.119
3	8	0.228	0.248	-0.020
3	9	-0.644	-0.604	-0.040
3	0	0.178	0.168	0.010
10	1	-0.772	-0.079	-0.693
10	2	-0.148	0.782	-0.931
10	3	-0.168	0.129	-0.297
10	4	0.049	-0.030	0.079
10	5	-0.099	0.713	-0.812
10	6	-0.644	-0.644	0.000
10	7	-0.129	-0.040	-0.089
10	8	0.287	0.238	0.049
10	9	0.436	-0.604	1.040
10	10	0.000	0.158	-0.158
20	11	-0.772	-0.644	-0.129
20	12	-0.148	0.010	-0.158
20	13	-0.168	0.049	-0.218
20	14	0.049	0.198	-0.148
20	15	-0.099	0.099	-0.198
20	16	-0.644	-0.475	-0.168
20	17	-0.129	0.178	-0.307
20	18	0.287	0.396	-0.109
20	19	0.436	0.535	-0.099
20	20	0.000	0.168	-0.168
20	21	0.337	0.554	-0.218
20	22	0.376	0.505	-0.129
20	23	-0.109	0.020	-0.129
20	24	-0.040	0.198	-0.238
20	25	-0.208	-0.079	-0.129
20	26	0.010	-0.337	0.347
20	27	-0.485	-0.059	-0.426
20	28	-0.139	-0.198	0.059
20	29	-0.376	0.148	-0.525
20	30	0.030	-0.257	0.287
20	31	-0.416	-0.139	-0.277
20	32	-0.238	-0.376	0.139
20	33	-0.436	0.188	-0.624
20	34	-0.515	-0.366	-0.149
20	35	-0.069	-0.079	0.010
20	36	0.178	-0.297	0.475
20	37	-0.099	0.020	-0.119
20	38	-0.208	-0.257	0.050
20	39	0.287	0.238	0.049
20	40	0.059	0.148	-0.089
20	41	-0.733	-0.683	-0.049
20	42	-0.228	-0.317	0.089
20	43	0.267	-0.416	0.683
20	44	0.129	0.198	-0.069
20	45	-0.356	-0.277	-0.079
20	46	0.178	0.109	0.069
20	47	0.683	0.624	0.059
20	48	-0.485	-0.505	0.020
20	49	0.505	0.535	-0.030
20	50	0.356	0.356	0.000
20	51	-0.703	-0.713	0.010
20	52	-1.030	-1.030	0.000
20	53	0.485	0.554	-0.069
20	54	-0.931	-0.911	-0.020
20	55	-0.010	0.010	-0.020
20	56	-0.743	-0.782	0.040
30	1	-0.139	-0.049	-0.089
30	2	0.683	0.752	-0.069
30	3	0.040	0.109	-0.069
30	4	-0.139	0.020	-0.158
30	5	0.624	0.673	-0.050
30	62	-0.554	-0.564	0.010
30	63	-0.049	-0.030	-0.020
30	64	-0.030	0.010	-0.040
30	65	-1.010	-0.970	-0.040
30	66	-1.139	-1.188	0.049
	Max	0.683	0.782	1.040
	Average	-0.112	-0.042	-0.069
	Min	-1.139	-1.188	-0.931
	Std Dev	0.429	0.452	0.267



	190.2__VOS_2p2V_PSRR	
Test Site	MLA	
Tester	ETS364	
Test Number	EB083902	
Max Limit	3.3	mV
Min Limit	-3.3	mV

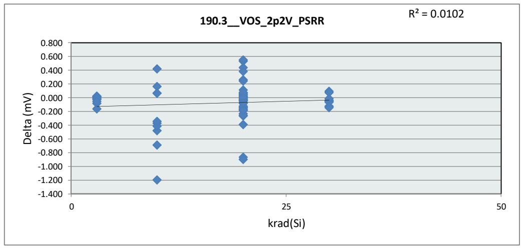
krad(Si)	3	10	20	30
LL	-3.300	-3.300	-3.300	-3.300
Min	-0.663	-0.644	-1.030	-1.188
Average	0.055	0.062	-0.069	-0.124
Max	0.743	0.782	0.624	0.753
UL	3.300	3.300	3.300	3.300



TID LDR Report
TLV1704-SEP

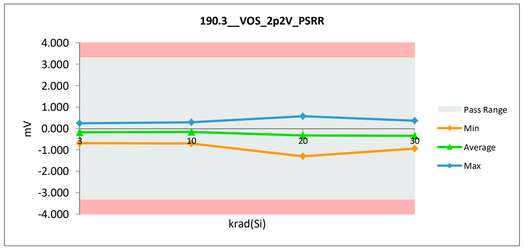
	190.3__VOS_2p2V_PSRR	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	mV	mV
Max Limit	3.3	3.3
Min Limit	-3.3	-3.3

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	-0.010	0.010	-0.020
3	2	-0.594	-0.505	-0.089
3	3	-0.040	0.129	-0.168
3	4	-0.347	-0.356	0.010
3	5	0.208	0.238	-0.030
3	6	-0.109	-0.129	0.020
3	7	-0.356	-0.356	0.000
3	8	-0.673	-0.683	0.010
3	9	-0.386	-0.366	-0.020
3	0	0.139	0.198	-0.059
10	1	-0.445	0.040	-0.485
10	2	-0.861	-0.485	-0.376
10	3	-0.525	0.168	-0.693
10	4	-0.307	-0.366	0.059
10	5	-0.129	0.287	-0.416
10	6	0.089	-0.069	0.158
10	7	-0.703	-0.356	-0.347
10	8	-0.287	-0.703	0.416
10	9	-0.277	-0.337	0.059
10	10	-1.030	0.168	-1.198
20	11	-0.445	-0.178	-0.267
20	12	-0.861	-0.713	-0.149
20	13	-0.525	-0.376	-0.149
20	14	-0.307	-0.218	-0.089
20	15	-0.129	0.020	-0.149
20	16	0.089	0.277	-0.188
20	17	-0.703	-0.465	-0.238
20	18	-0.287	-0.248	-0.040
20	19	-0.277	-0.109	-0.168
20	20	-1.030	-0.772	-0.257
20	21	0.218	0.396	-0.178
20	22	-0.545	-0.356	-0.188
20	23	-0.445	-0.396	-0.049
20	24	-0.911	-0.782	-0.129
20	25	-1.356	-1.228	-0.129
20	26	-0.970	-0.099	-0.871
20	27	-0.248	-0.069	-0.178
20	28	-0.178	0.218	-0.396
20	29	0.148	-0.109	0.257
20	30	-0.129	-0.366	0.238
20	31	-0.495	-0.931	0.436
20	32	-1.020	-0.119	-0.901
20	33	-0.277	-0.802	0.525
20	34	-0.673	-0.634	-0.040
20	35	-0.386	-0.356	-0.030
20	36	-0.564	-0.941	0.376
20	37	-0.445	-0.396	-0.049
20	38	0.505	0.535	-0.030
20	39	0.475	0.436	0.040
20	40	-0.248	-0.257	0.010
20	41	0.564	0.455	0.109
20	42	-0.891	-0.951	0.059
20	43	-0.396	-0.941	0.545
20	44	0.030	-0.020	0.049
20	45	-1.277	-1.297	0.020
20	46	-0.049	-0.049	0.000
20	47	-0.119	-0.188	0.069
20	48	-0.970	-0.951	-0.020
20	49	-0.970	-1.010	0.040
20	50	-0.614	-0.584	-0.030
20	51	-0.634	-0.654	0.020
20	52	-0.089	-0.158	0.069
20	53	-0.832	-0.792	-0.040
20	54	0.495	0.505	-0.010
20	55	0.089	0.089	0.000
20	56	0.495	0.574	-0.079
30	1	-0.010	0.030	-0.040
30	2	-0.594	-0.465	-0.129
30	3	-0.040	0.089	-0.129
30	4	-0.347	-0.287	-0.059
30	5	0.208	0.356	-0.149
30	62	-0.683	-0.634	-0.049
30	63	-0.644	-0.733	0.089
30	64	-0.604	-0.535	-0.069
30	65	-0.871	-0.941	0.069
30	66	-0.366	-0.347	-0.020
	Max	0.564	0.574	0.545
	Average	-0.366	-0.289	-0.077
	Min	-1.356	-1.297	-1.198
	Std Dev	0.431	0.441	0.277



	190.3__VOS_2p2V_PSRR	
Test Site	MLA	
Tester	ETS364	
Test Number	EB083902	
Max Limit	3.3	mV
Min Limit	-3.3	mV

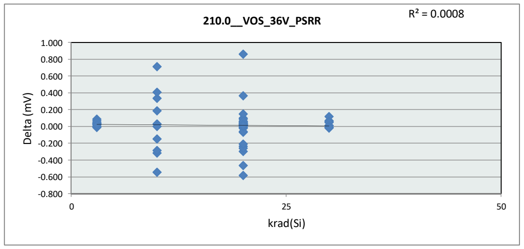
krad(Si)	3	10	20	30
LL	-3.300	-3.300	-3.300	-3.300
Min	-0.683	-0.703	-1.297	-0.941
Average	-0.182	-0.165	-0.326	-0.347
Max	0.238	0.287	0.574	0.356
UL	3.300	3.300	3.300	3.300



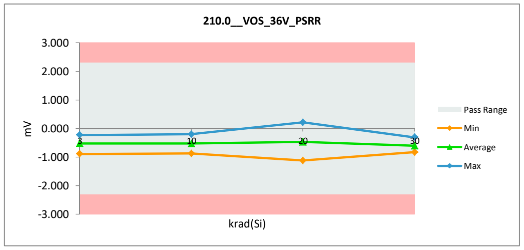
TID LDR Report
TLV1704-SEP

	210.0__VOS_36V_PSRR	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	mV	mV
Max Limit	2.3	2.3
Min Limit	-2.3	-2.3

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	-0.733	-0.762	0.030
3	2	-0.535	-0.624	0.089
3	3	-0.257	-0.297	0.040
3	4	-0.832	-0.822	-0.010
3	5	-0.505	-0.535	0.030
3	6	-0.158	-0.228	0.069
3	7	-0.485	-0.485	0.000
3	8	-0.198	-0.248	0.050
3	9	-0.317	-0.317	0.000
3	0	-0.871	-0.891	0.020
10	1	-0.743	-0.772	0.030
10	2	-0.317	-0.654	0.337
10	3	-0.119	-0.307	0.188
10	4	-0.119	-0.832	0.713
10	5	-0.554	-0.554	0.000
10	6	-0.743	-0.198	-0.545
10	7	-0.802	-0.485	-0.317
10	8	-0.535	-0.248	-0.287
10	9	-0.465	-0.317	-0.148
10	10	-0.465	-0.871	0.406
20	11	-0.743	-0.792	0.049
20	12	-0.317	-0.416	0.099
20	13	-0.119	-0.099	-0.020
20	14	-0.119	-0.139	0.020
20	15	-0.554	-0.614	0.059
20	16	-0.743	-0.762	0.020
20	17	-0.802	-0.822	0.020
20	18	-0.535	-0.574	0.040
20	19	-0.465	-0.485	0.020
20	20	-0.465	-0.455	-0.010
20	21	-0.743	-0.832	0.089
20	22	-0.347	-0.356	0.010
20	23	-0.634	-0.673	0.040
20	24	-1.099	-1.119	0.020
20	25	-0.822	-0.851	0.030
20	26	-0.673	-0.376	-0.297
20	27	-0.356	-0.337	-0.020
20	28	-0.327	0.139	-0.465
20	29	0.139	-0.228	0.366
20	30	-0.208	0.030	-0.238
20	31	0.049	-0.099	0.148
20	32	-0.079	-0.941	0.861
20	33	-0.911	-0.654	-0.257
20	34	-0.970	-1.000	0.030
20	35	-0.752	-0.762	0.010
20	36	-0.228	-0.020	-0.208
20	37	-0.584	-0.564	-0.020
20	38	-0.445	-0.455	0.010
20	39	-0.218	-0.257	0.040
20	40	-0.426	-0.475	0.049
20	41	0.059	0.000	0.059
20	42	-0.099	-0.119	0.020
20	43	-0.980	-0.396	-0.584
20	44	-0.752	-0.782	0.030
20	45	-0.703	-0.733	0.030
20	46	-0.238	-0.248	0.010
20	47	-0.584	-0.594	0.010
20	48	-0.535	-0.584	0.050
20	49	0.148	0.218	-0.069
20	50	-0.465	-0.475	0.010
20	51	-0.654	-0.713	0.059
20	52	-0.673	-0.703	0.030
20	53	0.069	0.129	-0.059
20	54	-0.554	-0.574	0.020
20	55	-0.911	-0.911	0.000
20	56	-0.287	-0.297	0.010
30	1	-0.733	-0.802	0.069
30	2	-0.535	-0.654	0.119
30	3	-0.257	-0.307	0.049
30	4	-0.832	-0.822	-0.010
30	5	-0.505	-0.564	0.059
30	62	-0.822	-0.832	0.010
30	63	-0.723	-0.772	0.049
30	64	-0.574	-0.554	-0.020
30	65	-0.297	-0.307	0.010
30	66	-0.475	-0.465	-0.010
	Max	0.148	0.218	0.861
	Average	-0.489	-0.504	0.015
	Min	-1.099	-1.119	-0.584
	Std Dev	0.288	0.294	0.204

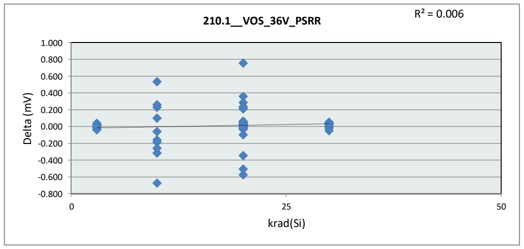


	210.0__VOS_36V_PSRR			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	2.3	mV		
Min Limit	-2.3	mV		
krad(Si)	3	10	20	30
LL	-2.300	-2.300	-2.300	-2.300
Min	-0.891	-0.871	-1.119	-0.832
Average	-0.521	-0.524	-0.473	-0.608
Max	-0.228	-0.198	0.218	-0.307
UL	2.300	2.300	2.300	2.300

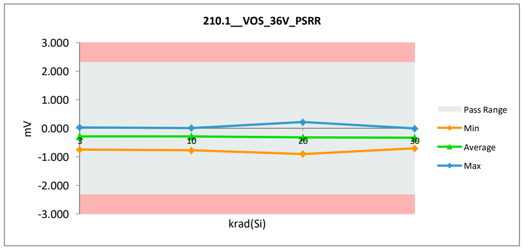


TID LDR Report
TLV1704-SEP

		210.1__VOS_36V_PSRR		
	Test Site	MLA	MLA	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	mV	mV	
	Max Limit	2.3	2.3	
	Min Limit	-2.3	-2.3	
krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	0.040	0.030	0.010
3	2	-0.317	-0.297	-0.020
3	3	-0.069	-0.089	0.020
3	4	-0.139	-0.148	0.010
3	5	-0.307	-0.297	-0.010
3	6	-0.485	-0.505	0.020
3	7	-0.267	-0.307	0.040
3	8	-0.792	-0.752	-0.040
3	9	-0.139	-0.099	-0.040
3	0	-0.376	-0.386	0.010
10	1	0.238	0.010	0.228
10	2	-0.356	-0.297	-0.059
10	3	0.010	-0.089	0.099
10	4	-0.842	-0.168	-0.673
10	5	-0.614	-0.297	-0.317
10	6	-0.703	-0.515	-0.188
10	7	-0.445	-0.287	-0.158
10	8	-0.238	-0.772	0.535
10	9	0.178	-0.079	0.257
10	10	-0.654	-0.396	-0.258
20	11	0.238	0.218	0.020
20	12	-0.356	-0.347	-0.010
20	13	0.010	-0.020	0.030
20	14	-0.842	-0.901	0.059
20	15	-0.614	-0.654	0.040
20	16	-0.703	-0.723	0.020
20	17	-0.445	-0.455	0.010
20	18	-0.238	-0.208	-0.030
20	19	0.178	0.158	0.020
20	20	-0.654	-0.654	0.000
20	21	-0.208	-0.248	0.040
20	22	-0.396	-0.406	0.010
20	23	-0.119	-0.139	0.020
20	24	-0.762	-0.772	0.010
20	25	-0.198	-0.238	0.040
20	26	-0.564	-0.059	-0.505
20	27	-0.049	-0.406	0.356
20	28	-0.356	-0.574	0.218
20	29	-0.535	0.040	-0.574
20	30	0.000	-0.287	0.287
20	31	-0.267	0.079	-0.347
20	32	0.119	0.218	-0.099
20	33	0.178	-0.574	0.752
20	34	-0.168	-0.178	0.010
20	35	-0.713	-0.743	0.030
20	36	-0.109	-0.317	0.208
20	37	-0.010	0.020	-0.030
20	38	-0.287	-0.297	0.010
20	39	0.040	0.049	-0.010
20	40	-0.198	-0.248	0.050
20	41	0.158	0.158	0.000
20	42	-0.851	-0.842	-0.010
20	43	-0.178	-0.416	0.238
20	44	-0.416	-0.445	0.030
20	45	-0.851	-0.901	0.050
20	46	-0.129	-0.099	-0.030
20	47	-0.327	-0.366	0.040
20	48	-0.445	-0.465	0.020
20	49	-0.515	-0.564	0.049
20	50	0.059	0.059	0.000
20	51	-0.644	-0.703	0.059
20	52	-0.178	-0.188	0.010
20	53	-0.307	-0.337	0.030
20	54	-0.396	-0.416	0.020
20	55	-0.535	-0.574	0.040
20	56	-0.099	-0.079	-0.020
30	1	0.040	-0.010	0.049
30	2	-0.317	-0.267	-0.049
30	3	-0.069	-0.109	0.040
30	4	-0.139	-0.158	0.020
30	5	-0.307	-0.307	0.000
30	62	-0.287	-0.317	0.030
30	63	-0.703	-0.703	0.000
30	64	-0.495	-0.545	0.050
30	65	-0.604	-0.584	-0.020
30	66	-0.277	-0.317	0.040
	Max	0.238	0.218	0.752
	Average	-0.304	-0.314	0.010
	Min	-0.851	-0.901	-0.673
	Std Dev	0.291	0.276	0.192

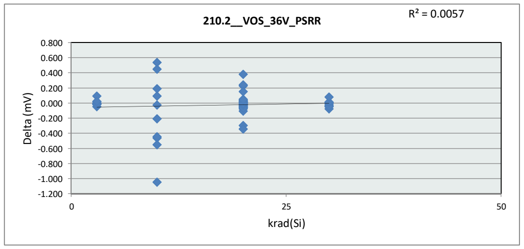


	210.1__VOS_36V_PSRR			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	2.3	mV		
Min Limit	-2.3	mV		
krad(Si)	3	10	20	30
LL	-2.300	-2.300	-2.300	-2.300
Min	-0.753	-0.772	-0.901	-0.703
Average	-0.285	-0.289	-0.323	-0.332
Max	0.030	0.010	0.218	-0.010
UL	2.300	2.300	2.300	2.300

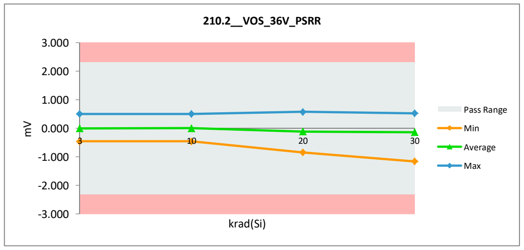


TID LDR Report
TLV1704-SEP

		210.2__VOS_36V_PSRR		
	Test Site	MLA	MLA	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	mV	mV	
	Max Limit	2.3	2.3	
	Min Limit	-2.3	-2.3	
krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	0.178	0.188	-0.010
3	2	0.495	0.505	-0.010
3	3	-0.168	-0.158	-0.010
3	4	0.020	0.069	-0.050
3	5	0.337	0.317	0.020
3	6	-0.327	-0.327	0.000
3	7	-0.366	-0.455	0.089
3	8	0.238	0.257	-0.020
3	9	-0.455	-0.436	-0.020
3	0	0.040	0.020	0.020
10	1	-0.851	0.198	-1.049
10	2	0.040	0.505	-0.465
10	3	-0.356	-0.148	-0.208
10	4	-0.465	0.089	-0.554
10	5	-0.109	0.337	-0.446
10	6	-0.347	-0.317	-0.030
10	7	0.079	-0.455	0.535
10	8	0.436	0.248	0.188
10	9	0.020	-0.426	0.446
10	10	0.089	0.000	0.089
20	11	-0.851	-0.842	-0.010
20	12	0.040	0.059	-0.020
20	13	-0.356	-0.327	-0.030
20	14	-0.465	-0.465	0.000
20	15	-0.109	-0.049	-0.059
20	16	-0.347	-0.327	-0.020
20	17	0.079	0.158	-0.079
20	18	0.436	0.436	0.000
20	19	0.020	0.079	-0.059
20	20	0.089	0.079	0.010
20	21	0.545	0.564	-0.020
20	22	0.030	0.069	-0.040
20	23	0.079	0.079	0.000
20	24	0.158	0.208	-0.050
20	25	-0.297	-0.317	0.020
20	26	-0.020	-0.248	0.228
20	27	-0.257	0.040	-0.297
20	28	0.020	0.069	-0.050
20	29	0.010	-0.228	0.238
20	30	-0.238	-0.386	0.148
20	31	-0.436	-0.465	0.030
20	32	-0.465	-0.356	-0.109
20	33	-0.327	0.020	-0.347
20	34	-0.089	-0.030	-0.059
20	35	-0.218	-0.188	-0.030
20	36	0.030	-0.347	0.376
20	37	0.158	0.178	-0.020
20	38	-0.248	-0.248	0.000
20	39	0.049	0.069	-0.020
20	40	-0.109	-0.119	0.010
20	41	-0.436	-0.445	0.010
20	42	-0.594	-0.614	0.020
20	43	0.158	0.188	-0.030
20	44	0.148	0.208	-0.059
20	45	0.000	0.020	-0.020
20	46	-0.069	-0.069	0.000
20	47	0.148	0.119	0.030
20	48	-0.376	-0.426	0.050
20	49	0.267	0.327	-0.059
20	50	-0.030	0.010	-0.040
20	51	-0.564	-0.584	0.020
20	52	-0.703	-0.723	0.020
20	53	0.505	0.574	-0.069
20	54	-0.762	-0.733	-0.030
20	55	0.307	0.317	-0.010
20	56	-0.683	-0.723	0.040
30	1	0.178	0.188	-0.010
30	2	0.495	0.525	-0.030
30	3	-0.168	-0.119	-0.050
30	4	0.020	0.099	-0.079
30	5	0.337	0.337	0.000
30	62	-0.554	-0.564	0.010
30	63	-0.238	-0.198	-0.040
30	64	-0.030	0.020	-0.049
30	65	-0.515	-0.525	0.010
30	66	-1.079	-1.158	0.079
	Max	0.545	0.574	0.535
	Average	-0.116	-0.089	-0.027
	Min	-1.079	-1.158	-1.049
	Std Dev	0.350	0.362	0.197

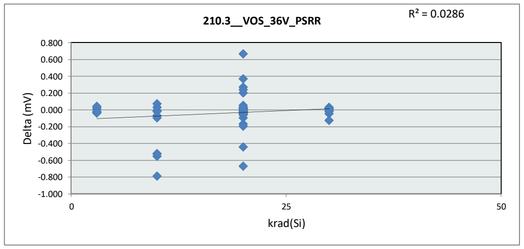


	210.2__VOS_36V_PSRR			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	2.3	mV		
Min Limit	-2.3	mV		
krad(Si)	3	10	20	30
LL	-2.300	-2.300	-2.300	-2.300
Min	-0.455	-0.455	-0.842	-1.158
Average	-0.002	0.003	-0.117	-0.140
Max	0.505	0.505	0.574	0.525
UL	2.300	2.300	2.300	2.300

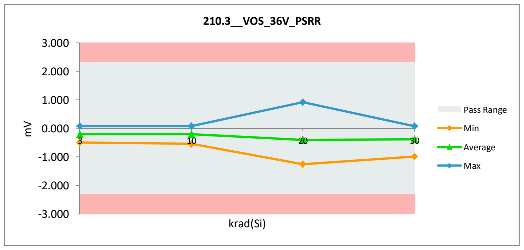


TID LDR Report
TLV1704-SEP

		210.3__VOS_36V_PSRR		
	Test Site	MLA	MLA	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	mV	mV	
	Max Limit	2.3	2.3	
	Min Limit	-2.3	-2.3	
krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	0.099	0.079	0.020
3	2	-0.307	-0.307	0.000
3	3	-0.049	-0.020	-0.030
3	4	-0.416	-0.455	0.040
3	5	-0.119	-0.079	-0.040
3	6	0.030	0.059	-0.030
3	7	-0.337	-0.317	-0.020
3	8	-0.525	-0.495	-0.030
3	9	-0.445	-0.416	-0.030
3	0	-0.158	-0.129	-0.030
10	1	-0.475	0.079	-0.554
10	2	-1.109	-0.317	-0.792
10	3	-0.535	-0.010	-0.525
10	4	-0.445	-0.436	-0.010
10	5	-0.089	-0.069	-0.020
10	6	-0.020	0.079	-0.099
10	7	-0.297	-0.327	0.030
10	8	-0.614	-0.545	-0.069
10	9	-0.337	-0.406	0.069
10	10	-0.644	-0.119	-0.525
20	11	-0.475	-0.376	-0.099
20	12	-1.109	-1.049	-0.059
20	13	-0.535	-0.525	-0.010
20	14	-0.445	-0.445	0.000
20	15	-0.089	-0.069	-0.020
20	16	-0.020	0.040	-0.059
20	17	-0.297	-0.238	-0.059
20	18	-0.614	-0.624	0.010
20	19	-0.337	-0.337	0.000
20	20	-0.644	-0.634	-0.010
20	21	0.000	-0.020	0.020
20	22	-0.564	-0.515	-0.049
20	23	-1.277	-1.257	-0.020
20	24	-0.931	-0.931	0.000
20	25	-0.842	-0.802	-0.040
20	26	-1.148	-0.703	-0.445
20	27	-0.693	-0.525	-0.168
20	28	-0.525	0.148	-0.673
20	29	0.099	-0.267	0.366
20	30	-0.287	-0.554	0.267
20	31	-0.574	-0.574	0.000
20	32	-0.634	-0.436	-0.198
20	33	-0.475	-1.139	0.663
20	34	-0.614	-0.574	-0.040
20	35	-0.535	-0.485	-0.050
20	36	-0.673	-0.871	0.198
20	37	-0.079	-0.079	0.000
20	38	0.000	0.049	-0.049
20	39	0.020	0.000	0.020
20	40	0.030	0.040	-0.010
20	41	0.040	0.059	-0.020
20	42	-0.772	-0.822	0.049
20	43	-0.554	-0.792	0.238
20	44	-0.277	-0.277	0.000
20	45	-1.238	-1.257	0.020
20	46	-0.277	-0.257	-0.020
20	47	-0.297	-0.277	-0.020
20	48	-0.347	-0.376	0.030
20	49	-0.851	-0.871	0.020
20	50	-0.307	-0.297	-0.010
20	51	-0.257	-0.267	0.010
20	52	-0.059	-0.079	0.020
20	53	-0.644	-0.604	-0.040
20	54	0.455	0.495	-0.040
20	55	-0.059	-0.049	-0.010
20	56	0.951	0.921	0.030
30	1	0.099	0.079	0.020
30	2	-0.307	-0.297	-0.010
30	3	-0.049	0.000	-0.049
30	4	-0.416	-0.426	0.010
30	5	-0.119	0.010	-0.129
30	62	-0.535	-0.535	0.000
30	63	-0.782	-0.812	0.030
30	64	-0.327	-0.307	-0.020
30	65	-0.970	-0.990	0.020
30	66	-0.554	-0.554	0.000
	Max	0.951	0.921	0.663
	Average	-0.388	-0.348	-0.040
	Min	-1.277	-1.257	-0.792
	Std Dev	0.381	0.385	0.197

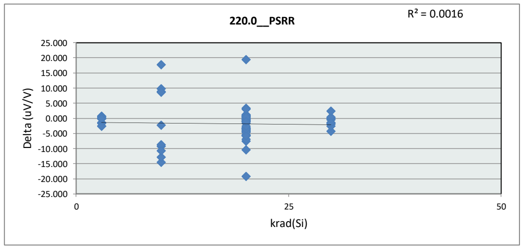


	210.3__VOS_36V_PSRR			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	2.3	mV		
Min Limit	-2.3	mV		
krad(Si)	3	10	20	30
LL	-2.300	-2.300	-2.300	-2.300
Min	-0.495	-0.545	-1.257	-0.990
Average	-0.208	-0.207	-0.402	-0.383
Max	0.079	0.079	0.921	0.079
UL	2.300	2.300	2.300	2.300

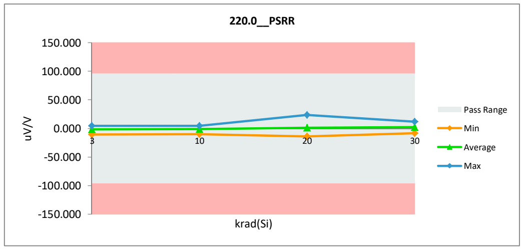


TID LDR Report
TLV1704-SEP

		220.0__PSRR		
	Test Site	MLA	MLA	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	uV/V	uV/V	
	Max Limit	96	96	
	Min Limit	-96	-96	
krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	3.222	4.687	-1.465
3	2	-1.465	1.172	-2.636
3	3	-0.879	0.879	-1.758
3	4	-0.879	1.758	-2.636
3	5	-9.960	-10.545	0.586
3	6	-7.909	-7.909	0.000
3	7	1.465	0.879	0.586
3	8	-1.465	-1.172	-0.293
3	9	-4.101	-4.394	0.293
3	0	-1.172	-0.879	-0.293
10	1	-4.687	4.687	-9.374
10	2	0.000	2.343	-2.343
10	3	-12.010	2.636	-14.647
10	4	-11.131	1.758	-12.889
10	5	7.616	-9.960	17.576
10	6	-16.990	-8.202	-8.788
10	7	10.838	1.172	9.667
10	8	-12.010	-1.172	-10.838
10	9	4.394	-4.394	8.788
10	10	8.202	-0.293	8.495
20	11	-4.687	1.172	-5.859
20	12	0.000	3.515	-3.515
20	13	-12.010	-4.394	-7.616
20	14	-11.131	-7.030	-4.101
20	15	7.616	12.010	-4.394
20	16	-16.990	-11.424	-5.566
20	17	10.838	14.646	-3.808
20	18	-12.010	-6.152	-5.859
20	19	4.394	7.616	-3.222
20	20	8.202	12.596	-4.394
20	21	11.424	17.283	-5.859
20	22	-3.222	-4.394	1.172
20	23	1.172	4.687	-3.515
20	24	3.808	7.323	-3.515
20	25	1.465	6.152	-4.687
20	26	-5.859	1.172	-7.030
20	27	-5.859	4.687	-10.546
20	28	4.101	23.434	-19.333
20	29	21.677	2.343	19.333
20	30	0.586	-0.293	0.879
20	31	-3.808	-4.394	0.586
20	32	-7.323	-2.636	-4.687
20	33	-6.444	-0.586	-5.858
20	34	-4.980	-3.808	-1.172
20	35	3.222	0.000	3.222
20	36	11.424	10.545	0.879
20	37	-16.990	-13.768	-3.222
20	38	6.444	7.030	-0.586
20	39	-7.323	-3.808	-3.515
20	40	11.424	11.131	0.293
20	41	-1.172	-1.758	0.586
20	42	-7.616	-5.859	-1.757
20	43	5.273	2.343	2.929
20	44	-2.929	-2.343	-0.586
20	45	8.495	8.788	-0.293
20	46	0.293	0.879	-0.586
20	47	-12.889	-11.717	-1.172
20	48	-1.465	-0.293	-1.172
20	49	-4.394	-4.394	0.000
20	50	-2.343	-2.929	0.586
20	51	-14.061	-11.424	-2.636
20	52	-2.636	-2.343	-0.293
20	53	-6.152	-5.273	-0.879
20	54	2.343	2.050	0.293
20	55	1.465	1.172	0.293
20	56	-2.343	-1.172	-1.172
30	1	3.222	3.808	-0.586
30	2	-1.465	0.586	-2.050
30	3	-0.879	3.515	-4.394
30	4	-0.879	0.879	-1.758
30	5	-9.960	-7.323	-2.636
30	62	1.172	1.465	-0.293
30	63	4.101	4.101	0.000
30	64	12.010	11.717	0.293
30	65	-9.667	-8.202	-1.465
30	66	12.596	10.252	2.343
	Max	21.677	23.434	19.333
	Average	-1.179	0.582	-1.761
	Min	-16.990	-13.768	-19.333
	Std Dev	7.926	6.987	5.663

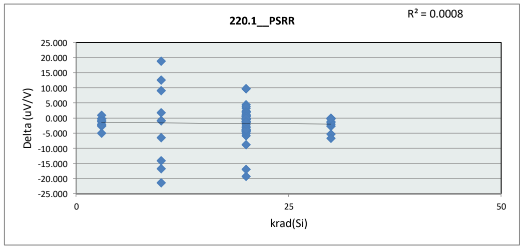


	220.0__PSRR			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	96	uV/V		
Min Limit	-96	uV/V		
krad(Si)	3	10	20	30
LL	-96.000	-96.000	-96.000	-96.000
Min	-10.545	-9.960	-13.768	-8.202
Average	-1.553	-1.142	1.095	2.080
Max	4.687	4.687	23.434	11.717
UL	96.000	96.000	96.000	96.000

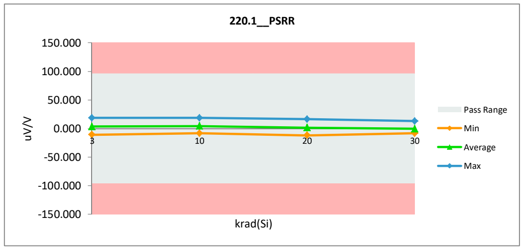


TID LDR Report
TLV1704-SEP

		220.1__PSRR		
	Test Site	MLA	MLA	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	uV/V	uV/V	
	Max Limit	96	96	
	Min Limit	-96	-96	
krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	4.980	7.030	-2.050
3	2	-11.131	-10.838	-0.293
3	3	6.737	7.909	-1.172
3	4	-10.252	-7.616	-2.636
3	5	6.444	11.424	-4.980
3	6	12.303	14.646	-2.343
3	7	4.687	4.980	-0.293
3	8	-2.929	-2.636	-0.293
3	9	-7.616	-8.495	0.879
3	0	17.576	18.455	-0.879
10	1	6.737	7.616	-0.879
10	2	0.879	-8.202	9.081
10	3	11.131	9.374	1.758
10	4	5.859	-6.737	12.596
10	5	-0.586	13.475	-14.061
10	6	-6.737	14.646	-21.384
10	7	-2.050	4.394	-6.444
10	8	-4.394	-3.515	-0.879
10	9	12.303	-6.444	18.747
10	10	1.758	18.455	-16.697
20	11	6.737	9.960	-3.222
20	12	0.879	3.515	-2.636
20	13	11.131	15.232	-4.101
20	14	5.859	10.838	-4.980
20	15	-0.586	3.222	-3.808
20	16	-6.737	-2.343	-4.394
20	17	-2.050	3.808	-5.859
20	18	-4.394	-0.586	-3.808
20	19	12.303	16.404	-4.101
20	20	1.758	6.737	-4.980
20	21	-5.859	-1.465	-4.394
20	22	-4.980	-1.758	-3.222
20	23	-6.152	-1.172	-4.980
20	24	-6.737	-2.343	-4.394
20	25	2.636	4.101	-1.465
20	26	3.515	-6.152	9.667
20	27	-14.939	4.394	-19.333
20	28	3.515	4.687	-1.172
20	29	1.172	-3.222	4.394
20	30	-4.394	-0.586	-3.808
20	31	-4.101	4.687	-8.788
20	32	2.636	-7.030	9.667
20	33	-8.788	8.202	-16.990
20	34	-9.667	-12.010	2.344
20	35	7.616	4.394	3.222
20	36	3.515	-0.293	3.808
20	37	-5.273	-4.101	-1.172
20	38	8.495	6.444	2.050
20	39	0.000	-0.586	0.586
20	40	-3.222	-3.808	0.586
20	41	-0.293	0.293	-0.586
20	42	8.202	8.788	-0.586
20	43	-2.343	-0.293	-2.051
20	44	0.879	0.293	0.586
20	45	3.222	4.394	-1.172
20	46	-2.636	-2.343	-0.293
20	47	9.081	7.323	1.758
20	48	4.394	4.394	0.000
20	49	-2.636	-3.515	0.879
20	50	-4.101	-4.101	0.000
20	51	0.586	-0.586	1.172
20	52	0.586	0.000	0.586
20	53	-1.758	-1.172	-0.586
20	54	-2.050	-1.758	-0.293
20	55	3.222	3.222	0.000
20	56	-5.859	-4.687	-1.172
30	1	4.980	6.152	-1.172
30	2	-11.131	-8.495	-2.636
30	3	6.737	9.374	-2.636
30	4	-10.252	-4.980	-5.273
30	5	6.444	13.182	-6.737
30	62	6.152	6.444	-0.293
30	63	-7.323	-7.323	0.000
30	64	-10.545	-8.495	-2.050
30	65	-5.566	-4.101	-1.465
30	66	-5.566	-5.273	-0.293
	Max	17.576	18.455	18.747
	Average	0.158	1.892	-1.734
	Min	-14.939	-12.010	-21.384
	Std Dev	6.744	7.324	6.061

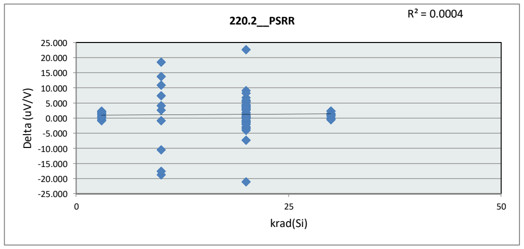


	220.1__PSRR			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	96	uV/V		
Min Limit	-96	uV/V		
krad(Si)	3	10	20	30
LL	-96.000	-96.000	-96.000	-96.000
Min	-10.838	-8.202	-12.010	-8.495
Average	3.486	4.306	1.509	-0.352
Max	18.455	18.455	16.404	13.182
UL	96.000	96.000	96.000	96.000

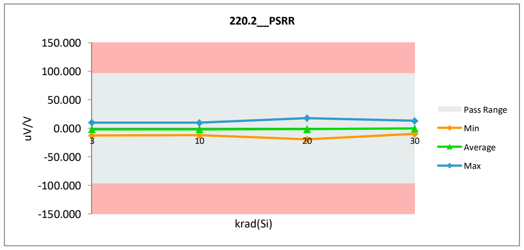


TID LDR Report
TLV1704-SEP

		220.2__PSRR		
	Test Site	MLA	MLA	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	uV/V	uV/V	
	Max Limit	96	96	
	Min Limit	-96	-96	
krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	9.374	7.323	2.050
3	2	-5.566	-7.030	1.465
3	3	-6.152	-8.495	2.343
3	4	4.687	3.515	1.172
3	5	-8.495	-10.252	1.758
3	6	9.374	9.960	-0.586
3	7	-13.768	-12.889	-0.879
3	8	0.293	0.293	0.000
3	9	5.566	4.980	0.586
3	0	-4.101	-4.394	0.293
10	1	-2.343	8.202	-10.545
10	2	5.566	-8.202	13.768
10	3	-5.566	-8.202	2.636
10	4	-15.232	3.515	-18.747
10	5	-0.293	-11.131	10.838
10	6	8.788	9.667	-0.879
10	7	6.152	-12.303	18.455
10	8	4.394	0.293	4.101
10	9	-12.303	5.273	-17.576
10	10	2.636	-4.687	7.323
20	11	-2.343	-5.859	3.515
20	12	5.566	1.465	4.101
20	13	-5.566	-11.131	5.566
20	14	-15.232	-19.626	4.394
20	15	-0.293	-4.394	4.101
20	16	8.788	4.394	4.394
20	17	6.152	-0.586	6.737
20	18	4.394	1.172	3.222
20	19	-12.303	-13.475	1.172
20	20	2.636	-2.636	5.273
20	21	6.152	0.293	5.859
20	22	-10.252	-12.889	2.636
20	23	5.566	1.758	3.808
20	24	5.859	0.293	5.566
20	25	-2.636	-7.030	4.394
20	26	-0.879	2.636	-3.515
20	27	6.737	2.929	3.808
20	28	4.687	7.909	-3.222
20	29	11.424	-11.131	22.556
20	30	-7.909	-3.808	-4.101
20	31	-0.586	-9.667	9.081
20	32	-6.737	0.586	-7.323
20	33	3.222	-4.980	8.202
20	34	12.596	9.960	2.636
20	35	-4.394	-3.222	-1.172
20	36	-4.394	-1.465	-2.929
20	37	7.616	4.687	2.929
20	38	-1.172	0.293	-1.465
20	39	-7.030	-4.980	-2.050
20	40	-4.980	-7.909	2.929
20	41	8.788	7.030	1.758
20	42	-10.838	-8.788	-2.050
20	43	-3.222	17.869	-21.091
20	44	0.586	0.293	0.293
20	45	10.545	8.788	1.757
20	46	-7.323	-5.273	-2.051
20	47	-15.818	-14.939	-0.879
20	48	3.222	2.343	0.879
20	49	-7.030	-6.152	-0.879
20	50	-11.424	-10.252	-1.172
20	51	4.101	3.808	0.293
20	52	9.667	9.081	0.586
20	53	0.586	0.586	0.000
20	54	4.980	5.273	-0.293
20	55	9.374	9.081	0.293
20	56	1.758	1.758	0.000
30	1	9.374	7.030	2.343
30	2	-5.566	-6.737	1.172
30	3	-6.152	-6.737	0.586
30	4	4.687	2.343	2.344
30	5	-8.495	-9.960	1.465
30	62	0.000	0.000	0.000
30	63	-5.566	-4.980	-0.586
30	64	0.000	0.293	-0.293
30	65	14.646	13.182	1.465
30	66	1.758	0.879	0.879
	Max	14.646	17.869	22.556
	Average	-0.127	-1.384	1.257
	Min	-15.818	-19.626	-21.091
	Std Dev	7.447	7.498	6.314

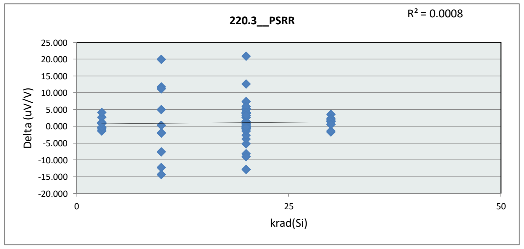


	220.2__PSRR			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	96	uV/V		
Min Limit	-96	uV/V		
krad(Si)	3	10	20	30
LL	-96.000	-96.000	-96.000	-96.000
Min	-12.889	-12.303	-19.626	-9.960
Average	-1.699	-1.758	-1.433	-0.469
Max	9.960	9.667	17.869	13.182
UL	96.000	96.000	96.000	96.000

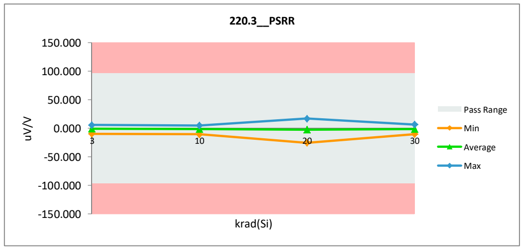


TID LDR Report
TLV1704-SEP

		220.3__PSRR		
	Test Site	MLA	MLA	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	uV/V	uV/V	
	Max Limit	96	96	
	Min Limit	-96	-96	
krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	3.222	2.050	1.172
3	2	8.495	5.859	2.636
3	3	-0.293	-4.394	4.101
3	4	-2.050	-2.929	0.879
3	5	-9.667	-9.374	-0.293
3	6	4.101	5.566	-1.465
3	7	0.586	1.172	-0.586
3	8	4.394	5.566	-1.172
3	9	-1.758	-1.465	-0.293
3	0	-8.788	-9.667	0.879
10	1	-0.879	1.172	-2.050
10	2	-7.323	4.980	-12.303
10	3	-0.293	-5.273	4.980
10	4	-4.101	-2.050	-2.050
10	5	1.172	-10.545	11.717
10	6	-3.222	4.394	-7.616
10	7	12.010	0.879	11.131
10	8	-9.667	4.687	-14.354
10	9	-1.758	-2.050	0.293
10	10	11.424	-8.495	19.919
20	11	-0.879	-5.859	4.980
20	12	-7.323	-9.960	2.636
20	13	-0.293	-4.394	4.101
20	14	-4.101	-6.737	2.636
20	15	1.172	-2.636	3.808
20	16	-3.222	-7.030	3.808
20	17	12.010	6.737	5.273
20	18	-9.667	-11.131	1.465
20	19	-1.758	-6.737	4.980
20	20	11.424	4.101	7.323
20	21	-6.444	-12.303	5.859
20	22	-0.586	-4.687	4.101
20	23	-24.606	-25.485	0.879
20	24	-0.586	-4.394	3.808
20	25	15.232	12.596	2.636
20	26	-5.273	-17.869	12.596
20	27	-13.182	-13.475	0.293
20	28	-10.252	-2.050	-8.202
20	29	-1.465	-4.687	3.222
20	30	-4.687	-5.566	0.879
20	31	-2.343	10.545	-12.889
20	32	11.424	-9.374	20.798
20	33	-5.859	-9.960	4.101
20	34	1.758	1.758	0.000
20	35	-4.394	-3.808	-0.586
20	36	-3.222	2.050	-5.273
20	37	10.838	9.374	1.465
20	38	-14.939	-14.354	-0.586
20	39	-13.475	-12.889	-0.586
20	40	8.202	8.788	-0.586
20	41	-15.525	-11.717	-3.808
20	42	3.515	3.808	-0.293
20	43	-4.687	4.394	-9.081
20	44	-9.081	-7.616	-1.465
20	45	1.172	1.172	0.000
20	46	-6.737	-6.152	-0.586
20	47	-5.273	-2.636	-2.636
20	48	18.455	16.990	1.465
20	49	3.515	4.101	-0.586
20	50	9.081	8.495	0.586
20	51	11.131	11.424	-0.293
20	52	0.879	2.343	-1.465
20	53	5.566	5.566	0.000
20	54	-1.172	-0.293	-0.879
20	55	-4.394	-4.101	-0.293
20	56	13.475	10.252	3.222
30	1	3.222	1.465	1.758
30	2	8.495	4.980	3.515
30	3	-0.293	-2.636	2.343
30	4	-2.050	-4.101	2.050
30	5	-9.667	-10.252	0.586
30	62	4.394	2.929	1.465
30	63	-4.101	-2.343	-1.758
30	64	8.202	6.737	1.465
30	65	-2.929	-1.465	-1.465
30	66	-5.566	-6.152	0.586
	Max	18.455	16.990	20.798
	Average	-0.675	-1.765	1.091
	Min	-24.606	-25.485	-14.354
	Std Dev	7.936	7.715	5.604

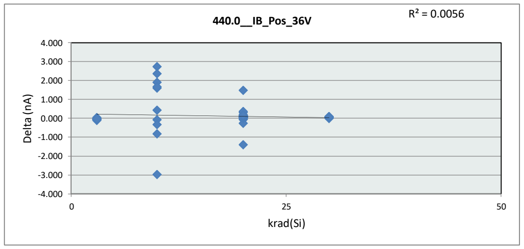


	220.3__PSRR			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	96	uV/V		
Min Limit	-96	uV/V		
krad(Si)	3	10	20	30
LL	-96.000	-96.000	-96.000	-96.000
Min	-9.667	-10.545	-25.485	-10.253
Average	-0.762	-1.230	-2.248	-1.084
Max	5.859	4.980	16.990	6.737
UL	96.000	96.000	96.000	96.000

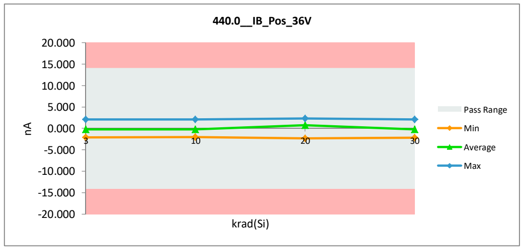


TID LDR Report
TLV1704-SEP

		440.0__IB_Pos_36V		
	Test Site	MLA	MLA	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	nA	nA	
	Max Limit	14	14	
	Min Limit	-14	-14	
krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	-2.168	-2.092	-0.075
3	2	-0.596	-0.529	-0.067
3	3	-0.804	-0.682	-0.122
3	4	-1.791	-1.735	-0.057
3	5	2.151	2.120	0.030
3	6	0.068	0.123	-0.054
3	7	0.043	0.104	-0.061
3	8	-0.393	-0.323	-0.070
3	9	0.516	0.547	-0.030
3	0	0.477	0.524	-0.047
10	1	0.699	-2.026	2.725
10	2	1.086	-0.506	1.592
10	3	-0.770	-0.675	-0.095
10	4	-1.273	-1.693	0.420
10	5	-0.884	2.093	-2.977
10	6	1.996	0.103	1.893
10	7	-0.280	0.058	-0.338
10	8	1.969	-0.371	2.340
10	9	2.158	0.507	1.651
10	10	-0.355	0.478	-0.833
20	11	0.699	0.658	0.041
20	12	1.086	1.027	0.058
20	13	-0.770	-0.811	0.041
20	14	-1.273	-1.308	0.035
20	15	-0.884	-0.920	0.036
20	16	1.996	1.956	0.040
20	17	-0.280	-0.335	0.056
20	18	1.969	1.924	0.045
20	19	2.158	2.126	0.032
20	20	-0.355	-0.417	0.062
20	21	-0.016	-0.100	0.084
20	22	2.194	2.175	0.018
20	23	1.875	1.825	0.051
20	24	2.077	2.035	0.042
20	25	1.971	1.920	0.052
20	26	2.020	2.056	-0.036
20	27	2.097	1.805	0.292
20	28	1.845	1.916	-0.071
20	29	1.964	2.038	-0.074
20	30	2.080	1.722	0.358
20	31	1.750	1.792	-0.041
20	32	1.834	2.109	-0.275
20	33	2.152	1.969	0.183
20	34	2.276	2.263	0.013
20	35	2.221	2.199	0.022
20	36	1.809	0.343	1.466
20	37	2.088	2.072	0.016
20	38	1.853	1.839	0.015
20	39	2.122	2.109	0.013
20	40	1.766	1.756	0.010
20	41	2.295	2.266	0.029
20	42	-0.233	-0.367	0.135
20	43	-1.329	0.088	-1.417
20	44	-0.116	-0.231	0.115
20	45	2.153	2.086	0.068
20	46	-0.197	-0.307	0.111
20	47	2.432	2.346	0.086
20	48	1.938	1.874	0.064
20	49	-0.585	-0.702	0.117
20	50	-1.687	-1.793	0.106
20	51	-2.193	-2.323	0.130
20	52	-0.855	-0.975	0.120
20	53	-0.728	-0.850	0.123
20	54	-1.131	-1.249	0.118
20	55	-2.002	-2.131	0.128
20	56	-1.898	-2.024	0.126
30	1	-2.168	-2.185	0.018
30	2	-0.596	-0.612	0.016
30	3	-0.804	-0.784	-0.021
30	4	-1.791	-1.818	0.026
30	5	2.151	2.105	0.046
30	62	-0.340	-0.401	0.061
30	63	0.665	0.591	0.074
30	64	-0.332	-0.402	0.069
30	65	-0.375	-0.454	0.079
30	66	2.068	2.001	0.067
	Max	2.432	2.346	2.725
	Average	0.507	0.388	0.118
	Min	-2.193	-2.323	-2.977
	Std Dev	1.479	1.464	0.686



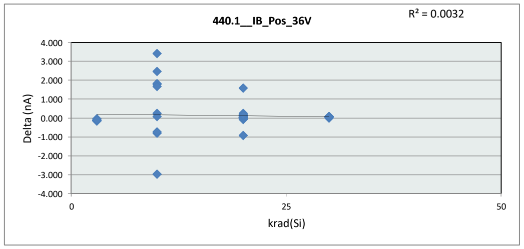
	440.0__IB_Pos_36V			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	14	nA		
Min Limit	-14	nA		
krad(Si)	3	10	20	30
LL	-14.000	-14.000	-14.000	-14.000
Min	-2.093	-2.027	-2.323	-2.185
Average	-0.194	-0.203	0.771	-0.196
Max	2.120	2.094	2.346	2.105
UL	14.000	14.000	14.000	14.000



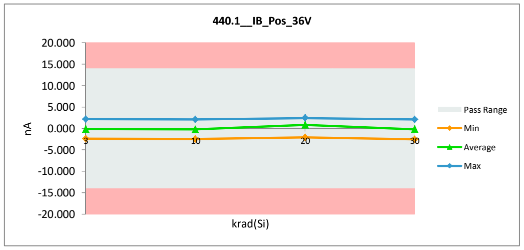
TID LDR Report
TLV1704-SEP

	440.1__IB_Pos_36V	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	nA	nA
Max Limit	14	14
Min Limit	-14	-14

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	-2.540	-2.420	-0.120
3	2	-0.773	-0.656	-0.117
3	3	-0.971	-0.845	-0.126
3	4	-1.242	-1.091	-0.152
3	5	2.155	2.199	-0.044
3	6	-0.143	-0.016	-0.127
3	7	-0.080	0.065	-0.145
3	8	-0.221	-0.099	-0.122
3	9	0.628	0.730	-0.102
3	0	0.639	0.742	-0.102
10	1	0.980	-2.440	3.420
10	2	1.085	-0.698	1.782
10	3	-0.663	-0.912	0.250
10	4	-1.093	-1.178	0.084
10	5	-0.835	2.129	-2.964
10	6	1.712	-0.107	1.819
10	7	-0.865	-0.060	-0.804
10	8	2.265	-0.198	2.463
10	9	2.307	0.640	1.667
10	10	-0.092	0.637	-0.730
20	11	0.980	0.952	0.027
20	12	1.085	1.045	0.039
20	13	-0.663	-0.692	0.030
20	14	-1.093	-1.109	0.015
20	15	-0.835	-0.861	0.027
20	16	1.712	1.676	0.036
20	17	-0.865	-0.892	0.027
20	18	2.265	2.230	0.035
20	19	2.307	2.270	0.037
20	20	-0.092	-0.128	0.036
20	21	0.099	0.046	0.053
20	22	1.840	1.812	0.027
20	23	2.081	2.048	0.033
20	24	2.228	2.205	0.023
20	25	1.725	1.703	0.022
20	26	2.143	2.169	-0.026
20	27	2.202	1.948	0.254
20	28	1.977	1.941	0.035
20	29	1.973	1.999	-0.026
20	30	2.036	2.108	-0.071
20	31	2.129	2.184	-0.055
20	32	2.214	2.038	0.176
20	33	2.061	2.112	-0.051
20	34	2.364	2.347	0.017
20	35	2.457	2.438	0.018
20	36	2.002	0.416	1.586
20	37	2.264	2.255	0.009
20	38	2.349	2.344	0.005
20	39	2.123	2.122	0.001
20	40	1.834	1.822	0.012
20	41	2.030	1.974	0.056
20	42	-0.121	-0.287	0.166
20	43	-1.163	-0.249	-0.914
20	44	0.340	0.199	0.141
20	45	2.161	2.071	0.090
20	46	-0.338	-0.487	0.150
20	47	2.067	1.975	0.092
20	48	2.488	2.394	0.094
20	49	-0.450	-0.590	0.140
20	50	-1.076	-1.235	0.159
20	51	-1.217	-1.362	0.145
20	52	-1.266	-1.382	0.116
20	53	-0.943	-1.090	0.147
20	54	-0.869	-1.024	0.155
20	55	-1.931	-2.082	0.151
20	56	-1.620	-1.775	0.155
30	1	-2.540	-2.544	0.004
30	2	-0.773	-0.790	0.017
30	3	-0.971	-0.979	0.008
30	4	-1.242	-1.261	0.018
30	5	2.155	2.126	0.029
30	62	-0.430	-0.502	0.071
30	63	0.418	0.336	0.082
30	64	-0.058	-0.134	0.076
30	65	-0.039	-0.124	0.085
30	66	2.142	2.059	0.082
	Max	2.488	2.438	3.420
	Average	0.578	0.450	0.128
	Min	-2.540	-2.544	-2.964
	Std Dev	1.480	1.473	0.728



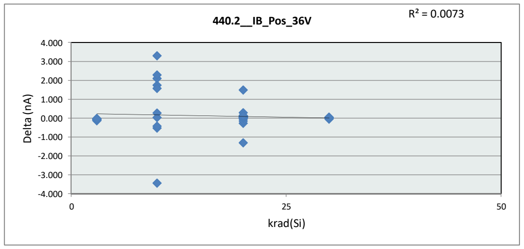
	440.1__IB_Pos_36V			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	14	nA		
Min Limit	-14	nA		
krad(Si)	3	10	20	30
LL	-14.000	-14.000	-14.000	-14.000
Min	-2.420	-2.440	-2.082	-2.544
Average	-0.139	-0.219	0.861	-0.181
Max	2.199	2.129	2.438	2.127
UL	14.000	14.000	14.000	14.000



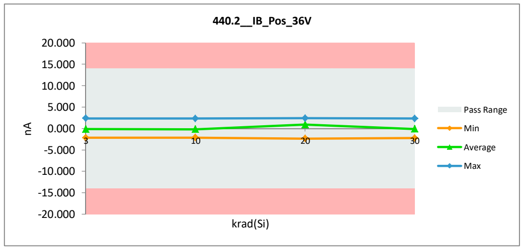
TID LDR Report
TLV1704-SEP

	440.2__IB_Pos_36V	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	nA	nA
Max Limit	14	14
Min Limit	-14	-14

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	-2.278	-2.168	-0.109
3	2	-0.712	-0.635	-0.077
3	3	-1.086	-0.971	-0.115
3	4	-0.937	-0.802	-0.135
3	5	2.349	2.365	-0.016
3	6	-0.066	-0.010	-0.056
3	7	-0.127	-0.051	-0.077
3	8	-0.333	-0.279	-0.054
3	9	0.732	0.780	-0.048
3	0	0.176	0.208	-0.032
10	1	1.175	-2.114	3.288
10	2	1.125	-0.610	1.736
10	3	-0.724	-0.991	0.266
10	4	-1.354	-0.825	-0.528
10	5	-1.086	2.356	-3.442
10	6	2.065	-0.023	2.087
10	7	-0.070	-0.106	0.036
10	8	1.953	-0.324	2.277
10	9	2.284	0.720	1.564
10	10	-0.245	0.185	-0.430
20	11	1.175	1.153	0.022
20	12	1.125	1.097	0.029
20	13	-0.724	-0.748	0.024
20	14	-1.354	-1.358	0.004
20	15	-1.086	-1.106	0.021
20	16	2.065	2.058	0.007
20	17	-0.070	-0.085	0.015
20	18	1.953	1.950	0.003
20	19	2.284	2.226	0.058
20	20	-0.245	-0.258	0.013
20	21	-0.002	-0.023	0.021
20	22	2.063	2.054	0.010
20	23	1.834	1.812	0.022
20	24	2.214	2.191	0.024
20	25	1.903	1.887	0.015
20	26	2.059	2.342	-0.282
20	27	2.336	2.061	0.275
20	28	2.074	2.082	-0.008
20	29	2.101	2.149	-0.048
20	30	2.171	2.100	0.071
20	31	2.132	1.998	0.134
20	32	2.010	1.911	0.099
20	33	1.892	2.042	-0.150
20	34	2.137	2.146	-0.009
20	35	2.304	2.290	0.014
20	36	2.070	0.579	1.491
20	37	2.425	2.417	0.009
20	38	2.312	2.297	0.015
20	39	2.383	2.347	0.036
20	40	2.122	2.110	0.011
20	41	2.111	2.093	0.017
20	42	-0.397	-0.526	0.128
20	43	-1.050	0.257	-1.307
20	44	0.391	0.292	0.099
20	45	2.406	2.373	0.033
20	46	-0.218	-0.309	0.090
20	47	2.294	2.260	0.033
20	48	2.035	2.003	0.032
20	49	-0.351	-0.444	0.093
20	50	-1.039	-1.146	0.107
20	51	-1.984	-2.100	0.116
20	52	-0.618	-0.704	0.086
20	53	-1.238	-1.339	0.101
20	54	-1.184	-1.281	0.097
20	55	-2.251	-2.351	0.100
20	56	-1.761	-1.866	0.105
30	1	-2.278	-2.227	-0.051
30	2	-0.712	-0.718	0.006
30	3	-1.086	-1.072	-0.014
30	4	-0.937	-0.933	-0.004
30	5	2.349	2.353	-0.004
30	62	-0.300	-0.329	0.030
30	63	0.425	0.394	0.031
30	64	-0.353	-0.392	0.039
30	65	-0.394	-0.433	0.038
30	66	2.336	2.300	0.036
	Max	2.425	2.417	3.288
	Average	0.588	0.481	0.107
	Min	-2.278	-2.351	-3.442
	Std Dev	1.509	1.491	0.745

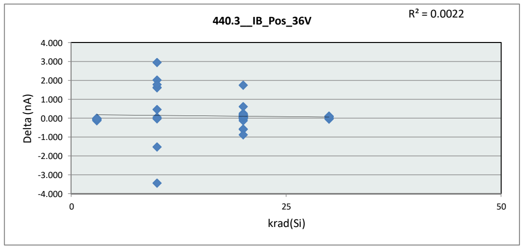


	440.2__IB_Pos_36V			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	14	nA		
Min Limit	-14	nA		
krad(Si)	3	10	20	30
LL	-14.000	-14.000	-14.000	-14.000
Min	-2.168	-2.114	-2.351	-2.227
Average	-0.156	-0.173	0.890	-0.106
Max	2.365	2.356	2.417	2.353
UL	14.000	14.000	14.000	14.000

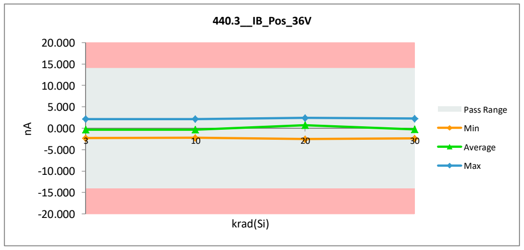


TID LDR Report
TLV1704-SEP

		440.3__IB_Pos_36V		
	Test Site	MLA	MLA	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	nA	nA	
	Max Limit	14	14	
	Min Limit	-14	-14	
krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	-2.398	-2.291	-0.107
3	2	-0.766	-0.686	-0.080
3	3	-1.204	-1.105	-0.100
3	4	-1.561	-1.414	-0.147
3	5	2.142	2.149	-0.007
3	6	-0.133	-0.083	-0.050
3	7	-0.187	-0.133	-0.054
3	8	-0.349	-0.297	-0.052
3	9	0.118	0.159	-0.041
3	0	0.398	0.435	-0.037
10	1	0.710	-2.236	2.945
10	2	0.956	-0.662	1.618
10	3	-0.654	-1.098	0.444
10	4	-1.316	-1.366	0.050
10	5	-1.293	2.148	-3.441
10	6	1.929	-0.079	2.008
10	7	-0.211	-0.172	-0.039
10	8	1.269	-0.335	1.604
10	9	1.881	0.118	1.763
10	10	-1.131	0.404	-1.535
20	11	0.710	0.692	0.018
20	12	0.956	0.938	0.018
20	13	-0.654	-0.694	0.040
20	14	-1.316	-1.320	0.004
20	15	-1.293	-1.305	0.012
20	16	1.929	1.900	0.029
20	17	-0.211	-0.258	0.047
20	18	1.269	1.870	-0.601
20	19	1.881	1.846	0.035
20	20	-1.131	-1.162	0.032
20	21	-0.118	-0.166	0.048
20	22	2.004	1.994	0.010
20	23	1.820	1.812	0.008
20	24	1.992	1.970	0.022
20	25	2.069	2.039	0.030
20	26	2.029	1.786	0.242
20	27	1.810	2.391	-0.581
20	28	2.417	1.811	0.606
20	29	1.819	1.867	-0.047
20	30	1.896	1.955	-0.059
20	31	1.986	1.886	0.100
20	32	1.912	1.837	0.076
20	33	1.867	2.012	-0.145
20	34	1.852	1.821	0.031
20	35	1.964	1.930	0.034
20	36	1.975	0.245	1.730
20	37	2.167	2.142	0.025
20	38	2.199	2.174	0.025
20	39	2.270	2.232	0.038
20	40	1.895	1.867	0.028
20	41	2.057	1.912	0.145
20	42	-0.511	-0.699	0.188
20	43	-1.213	-0.330	-0.883
20	44	-0.066	-0.230	0.164
20	45	2.431	2.313	0.118
20	46	-0.124	-0.287	0.163
20	47	2.529	2.414	0.115
20	48	2.430	2.314	0.116
20	49	-0.630	-0.770	0.140
20	50	-0.939	-1.108	0.169
20	51	-1.995	-2.192	0.197
20	52	-0.738	-0.887	0.150
20	53	-1.305	-1.404	0.099
20	54	-1.295	-1.459	0.164
20	55	-2.367	-2.532	0.165
20	56	-1.788	-1.954	0.166
30	1	-2.398	-2.381	-0.017
30	2	-0.766	-0.765	-0.001
30	3	-1.204	-1.216	0.011
30	4	-1.561	-1.505	-0.056
30	5	2.142	2.124	0.018
30	62	-0.382	-0.475	0.093
30	63	0.433	0.346	0.088
30	64	-0.275	-0.367	0.092
30	65	-0.391	-0.491	0.100
30	66	2.338	2.257	0.081
	Max	2.529	2.414	2.945
	Average	0.429	0.318	0.110
	Min	-2.398	-2.532	-3.441
	Std Dev	1.512	1.508	0.729



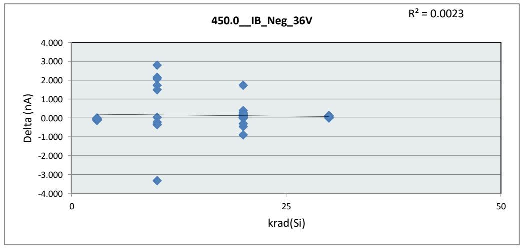
	440.3__IB_Pos_36V			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	14	nA		
Min Limit	-14	nA		
krad(Si)	3	10	20	30
LL	-14.000	-14.000	-14.000	-14.000
Min	-2.291	-2.236	-2.532	-2.381
Average	-0.327	-0.328	0.722	-0.247
Max	2.149	2.148	2.414	2.257
UL	14.000	14.000	14.000	14.000



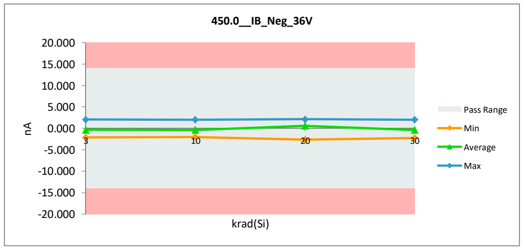
TID LDR Report
TLV1704-SEP

	450.0__IB_Neg_36V	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	nA	nA
Max Limit	14	14
Min Limit	-14	-14

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	-2.259	-2.143	-0.116
3	2	-1.085	-0.986	-0.099
3	3	-1.154	-1.063	-0.092
3	4	-1.388	-1.253	-0.135
3	5	2.038	2.038	0.000
3	6	-0.228	-0.177	-0.051
3	7	-0.310	-0.239	-0.071
3	8	-0.339	-0.273	-0.066
3	9	0.424	0.483	-0.059
3	0	0.045	0.080	-0.036
10	1	0.740	-2.054	2.794
10	2	0.560	-0.927	1.487
10	3	-1.383	-1.047	-0.336
10	4	-1.229	-1.254	0.025
10	5	-1.307	2.022	-3.330
10	6	1.963	-0.189	2.152
10	7	-0.528	-0.298	-0.230
10	8	1.741	-0.325	2.067
10	9	2.148	0.430	1.719
10	10	-0.315	0.043	-0.358
20	11	0.740	0.718	0.022
20	12	0.560	0.527	0.033
20	13	-1.383	-1.399	0.015
20	14	-1.229	-1.239	0.010
20	15	-1.307	-1.325	0.018
20	16	1.963	1.962	0.001
20	17	-0.528	-0.557	0.029
20	18	1.741	1.722	0.020
20	19	2.148	2.132	0.017
20	20	-0.315	-0.374	0.059
20	21	-0.181	-0.226	0.045
20	22	1.646	1.620	0.026
20	23	1.837	1.822	0.015
20	24	1.662	1.651	0.011
20	25	1.788	1.785	0.004
20	26	1.959	1.800	0.159
20	27	1.832	1.733	0.099
20	28	1.735	1.463	0.272
20	29	1.490	1.949	-0.459
20	30	1.973	2.003	-0.030
20	31	2.045	1.660	0.386
20	32	1.676	1.984	-0.308
20	33	1.988	1.939	0.049
20	34	2.051	2.043	0.008
20	35	1.799	1.772	0.027
20	36	2.032	0.314	1.718
20	37	1.806	1.794	0.012
20	38	2.102	2.071	0.031
20	39	1.916	1.894	0.022
20	40	1.751	1.730	0.022
20	41	2.125	2.001	0.124
20	42	-0.445	-0.643	0.198
20	43	-1.285	-0.381	-0.904
20	44	-0.175	-0.345	0.170
20	45	2.136	2.020	0.116
20	46	-0.726	-0.899	0.173
20	47	2.133	1.983	0.150
20	48	1.926	1.822	0.104
20	49	-0.554	-0.690	0.136
20	50	-0.858	-1.036	0.178
20	51	-2.121	-2.320	0.199
20	52	-1.097	-1.255	0.158
20	53	-1.099	-1.271	0.172
20	54	-1.427	-1.606	0.178
20	55	-2.456	-2.647	0.191
20	56	-1.946	-2.148	0.202
30	1	-2.259	-2.249	-0.010
30	2	-1.085	-1.085	0.000
30	3	-1.154	-1.179	0.025
30	4	-1.388	-1.389	0.001
30	5	2.038	1.993	0.044
30	62	-0.717	-0.814	0.097
30	63	0.317	0.201	0.116
30	64	-0.729	-0.829	0.100
30	65	-0.253	-0.372	0.119
30	66	2.099	1.988	0.111
	Max	2.148	2.132	2.794
	Average	0.348	0.220	0.128
	Min	-2.456	-2.647	-3.330
	Std Dev	1.483	1.458	0.701



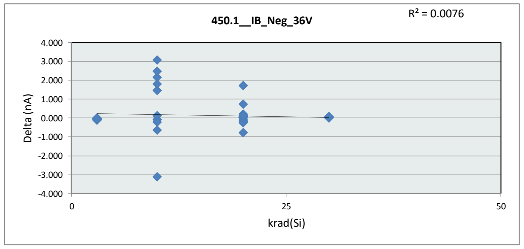
	450.0__IB_Neg_36V			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	14	nA		
Min Limit	-14	nA		
krad(Si)	3	10	20	30
LL	-14.000	-14.000	-14.000	-14.000
Min	-2.143	-2.054	-2.647	-2.249
Average	-0.353	-0.360	0.599	-0.373
Max	2.038	2.022	2.132	1.994
UL	14.000	14.000	14.000	14.000



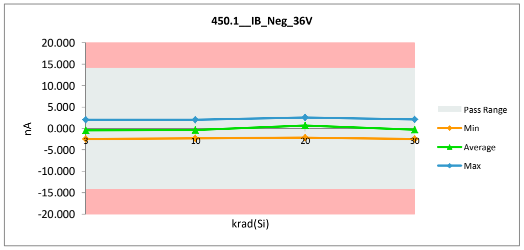
TID LDR Report
TLV1704-SEP

	450.1__IB_Neg_36V	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	nA	nA
Max Limit	14	14
Min Limit	-14	-14

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	-2.507	-2.451	-0.056
3	2	-0.848	-0.755	-0.093
3	3	-1.222	-1.138	-0.084
3	4	-1.374	-1.256	-0.118
3	5	2.028	2.030	-0.002
3	6	-0.140	-0.085	-0.055
3	7	-0.497	-0.442	-0.055
3	8	-0.555	-0.493	-0.062
3	9	0.146	0.169	-0.023
3	0	0.182	0.220	-0.039
10	1	0.716	-2.335	3.051
10	2	0.752	-0.693	1.444
10	3	-1.195	-1.113	-0.083
10	4	-1.480	-1.253	-0.228
10	5	-1.090	2.037	-3.127
10	6	2.046	-0.089	2.135
10	7	-0.353	-0.470	0.117
10	8	1.943	-0.526	2.469
10	9	1.947	0.154	1.793
10	10	-0.453	0.191	-0.645
20	11	0.716	0.687	0.030
20	12	0.752	0.735	0.016
20	13	-1.195	-1.217	0.021
20	14	-1.480	-1.504	0.023
20	15	-1.090	-1.109	0.019
20	16	2.046	2.023	0.023
20	17	-0.353	-0.366	0.013
20	18	1.943	1.923	0.020
20	19	1.947	1.926	0.021
20	20	-0.453	-0.464	0.011
20	21	-0.261	-0.296	0.035
20	22	2.041	2.031	0.009
20	23	1.828	1.808	0.020
20	24	1.598	1.577	0.021
20	25	1.507	1.485	0.021
20	26	1.626	1.471	0.155
20	27	1.500	1.758	-0.258
20	28	1.777	1.938	-0.161
20	29	1.954	1.765	0.190
20	30	1.782	1.855	-0.073
20	31	1.880	2.082	-0.202
20	32	2.102	1.374	0.729
20	33	1.395	1.613	-0.217
20	34	1.976	1.966	0.010
20	35	1.913	1.888	0.026
20	36	1.990	0.293	1.697
20	37	1.872	1.860	0.012
20	38	2.074	2.059	0.015
20	39	2.059	2.042	0.017
20	40	2.584	2.549	0.036
20	41	1.998	1.941	0.057
20	42	-0.423	-0.530	0.107
20	43	-1.017	-0.241	-0.776
20	44	0.178	0.072	0.106
20	45	1.827	1.789	0.039
20	46	-0.138	-0.233	0.095
20	47	1.509	1.453	0.056
20	48	2.010	1.965	0.044
20	49	-0.818	-0.902	0.084
20	50	-0.822	-0.926	0.104
20	51	-1.964	-2.081	0.117
20	52	-1.138	-1.214	0.077
20	53	-1.149	-1.260	0.111
20	54	-1.092	-1.193	0.101
20	55	-2.073	-2.181	0.108
20	56	-1.982	-2.092	0.110
30	1	-2.507	-2.501	-0.005
30	2	-0.848	-0.835	-0.013
30	3	-1.222	-1.222	0.000
30	4	-1.374	-1.388	0.014
30	5	2.028	2.022	0.005
30	62	-0.429	-0.458	0.030
30	63	0.242	0.219	0.023
30	64	-0.470	-0.507	0.037
30	65	-0.257	-0.312	0.055
30	66	2.105	2.064	0.042
	Max	2.584	2.549	3.051
	Average	0.372	0.249	0.123
	Min	-2.507	-2.501	-3.127
	Std Dev	1.459	1.440	0.719

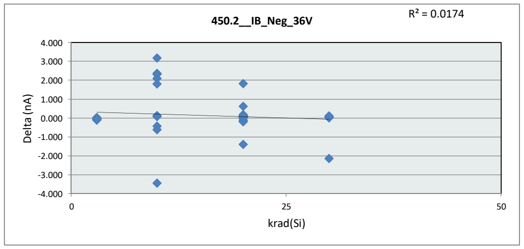


	450.1__IB_Neg_36V			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	14	nA		
Min Limit	-14	nA		
krad(Si)	3	10	20	30
LL	-14.000	-14.000	-14.000	-14.000
Min	-2.451	-2.335	-2.181	-2.501
Average	-0.420	-0.410	0.655	-0.292
Max	2.030	2.037	2.549	2.064
UL	14.000	14.000	14.000	14.000

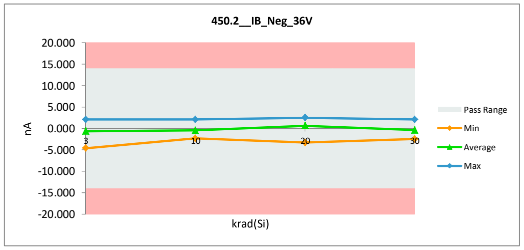


TID LDR Report
TLV1704-SEP

		450.2__IB_Neg_36V		
	Test Site	MLA	MLA	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	nA	nA	
	Max Limit	14	14	
	Min Limit	-14	-14	
krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	-4.612	-4.594	-0.018
3	2	-1.153	-1.080	-0.073
3	3	-1.162	-1.071	-0.091
3	4	-1.575	-1.470	-0.105
3	5	2.132	2.112	0.021
3	6	-0.468	-0.391	-0.077
3	7	-0.183	-0.108	-0.075
3	8	-0.706	-0.632	-0.075
3	9	0.390	0.451	-0.061
3	0	0.393	0.442	-0.049
10	1	0.876	-2.306	3.182
10	2	1.047	-1.045	2.092
10	3	-0.931	-1.059	0.128
10	4	-1.403	-1.476	0.072
10	5	-1.331	2.107	-3.438
10	6	1.968	-0.401	2.369
10	7	-0.587	-0.161	-0.426
10	8	1.626	-0.689	2.315
10	9	2.198	0.400	1.798
10	10	-0.196	0.421	-0.617
20	11	0.876	0.842	0.034
20	12	1.047	0.987	0.060
20	13	-0.931	-0.987	0.056
20	14	-1.403	-1.438	0.034
20	15	-1.331	-1.371	0.040
20	16	1.968	1.926	0.042
20	17	-0.587	-0.663	0.076
20	18	1.626	1.590	0.036
20	19	2.198	2.160	0.038
20	20	-0.196	-0.250	0.054
20	21	-0.186	-0.252	0.067
20	22	1.652	1.608	0.044
20	23	1.907	1.865	0.041
20	24	2.101	2.054	0.047
20	25	2.009	1.968	0.041
20	26	1.801	1.904	-0.103
20	27	1.941	1.765	0.176
20	28	1.792	1.771	0.021
20	29	1.808	1.999	-0.191
20	30	2.038	2.154	-0.116
20	31	2.200	1.586	0.614
20	32	1.639	1.825	-0.187
20	33	1.860	1.753	0.107
20	34	2.121	2.113	0.008
20	35	2.091	2.053	0.038
20	36	1.875	0.053	1.822
20	37	2.517	2.508	0.009
20	38	1.842	1.829	0.013
20	39	2.113	2.093	0.020
20	40	1.372	1.357	0.015
20	41	1.850	1.806	0.043
20	42	-0.341	-0.454	0.113
20	43	-1.349	0.051	-1.399
20	44	-0.075	-0.191	0.116
20	45	1.992	1.946	0.046
20	46	-0.315	-0.427	0.112
20	47	1.760	1.709	0.051
20	48	1.835	1.796	0.039
20	49	-0.598	-0.707	0.109
20	50	-1.206	-1.315	0.109
20	51	-2.123	-2.267	0.144
20	52	-1.003	-1.104	0.101
20	53	-1.223	-1.336	0.113
20	54	-1.432	-1.554	0.123
20	55	-3.174	-3.277	0.103
20	56	-1.981	-2.111	0.130
30	1	-4.612	-2.474	-2.138
30	2	-1.153	-1.179	0.027
30	3	-1.162	-1.177	0.015
30	4	-1.575	-1.615	0.040
30	5	2.132	2.084	0.048
30	62	-0.548	-0.589	0.041
30	63	0.182	0.128	0.054
30	64	-0.199	-0.250	0.051
30	65	-0.792	-0.855	0.062
30	66	2.212	2.104	0.108
	Max	2.517	2.508	3.182
	Average	0.305	0.197	0.108
	Min	-4.612	-4.594	-3.438
	Std Dev	1.677	1.593	0.824



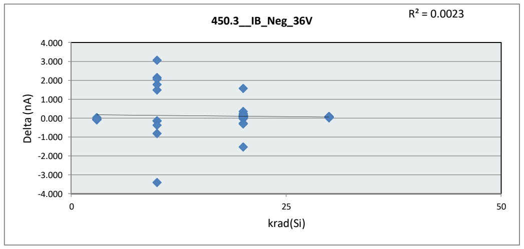
	450.2__IB_Neg_36V			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	14	nA		
Min Limit	-14	nA		
krad(Si)	3	10	20	30
LL	-14.000	-14.000	-14.000	-14.000
Min	-4.594	-2.306	-3.277	-2.474
Average	-0.634	-0.421	0.638	-0.382
Max	2.112	2.107	2.508	2.104
UL	14.000	14.000	14.000	14.000



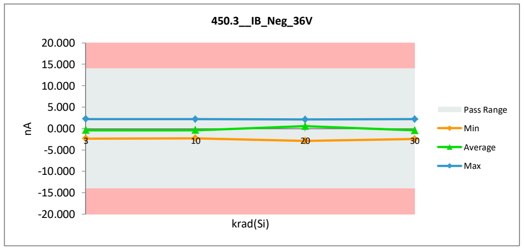
TID LDR Report
TLV1704-SEP

	450.3__IB_Neg_36V	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	nA	nA
Max Limit	14	14
Min Limit	-14	-14

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	-2.420	-2.340	-0.080
3	2	-1.087	-1.028	-0.059
3	3	-1.275	-1.190	-0.085
3	4	-1.477	-1.381	-0.096
3	5	2.233	2.211	0.022
3	6	-0.214	-0.140	-0.074
3	7	-0.150	-0.083	-0.067
3	8	-0.428	-0.352	-0.076
3	9	-0.016	0.060	-0.077
3	0	0.245	0.301	-0.056
10	1	0.796	-2.260	3.056
10	2	0.495	-0.995	1.490
10	3	-1.338	-1.178	-0.160
10	4	-1.530	-1.387	-0.144
10	5	-1.194	2.208	-3.402
10	6	1.614	-0.155	1.769
10	7	-0.503	-0.132	-0.371
10	8	1.736	-0.416	2.152
10	9	2.079	0.018	2.061
10	10	-0.561	0.255	-0.815
20	11	0.796	0.757	0.039
20	12	0.495	0.450	0.045
20	13	-1.338	-1.403	0.065
20	14	-1.530	-1.569	0.038
20	15	-1.194	-1.232	0.037
20	16	1.614	1.576	0.038
20	17	-0.503	-0.547	0.044
20	18	1.736	1.705	0.031
20	19	2.079	2.033	0.046
20	20	-0.561	-0.628	0.067
20	21	-0.232	-0.306	0.075
20	22	1.987	1.948	0.039
20	23	1.827	1.788	0.040
20	24	1.889	1.837	0.052
20	25	2.103	2.071	0.032
20	26	1.949	1.721	0.228
20	27	1.768	1.707	0.061
20	28	1.748	1.632	0.117
20	29	1.679	1.712	-0.033
20	30	1.761	2.041	-0.280
20	31	2.086	1.859	0.226
20	32	1.898	1.555	0.344
20	33	1.606	1.913	-0.307
20	34	1.855	1.839	0.016
20	35	1.857	1.827	0.030
20	36	1.812	0.252	1.560
20	37	1.880	1.864	0.016
20	38	1.936	1.916	0.020
20	39	2.120	2.108	0.012
20	40	1.765	1.750	0.015
20	41	1.911	1.817	0.094
20	42	-0.395	-0.551	0.156
20	43	-1.701	-0.171	-1.530
20	44	-0.255	-0.383	0.128
20	45	1.992	1.905	0.088
20	46	-0.577	-0.722	0.145
20	47	2.016	1.932	0.084
20	48	2.046	1.959	0.087
20	49	-0.831	-0.955	0.124
20	50	-1.132	-1.281	0.149
20	51	-2.510	-2.680	0.170
20	52	-1.851	-1.960	0.109
20	53	-1.606	-1.737	0.130
20	54	-1.398	-1.548	0.150
20	55	-2.709	-2.872	0.163
20	56	-2.059	-2.213	0.154
30	1	-2.420	-2.438	0.019
30	2	-1.087	-1.131	0.043
30	3	-1.275	-1.300	0.025
30	4	-1.477	-1.528	0.051
30	5	2.233	2.182	0.052
30	62	-0.779	-0.839	0.060
30	63	0.342	0.258	0.084
30	64	-0.324	-0.396	0.072
30	65	-0.766	-0.847	0.081
30	66	1.764	1.690	0.074
	Max	2.233	2.211	3.056
	Average	0.277	0.163	0.114
	Min	-2.709	-2.872	-3.402
	Std Dev	1.543	1.523	0.736



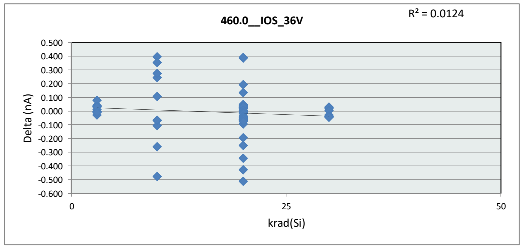
	450.3__IB_Neg_36V			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	14	nA		
Min Limit	-14	nA		
krad(Si)	3	10	20	30
LL	-14.000	-14.000	-14.000	-14.000
Min	-2.340	-2.260	-2.872	-2.438
Average	-0.394	-0.404	0.537	-0.435
Max	2.211	2.208	2.108	2.182
UL	14.000	14.000	14.000	14.000



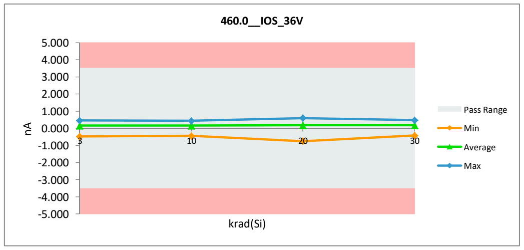
TID LDR Report
TLV1704-SEP

	460.0__IOS_36V	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	nA	nA
Max Limit	3.5	3.5
Min Limit	-3.5	-3.5

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	0.091	0.051	0.041
3	2	0.489	0.457	0.032
3	3	0.350	0.380	-0.030
3	4	-0.403	-0.481	0.078
3	5	0.113	0.082	0.031
3	6	0.296	0.299	-0.003
3	7	0.352	0.343	0.009
3	8	-0.054	-0.050	-0.004
3	9	0.093	0.064	0.029
3	0	0.432	0.443	-0.011
10	1	-0.041	0.027	-0.069
10	2	0.525	0.421	0.104
10	3	0.614	0.372	0.242
10	4	-0.045	-0.439	0.395
10	5	0.424	0.071	0.352
10	6	0.033	0.292	-0.259
10	7	0.248	0.356	-0.108
10	8	0.228	-0.046	0.274
10	9	0.010	0.078	-0.068
10	10	-0.041	0.435	-0.476
20	11	-0.041	-0.060	0.019
20	12	0.525	0.500	0.025
20	13	0.614	0.588	0.026
20	14	-0.045	-0.069	0.024
20	15	0.424	0.405	0.019
20	16	0.033	-0.006	0.039
20	17	0.248	0.222	0.027
20	18	0.228	0.202	0.025
20	19	0.010	-0.006	0.016
20	20	-0.041	-0.043	0.003
20	21	0.164	0.126	0.038
20	22	0.548	0.556	-0.008
20	23	0.038	0.003	0.035
20	24	0.415	0.384	0.031
20	25	0.183	0.135	0.048
20	26	0.060	0.256	-0.195
20	27	0.264	0.072	0.192
20	28	0.110	0.453	-0.343
20	29	0.474	0.090	0.384
20	30	0.107	-0.282	0.388
20	31	-0.295	0.132	-0.427
20	32	0.157	0.124	0.033
20	33	0.164	0.030	0.133
20	34	0.224	0.220	0.005
20	35	0.422	0.427	-0.005
20	36	-0.223	0.028	-0.251
20	37	0.282	0.278	0.005
20	38	-0.249	-0.233	-0.016
20	39	0.206	0.215	-0.010
20	40	0.015	0.026	-0.011
20	41	0.170	0.265	-0.095
20	42	0.213	0.276	-0.063
20	43	-0.043	0.469	-0.512
20	44	0.059	0.113	-0.054
20	45	0.017	0.066	-0.049
20	46	0.530	0.592	-0.062
20	47	0.299	0.363	-0.064
20	48	0.012	0.052	-0.040
20	49	-0.031	-0.013	-0.019
20	50	-0.830	-0.757	-0.073
20	51	-0.072	-0.003	-0.069
20	52	0.242	0.280	-0.038
20	53	0.371	0.420	-0.049
20	54	0.296	0.357	-0.060
20	55	0.454	0.516	-0.062
20	56	0.048	0.124	-0.076
30	1	0.091	0.064	0.028
30	2	0.489	0.473	0.016
30	3	0.350	0.395	-0.046
30	4	-0.403	-0.429	0.025
30	5	0.113	0.111	0.002
30	62	0.377	0.413	-0.036
30	63	0.347	0.389	-0.042
30	64	0.397	0.427	-0.030
30	65	-0.122	-0.082	-0.040
30	66	-0.032	0.013	-0.045
	Max	0.614	0.592	0.395
	Average	0.159	0.169	-0.010
	Min	-0.830	-0.757	-0.512
	Std Dev	0.259	0.261	0.157

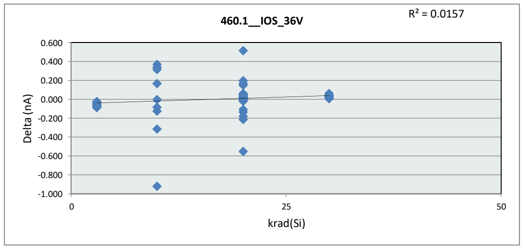


	460.0__IOS_36V			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	3.5	nA		
Min Limit	-3.5	nA		
krad(Si)	3	10	20	30
LL	-3.500	-3.500	-3.500	-3.500
Min	-0.481	-0.439	-0.757	-0.429
Average	0.159	0.157	0.172	0.178
Max	0.457	0.435	0.592	0.473
UL	3.500	3.500	3.500	3.500

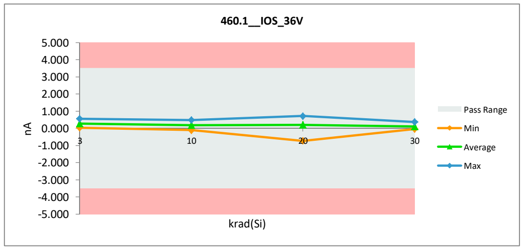


TID LDR Report
TLV1704-SEP

		460.1__IOS_36V		
	Test Site	MLA	MLA	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	nA	nA	
	Max Limit	3.5	3.5	
	Min Limit	-3.5	-3.5	
krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	-0.033	0.031	-0.064
3	2	0.075	0.100	-0.025
3	3	0.250	0.293	-0.042
3	4	0.131	0.165	-0.034
3	5	0.128	0.170	-0.042
3	6	-0.003	0.068	-0.072
3	7	0.417	0.507	-0.090
3	8	0.333	0.393	-0.060
3	9	0.482	0.561	-0.079
3	0	0.457	0.521	-0.064
10	1	0.264	-0.105	0.369
10	2	0.333	-0.005	0.338
10	3	0.533	0.200	0.332
10	4	0.387	0.075	0.312
10	5	0.255	0.093	0.163
10	6	-0.335	-0.018	-0.317
10	7	-0.512	0.410	-0.921
10	8	0.322	0.328	-0.006
10	9	0.360	0.486	-0.126
10	10	0.361	0.446	-0.085
20	11	0.264	0.266	-0.002
20	12	0.333	0.310	0.023
20	13	0.533	0.524	0.009
20	14	0.387	0.395	-0.008
20	15	0.255	0.248	0.008
20	16	-0.335	-0.347	0.012
20	17	-0.512	-0.526	0.014
20	18	0.322	0.307	0.015
20	19	0.360	0.343	0.016
20	20	0.361	0.336	0.025
20	21	0.360	0.342	0.019
20	22	-0.201	-0.219	0.018
20	23	0.253	0.240	0.012
20	24	0.630	0.628	0.002
20	25	0.218	0.218	0.000
20	26	0.517	0.698	-0.181
20	27	0.702	0.190	0.512
20	28	0.200	0.004	0.196
20	29	0.019	0.235	-0.216
20	30	0.255	0.253	0.002
20	31	0.249	0.102	0.146
20	32	0.112	0.664	-0.552
20	33	0.666	0.500	0.166
20	34	0.387	0.380	0.007
20	35	0.544	0.551	-0.007
20	36	0.012	0.123	-0.111
20	37	0.392	0.395	-0.003
20	38	0.276	0.286	-0.010
20	39	0.064	0.080	-0.016
20	40	-0.750	-0.727	-0.023
20	41	0.031	0.032	-0.001
20	42	0.302	0.243	0.059
20	43	-0.146	-0.008	-0.138
20	44	0.161	0.126	0.035
20	45	0.334	0.282	0.052
20	46	-0.199	-0.254	0.055
20	47	0.558	0.522	0.036
20	48	0.479	0.429	0.050
20	49	0.369	0.313	0.056
20	50	-0.255	-0.309	0.055
20	51	0.747	0.720	0.028
20	52	-0.129	-0.168	0.039
20	53	0.206	0.169	0.036
20	54	0.223	0.169	0.054
20	55	0.142	0.099	0.043
20	56	0.362	0.317	0.044
30	1	-0.033	-0.043	0.010
30	2	0.075	0.045	0.030
30	3	0.250	0.243	0.007
30	4	0.131	0.127	0.004
30	5	0.128	0.104	0.024
30	62	-0.001	-0.043	0.042
30	63	0.176	0.117	0.059
30	64	0.412	0.373	0.039
30	65	0.218	0.188	0.030
30	66	0.037	-0.004	0.041
	Max	0.747	0.720	0.512
	Average	0.206	0.201	0.005
	Min	-0.750	-0.727	-0.921
	Std Dev	0.282	0.267	0.175

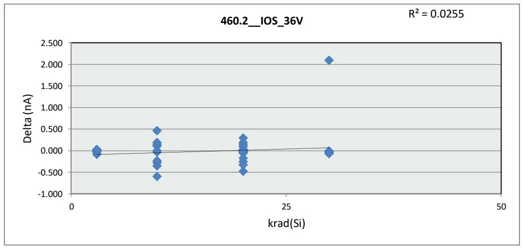


	460.1__IOS_36V			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	3.5	nA		
Min Limit	-3.5	nA		
krad(Si)	3	10	20	30
LL	-3.500	-3.500	-3.500	-3.500
Min	0.031	-0.105	-0.727	-0.043
Average	0.281	0.191	0.206	0.111
Max	0.561	0.486	0.720	0.373
UL	3.500	3.500	3.500	3.500

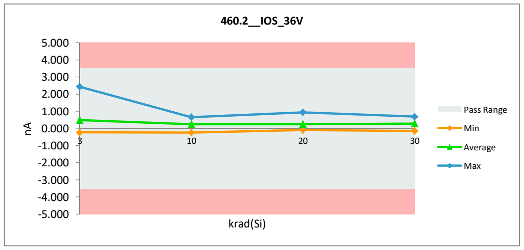


TID LDR Report
TLV1704-SEP

		460.2__IOS_36V		
	Test Site	MLA	MLA	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	nA	nA	
	Max Limit	3.5	3.5	
	Min Limit	-3.5	-3.5	
krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	2.334	2.426	-0.092
3	2	0.440	0.445	-0.005
3	3	0.077	0.101	-0.024
3	4	0.638	0.668	-0.030
3	5	0.216	0.254	-0.037
3	6	0.402	0.381	0.021
3	7	0.056	0.058	-0.001
3	8	0.373	0.352	0.021
3	9	0.343	0.329	0.014
3	0	-0.217	-0.234	0.017
10	1	0.298	0.192	0.106
10	2	0.078	0.435	-0.357
10	3	0.206	0.068	0.138
10	4	0.050	0.651	-0.601
10	5	0.246	0.250	-0.004
10	6	0.096	0.378	-0.282
10	7	0.517	0.055	0.461
10	8	0.327	0.365	-0.038
10	9	0.086	0.320	-0.234
10	10	-0.049	-0.236	0.187
20	11	0.298	0.311	-0.013
20	12	0.078	0.109	-0.031
20	13	0.206	0.239	-0.033
20	14	0.050	0.080	-0.030
20	15	0.246	0.265	-0.019
20	16	0.096	0.132	-0.035
20	17	0.517	0.578	-0.061
20	18	0.327	0.360	-0.033
20	19	0.086	0.066	0.020
20	20	-0.049	-0.008	-0.041
20	21	0.184	0.229	-0.046
20	22	0.411	0.446	-0.035
20	23	-0.072	-0.054	-0.019
20	24	0.113	0.137	-0.023
20	25	-0.106	-0.081	-0.025
20	26	0.258	0.437	-0.179
20	27	0.395	0.297	0.098
20	28	0.282	0.311	-0.029
20	29	0.293	0.150	0.143
20	30	0.133	-0.054	0.187
20	31	-0.068	0.412	-0.480
20	32	0.371	0.086	0.285
20	33	0.032	0.289	-0.257
20	34	0.017	0.033	-0.017
20	35	0.213	0.237	-0.024
20	36	0.195	0.526	-0.331
20	37	-0.092	-0.091	-0.001
20	38	0.470	0.468	0.002
20	39	0.270	0.254	0.016
20	40	0.750	0.753	-0.003
20	41	0.261	0.287	-0.026
20	42	-0.056	-0.072	0.016
20	43	0.299	0.206	0.092
20	44	0.466	0.483	-0.017
20	45	0.414	0.427	-0.013
20	46	0.096	0.119	-0.022
20	47	0.534	0.551	-0.017
20	48	0.200	0.208	-0.008
20	49	0.247	0.263	-0.016
20	50	0.167	0.169	-0.002
20	51	0.140	0.167	-0.028
20	52	0.385	0.400	-0.014
20	53	-0.015	-0.002	-0.013
20	54	0.248	0.273	-0.025
20	55	0.923	0.926	-0.003
20	56	0.220	0.245	-0.026
30	1	2.334	0.248	2.087
30	2	0.440	0.461	-0.021
30	3	0.077	0.106	-0.029
30	4	0.638	0.683	-0.044
30	5	0.216	0.269	-0.052
30	62	0.248	0.259	-0.011
30	63	0.243	0.266	-0.023
30	64	-0.154	-0.142	-0.011
30	65	0.398	0.422	-0.024
30	66	0.124	0.196	-0.072
	Max	2.334	2.426	2.087
	Average	0.283	0.284	-0.001
	Min	-0.217	-0.236	-0.601
	Std Dev	0.399	0.333	0.280

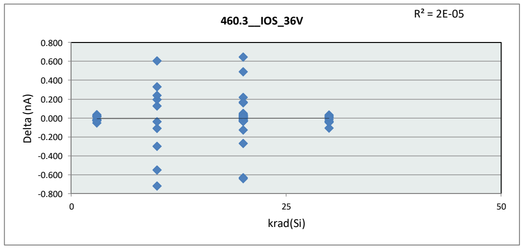


	460.2__IOS_36V			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	3.5	nA		
Min Limit	-3.5	nA		
krad(Si)	3	10	20	30
LL	-3.500	-3.500	-3.500	-3.500
Min	-0.234	-0.236	-0.091	-0.142
Average	0.478	0.248	0.252	0.277
Max	2.426	0.651	0.926	0.683
UL	3.500	3.500	3.500	3.500

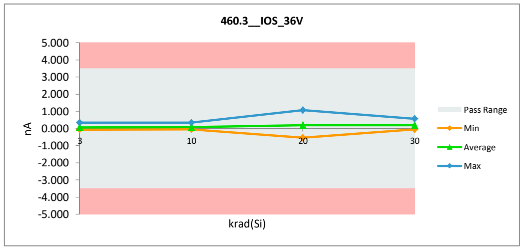


TID LDR Report
TLV1704-SEP

		460.3__IOS_36V		
	Test Site	MLA	MLA	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	nA	nA	
	Max Limit	3.5	3.5	
	Min Limit	-3.5	-3.5	
krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	0.022	0.049	-0.028
3	2	0.322	0.342	-0.020
3	3	0.070	0.085	-0.015
3	4	-0.084	-0.033	-0.051
3	5	-0.091	-0.062	-0.029
3	6	0.080	0.057	0.024
3	7	-0.037	-0.051	0.014
3	8	0.079	0.055	0.024
3	9	0.134	0.099	0.035
3	0	0.154	0.134	0.019
10	1	-0.086	0.025	-0.111
10	2	0.461	0.333	0.128
10	3	0.684	0.080	0.603
10	4	0.215	0.021	0.194
10	5	-0.099	-0.060	-0.038
10	6	0.315	0.076	0.239
10	7	0.292	-0.040	0.332
10	8	-0.467	0.081	-0.548
10	9	-0.198	0.100	-0.298
10	10	-0.570	0.150	-0.720
20	11	-0.086	-0.065	-0.021
20	12	0.461	0.488	-0.027
20	13	0.684	0.709	-0.025
20	14	0.215	0.249	-0.034
20	15	-0.099	-0.074	-0.025
20	16	0.315	0.324	-0.009
20	17	0.292	0.289	0.003
20	18	-0.467	0.165	-0.632
20	19	-0.198	-0.187	-0.011
20	20	-0.570	-0.535	-0.035
20	21	0.114	0.140	-0.027
20	22	0.018	0.046	-0.029
20	23	-0.007	0.024	-0.031
20	24	0.103	0.134	-0.031
20	25	-0.034	-0.032	-0.002
20	26	0.080	0.066	0.014
20	27	0.042	0.683	-0.642
20	28	0.668	0.179	0.489
20	29	0.141	0.155	-0.014
20	30	0.134	-0.086	0.220
20	31	-0.099	0.026	-0.126
20	32	0.014	0.282	-0.268
20	33	0.262	0.100	0.162
20	34	-0.004	-0.019	0.015
20	35	0.107	0.103	0.003
20	36	0.163	-0.007	0.170
20	37	0.287	0.278	0.008
20	38	0.263	0.257	0.005
20	39	0.150	0.124	0.026
20	40	0.130	0.117	0.013
20	41	0.146	0.095	0.051
20	42	-0.116	-0.148	0.032
20	43	0.488	-0.159	0.647
20	44	0.189	0.153	0.036
20	45	0.438	0.408	0.030
20	46	0.452	0.435	0.018
20	47	0.513	0.482	0.031
20	48	0.384	0.355	0.029
20	49	0.202	0.185	0.017
20	50	0.193	0.173	0.020
20	51	0.516	0.488	0.028
20	52	1.113	1.073	0.040
20	53	0.301	0.333	-0.032
20	54	0.103	0.089	0.014
20	55	0.343	0.340	0.002
20	56	0.271	0.259	0.012
30	1	0.022	0.058	-0.036
30	2	0.322	0.366	-0.044
30	3	0.070	0.084	-0.014
30	4	-0.084	0.023	-0.107
30	5	-0.091	-0.058	-0.034
30	62	0.396	0.363	0.033
30	63	0.091	0.088	0.003
30	64	0.049	0.029	0.020
30	65	0.375	0.356	0.019
30	66	0.574	0.568	0.007
	Max	1.113	1.073	0.647
	Average	0.152	0.155	-0.004
	Min	-0.570	-0.535	-0.720
	Std Dev	0.283	0.230	0.207



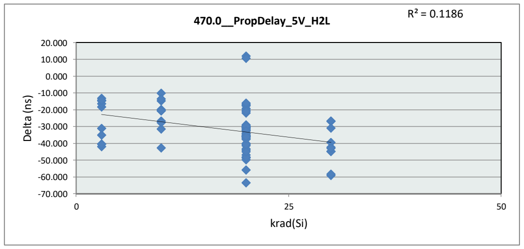
	460.3__IOS_36V			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	3.5	nA		
Min Limit	-3.5	nA		
krad(Si)	3	10	20	30
LL	-3.500	-3.500	-3.500	-3.500
Min	-0.062	-0.060	-0.535	-0.058
Average	0.068	0.077	0.185	0.188
Max	0.342	0.333	1.073	0.568
UL	3.500	3.500	3.500	3.500



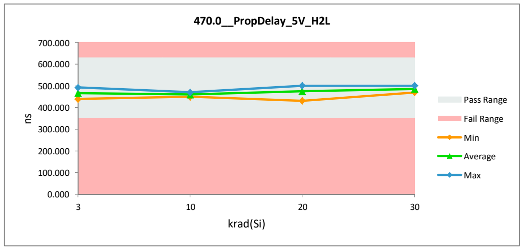
TID LDR Report
TLV1704-SEP

	470.0__PropDelay_5V_H2L	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	ns	ns
Max Limit	630	630
Min Limit	350	350

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	461.020	492.098	-31.078
3	2	446.849	487.265	-40.416
3	3	442.984	485.012	-42.028
3	4	443.591	483.997	-40.407
3	5	438.433	473.491	-35.057
3	6	435.135	448.457	-13.322
3	7	437.994	456.419	-18.424
3	8	439.635	456.146	-16.511
3	9	424.193	439.026	-14.834
3	0	430.230	444.594	-14.364
10	1	427.517	470.232	-42.715
10	2	429.475	461.052	-31.576
10	3	439.353	460.064	-20.711
10	4	445.428	460.147	-14.719
10	5	447.458	457.737	-10.279
10	6	441.717	461.569	-19.852
10	7	435.201	461.987	-26.786
10	8	436.035	463.773	-27.738
10	9	436.060	449.741	-13.681
10	10	434.003	454.666	-20.663
20	11	427.517	446.848	-19.330
20	12	429.475	447.190	-17.714
20	13	439.353	457.053	-17.700
20	14	445.428	462.249	-16.821
20	15	447.458	463.666	-16.208
20	16	441.717	474.247	-32.531
20	17	435.201	455.574	-20.372
20	18	436.035	469.994	-33.959
20	19	436.060	484.808	-48.749
20	20	434.003	456.004	-22.001
20	21	435.808	456.793	-20.986
20	22	440.802	471.782	-30.979
20	23	443.153	479.079	-35.925
20	24	445.000	479.456	-34.456
20	25	436.519	480.538	-44.019
20	26	439.842	470.304	-30.462
20	27	441.087	476.725	-35.638
20	28	439.323	475.822	-36.498
20	29	444.044	475.567	-31.522
20	30	441.475	476.927	-35.452
20	31	440.477	478.095	-37.618
20	32	445.640	476.228	-30.588
20	33	440.799	484.196	-43.397
20	34	436.723	486.536	-49.813
20	35	442.924	489.877	-46.953
20	36	442.827	430.928	11.899
20	37	437.075	485.296	-48.221
20	38	436.853	500.352	-63.498
20	39	434.997	490.857	-55.860
20	40	436.660	484.994	-48.334
20	41	443.852	485.270	-41.418
20	42	445.151	475.388	-30.237
20	43	451.060	440.440	10.619
20	44	446.733	481.815	-35.082
20	45	440.815	485.925	-45.110
20	46	449.729	481.813	-32.084
20	47	439.614	479.788	-40.174
20	48	435.773	476.411	-40.638
20	49	445.836	475.655	-29.819
20	50	448.990	478.097	-29.107
20	51	453.453	489.505	-36.053
20	52	450.692	481.205	-30.513
20	53	451.163	481.010	-29.846
20	54	449.909	482.559	-32.650
20	55	454.556	491.774	-37.218
20	56	450.136	486.289	-36.153
30	1	461.020	500.578	-39.558
30	2	446.849	473.878	-27.029
30	3	442.984	469.743	-26.760
30	4	443.591	474.510	-30.919
30	5	438.433	497.630	-59.196
30	62	449.522	491.886	-42.364
30	63	427.087	471.944	-44.858
30	64	451.927	496.832	-44.905
30	65	445.968	488.974	-43.006
30	66	434.166	492.596	-58.431
	Max	461.020	500.578	11.899
	Average	441.389	473.250	-31.860
	Min	424.193	430.928	-63.498
	Std Dev	7.378	15.596	13.832



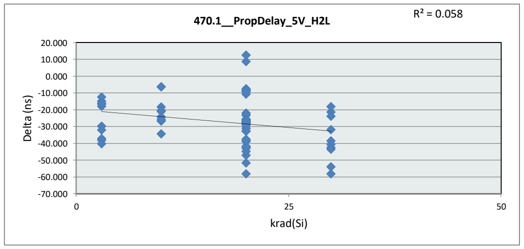
	470.0__PropDelay_5V_H2L			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	630	ns		
Min Limit	350	ns		
krad(Si)	3	10	20	30
LL	350.000	350.000	350.000	350.000
Min	439.027	449.741	430.928	469.743
Average	466.651	460.097	474.803	485.857
Max	492.098	470.232	500.352	500.578
UL	630.000	630.000	630.000	630.000



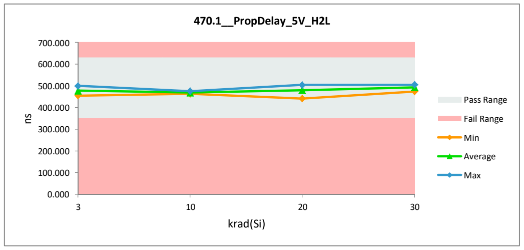
TID LDR Report
TLV1704-SEP

	470.1__PropDelay_5V_H2L	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	ns	ns
Max Limit	630	630
Min Limit	350	350

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	470.262	500.165	-29.903
3	2	456.630	494.894	-38.264
3	3	456.209	493.547	-37.338
3	4	454.811	495.008	-40.197
3	5	451.470	483.581	-32.111
3	6	449.005	461.524	-12.519
3	7	446.771	464.694	-17.923
3	8	447.554	464.297	-16.743
3	9	439.933	454.874	-14.940
3	0	448.711	464.764	-16.052
10	1	438.926	473.336	-34.410
10	2	439.568	466.233	-26.665
10	3	448.527	466.898	-18.370
10	4	457.646	464.099	-6.453
10	5	457.134	463.541	-6.407
10	6	449.014	475.736	-26.722
10	7	446.479	470.776	-24.296
10	8	450.788	471.190	-20.402
10	9	443.864	464.835	-20.971
10	10	447.134	472.910	-25.777
20	11	438.926	447.152	-8.227
20	12	439.568	447.715	-8.147
20	13	448.527	457.425	-8.898
20	14	457.646	466.994	-9.348
20	15	457.134	464.732	-7.598
20	16	449.014	477.759	-28.744
20	17	446.479	457.355	-10.876
20	18	450.788	474.067	-23.279
20	19	443.864	485.722	-41.858
20	20	447.134	455.944	-8.810
20	21	449.962	459.228	-9.266
20	22	449.670	477.539	-27.869
20	23	450.987	476.958	-25.972
20	24	452.298	484.915	-32.617
20	25	450.413	489.295	-38.882
20	26	447.251	473.660	-26.409
20	27	451.200	479.384	-28.184
20	28	453.390	479.248	-25.858
20	29	453.442	475.368	-21.926
20	30	450.290	477.701	-27.410
20	31	451.929	475.062	-23.133
20	32	448.568	479.506	-30.938
20	33	455.297	484.198	-28.901
20	34	450.012	492.935	-42.924
20	35	454.791	497.213	-42.422
20	36	449.840	441.183	8.657
20	37	440.002	487.182	-47.181
20	38	444.224	502.442	-58.218
20	39	442.953	494.646	-51.694
20	40	449.640	494.434	-44.794
20	41	454.937	492.467	-37.530
20	42	461.918	487.496	-25.578
20	43	464.532	452.057	12.475
20	44	455.231	487.856	-32.625
20	45	449.552	491.322	-41.770
20	46	453.493	480.603	-27.110
20	47	450.777	489.589	-38.811
20	48	445.381	483.645	-38.264
20	49	457.386	486.337	-28.951
20	50	464.652	491.981	-27.329
20	51	464.141	495.198	-31.058
20	52	462.853	489.678	-26.825
20	53	460.074	487.619	-27.545
20	54	465.928	493.198	-27.270
20	55	471.204	504.105	-32.901
20	56	461.554	490.796	-29.242
30	1	470.262	502.226	-31.964
30	2	456.630	478.168	-21.538
30	3	456.209	474.479	-18.270
30	4	454.811	478.671	-23.859
30	5	451.470	505.511	-54.041
30	62	458.703	499.447	-40.745
30	63	444.458	486.963	-42.504
30	64	458.756	502.258	-43.501
30	65	457.871	496.444	-38.572
30	66	446.488	504.662	-58.174
	Max	471.204	505.511	12.475
	Average	452.302	479.693	-27.391
	Min	438.926	441.183	-58.218
	Std Dev	7.401	15.336	13.789

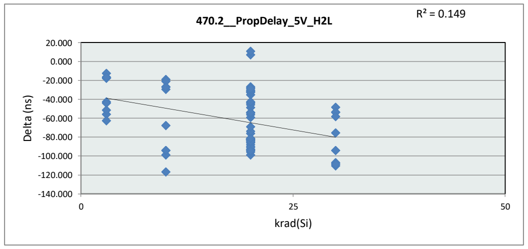


	470.1__PropDelay_5V_H2L			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	630	ns		
Min Limit	350	ns		
krad(Si)	3	10	20	30
LL	350.000	350.000	350.000	350.000
Min	454.874	463.541	441.183	474.479
Average	477.735	468.955	479.585	492.883
Max	500.165	475.736	504.105	505.511
UL	630.000	630.000	630.000	630.000

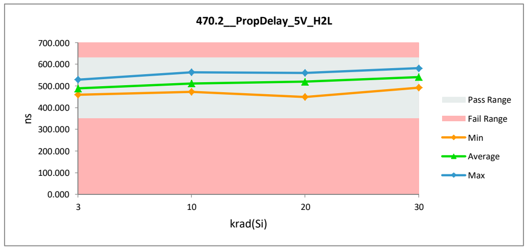


TID LDR Report
TLV1704-SEP

		470.2__PropDelay_5V_H2L		
	Test Site	MLA	MLA	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	ns	ns	
	Max Limit	630	630	
	Min Limit	350	350	
krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	472.605	528.687	-56.083
3	2	452.551	495.402	-42.851
3	3	463.571	515.060	-51.489
3	4	459.735	503.926	-44.191
3	5	454.536	517.348	-62.812
3	6	451.224	463.981	-12.757
3	7	450.598	468.387	-17.789
3	8	449.238	467.083	-17.845
3	9	443.243	460.030	-16.787
3	0	445.498	462.203	-16.704
10	1	445.417	562.367	-116.950
10	2	440.784	539.852	-99.067
10	3	454.685	549.132	-94.446
10	4	454.765	549.174	-94.409
10	5	463.593	531.531	-67.938
10	6	453.720	480.538	-26.818
10	7	447.504	477.187	-29.682
10	8	456.486	475.812	-19.326
10	9	450.973	472.212	-21.239
10	10	446.878	474.294	-27.416
20	11	445.417	535.496	-90.079
20	12	440.784	528.880	-88.096
20	13	454.685	548.742	-94.056
20	14	454.765	553.767	-99.002
20	15	463.593	559.631	-96.038
20	16	453.720	536.399	-82.678
20	17	447.504	540.430	-92.926
20	18	456.486	539.872	-83.387
20	19	450.973	537.290	-86.317
20	20	446.878	539.988	-93.110
20	21	446.067	536.886	-90.820
20	22	462.479	544.631	-82.151
20	23	455.344	537.866	-82.523
20	24	454.393	536.590	-82.197
20	25	452.393	538.034	-85.641
20	26	454.326	530.831	-76.505
20	27	449.943	544.423	-94.479
20	28	461.375	543.107	-81.732
20	29	459.671	542.091	-82.421
20	30	458.046	541.860	-83.814
20	31	458.522	541.577	-83.055
20	32	456.051	540.827	-84.776
20	33	457.211	538.718	-81.507
20	34	454.267	513.840	-59.573
20	35	459.191	515.519	-56.329
20	36	456.599	449.638	6.962
20	37	451.094	500.042	-48.948
20	38	453.163	527.301	-74.138
20	39	450.966	520.068	-69.102
20	40	451.682	505.789	-54.107
20	41	459.195	503.423	-44.228
20	42	461.236	493.764	-32.528
20	43	467.613	456.962	10.651
20	44	455.621	499.595	-43.975
20	45	453.923	499.758	-45.835
20	46	459.958	495.350	-35.392
20	47	451.488	506.337	-54.849
20	48	456.467	510.943	-54.477
20	49	459.247	491.786	-32.538
20	50	462.056	493.552	-31.495
20	51	464.084	491.180	-27.097
20	52	461.717	494.142	-32.425
20	53	464.906	492.771	-27.865
20	54	463.008	493.787	-30.779
20	55	464.170	506.930	-42.761
20	56	463.359	492.350	-28.991
30	1	472.605	581.232	-108.627
30	2	452.551	559.549	-106.998
30	3	463.571	573.989	-110.418
30	4	459.735	568.442	-108.707
30	5	454.536	548.980	-94.444
30	62	463.245	517.116	-53.871
30	63	443.925	492.469	-48.543
30	64	462.978	516.526	-53.548
30	65	463.136	521.625	-58.489
30	66	454.351	530.141	-75.790
	Max	472.605	581.232	10.651
	Average	455.709	517.066	-61.357
	Min	440.784	449.638	-116.950
	Std Dev	6.847	30.651	30.667

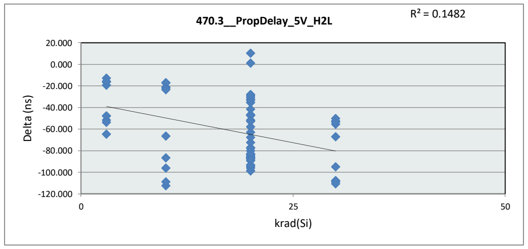


	470.2__PropDelay_5V_H2L			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	630	ns		
Min Limit	350	ns		
krad(Si)	3	10	20	30
LL	350.000	350.000	350.000	350.000
Min	460.030	472.212	449.638	492.469
Average	488.211	511.210	519.408	541.007
Max	528.687	562.367	559.631	581.232
UL	630.000	630.000	630.000	630.000

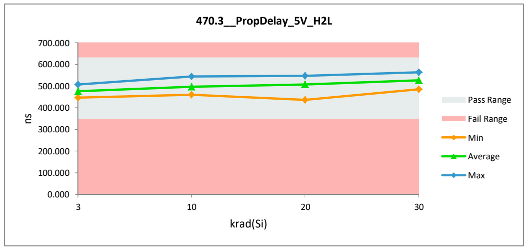


TID LDR Report
TLV1704-SEP

		470.3__PropDelay_5V_H2L		
	Test Site	MLA	MLA	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	ns	ns	
	Max Limit	630	630	
	Min Limit	350	350	
krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	455.199	507.168	-51.970
3	2	446.731	494.820	-48.089
3	3	446.091	494.249	-48.157
3	4	447.175	501.049	-53.874
3	5	441.513	506.366	-64.854
3	6	432.686	445.806	-13.120
3	7	436.177	455.684	-19.507
3	8	436.322	453.093	-16.771
3	9	434.657	451.038	-16.381
3	0	432.412	448.513	-16.101
10	1	430.697	543.146	-112.449
10	2	426.003	534.904	-108.901
10	3	441.806	528.742	-86.936
10	4	439.801	535.979	-96.178
10	5	448.114	514.697	-66.583
10	6	442.051	459.703	-17.652
10	7	439.138	460.585	-21.446
10	8	442.521	459.822	-17.300
10	9	439.012	461.299	-22.287
10	10	435.961	459.711	-23.750
20	11	430.697	520.100	-89.403
20	12	426.003	513.546	-87.543
20	13	441.806	538.176	-96.370
20	14	439.801	538.640	-98.839
20	15	448.114	546.860	-98.746
20	16	442.051	528.267	-86.215
20	17	439.138	533.207	-94.069
20	18	442.521	526.566	-84.045
20	19	439.012	525.240	-86.228
20	20	435.961	531.172	-95.211
20	21	439.610	532.909	-93.300
20	22	438.987	519.307	-80.319
20	23	441.805	525.195	-83.389
20	24	446.431	530.250	-83.819
20	25	440.516	527.289	-86.773
20	26	440.596	527.865	-87.268
20	27	443.369	528.734	-85.365
20	28	444.746	531.531	-86.785
20	29	446.132	523.412	-77.280
20	30	440.692	527.738	-87.046
20	31	445.171	528.028	-82.857
20	32	443.731	532.362	-88.630
20	33	448.028	525.937	-77.909
20	34	441.858	504.835	-62.978
20	35	441.652	499.839	-58.187
20	36	437.544	436.642	0.902
20	37	434.253	481.291	-47.039
20	38	432.390	505.058	-72.668
20	39	439.492	507.272	-67.780
20	40	435.369	487.849	-52.480
20	41	447.664	494.525	-46.861
20	42	447.882	483.492	-35.609
20	43	452.318	442.214	10.104
20	44	443.713	490.805	-47.092
20	45	445.352	493.012	-47.660
20	46	450.949	483.507	-32.558
20	47	436.643	488.404	-51.760
20	48	438.542	491.595	-53.053
20	49	447.597	483.282	-35.685
20	50	450.906	481.666	-30.760
20	51	450.868	479.847	-28.979
20	52	449.669	482.302	-32.632
20	53	448.128	481.594	-33.466
20	54	445.820	476.490	-30.670
20	55	455.386	497.318	-41.932
20	56	442.077	470.136	-28.058
30	1	455.199	563.146	-107.948
30	2	446.731	555.830	-109.099
30	3	446.091	554.587	-108.495
30	4	447.175	557.979	-110.804
30	5	441.513	536.563	-95.050
30	62	448.512	501.254	-52.742
30	63	434.223	484.625	-50.402
30	64	447.326	503.122	-55.796
30	65	447.077	500.849	-53.772
30	66	436.104	503.405	-67.302
	Max	455.386	563.146	10.104
	Average	442.171	503.724	-61.553
	Min	426.003	436.642	-112.449
	Std Dev	6.382	30.926	30.878



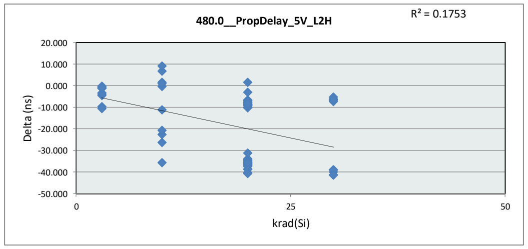
	470.3__PropDelay_5V_H2L			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	630	ns		
Min Limit	350	ns		
krad(Si)	3	10	20	30
LL	350.000	350.000	350.000	350.000
Min	445.807	459.703	436.642	484.625
Average	475.779	495.859	506.637	526.136
Max	507.169	543.146	546.860	563.147
UL	630.000	630.000	630.000	630.000



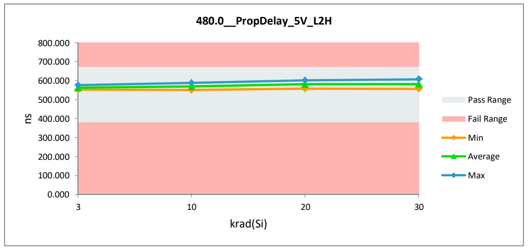
TID LDR Report
TLV1704-SEP

	480.0__PropDelay_5V_L2H	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	ns	ns
Max Limit	670	670
Min Limit	380	380

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	565.786	575.469	-9.683
3	2	561.594	565.531	-3.938
3	3	563.140	567.623	-4.483
3	4	562.839	566.208	-3.368
3	5	555.333	565.888	-10.555
3	6	555.238	556.363	-1.125
3	7	554.510	555.514	-1.004
3	8	559.540	560.120	-0.580
3	9	552.030	552.344	-0.313
3	0	553.561	554.876	-1.315
10	1	552.727	588.384	-35.656
10	2	557.143	583.432	-26.290
10	3	560.689	583.217	-22.528
10	4	563.573	584.308	-20.735
10	5	565.152	576.405	-11.253
10	6	560.282	553.500	6.782
10	7	554.836	555.193	-0.356
10	8	559.290	557.768	1.523
10	9	560.406	551.324	9.082
10	10	554.606	553.714	0.892
20	11	552.727	587.401	-34.673
20	12	557.143	591.640	-34.497
20	13	560.689	598.132	-37.443
20	14	563.573	600.419	-36.846
20	15	565.152	600.953	-35.801
20	16	560.282	595.586	-35.304
20	17	554.836	593.515	-38.679
20	18	559.290	593.187	-33.897
20	19	560.406	596.924	-36.518
20	20	554.606	590.716	-36.109
20	21	554.894	595.065	-40.171
20	22	556.498	593.327	-36.829
20	23	558.089	593.813	-35.724
20	24	560.982	597.318	-36.336
20	25	557.355	593.435	-36.079
20	26	559.948	594.122	-34.174
20	27	558.617	594.131	-35.514
20	28	558.139	596.728	-38.589
20	29	560.919	597.724	-36.804
20	30	562.691	593.848	-31.156
20	31	556.851	597.440	-40.589
20	32	560.697	595.883	-35.185
20	33	559.709	595.364	-35.655
20	34	558.088	565.059	-6.971
20	35	558.116	566.937	-8.821
20	36	559.239	557.672	1.567
20	37	556.503	564.287	-7.784
20	38	557.598	565.447	-7.848
20	39	554.337	560.982	-6.645
20	40	552.392	559.318	-6.927
20	41	550.375	560.553	-10.178
20	42	554.648	564.879	-10.230
20	43	560.383	563.397	-3.013
20	44	559.898	568.406	-8.508
20	45	552.471	561.696	-9.224
20	46	560.193	569.394	-9.202
20	47	549.997	559.064	-9.067
20	48	547.607	557.751	-10.144
20	49	557.996	567.163	-9.168
20	50	562.582	571.121	-8.539
20	51	571.805	580.805	-9.001
20	52	562.104	570.799	-8.695
20	53	561.565	570.138	-8.574
20	54	560.505	568.017	-7.512
20	55	569.835	578.328	-8.493
20	56	566.739	575.059	-8.320
30	1	565.786	607.225	-41.439
30	2	561.594	601.560	-39.967
30	3	563.140	601.976	-38.836
30	4	562.839	601.852	-39.013
30	5	555.333	596.601	-41.268
30	62	559.062	565.865	-6.803
30	63	550.496	556.654	-6.158
30	64	559.089	566.444	-7.355
30	65	560.125	565.363	-5.238
30	66	551.607	558.000	-6.393
	Max	571.805	607.225	9.082
	Average	558.690	576.864	-18.174
	Min	547.607	551.324	-41.439
	Std Dev	4.585	16.756	15.650



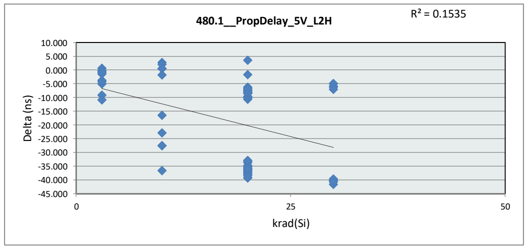
	480.0__PropDelay_5V_L2H			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	670	ns		
Min Limit	380	ns		
krad(Si)	3	10	20	30
LL	380.000	380.000	380.000	380.000
Min	552.344	551.324	557.672	556.654
Average	561.994	568.724	580.716	582.154
Max	575.469	588.384	600.953	607.225
UL	670.000	670.000	670.000	670.000



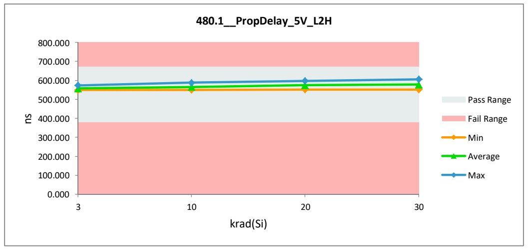
TID LDR Report
TLV1704-SEP

	480.1__PropDelay_5V_L2H	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	ns	ns
Max Limit	670	670
Min Limit	380	380

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	564.295	573.505	-9.211
3	2	557.716	562.748	-5.032
3	3	556.479	560.315	-3.837
3	4	559.595	563.832	-4.237
3	5	551.069	561.931	-10.862
3	6	550.236	549.675	0.561
3	7	551.709	551.912	-0.203
3	8	550.247	550.909	-0.662
3	9	548.913	550.413	-1.500
3	0	548.806	549.753	-0.948
10	1	551.372	587.989	-36.617
10	2	553.224	580.816	-27.593
10	3	551.470	578.998	-27.529
10	4	559.444	582.329	-22.885
10	5	557.204	573.669	-16.464
10	6	552.517	549.763	2.754
10	7	550.211	552.086	-1.876
10	8	552.561	550.589	1.972
10	9	551.062	550.556	0.505
10	10	550.354	549.812	0.542
20	11	551.372	585.065	-33.693
20	12	553.224	588.009	-34.786
20	13	551.470	588.715	-37.245
20	14	559.444	597.667	-38.223
20	15	557.204	595.348	-38.143
20	16	552.517	587.660	-35.143
20	17	550.211	587.917	-37.706
20	18	552.561	588.692	-36.131
20	19	551.062	587.571	-36.509
20	20	550.354	588.546	-38.192
20	21	548.255	586.422	-38.167
20	22	553.484	590.378	-36.894
20	23	555.542	591.218	-35.676
20	24	556.580	591.839	-35.259
20	25	554.739	590.484	-35.745
20	26	551.279	590.552	-39.274
20	27	555.737	588.980	-33.243
20	28	554.876	592.380	-37.503
20	29	557.099	589.953	-32.854
20	30	553.510	590.016	-36.506
20	31	552.328	588.258	-35.930
20	32	551.591	590.621	-39.030
20	33	553.687	589.527	-35.841
20	34	552.319	558.583	-6.264
20	35	551.171	558.623	-7.452
20	36	551.078	552.747	-1.668
20	37	546.804	554.356	-7.553
20	38	548.299	555.712	-7.413
20	39	550.527	558.280	-7.753
20	40	550.906	557.492	-6.585
20	41	546.145	556.779	-10.633
20	42	550.098	559.801	-9.703
20	43	557.348	553.811	3.537
20	44	551.190	559.192	-8.002
20	45	543.379	553.408	-10.029
20	46	551.986	560.403	-8.417
20	47	545.040	555.291	-10.251
20	48	541.974	551.571	-9.597
20	49	552.563	560.990	-8.427
20	50	559.767	568.240	-8.473
20	51	565.180	573.387	-8.206
20	52	555.185	563.244	-8.059
20	53	554.128	561.178	-7.050
20	54	557.125	565.648	-8.522
20	55	567.076	575.410	-8.334
20	56	564.281	571.052	-6.771
30	1	564.295	605.905	-41.610
30	2	557.716	598.031	-40.315
30	3	556.479	596.527	-40.048
30	4	559.595	599.285	-39.689
30	5	551.069	591.724	-40.655
30	62	553.432	558.370	-4.937
30	63	550.845	556.705	-5.860
30	64	554.941	559.885	-4.945
30	65	551.754	558.051	-6.297
30	66	545.119	552.132	-7.013
	Max	567.076	605.905	3.537
	Average	553.361	571.832	-18.471
	Min	541.974	549.675	-41.610
	Std Dev	4.837	17.056	15.673

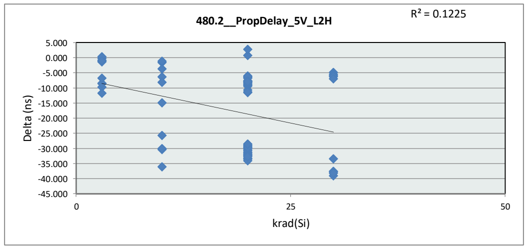


	480.1__PropDelay_5V_L2H			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	670	ns		
Min Limit	380	ns		
krad(Si)	3	10	20	30
LL	380.000	380.000	380.000	380.000
Min	549.675	549.763	551.571	552.132
Average	557.500	565.661	575.022	577.662
Max	573.505	587.989	597.667	605.905
UL	670.000	670.000	670.000	670.000

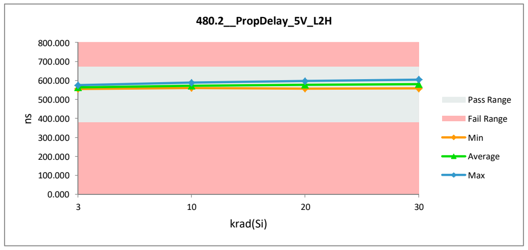


TID LDR Report
TLV1704-SEP

		480.2__PropDelay_5V_L2H		
	Test Site	MLA	MLA	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	ns	ns	
	Max Limit	670	670	
	Min Limit	380	380	
krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	566.461	574.950	-8.489
3	2	557.617	567.340	-9.723
3	3	563.393	571.965	-8.572
3	4	563.562	570.325	-6.763
3	5	556.339	568.083	-11.744
3	6	555.858	556.076	-0.218
3	7	555.943	556.849	-0.906
3	8	554.781	556.177	-1.395
3	9	556.876	556.574	0.302
3	0	554.472	555.531	-1.059
10	1	552.038	588.195	-36.157
10	2	553.783	579.510	-25.727
10	3	555.975	586.396	-30.421
10	4	556.727	586.786	-30.059
10	5	563.209	578.153	-14.944
10	6	558.249	559.916	-1.667
10	7	554.560	560.994	-6.434
10	8	558.924	560.087	-1.162
10	9	557.385	561.092	-3.707
10	10	552.075	560.315	-8.240
20	11	552.038	583.410	-31.372
20	12	553.783	585.936	-32.153
20	13	555.975	588.042	-32.067
20	14	556.727	590.285	-33.558
20	15	563.209	596.443	-33.234
20	16	558.249	588.790	-30.541
20	17	554.560	586.193	-31.633
20	18	558.924	590.229	-31.305
20	19	557.385	588.254	-30.869
20	20	552.075	584.207	-32.132
20	21	554.364	586.833	-32.469
20	22	562.295	594.773	-32.478
20	23	560.851	589.827	-28.976
20	24	561.387	590.473	-29.086
20	25	559.135	589.262	-30.128
20	26	557.568	587.328	-29.761
20	27	557.562	590.962	-33.400
20	28	560.954	595.082	-34.128
20	29	563.466	592.911	-29.445
20	30	560.109	589.904	-29.794
20	31	558.462	587.108	-28.646
20	32	557.078	589.853	-32.775
20	33	559.458	588.101	-28.643
20	34	558.311	564.754	-6.443
20	35	558.372	565.122	-6.750
20	36	557.418	556.724	0.693
20	37	555.745	562.553	-6.808
20	38	555.359	562.972	-7.613
20	39	555.391	563.350	-7.958
20	40	555.207	561.293	-6.086
20	41	550.909	562.511	-11.603
20	42	552.907	563.636	-10.729
20	43	562.882	560.191	2.691
20	44	553.558	561.352	-7.794
20	45	553.909	562.149	-8.240
20	46	555.029	564.059	-9.030
20	47	550.767	560.182	-9.415
20	48	548.831	557.989	-9.158
20	49	557.342	566.226	-8.884
20	50	559.044	567.545	-8.501
20	51	566.614	577.971	-11.357
20	52	559.541	565.848	-6.307
20	53	560.883	568.654	-7.771
20	54	561.650	570.081	-8.431
20	55	568.310	576.208	-7.898
20	56	563.752	571.703	-7.952
30	1	566.461	604.232	-37.771
30	2	557.617	595.203	-37.586
30	3	563.393	602.421	-39.028
30	4	563.562	601.775	-38.214
30	5	556.339	589.820	-33.481
30	62	558.269	563.227	-4.957
30	63	552.479	558.021	-5.542
30	64	558.564	564.545	-5.981
30	65	557.645	563.914	-6.268
30	66	551.410	558.456	-7.046
	Max	568.310	604.232	2.691
	Average	557.780	575.055	-17.275
	Min	548.831	555.531	-39.028
	Std Dev	4.145	14.238	13.187



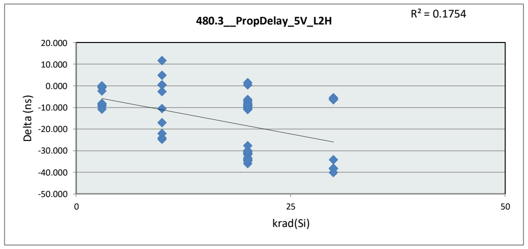
	480.2__PropDelay_5V_L2H			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	670	ns		
Min Limit	380	ns		
krad(Si)	3	10	20	30
LL	380.000	380.000	380.000	380.000
Min	555.531	559.916	556.724	558.021
Average	563.387	572.144	577.115	580.161
Max	574.950	588.195	596.443	604.232
UL	670.000	670.000	670.000	670.000



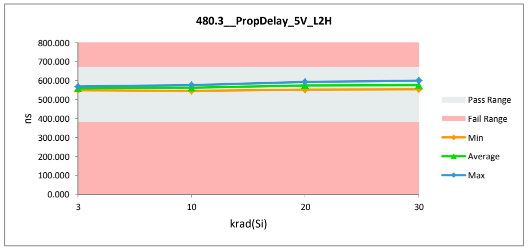
TID LDR Report
TLV1704-SEP

	480.3__PropDelay_5V_L2H	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	ns	ns
Max Limit	670	670
Min Limit	380	380

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	558.486	568.088	-9.602
3	2	557.200	565.732	-8.532
3	3	557.707	566.852	-9.145
3	4	558.724	567.030	-8.306
3	5	552.152	563.005	-10.852
3	6	548.479	548.978	-0.499
3	7	552.079	552.909	-0.831
3	8	549.812	550.637	-0.824
3	9	552.309	554.808	-2.500
3	0	552.078	552.208	-0.130
10	1	550.322	575.100	-24.778
10	2	549.804	574.022	-24.218
10	3	557.625	574.810	-17.185
10	4	554.291	576.381	-22.091
10	5	557.588	568.177	-10.589
10	6	557.417	545.844	11.574
10	7	551.202	550.881	0.321
10	8	553.836	549.112	4.724
10	9	553.149	552.857	0.292
10	10	548.147	550.971	-2.824
20	11	550.322	581.962	-31.640
20	12	549.804	581.244	-31.440
20	13	557.625	592.522	-34.897
20	14	554.291	588.746	-34.455
20	15	557.588	592.138	-34.550
20	16	557.417	588.492	-31.075
20	17	551.202	585.404	-34.201
20	18	553.836	585.825	-31.989
20	19	553.149	584.830	-31.681
20	20	548.147	581.502	-33.355
20	21	553.785	587.667	-33.882
20	22	552.971	583.247	-30.276
20	23	554.935	585.995	-31.061
20	24	559.321	590.790	-31.469
20	25	556.065	586.454	-30.389
20	26	552.634	588.632	-35.999
20	27	556.863	588.141	-31.279
20	28	555.701	590.355	-34.653
20	29	557.873	587.962	-30.089
20	30	555.760	583.527	-27.767
20	31	551.389	585.102	-33.713
20	32	552.714	587.055	-34.341
20	33	553.999	584.125	-30.126
20	34	551.554	558.232	-6.677
20	35	553.392	559.869	-6.477
20	36	552.132	551.854	0.279
20	37	549.155	556.645	-7.490
20	38	548.347	557.182	-8.835
20	39	551.008	558.384	-7.376
20	40	551.623	558.076	-6.454
20	41	548.780	559.819	-11.039
20	42	552.124	562.931	-10.807
20	43	557.628	556.294	1.334
20	44	553.212	561.532	-8.320
20	45	551.203	559.608	-8.405
20	46	554.496	564.163	-9.667
20	47	547.719	556.163	-8.444
20	48	546.417	557.198	-10.781
20	49	554.048	563.880	-9.832
20	50	557.849	566.446	-8.597
20	51	563.576	572.784	-9.208
20	52	554.301	563.936	-9.635
20	53	552.816	561.708	-8.893
20	54	554.906	565.247	-10.342
20	55	566.895	576.015	-9.120
20	56	561.104	570.318	-9.213
30	1	558.486	596.710	-38.224
30	2	557.200	595.708	-38.508
30	3	557.707	595.935	-38.228
30	4	558.724	598.875	-40.151
30	5	552.152	586.450	-34.298
30	62	552.915	559.024	-6.109
30	63	550.831	556.468	-5.637
30	64	551.146	557.571	-6.425
30	65	553.876	559.954	-6.078
30	66	547.170	553.653	-6.482
	Max	566.895	598.875	11.574
	Average	553.872	570.773	-16.901
	Min	546.417	545.844	-40.151
	Std Dev	3.856	14.928	13.779

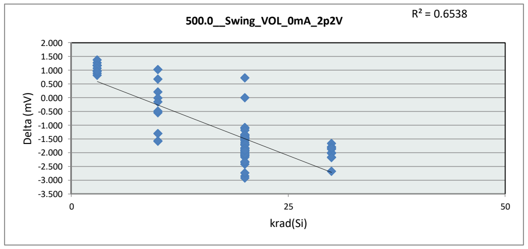


	480.3__PropDelay_5V_L2H			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	670	ns		
Min Limit	380	ns		
krad(Si)	3	10	20	30
LL	380.000	380.000	380.000	380.000
Min	548.978	545.844	551.854	553.653
Average	559.025	561.816	574.130	576.035
Max	568.088	576.381	592.522	598.875
UL	670.000	670.000	670.000	670.000

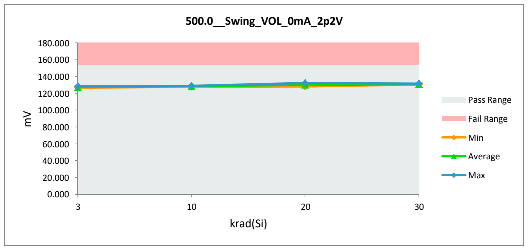


TID LDR Report
TLV1704-SEP

		500.0__Swing_VOL_0mA_2p2V		
	Test Site	MLA	MLA	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	mV	mV	
	Max Limit	153	153	
	Min Limit	0.1	0.1	
krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	129.225	128.417	0.807
3	2	128.632	127.660	0.972
3	3	128.596	127.723	0.873
3	4	128.517	127.355	1.162
3	5	128.403	127.140	1.263
3	6	128.408	127.250	1.158
3	7	128.451	127.084	1.367
3	8	128.608	127.438	1.170
3	9	127.584	126.529	1.056
3	0	127.828	126.883	0.945
10	1	126.801	128.396	-1.595
10	2	126.649	127.964	-1.314
10	3	128.800	128.133	0.667
10	4	128.705	128.509	0.196
10	5	128.998	127.987	1.011
10	6	127.705	128.264	-0.559
10	7	128.641	128.664	-0.023
10	8	127.300	128.879	-1.579
10	9	127.669	127.827	-0.158
10	10	128.342	128.840	-0.498
20	11	126.801	128.643	-1.841
20	12	126.649	128.063	-1.414
20	13	128.800	130.655	-1.855
20	14	128.705	130.100	-1.395
20	15	128.998	130.344	-1.346
20	16	127.705	129.635	-1.930
20	17	128.641	130.012	-1.371
20	18	127.300	128.766	-1.466
20	19	127.669	129.232	-1.563
20	20	128.342	130.072	-1.730
20	21	127.867	129.917	-2.049
20	22	127.781	129.475	-1.694
20	23	127.422	128.916	-1.494
20	24	127.455	128.904	-1.448
20	25	127.498	129.028	-1.531
20	26	127.816	129.552	-1.736
20	27	128.157	129.617	-1.459
20	28	128.135	129.687	-1.551
20	29	128.188	129.314	-1.126
20	30	127.759	130.621	-2.862
20	31	128.547	130.518	-1.971
20	32	128.596	129.681	-1.085
20	33	127.893	129.801	-1.908
20	34	128.299	129.491	-1.192
20	35	128.237	129.595	-1.358
20	36	128.645	127.935	0.710
20	37	128.597	130.075	-1.478
20	38	128.978	130.615	-1.637
20	39	128.520	130.358	-1.839
20	40	129.142	131.214	-2.072
20	41	127.753	130.680	-2.927
20	42	128.070	130.814	-2.744
20	43	128.551	128.562	-0.010
20	44	128.341	130.765	-2.425
20	45	128.386	130.493	-2.107
20	46	129.695	131.396	-1.701
20	47	128.650	130.780	-2.131
20	48	128.786	130.791	-2.005
20	49	128.698	130.868	-2.170
20	50	128.821	130.940	-2.119
20	51	127.486	129.846	-2.360
20	52	129.027	130.876	-1.849
20	53	129.454	131.383	-1.929
20	54	129.897	132.234	-2.337
20	55	127.757	129.809	-2.052
20	56	128.713	130.644	-1.931
30	1	129.225	131.235	-2.010
30	2	128.632	130.303	-1.671
30	3	128.596	130.473	-1.877
30	4	128.517	130.699	-2.182
30	5	128.403	130.431	-2.028
30	62	129.670	131.472	-1.802
30	63	128.566	130.738	-2.172
30	64	129.700	131.503	-1.803
30	65	128.960	130.812	-1.851
30	66	128.253	130.941	-2.688
	Max	129.897	132.234	1.367
	Average	128.337	129.556	-1.219
	Min	126.649	126.529	-2.927
	Std Dev	0.697	1.331	1.175



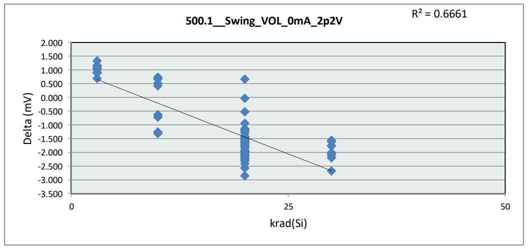
	500.0__Swing_VOL_0mA_2p2			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	153	mV		
Min Limit	0.1	mV		
krad(Si)	3	10	20	30
LL	0.100	0.100	0.100	0.100
Min	126.529	127.827	127.935	130.303
Average	127.348	128.346	130.016	130.861
Max	128.417	128.879	132.234	131.503
UL	153.000	153.000	153.000	153.000



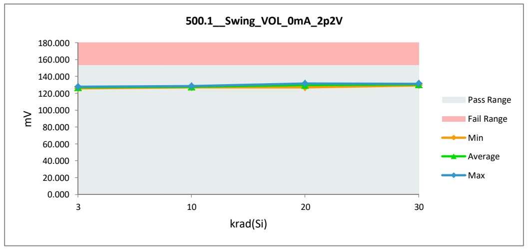
TID LDR Report
TLV1704-SEP

	500.1__Swing_VOL_0mA_2p2V	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	mV	mV
Max Limit	153	153
Min Limit	0.1	0.1

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	128.157	127.466	0.691
3	2	127.925	126.894	1.031
3	3	128.516	127.629	0.887
3	4	127.406	126.242	1.164
3	5	128.558	127.425	1.133
3	6	128.023	126.971	1.052
3	7	127.689	126.362	1.328
3	8	127.982	126.864	1.118
3	9	126.716	125.798	0.918
3	0	127.974	127.078	0.896
10	1	125.999	127.256	-1.256
10	2	125.726	127.037	-1.311
10	3	128.529	127.799	0.731
10	4	127.802	127.083	0.719
10	5	128.598	128.175	0.423
10	6	127.091	127.789	-0.698
10	7	128.193	127.681	0.512
10	8	127.532	128.156	-0.625
10	9	127.550	126.890	0.660
10	10	127.768	128.486	-0.718
20	11	125.999	127.951	-1.952
20	12	125.726	126.941	-1.216
20	13	128.529	130.367	-1.837
20	14	127.802	128.991	-1.189
20	15	128.598	129.898	-1.300
20	16	127.091	129.068	-1.977
20	17	128.193	129.742	-1.549
20	18	127.532	128.985	-1.453
20	19	127.550	129.157	-1.607
20	20	127.768	129.518	-1.749
20	21	128.293	130.296	-2.004
20	22	126.855	128.517	-1.663
20	23	126.978	128.494	-1.516
20	24	127.066	128.530	-1.464
20	25	127.487	129.026	-1.540
20	26	127.636	128.575	-0.939
20	27	127.233	129.534	-2.300
20	28	128.072	128.592	-0.520
20	29	127.085	129.278	-2.193
20	30	127.570	129.613	-2.043
20	31	127.623	129.547	-1.924
20	32	127.552	129.797	-2.245
20	33	128.116	129.321	-1.206
20	34	128.187	129.327	-1.140
20	35	129.108	130.529	-1.421
20	36	128.232	127.563	0.670
20	37	128.367	129.789	-1.422
20	38	129.130	130.766	-1.635
20	39	127.734	129.323	-1.589
20	40	129.020	130.835	-1.814
20	41	127.408	130.252	-2.844
20	42	128.121	130.693	-2.572
20	43	128.464	128.493	-0.029
20	44	127.772	130.181	-2.409
20	45	127.946	130.044	-2.098
20	46	128.295	130.012	-1.717
20	47	128.406	130.493	-2.086
20	48	128.320	130.272	-1.952
20	49	128.415	130.543	-2.127
20	50	128.425	130.540	-2.115
20	51	127.276	129.499	-2.223
20	52	128.609	130.436	-1.826
20	53	128.860	130.811	-1.951
20	54	129.400	131.537	-2.137
20	55	128.062	129.998	-1.936
20	56	127.514	129.526	-2.012
30	1	128.157	130.263	-2.105
30	2	127.925	129.482	-1.557
30	3	128.516	130.115	-1.599
30	4	127.406	129.442	-2.036
30	5	128.558	130.754	-2.196
30	62	128.836	130.607	-1.771
30	63	127.778	129.787	-2.009
30	64	128.620	130.376	-1.756
30	65	129.376	131.386	-2.010
30	66	128.375	131.046	-2.672
	Max	129.400	131.537	1.328
	Average	127.904	129.073	-1.169
	Min	125.726	125.798	-2.844
	Std Dev	0.759	1.394	1.167



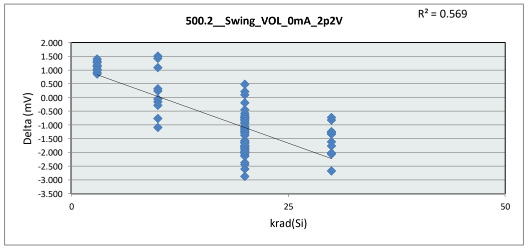
	500.1__Swing_VOL_0mA_2p2			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	153	mV		
Min Limit	0.1	mV		
krad(Si)	3	10	20	30
LL	0.100	0.100	0.100	0.100
Min	125.798	126.890	126.941	129.442
Average	126.873	127.635	129.591	130.326
Max	127.629	128.486	131.537	131.386
UL	153.000	153.000	153.000	153.000



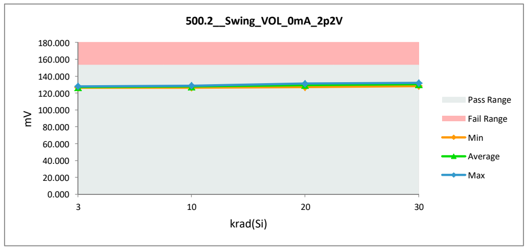
TID LDR Report
TLV1704-SEP

	500.2__Swing_VOL_0mA_2p2V	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	mV	mV
Max Limit	153	153
Min Limit	0.1	0.1

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	128.615	127.716	0.899
3	2	127.598	126.454	1.144
3	3	128.891	127.912	0.979
3	4	128.253	126.933	1.320
3	5	128.431	127.029	1.402
3	6	128.464	127.348	1.116
3	7	128.150	126.878	1.272
3	8	128.282	127.112	1.170
3	9	127.222	126.365	0.857
3	0	127.895	126.870	1.024
10	1	127.255	127.420	-0.165
10	2	126.336	126.394	-0.058
10	3	128.911	127.829	1.081
10	4	129.091	127.583	1.508
10	5	128.937	127.512	1.426
10	6	127.089	128.186	-1.096
10	7	128.459	128.744	-0.285
10	8	127.653	128.423	-0.770
10	9	127.713	127.399	0.315
10	10	128.536	128.299	0.237
20	11	127.255	128.523	-1.268
20	12	126.336	126.912	-0.577
20	13	128.911	130.149	-1.238
20	14	129.091	129.739	-0.648
20	15	128.937	129.649	-0.712
20	16	127.089	128.261	-1.172
20	17	128.459	129.198	-0.738
20	18	127.653	128.368	-0.715
20	19	127.713	128.515	-0.802
20	20	128.536	129.586	-1.050
20	21	127.687	129.070	-1.383
20	22	127.814	128.717	-0.903
20	23	127.345	128.283	-0.938
20	24	127.338	128.086	-0.748
20	25	127.580	128.425	-0.846
20	26	127.636	127.536	0.100
20	27	126.932	129.369	-2.437
20	28	128.588	128.105	0.483
20	29	127.258	128.830	-1.572
20	30	127.790	128.926	-1.136
20	31	127.583	129.369	-1.786
20	32	128.144	129.358	-1.214
20	33	128.323	128.515	-0.192
20	34	128.303	129.390	-1.086
20	35	128.615	129.935	-1.321
20	36	128.530	128.324	0.206
20	37	128.783	130.409	-1.626
20	38	128.926	130.586	-1.660
20	39	128.184	129.805	-1.621
20	40	128.923	130.734	-1.812
20	41	127.546	130.416	-2.870
20	42	128.636	131.236	-2.599
20	43	128.564	129.019	-0.455
20	44	128.686	131.053	-2.367
20	45	127.520	129.634	-2.113
20	46	129.504	131.128	-1.624
20	47	128.367	130.126	-1.759
20	48	129.402	131.243	-1.842
20	49	128.880	130.788	-1.909
20	50	128.883	130.930	-2.046
20	51	127.677	129.819	-2.142
20	52	129.217	130.957	-1.741
20	53	128.815	130.721	-1.906
20	54	128.874	130.886	-2.012
20	55	127.809	129.788	-1.979
20	56	128.361	130.339	-1.978
30	1	128.615	129.862	-1.247
30	2	127.598	128.422	-0.824
30	3	128.891	129.624	-0.733
30	4	128.253	129.594	-1.341
30	5	128.431	129.725	-1.294
30	62	129.509	131.125	-1.616
30	63	128.272	130.324	-2.052
30	64	129.520	131.288	-1.769
30	65	129.540	131.563	-2.023
30	66	129.293	131.972	-2.679
	Max	129.540	131.972	1.508
	Average	128.246	129.088	-0.842
	Min	126.336	126.365	-2.870
	Std Dev	0.741	1.431	1.164



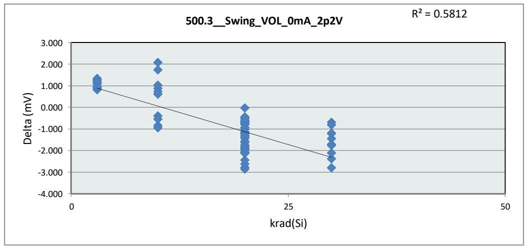
	500.2__Swing_VOL_0mA_2p2			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	153	mV		
Min Limit	0.1	mV		
krad(Si)	3	10	20	30
LL	0.100	0.100	0.100	0.100
Min	126.365	126.394	126.912	128.422
Average	127.062	127.779	129.538	130.350
Max	127.912	128.744	131.244	131.972
UL	153.000	153.000	153.000	153.000



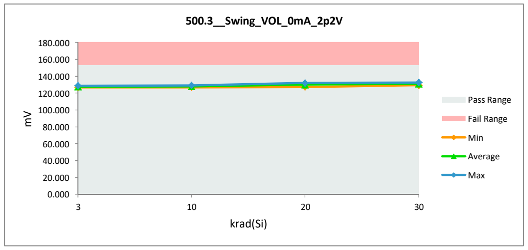
TID LDR Report
TLV1704-SEP

	500.3__Swing_VOL_0mA_2p2V	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	mV	mV
Max Limit	153	153
Min Limit	0.1	0.1

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	129.688	128.877	0.810
3	2	128.646	127.462	1.185
3	3	129.027	128.112	0.914
3	4	129.209	127.945	1.264
3	5	128.738	127.409	1.329
3	6	128.902	127.821	1.081
3	7	128.779	127.502	1.277
3	8	129.313	128.168	1.145
3	9	127.936	127.070	0.866
3	0	127.765	126.799	0.966
10	1	127.161	128.001	-0.840
10	2	126.562	126.964	-0.403
10	3	128.178	127.573	0.606
10	4	129.006	128.137	0.869
10	5	129.536	127.464	2.071
10	6	127.651	128.199	-0.548
10	7	129.217	128.492	0.724
10	8	128.174	129.127	-0.953
10	9	128.691	127.667	1.025
10	10	129.541	127.806	1.735
20	11	127.161	128.319	-1.159
20	12	126.562	127.193	-0.632
20	13	128.178	129.315	-1.137
20	14	129.006	129.534	-0.528
20	15	129.536	130.154	-0.619
20	16	127.651	128.839	-1.189
20	17	129.217	129.908	-0.691
20	18	128.174	128.893	-0.718
20	19	128.691	129.449	-0.757
20	20	129.541	130.569	-1.028
20	21	128.182	129.497	-1.315
20	22	127.799	128.743	-0.944
20	23	127.734	128.670	-0.936
20	24	127.550	128.334	-0.784
20	25	127.965	128.763	-0.798
20	26	128.282	128.728	-0.445
20	27	127.810	129.245	-1.434
20	28	128.490	128.983	-0.492
20	29	128.234	128.923	-0.689
20	30	127.771	130.557	-2.786
20	31	129.177	130.399	-1.222
20	32	129.073	130.306	-1.233
20	33	129.147	129.180	-0.033
20	34	128.966	130.123	-1.157
20	35	129.153	130.478	-1.325
20	36	128.234	129.612	-1.378
20	37	129.149	130.741	-1.592
20	38	128.735	130.320	-1.584
20	39	129.437	131.064	-1.626
20	40	128.833	130.629	-1.796
20	41	127.758	130.616	-2.858
20	42	128.749	131.364	-2.615
20	43	128.816	129.425	-0.609
20	44	129.004	131.450	-2.446
20	45	128.547	130.624	-2.076
20	46	129.702	131.449	-1.747
20	47	128.537	130.623	-2.086
20	48	128.915	130.803	-1.888
20	49	129.872	131.956	-2.084
20	50	129.316	131.404	-2.088
20	51	128.319	130.447	-2.127
20	52	129.601	131.447	-1.846
20	53	130.057	132.004	-1.946
20	54	129.557	131.646	-2.089
20	55	128.476	130.426	-1.951
20	56	128.303	130.380	-2.077
30	1	129.688	130.888	-1.201
30	2	128.646	129.338	-0.692
30	3	129.027	129.844	-0.818
30	4	129.209	130.427	-1.218
30	5	128.738	130.194	-1.456
30	62	129.915	131.637	-1.722
30	63	129.150	131.542	-2.392
30	64	130.813	132.571	-1.758
30	65	129.794	131.917	-2.124
30	66	129.226	132.020	-2.794
	Max	130.813	132.571	2.071
	Average	128.722	129.586	-0.863
	Min	126.562	126.799	-2.858
	Std Dev	0.802	1.473	1.208



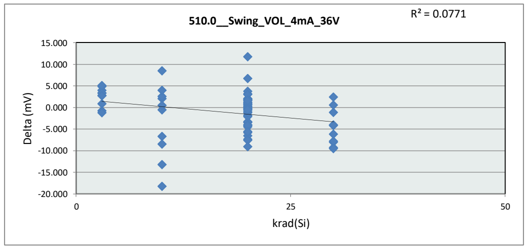
	500.3__Swing_VOL_0mA_2p2			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	153	mV		
Min Limit	0.1	mV		
krad(Si)	3	10	20	30
LL	0.100	0.100	0.100	0.100
Min	126.799	126.964	127.193	129.338
Average	127.716	127.943	130.033	131.038
Max	128.877	129.127	132.004	132.571
UL	153.000	153.000	153.000	153.000



TID LDR Report
TLV1704-SEP

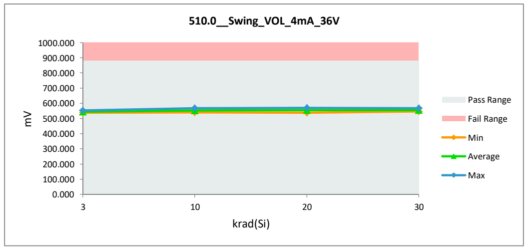
	510.0__Swing_VOL_4mA_36V	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	mV	mV
Max Limit	880	880
Min Limit	0.1	0.1

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	540.310	537.544	2.766
3	2	545.736	542.482	3.255
3	3	548.085	548.932	-0.847
3	4	544.346	540.461	3.885
3	5	558.512	553.732	4.780
3	6	547.409	546.599	0.810
3	7	548.287	543.261	5.026
3	8	545.751	542.435	3.316
3	9	551.995	549.360	2.635
3	0	545.115	546.377	-1.262
10	1	549.403	540.982	8.422
10	2	549.797	547.839	1.958
10	3	546.406	553.152	-6.746
10	4	547.429	555.940	-8.511
10	5	547.288	560.574	-13.286
10	6	556.618	554.093	2.525
10	7	551.821	552.408	-0.587
10	8	554.406	550.458	3.948
10	9	554.984	554.513	0.471
10	10	548.694	566.968	-18.274
20	11	549.403	556.849	-7.446
20	12	549.797	550.467	-0.671
20	13	546.406	550.937	-4.531
20	14	547.429	547.975	-0.547
20	15	547.288	547.411	-0.123
20	16	556.618	563.239	-6.622
20	17	551.821	548.719	3.103
20	18	554.406	552.406	2.000
20	19	554.984	554.874	0.110
20	20	548.694	552.200	-3.506
20	21	547.474	550.976	-3.502
20	22	558.413	558.519	-0.106
20	23	556.887	556.307	0.580
20	24	556.367	554.633	1.734
20	25	556.989	555.166	1.824
20	26	556.034	555.726	0.308
20	27	558.511	554.798	3.713
20	28	558.089	556.067	2.022
20	29	557.520	556.873	0.647
20	30	560.363	558.631	1.732
20	31	557.183	564.832	-7.649
20	32	559.535	558.007	1.528
20	33	556.417	562.250	-5.833
20	34	559.960	557.027	2.933
20	35	561.920	560.759	1.161
20	36	560.075	548.387	11.687
20	37	558.069	557.406	0.663
20	38	555.658	556.677	-1.018
20	39	558.108	561.481	-3.373
20	40	561.130	570.261	-9.131
20	41	555.834	560.009	-4.175
20	42	548.817	550.690	-1.872
20	43	544.729	546.915	-2.185
20	44	548.308	552.352	-4.044
20	45	558.272	557.396	0.876
20	46	556.865	550.216	6.650
20	47	560.998	562.284	-1.286
20	48	560.334	559.287	1.047
20	49	547.431	551.536	-4.105
20	50	545.755	546.070	-0.315
20	51	536.580	540.790	-4.211
20	52	547.818	546.133	1.684
20	53	547.443	547.677	-0.233
20	54	556.528	562.192	-5.663
20	55	537.610	538.224	-0.615
20	56	545.869	544.291	1.578
30	1	540.310	548.407	-8.098
30	2	545.736	546.948	-1.212
30	3	548.085	557.456	-9.371
30	4	544.346	552.219	-7.872
30	5	558.512	564.756	-6.244
30	62	553.320	557.579	-4.259
30	63	548.962	553.064	-4.102
30	64	554.564	554.081	0.483
30	65	559.119	556.749	2.370
30	66	558.814	568.388	-9.574
	Max	561.920	570.261	11.687
	Average	552.038	553.206	-1.168
	Min	536.580	537.544	-18.274
	Std Dev	6.130	7.057	4.898



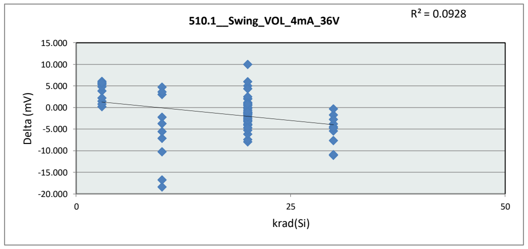
	510.0__Swing_VOL_4mA_36V	
Test Site	MLA	
Tester	ETS364	
Test Number	EB083902	
Max Limit	880	mV
Min Limit	0.1	mV

krad(Si)	3	10	20	30
LL	0.100	0.100	0.100	0.100
Min	537.544	540.982	538.224	546.948
Average	545.118	553.693	554.259	555.965
Max	553.732	566.968	570.261	568.388
UL	880.000	880.000	880.000	880.000

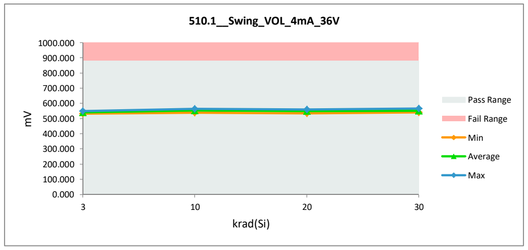


TID LDR Report
TLV1704-SEP

		510.1__Swing_VOL_4mA_36V		
	Test Site	MLA	MLA	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	mV	mV	
	Max Limit	880	880	
	Min Limit	0.1	0.1	
krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	534.952	531.206	3.745
3	2	539.600	534.365	5.235
3	3	547.733	546.344	1.388
3	4	539.757	534.997	4.760
3	5	555.157	549.670	5.486
3	6	544.634	542.505	2.129
3	7	543.924	537.923	6.001
3	8	542.122	536.412	5.711
3	9	546.668	546.558	0.110
3	0	546.773	546.053	0.720
10	1	543.875	539.195	4.680
10	2	547.596	544.650	2.946
10	3	544.015	554.322	-10.307
10	4	543.599	550.766	-7.167
10	5	544.349	562.813	-18.464
10	6	552.622	554.905	-2.282
10	7	544.547	550.188	-5.641
10	8	553.338	549.771	3.567
10	9	551.193	554.963	-3.770
10	10	545.659	562.486	-16.827
20	11	543.875	551.911	-8.036
20	12	547.596	545.600	1.997
20	13	544.015	548.726	-4.711
20	14	543.599	541.678	1.920
20	15	544.349	543.922	0.427
20	16	552.622	560.094	-7.472
20	17	544.547	545.813	-1.265
20	18	553.338	552.563	0.775
20	19	551.193	552.493	-1.300
20	20	545.659	549.602	-3.943
20	21	545.071	549.190	-4.120
20	22	554.112	555.638	-1.526
20	23	548.869	550.710	-1.841
20	24	549.236	548.721	0.515
20	25	551.981	552.201	-0.219
20	26	552.190	547.254	4.936
20	27	550.866	554.229	-3.363
20	28	556.771	550.836	5.936
20	29	551.206	554.174	-2.968
20	30	553.528	554.202	-0.674
20	31	551.917	558.145	-6.228
20	32	552.076	552.315	-0.238
20	33	552.897	551.791	1.106
20	34	554.410	551.971	2.439
20	35	555.845	557.142	-1.297
20	36	553.831	543.886	9.944
20	37	551.296	550.873	0.423
20	38	553.056	555.558	-2.502
20	39	552.508	553.160	-0.652
20	40	552.802	556.721	-3.920
20	41	550.094	554.025	-3.930
20	42	546.823	549.500	-2.677
20	43	542.552	545.635	-3.083
20	44	543.996	549.311	-5.315
20	45	554.526	553.473	1.053
20	46	548.092	543.813	4.279
20	47	554.906	556.571	-1.665
20	48	554.792	554.828	-0.036
20	49	545.203	549.911	-4.709
20	50	540.786	542.003	-1.216
20	51	533.229	535.450	-2.221
20	52	544.667	543.920	0.746
20	53	544.938	546.137	-1.199
20	54	540.510	541.910	-1.400
20	55	532.392	533.987	-1.595
20	56	535.964	537.018	-1.054
30	1	534.952	546.063	-11.112
30	2	539.600	541.418	-1.818
30	3	547.733	551.555	-3.822
30	4	539.757	545.218	-5.461
30	5	555.157	562.874	-7.718
30	62	543.148	547.660	-4.511
30	63	545.810	550.596	-4.786
30	64	547.751	548.127	-0.376
30	65	546.379	549.182	-2.803
30	66	554.733	565.661	-10.927
	Max	556.771	565.661	9.944
	Average	547.314	548.909	-1.595
	Min	532.392	531.206	-18.464
	Std Dev	5.801	7.134	4.919



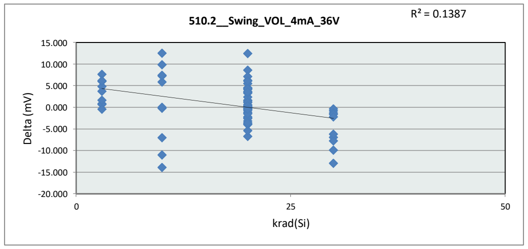
	510.1__Swing_VOL_4mA_36V			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	880	mV		
Min Limit	0.1	mV		
krad(Si)	3	10	20	30
LL	0.100	0.100	0.100	0.100
Min	531.206	539.195	533.987	541.418
Average	540.603	552.406	549.535	550.835
Max	549.670	562.813	560.094	565.661
UL	880.000	880.000	880.000	880.000



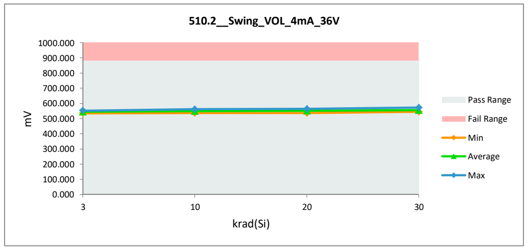
TID LDR Report
TLV1704-SEP

	510.2__Swing_VOL_4mA_36V	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	mV	mV
Max Limit	880	880
Min Limit	0.1	0.1

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	540.589	535.765	4.824
3	2	544.116	538.119	5.996
3	3	552.955	552.118	0.837
3	4	545.420	539.374	6.046
3	5	559.736	552.120	7.615
3	6	546.105	545.477	0.628
3	7	548.536	542.398	6.138
3	8	546.405	542.695	3.710
3	9	548.148	548.570	-0.422
3	0	549.150	547.542	1.608
10	1	549.787	537.312	12.475
10	2	549.579	539.717	9.863
10	3	548.794	549.027	-0.233
10	4	547.921	547.924	-0.004
10	5	544.240	555.293	-11.053
10	6	555.923	550.064	5.859
10	7	548.212	562.157	-13.945
10	8	554.943	547.709	7.234
10	9	556.086	548.722	7.364
10	10	548.063	555.084	-7.020
20	11	549.787	556.532	-6.745
20	12	549.579	545.254	4.326
20	13	548.794	552.819	-4.025
20	14	547.921	544.526	3.395
20	15	544.240	543.031	1.209
20	16	555.923	561.348	-5.425
20	17	548.212	543.690	4.522
20	18	554.943	550.773	4.170
20	19	556.086	555.813	0.273
20	20	548.063	548.013	0.050
20	21	546.996	549.188	-2.192
20	22	558.598	553.134	5.464
20	23	554.707	555.237	-0.530
20	24	556.242	552.656	3.586
20	25	556.593	557.009	-0.416
20	26	555.355	550.888	4.467
20	27	556.272	557.013	-0.741
20	28	561.557	552.940	8.617
20	29	555.781	554.193	1.588
20	30	556.177	554.739	1.438
20	31	555.490	559.432	-3.941
20	32	556.069	553.686	2.383
20	33	557.148	550.948	6.201
20	34	557.497	553.195	4.303
20	35	559.202	560.698	-1.497
20	36	559.320	546.900	12.421
20	37	556.366	558.811	-2.445
20	38	555.303	556.475	-1.173
20	39	557.016	557.166	-0.150
20	40	559.616	563.267	-3.651
20	41	550.865	553.486	-2.622
20	42	550.195	550.403	-0.208
20	43	544.890	548.073	-3.182
20	44	549.611	553.241	-3.630
20	45	553.633	553.071	0.562
20	46	552.829	545.703	7.126
20	47	562.390	556.317	6.073
20	48	558.899	555.616	3.283
20	49	548.178	549.696	-1.518
20	50	547.091	546.012	1.079
20	51	536.968	537.177	-0.209
20	52	546.275	542.706	3.569
20	53	545.722	545.688	0.035
20	54	544.284	544.181	0.103
20	55	536.364	535.977	0.387
20	56	537.555	538.028	-0.473
30	1	540.589	547.579	-6.991
30	2	544.116	544.927	-0.811
30	3	552.955	553.313	-0.358
30	4	545.420	555.332	-9.913
30	5	559.736	567.481	-7.745
30	62	548.898	550.233	-1.335
30	63	550.281	556.524	-6.243
30	64	554.789	556.424	-1.635
30	65	549.592	551.850	-2.258
30	66	559.112	572.098	-12.987
	Max	562.390	572.098	12.475
	Average	551.195	550.628	0.567
	Min	536.364	535.765	-13.945
	Std Dev	5.999	7.207	5.264

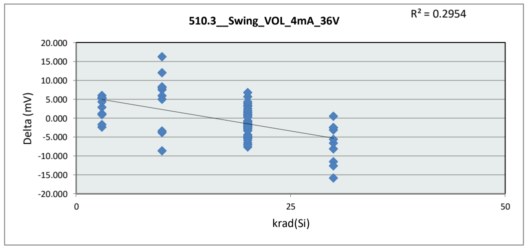


	510.2__Swing_VOL_4mA_36V			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	880	mV		
Min Limit	0.1	mV		
krad(Si)	3	10	20	30
LL	0.100	0.100	0.100	0.100
Min	535.765	537.312	535.977	544.927
Average	544.418	549.301	551.190	555.576
Max	552.120	562.157	563.267	572.098
UL	880.000	880.000	880.000	880.000

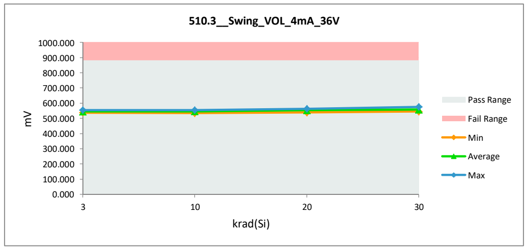


TID LDR Report
TLV1704-SEP

		510.3__Swing_VOL_4mA_36V		
	Test Site	MLA	MLA	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	mV	mV	
	Max Limit	880	880	
	Min Limit	0.1	0.1	
krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	540.525	537.674	2.851
3	2	546.157	540.798	5.360
3	3	552.394	554.769	-2.375
3	4	544.410	539.265	5.145
3	5	560.522	554.529	5.993
3	6	546.867	545.700	1.168
3	7	546.540	541.158	5.382
3	8	544.418	540.102	4.316
3	9	547.675	549.379	-1.704
3	0	547.266	546.352	0.914
10	1	550.692	534.500	16.192
10	2	547.854	540.311	7.543
10	3	545.259	549.125	-3.866
10	4	551.579	545.703	5.876
10	5	546.388	555.063	-8.675
10	6	555.841	547.791	8.049
10	7	551.343	546.372	4.971
10	8	556.500	544.500	12.000
10	9	555.835	547.571	8.264
10	10	548.959	552.378	-3.419
20	11	550.692	556.041	-5.349
20	12	547.854	546.742	1.112
20	13	545.259	549.664	-4.405
20	14	551.579	548.182	3.397
20	15	546.388	544.859	1.529
20	16	555.841	563.443	-7.602
20	17	551.343	548.271	3.072
20	18	556.500	553.994	2.507
20	19	555.835	555.019	0.816
20	20	548.959	551.845	-2.886
20	21	547.495	550.789	-3.294
20	22	557.186	556.338	0.848
20	23	553.882	555.472	-1.590
20	24	554.990	553.453	1.537
20	25	557.095	555.212	1.883
20	26	556.028	563.106	-7.078
20	27	559.915	556.626	3.289
20	28	559.409	555.543	3.865
20	29	557.380	557.071	0.308
20	30	555.929	558.214	-2.285
20	31	556.389	562.957	-6.568
20	32	556.972	562.245	-5.273
20	33	559.324	553.718	5.606
20	34	561.096	559.133	1.963
20	35	559.846	560.648	-0.802
20	36	558.188	551.476	6.712
20	37	557.013	561.957	-4.944
20	38	555.826	557.916	-2.090
20	39	559.470	560.973	-1.502
20	40	556.087	561.441	-5.355
20	41	554.004	558.779	-4.775
20	42	548.851	551.469	-2.618
20	43	544.764	551.773	-7.009
20	44	547.547	553.451	-5.904
20	45	557.672	558.367	-0.696
20	46	551.770	547.485	4.285
20	47	555.327	557.756	-2.429
20	48	559.001	558.250	0.752
20	49	549.107	552.453	-3.347
20	50	546.226	547.502	-1.277
20	51	537.696	538.648	-0.951
20	52	545.963	545.699	0.264
20	53	547.085	549.334	-2.249
20	54	544.969	546.773	-1.805
20	55	536.437	538.600	-2.163
20	56	536.965	539.304	-2.339
30	1	540.525	548.653	-8.128
30	2	546.157	545.677	0.481
30	3	552.394	555.584	-3.190
30	4	544.410	551.027	-6.617
30	5	560.522	572.091	-11.570
30	62	550.527	552.990	-2.463
30	63	550.676	563.300	-12.624
30	64	555.260	557.833	-2.573
30	65	549.388	555.036	-5.648
30	66	560.466	576.291	-15.825
	Max	561.096	576.291	16.192
	Average	551.454	552.099	-0.645
	Min	536.437	534.500	-15.825
	Std Dev	6.097	7.910	5.442



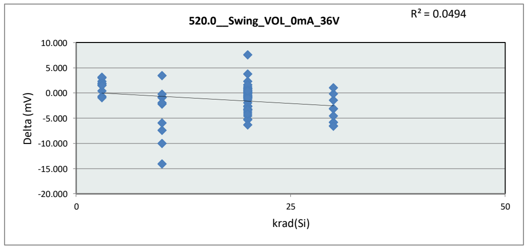
	510.3__Swing_VOL_4mA_36V			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	880	mV		
Min Limit	0.1	mV		
krad(Si)	3	10	20	30
LL	0.100	0.100	0.100	0.100
Min	537.674	534.500	538.600	545.677
Average	544.973	546.331	553.652	557.848
Max	554.769	555.063	563.443	576.291
UL	880.000	880.000	880.000	880.000



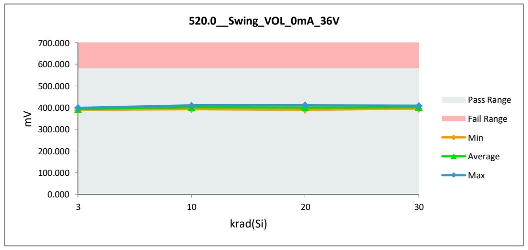
TID LDR Report
TLV1704-SEP

	520.0__Swing_VOL_0mA_36V	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	mV	mV
Max Limit	580	580
Min Limit	0.1	0.1

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	390.670	389.121	1.549
3	2	393.848	392.011	1.838
3	3	395.197	395.920	-0.722
3	4	393.011	390.736	2.275
3	5	401.872	398.915	2.957
3	6	395.153	394.785	0.368
3	7	395.428	392.321	3.107
3	8	394.237	392.345	1.892
3	9	397.486	396.064	1.422
3	0	393.511	394.477	-0.967
10	1	396.448	393.035	3.414
10	2	396.329	397.273	-0.943
10	3	394.512	400.487	-5.975
10	4	395.234	402.680	-7.446
10	5	395.187	405.231	-10.045
10	6	400.804	401.637	-0.834
10	7	398.129	400.347	-2.218
10	8	399.466	399.697	-0.231
10	9	399.610	401.554	-1.944
10	10	395.876	409.983	-14.107
20	11	396.448	401.805	-5.357
20	12	396.329	397.349	-1.020
20	13	394.512	397.876	-3.364
20	14	395.234	395.954	-0.721
20	15	395.187	395.715	-0.528
20	16	400.804	405.382	-4.578
20	17	398.129	396.525	1.604
20	18	399.466	398.551	0.915
20	19	399.610	399.803	-0.193
20	20	395.876	398.523	-2.647
20	21	395.554	398.270	-2.716
20	22	402.048	402.497	-0.449
20	23	400.843	400.829	0.014
20	24	400.598	399.812	0.786
20	25	400.631	399.816	0.815
20	26	400.141	401.139	-0.998
20	27	402.593	400.292	2.301
20	28	402.069	400.879	1.190
20	29	401.440	401.316	0.124
20	30	403.162	402.765	0.397
20	31	401.327	406.617	-5.290
20	32	402.873	402.069	0.804
20	33	400.644	404.488	-3.844
20	34	402.844	401.283	1.561
20	35	404.439	403.975	0.464
20	36	403.035	395.477	7.559
20	37	401.991	401.942	0.049
20	38	400.174	401.240	-1.066
20	39	401.271	403.863	-2.592
20	40	404.005	410.334	-6.328
20	41	400.135	403.572	-3.437
20	42	396.504	398.487	-1.984
20	43	393.932	394.762	-0.829
20	44	395.968	399.220	-3.252
20	45	401.700	401.716	-0.015
20	46	401.868	398.146	3.723
20	47	403.317	404.747	-1.431
20	48	403.010	402.835	0.176
20	49	395.662	398.881	-3.219
20	50	394.849	395.596	-0.748
20	51	388.993	392.358	-3.365
20	52	396.148	395.603	0.545
20	53	396.052	396.723	-0.671
20	54	401.933	406.123	-4.191
20	55	389.122	390.110	-0.989
20	56	394.975	394.585	0.390
30	1	390.670	396.526	-5.856
30	2	393.848	395.322	-1.473
30	3	395.197	401.765	-6.568
30	4	393.011	398.839	-5.828
30	5	401.872	406.476	-4.604
30	62	399.741	402.898	-3.157
30	63	396.642	399.760	-3.118
30	64	400.274	400.469	-0.194
30	65	403.009	401.983	1.026
30	66	401.928	408.548	-6.620
	Max	404.439	410.334	7.559
	Average	398.101	399.488	-1.387
	Min	388.993	389.121	-14.107
	Std Dev	3.791	4.504	3.324



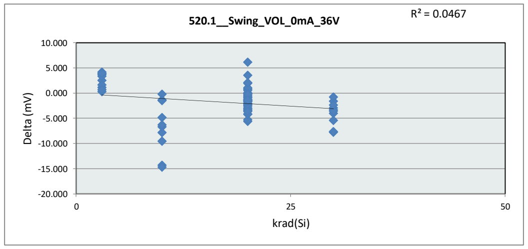
	520.0__Swing_VOL_0mA_36V			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	580	mV		
Min Limit	0.1	mV		
krad(Si)	3	10	20	30
LL	0.100	0.100	0.100	0.100
Min	389.121	393.035	390.110	395.322
Average	393.670	401.192	399.997	401.258
Max	398.916	409.983	410.334	408.548
UL	580.000	580.000	580.000	580.000



TID LDR Report
TLV1704-SEP

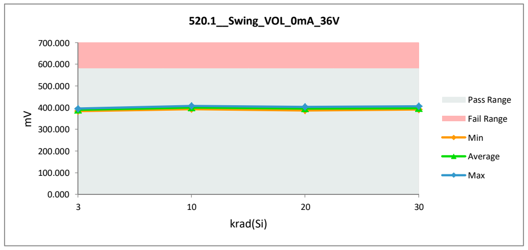
	520.1__Swing_VOL_0mA_36V	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	mV	mV
Max Limit	580	580
Min Limit	0.1	0.1

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	386.664	384.186	2.478
3	2	389.550	385.940	3.610
3	3	394.536	393.465	1.071
3	4	389.651	386.333	3.318
3	5	399.056	395.266	3.790
3	6	392.668	391.061	1.607
3	7	392.207	388.068	4.138
3	8	391.294	387.421	3.874
3	9	393.825	393.577	0.248
3	0	394.477	393.854	0.623
10	1	392.215	392.445	-0.230
10	2	394.393	395.769	-1.376
10	3	392.299	401.883	-9.584
10	4	391.964	399.826	-7.862
10	5	392.767	407.134	-14.367
10	6	397.624	402.520	-4.896
10	7	392.797	399.533	-6.736
10	8	398.023	399.585	-1.562
10	9	396.273	402.652	-6.379
10	10	393.379	408.081	-14.702
20	11	392.215	397.847	-5.633
20	12	394.393	393.627	0.767
20	13	392.299	395.876	-3.577
20	14	391.964	391.193	0.771
20	15	392.767	392.993	-0.226
20	16	397.624	402.988	-5.364
20	17	392.797	394.151	-1.354
20	18	398.023	398.043	-0.020
20	19	396.273	397.582	-1.309
20	20	393.379	396.399	-3.020
20	21	393.092	396.364	-3.272
20	22	398.286	399.900	-1.613
20	23	395.070	396.652	-1.581
20	24	395.172	395.287	-0.115
20	25	396.825	397.365	-0.540
20	26	396.912	395.035	1.878
20	27	396.879	399.246	-2.366
20	28	400.358	396.904	3.454
20	29	396.596	399.213	-2.617
20	30	398.311	399.145	-0.833
20	31	397.110	401.399	-4.289
20	32	396.965	397.787	-0.822
20	33	397.710	397.215	0.495
20	34	398.720	397.690	1.031
20	35	400.109	401.470	-1.361
20	36	398.240	392.171	6.069
20	37	396.790	397.015	-0.224
20	38	397.716	399.831	-2.115
20	39	397.113	398.128	-1.015
20	40	397.655	400.725	-3.070
20	41	395.499	398.943	-3.445
20	42	394.637	397.240	-2.603
20	43	391.963	393.474	-1.511
20	44	392.598	396.779	-4.182
20	45	398.184	398.335	-0.151
20	46	395.307	393.255	2.052
20	47	398.489	400.272	-1.783
20	48	398.524	399.266	-0.742
20	49	393.400	397.083	-3.683
20	50	390.651	392.126	-1.475
20	51	386.199	388.457	-2.258
20	52	393.380	393.611	-0.231
20	53	393.464	394.961	-1.497
20	54	391.114	392.753	-1.639
20	55	385.378	387.104	-1.726
20	56	387.828	389.224	-1.396
30	1	386.664	394.470	-7.806
30	2	389.550	391.196	-1.647
30	3	394.536	397.512	-2.976
30	4	389.651	393.744	-4.093
30	5	399.056	404.519	-5.463
30	62	392.208	395.608	-3.400
30	63	393.913	397.556	-3.643
30	64	395.148	395.992	-0.844
30	65	394.427	396.849	-2.422
30	66	398.538	406.239	-7.701
	Max	400.358	408.081	6.069
	Average	394.386	396.242	-1.856
	Min	385.378	384.186	-14.702
	Std Dev	3.443	4.782	3.656



	520.1__Swing_VOL_0mA_36V	
Test Site	MLA	
Tester	ETS364	
Test Number	EB083902	
Max Limit	580	mV
Min Limit	0.1	mV

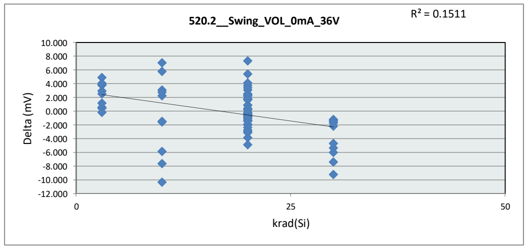
krad(Si)	3	10	20	30
LL	0.100	0.100	0.100	0.100
Min	384.186	392.445	387.104	391.196
Average	389.917	400.943	396.350	397.369
Max	395.266	408.081	402.988	406.239
UL	580.000	580.000	580.000	580.000



TID LDR Report
TLV1704-SEP

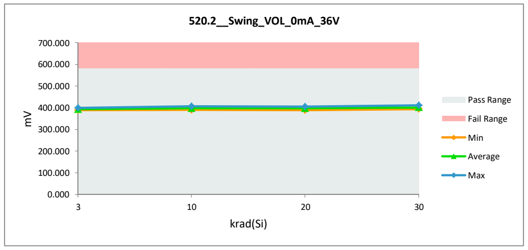
	520.2__Swing_VOL_0mA_36V	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	mV	mV
Max Limit	580	580
Min Limit	0.1	0.1

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	391.055	388.138	2.918
3	2	392.558	388.776	3.782
3	3	398.980	398.542	0.438
3	4	394.089	390.217	3.872
3	5	402.572	397.677	4.895
3	6	394.700	394.116	0.583
3	7	396.236	392.156	4.081
3	8	394.548	392.026	2.522
3	9	395.736	395.895	-0.159
3	0	396.535	395.375	1.160
10	1	397.116	390.082	7.034
10	2	396.606	390.815	5.792
10	3	396.022	397.601	-1.579
10	4	395.439	396.921	-1.481
10	5	393.272	400.879	-7.607
10	6	400.448	398.213	2.235
10	7	395.842	406.179	-10.337
10	8	399.651	396.572	3.079
10	9	400.042	397.288	2.754
10	10	395.668	401.543	-5.876
20	11	397.116	401.997	-4.880
20	12	396.606	394.239	2.367
20	13	396.022	399.123	-3.101
20	14	395.439	393.723	1.716
20	15	393.272	392.922	0.349
20	16	400.448	404.315	-3.867
20	17	395.842	393.343	2.499
20	18	399.651	397.329	2.322
20	19	400.042	400.289	-0.247
20	20	395.668	396.085	-0.417
20	21	394.620	396.596	-1.976
20	22	401.813	398.751	3.061
20	23	399.371	400.100	-0.729
20	24	400.357	398.525	1.831
20	25	400.578	401.258	-0.680
20	26	399.616	397.417	2.199
20	27	400.437	401.851	-1.413
20	28	404.284	398.891	5.393
20	29	400.284	399.907	0.377
20	30	400.707	399.853	0.854
20	31	399.750	402.836	-3.086
20	32	400.173	399.263	0.911
20	33	400.971	397.246	3.725
20	34	400.871	398.474	2.396
20	35	402.375	403.653	-1.278
20	36	402.279	394.987	7.292
20	37	400.694	402.600	-1.906
20	38	399.835	400.915	-1.080
20	39	400.742	401.175	-0.433
20	40	402.605	405.338	-2.733
20	41	396.366	398.711	-2.345
20	42	397.220	398.082	-0.862
20	43	394.211	395.608	-1.396
20	44	397.018	399.950	-2.932
20	45	398.415	398.582	-0.167
20	46	399.197	395.102	4.095
20	47	404.251	400.845	3.406
20	48	402.110	400.471	1.638
20	49	396.184	397.605	-1.421
20	50	395.363	395.191	0.172
20	51	388.942	389.669	-0.727
20	52	395.123	393.383	1.740
20	53	394.891	395.436	-0.545
20	54	393.871	394.396	-0.524
20	55	388.450	388.787	-0.337
20	56	389.726	390.540	-0.814
30	1	391.055	396.420	-5.365
30	2	392.558	393.889	-1.332
30	3	398.980	400.170	-1.190
30	4	394.089	401.474	-7.385
30	5	402.572	408.548	-5.975
30	62	396.516	398.039	-1.524
30	63	397.536	402.244	-4.708
30	64	400.429	402.129	-1.700
30	65	397.036	399.198	-2.161
30	66	402.291	411.515	-9.224
	Max	404.284	411.515	7.292
	Average	397.552	397.737	-0.184
	Min	388.450	388.138	-10.337
	Std Dev	3.574	4.541	3.479



	520.2__Swing_VOL_0mA_36V	
Test Site	MLA	
Tester	ETS364	
Test Number	EB083902	
Max Limit	580	mV
Min Limit	0.1	mV

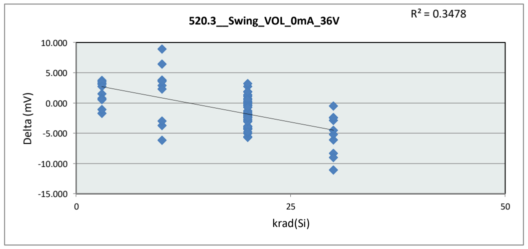
krad(Si)	3	10	20	30
LL	0.100	0.100	0.100	0.100
Min	388.138	390.083	388.787	393.889
Average	393.292	397.609	397.943	401.363
Max	398.542	406.179	405.338	411.515
UL	580.000	580.000	580.000	580.000



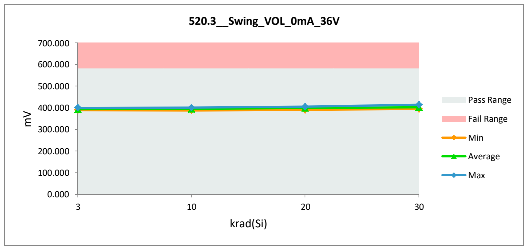
TID LDR Report
TLV1704-SEP

	520.3__Swing_VOL_0mA_36V	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	mV	mV
Max Limit	580	580
Min Limit	0.1	0.1

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	391.100	389.596	1.504
3	2	394.304	391.076	3.229
3	3	398.183	399.917	-1.734
3	4	392.652	389.542	3.110
3	5	402.831	399.130	3.700
3	6	394.646	393.901	0.745
3	7	394.544	391.033	3.512
3	8	393.174	390.440	2.734
3	9	395.317	396.406	-1.089
3	0	394.699	394.157	0.542
10	1	397.074	388.171	8.903
10	2	395.189	391.426	3.763
10	3	393.243	396.989	-3.746
10	4	397.352	394.489	2.864
10	5	394.165	400.326	-6.161
10	6	399.775	396.049	3.726
10	7	397.633	395.352	2.281
10	8	400.676	394.235	6.441
10	9	399.754	396.180	3.574
10	10	395.948	398.967	-3.018
20	11	397.074	401.415	-4.341
20	12	395.189	395.301	-0.113
20	13	393.243	397.090	-3.847
20	14	397.352	396.061	1.291
20	15	394.165	394.079	0.086
20	16	399.775	405.471	-5.696
20	17	397.633	396.545	1.088
20	18	400.676	399.943	0.733
20	19	399.754	400.081	-0.327
20	20	395.948	398.737	-2.789
20	21	394.673	397.797	-3.124
20	22	400.418	400.813	-0.395
20	23	398.551	400.442	-1.892
20	24	399.234	399.118	0.116
20	25	400.383	400.102	0.282
20	26	399.917	405.476	-5.558
20	27	402.612	401.272	1.339
20	28	402.197	400.360	1.837
20	29	400.762	401.457	-0.695
20	30	399.784	402.580	-2.796
20	31	400.350	405.427	-5.077
20	32	400.676	404.847	-4.171
20	33	402.065	399.336	2.729
20	34	403.092	402.548	0.544
20	35	402.369	403.654	-1.285
20	36	401.107	397.906	3.201
20	37	400.573	404.454	-3.881
20	38	399.679	401.737	-2.057
20	39	402.337	404.135	-1.798
20	40	399.797	404.052	-4.255
20	41	398.148	402.363	-4.216
20	42	395.957	398.774	-2.817
20	43	393.813	397.767	-3.954
20	44	395.444	400.227	-4.783
20	45	400.592	401.962	-1.370
20	46	398.571	396.674	1.897
20	47	399.425	401.913	-2.487
20	48	401.491	401.941	-0.450
20	49	396.657	399.715	-3.058
20	50	394.618	396.424	-1.806
20	51	388.882	390.461	-1.579
20	52	394.352	395.075	-0.724
20	53	395.520	397.873	-2.353
20	54	394.000	396.128	-2.129
20	55	388.140	390.472	-2.331
20	56	388.810	391.255	-2.445
30	1	391.100	397.224	-6.124
30	2	394.304	394.831	-0.527
30	3	398.183	401.089	-2.907
30	4	392.652	397.861	-5.209
30	5	402.831	411.154	-8.323
30	62	396.901	399.319	-2.418
30	63	397.306	406.318	-9.011
30	64	400.240	402.723	-2.483
30	65	396.845	401.396	-4.551
30	66	402.492	413.600	-11.108
	Max	403.092	413.600	8.903
	Average	397.381	398.607	-1.227
	Min	388.140	388.171	-11.108
	Std Dev	3.605	4.902	3.492



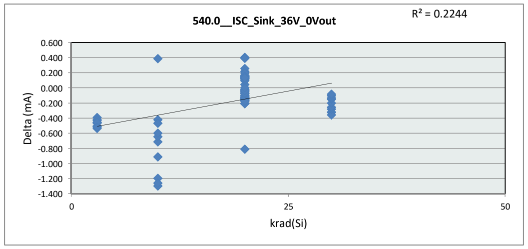
	520.3__Swing_VOL_0mA_36V			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	580	mV		
Min Limit	0.1	mV		
krad(Si)	3	10	20	30
LL	0.100	0.100	0.100	0.100
Min	389.542	388.171	390.461	394.831
Average	393.520	395.218	399.593	402.552
Max	399.917	400.326	405.476	413.600
UL	580.000	580.000	580.000	580.000



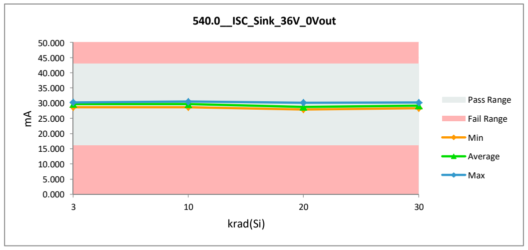
TID LDR Report
TLV1704-SEP

	540.0__ISC_Sink_36V_0Vout	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	mA	mA
Max Limit	43	43
Min Limit	16	16

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	29.885	30.279	-0.393
3	2	29.072	29.493	-0.421
3	3	29.224	29.689	-0.465
3	4	29.217	29.724	-0.507
3	5	28.187	28.692	-0.506
3	6	29.371	29.802	-0.430
3	7	29.275	29.811	-0.536
3	8	29.291	29.755	-0.464
3	9	29.511	29.969	-0.458
3	0	29.518	30.037	-0.519
10	1	29.243	30.541	-1.298
10	2	29.288	29.712	-0.424
10	3	29.154	29.868	-0.715
10	4	29.158	29.804	-0.646
10	5	29.053	28.668	0.386
10	6	28.629	29.826	-1.197
10	7	29.109	29.577	-0.467
10	8	28.613	29.526	-0.913
10	9	28.499	29.760	-1.260
10	10	29.197	29.797	-0.600
20	11	29.243	29.370	-0.127
20	12	29.288	29.439	-0.151
20	13	29.154	29.206	-0.052
20	14	29.158	29.365	-0.207
20	15	29.053	29.226	-0.172
20	16	28.629	28.800	-0.171
20	17	29.109	29.250	-0.141
20	18	28.613	28.742	-0.128
20	19	28.499	28.663	-0.164
20	20	29.197	29.328	-0.132
20	21	29.476	29.495	-0.019
20	22	28.532	28.602	-0.070
20	23	28.548	28.686	-0.138
20	24	28.577	28.686	-0.109
20	25	28.535	28.643	-0.108
20	26	28.523	28.631	-0.108
20	27	28.416	28.515	-0.099
20	28	28.420	28.379	0.042
20	29	28.277	28.304	-0.028
20	30	28.255	28.333	-0.079
20	31	28.379	28.258	0.122
20	32	28.212	28.361	-0.149
20	33	28.334	28.546	-0.212
20	34	28.254	28.400	-0.146
20	35	28.052	28.228	-0.175
20	36	28.257	29.067	-0.810
20	37	28.101	28.157	-0.056
20	38	28.439	28.512	-0.073
20	39	28.262	28.299	-0.037
20	40	27.945	27.946	-0.001
20	41	28.404	28.003	0.402
20	42	29.247	28.856	0.391
20	43	29.525	29.272	0.253
20	44	29.271	29.054	0.217
20	45	28.277	28.121	0.155
20	46	28.958	28.813	0.145
20	47	28.188	28.058	0.130
20	48	28.139	28.015	0.124
20	49	28.988	28.844	0.145
20	50	29.430	29.263	0.166
20	51	30.192	29.996	0.196
20	52	29.276	29.184	0.093
20	53	29.392	29.284	0.108
20	54	29.435	29.281	0.154
20	55	30.295	30.162	0.133
20	56	30.014	29.883	0.130
30	1	29.885	30.208	-0.322
30	2	29.072	29.398	-0.326
30	3	29.224	29.584	-0.360
30	4	29.217	29.501	-0.285
30	5	28.187	28.444	-0.257
30	62	29.084	29.287	-0.202
30	63	29.159	29.310	-0.152
30	64	28.912	29.045	-0.133
30	65	28.808	28.914	-0.106
30	66	28.310	28.393	-0.084
	Max	30.295	30.541	0.402
	Average	28.910	29.104	-0.195
	Min	27.945	27.946	-1.298
	Std Dev	0.543	0.645	0.348



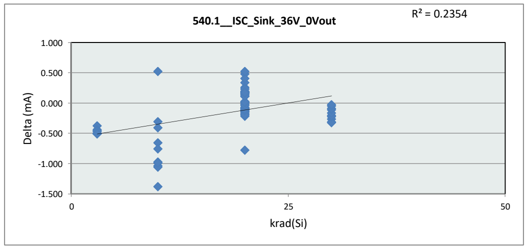
	540.0__ISC_Sink_36V_0Vout			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	43	mA		
Min Limit	16	mA		
krad(Si)	3	10	20	30
LL	16.000	16.000	16.000	16.000
Min	28.692	28.668	27.946	28.394
Average	29.725	29.708	28.816	29.208
Max	30.279	30.541	30.162	30.208
UL	43.000	43.000	43.000	43.000



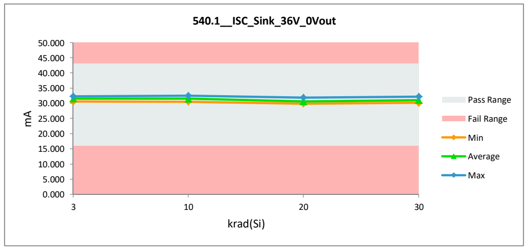
TID LDR Report
TLV1704-SEP

	540.1__ISC_Sink_36V_0Vout	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	mA	mA
Max Limit	43	43
Min Limit	16	16

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	31.879	32.257	-0.378
3	2	31.332	31.795	-0.463
3	3	30.987	31.486	-0.499
3	4	31.135	31.644	-0.509
3	5	30.050	30.552	-0.502
3	6	31.015	31.456	-0.440
3	7	31.123	31.635	-0.512
3	8	31.150	31.614	-0.464
3	9	31.061	31.528	-0.467
3	0	30.994	31.501	-0.508
10	1	31.149	32.533	-1.384
10	2	30.965	32.003	-1.038
10	3	30.954	31.615	-0.661
10	4	30.935	31.695	-0.760
10	5	31.044	30.522	0.522
10	6	30.389	31.447	-1.058
10	7	30.956	31.365	-0.409
10	8	30.393	31.368	-0.975
10	9	30.285	31.279	-0.994
10	10	30.931	31.241	-0.310
20	11	31.149	31.245	-0.097
20	12	30.965	31.108	-0.143
20	13	30.954	31.027	-0.073
20	14	30.935	31.106	-0.171
20	15	31.044	31.194	-0.150
20	16	30.389	30.517	-0.128
20	17	30.956	31.058	-0.103
20	18	30.393	30.501	-0.108
20	19	30.285	30.393	-0.109
20	20	30.931	31.028	-0.097
20	21	31.073	31.068	0.004
20	22	30.220	30.239	-0.019
20	23	30.546	30.642	-0.096
20	24	30.545	30.626	-0.081
20	25	30.428	30.515	-0.087
20	26	30.367	30.557	-0.190
20	27	30.444	30.108	0.336
20	28	30.051	30.271	-0.219
20	29	30.221	30.078	0.143
20	30	30.085	30.232	-0.146
20	31	30.330	30.222	0.108
20	32	30.201	30.176	0.025
20	33	30.163	30.359	-0.197
20	34	30.049	30.173	-0.124
20	35	30.168	30.279	-0.111
20	36	30.124	30.905	-0.782
20	37	30.259	30.298	-0.039
20	38	30.207	30.242	-0.035
20	39	30.160	30.146	0.015
20	40	30.082	30.069	0.012
20	41	30.472	29.992	0.479
20	42	30.931	30.525	0.406
20	43	31.194	30.671	0.522
20	44	31.098	30.839	0.259
20	45	30.247	30.017	0.231
20	46	30.925	30.751	0.175
20	47	29.987	29.825	0.163
20	48	30.098	29.923	0.174
20	49	30.718	30.554	0.163
20	50	31.087	30.896	0.191
20	51	31.744	31.514	0.230
20	52	30.842	30.714	0.128
20	53	30.882	30.773	0.110
20	54	31.236	31.051	0.185
20	55	31.994	31.830	0.165
20	56	31.568	31.403	0.165
30	1	31.879	32.149	-0.270
30	2	31.332	31.645	-0.313
30	3	30.987	31.312	-0.325
30	4	31.135	31.358	-0.223
30	5	30.050	30.257	-0.207
30	62	30.847	31.016	-0.169
30	63	30.895	31.011	-0.116
30	64	30.726	30.820	-0.094
30	65	30.594	30.647	-0.053
30	66	30.099	30.130	-0.031
	Max	31.994	32.533	0.522
	Average	30.737	30.902	-0.165
	Min	29.987	29.825	-1.384
	Std Dev	0.492	0.625	0.373



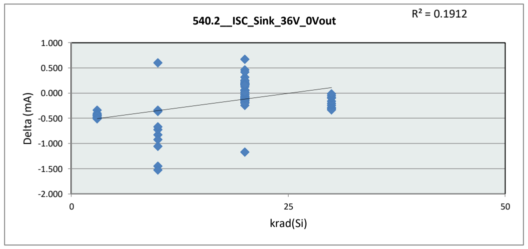
	540.1__ISC_Sink_36V_0Vout			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	43	mA		
Min Limit	16	mA		
krad(Si)	3	10	20	30
LL	16.000	16.000	16.000	16.000
Min	30.553	30.522	29.825	30.130
Average	31.547	31.507	30.601	31.035
Max	32.257	32.533	31.830	32.149
UL	43.000	43.000	43.000	43.000



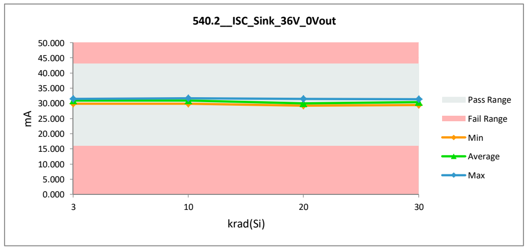
TID LDR Report
TLV1704-SEP

	540.2__ISC_Sink_36V_0Vout	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	mA	mA
Max Limit	43	43
Min Limit	16	16

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	31.071	31.413	-0.342
3	2	30.448	30.854	-0.406
3	3	30.308	30.757	-0.449
3	4	30.428	30.916	-0.488
3	5	29.375	29.854	-0.479
3	6	30.689	31.125	-0.436
3	7	30.622	31.136	-0.514
3	8	30.496	30.925	-0.430
3	9	30.861	31.309	-0.447
3	0	30.851	31.350	-0.499
10	1	30.635	31.694	-1.059
10	2	30.711	31.083	-0.372
10	3	30.079	30.908	-0.829
10	4	30.244	30.978	-0.734
10	5	30.425	29.829	0.596
10	6	29.638	31.095	-1.457
10	7	30.519	30.863	-0.344
10	8	29.760	30.686	-0.926
10	9	29.550	31.080	-1.530
10	10	30.416	31.088	-0.672
20	11	30.635	30.738	-0.102
20	12	30.711	30.839	-0.128
20	13	30.079	30.152	-0.073
20	14	30.244	30.430	-0.186
20	15	30.425	30.585	-0.160
20	16	29.638	29.755	-0.117
20	17	30.519	30.667	-0.149
20	18	29.760	29.877	-0.116
20	19	29.550	29.694	-0.144
20	20	30.416	30.524	-0.109
20	21	30.813	30.809	0.004
20	22	29.681	29.719	-0.037
20	23	29.744	29.853	-0.109
20	24	29.799	29.872	-0.073
20	25	29.645	29.723	-0.078
20	26	29.647	29.896	-0.249
20	27	29.777	29.468	0.310
20	28	29.406	29.603	-0.198
20	29	29.538	29.486	0.052
20	30	29.492	29.437	0.055
20	31	29.554	29.497	0.057
20	32	29.486	29.441	0.044
20	33	29.448	29.649	-0.201
20	34	29.497	29.614	-0.117
20	35	29.411	29.502	-0.091
20	36	29.281	30.458	-1.177
20	37	29.229	29.262	-0.033
20	38	29.544	29.579	-0.035
20	39	29.366	29.361	0.004
20	40	29.199	29.195	0.004
20	41	29.812	29.352	0.459
20	42	30.396	29.985	0.410
20	43	30.962	30.294	0.668
20	44	30.458	30.214	0.244
20	45	29.636	29.421	0.214
20	46	30.408	30.228	0.180
20	47	29.507	29.349	0.158
20	48	29.461	29.275	0.186
20	49	30.275	30.101	0.174
20	50	30.378	30.187	0.192
20	51	31.618	31.374	0.244
20	52	30.516	30.394	0.122
20	53	30.683	30.529	0.155
20	54	30.597	30.417	0.181
20	55	31.587	31.425	0.162
20	56	31.282	31.124	0.158
30	1	31.071	31.362	-0.291
30	2	30.448	30.761	-0.313
30	3	30.308	30.643	-0.335
30	4	30.428	30.679	-0.250
30	5	29.375	29.582	-0.207
30	62	30.083	30.248	-0.166
30	63	30.517	30.621	-0.104
30	64	29.900	29.995	-0.095
30	65	30.150	30.206	-0.056
30	66	29.451	29.469	-0.018
	Max	31.618	31.694	0.668
	Average	30.131	30.301	-0.170
	Min	29.199	29.195	-1.530
	Std Dev	0.587	0.678	0.403



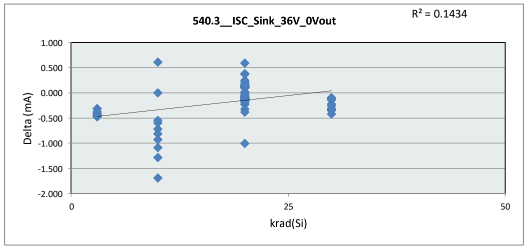
	540.2__ISC_Sink_36V_0Vout			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	43	mA		
Min Limit	16	mA		
krad(Si)	3	10	20	30
LL	16.000	16.000	16.000	16.000
Min	29.854	29.829	29.195	29.470
Average	30.964	30.930	30.008	30.357
Max	31.413	31.694	31.425	31.362
UL	43.000	43.000	43.000	43.000



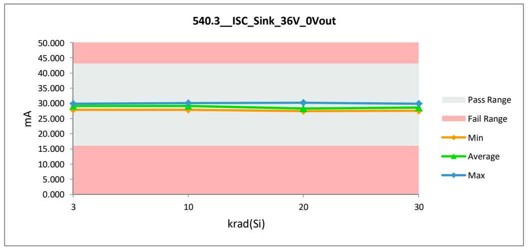
TID LDR Report
TLV1704-SEP

	540.3__ISC_Sink_36V_0Vout	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	mA	mA
Max Limit	43	43
Min Limit	16	16

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	29.539	29.855	-0.317
3	2	28.516	28.892	-0.375
3	3	28.457	28.898	-0.441
3	4	28.637	29.097	-0.461
3	5	27.421	27.859	-0.438
3	6	28.905	29.218	-0.313
3	7	28.924	29.402	-0.478
3	8	28.654	29.058	-0.404
3	9	29.308	29.711	-0.403
3	0	29.297	29.758	-0.460
10	1	29.032	30.120	-1.088
10	2	29.115	29.115	0.000
10	3	28.520	29.116	-0.596
10	4	28.458	29.173	-0.715
10	5	28.461	27.851	0.611
10	6	28.008	29.290	-1.282
10	7	28.620	29.165	-0.545
10	8	27.919	28.847	-0.929
10	9	27.812	29.500	-1.688
10	10	28.710	29.526	-0.815
20	11	29.032	29.163	-0.132
20	12	29.115	29.272	-0.157
20	13	28.520	28.589	-0.069
20	14	28.458	28.685	-0.227
20	15	28.461	28.657	-0.196
20	16	28.008	28.165	-0.157
20	17	28.620	28.770	-0.150
20	18	27.919	28.051	-0.133
20	19	27.812	27.962	-0.149
20	20	28.710	28.834	-0.124
20	21	28.966	28.974	-0.008
20	22	27.869	27.940	-0.071
20	23	27.999	28.129	-0.130
20	24	27.971	28.077	-0.106
20	25	27.827	27.935	-0.108
20	26	27.895	28.218	-0.323
20	27	28.034	27.785	0.249
20	28	27.698	27.849	-0.152
20	29	27.730	27.773	-0.042
20	30	27.730	27.617	0.114
20	31	27.684	27.771	-0.088
20	32	27.712	27.573	0.139
20	33	27.541	27.920	-0.379
20	34	27.303	27.458	-0.155
20	35	27.549	27.712	-0.163
20	36	27.591	28.596	-1.006
20	37	27.476	27.573	-0.098
20	38	27.624	27.720	-0.096
20	39	27.448	27.486	-0.038
20	40	27.527	27.508	0.020
20	41	27.863	27.481	0.382
20	42	28.615	28.247	0.369
20	43	29.027	28.437	0.590
20	44	28.917	28.714	0.203
20	45	27.649	27.493	0.156
20	46	28.615	28.495	0.120
20	47	27.779	27.665	0.114
20	48	27.641	27.525	0.116
20	49	28.563	28.441	0.122
20	50	28.784	28.622	0.161
20	51	30.097	29.886	0.211
20	52	28.810	28.718	0.092
20	53	28.965	28.864	0.101
20	54	29.100	28.948	0.152
20	55	30.314	30.181	0.134
20	56	29.957	29.809	0.148
30	1	29.539	29.863	-0.324
30	2	28.516	28.868	-0.352
30	3	28.457	28.873	-0.417
30	4	28.637	28.947	-0.311
30	5	27.421	27.675	-0.254
30	62	28.324	28.543	-0.220
30	63	28.840	28.965	-0.124
30	64	28.311	28.450	-0.139
30	65	28.344	28.457	-0.113
30	66	27.435	27.530	-0.095
	Max	30.314	30.181	0.611
	Average	28.377	28.565	-0.187
	Min	27.303	27.458	-1.688
	Std Dev	0.681	0.748	0.384

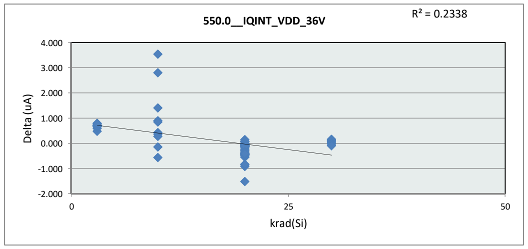


	540.3__ISC_Sink_36V_0Vout			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	43	mA		
Min Limit	16	mA		
krad(Si)	3	10	20	30
LL	16.000	16.000	16.000	16.000
Min	27.859	27.851	27.458	27.530
Average	29.175	29.170	28.289	28.617
Max	29.855	30.120	30.181	29.863
UL	43.000	43.000	43.000	43.000

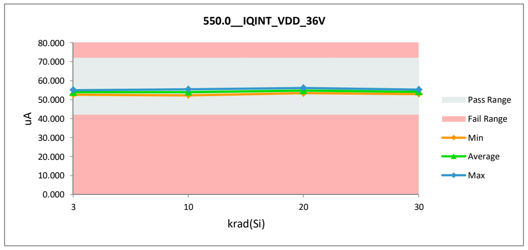


TID LDR Report
TLV1704-SEP

		550.0__IQINT_VDD_36V		
	Test Site	MLA	MLA	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	uA	uA	
	Max Limit	72	72	
	Min Limit	42	42	
krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	53.107	52.627	0.480
3	2	54.099	53.515	0.584
3	3	54.052	53.405	0.647
3	4	54.036	53.317	0.719
3	5	54.853	54.140	0.713
3	6	54.863	54.157	0.706
3	7	54.777	53.985	0.792
3	8	54.836	54.160	0.676
3	9	55.694	54.998	0.696
3	0	55.246	54.483	0.763
10	1	55.819	52.289	3.530
10	2	56.052	53.255	2.797
10	3	54.661	53.264	1.397
10	4	54.214	53.314	0.900
10	5	53.659	54.229	-0.570
10	6	55.088	54.240	0.848
10	7	54.885	54.460	0.425
10	8	54.960	54.596	0.365
10	9	55.275	55.417	-0.142
10	10	55.195	54.921	0.274
20	11	55.819	55.912	-0.094
20	12	56.052	56.101	-0.050
20	13	54.661	54.811	-0.150
20	14	54.214	54.203	0.011
20	15	53.659	53.674	-0.014
20	16	55.088	55.129	-0.041
20	17	54.885	54.982	-0.098
20	18	54.960	55.034	-0.073
20	19	55.275	55.340	-0.065
20	20	55.195	55.335	-0.139
20	21	54.746	55.036	-0.290
20	22	54.746	54.905	-0.159
20	23	54.768	54.847	-0.079
20	24	54.542	54.660	-0.119
20	25	55.052	55.184	-0.132
20	26	55.069	54.923	0.146
20	27	54.901	54.813	0.089
20	28	54.655	54.570	0.085
20	29	54.431	54.980	-0.549
20	30	54.730	54.986	-0.256
20	31	54.604	54.821	-0.217
20	32	54.615	54.701	-0.085
20	33	54.460	55.314	-0.854
20	34	54.905	54.841	0.064
20	35	54.580	54.569	0.012
20	36	54.818	54.834	-0.016
20	37	55.245	55.305	-0.059
20	38	55.192	55.265	-0.073
20	39	55.276	55.417	-0.141
20	40	55.193	55.309	-0.116
20	41	54.265	55.181	-0.916
20	42	53.635	54.470	-0.835
20	43	53.311	54.824	-1.513
20	44	53.932	54.468	-0.535
20	45	54.738	55.216	-0.478
20	46	53.612	54.064	-0.452
20	47	54.902	55.313	-0.411
20	48	55.129	55.564	-0.435
20	49	53.854	54.292	-0.438
20	50	53.579	54.027	-0.448
20	51	53.068	53.543	-0.475
20	52	53.700	54.037	-0.337
20	53	53.636	54.003	-0.367
20	54	53.546	53.978	-0.432
20	55	52.999	53.393	-0.394
20	56	53.449	53.862	-0.413
30	1	53.107	52.997	0.110
30	2	54.099	53.952	0.147
30	3	54.052	53.888	0.164
30	4	54.036	53.958	0.078
30	5	54.853	54.762	0.091
30	62	53.911	53.786	0.125
30	63	55.022	54.980	0.042
30	64	53.977	53.981	-0.005
30	65	54.101	54.168	-0.067
30	66	55.131	55.226	-0.095
	Max	56.052	56.101	3.530
	Average	54.544	54.480	0.064
	Min	52.999	52.289	-1.513
	Std Dev	0.719	0.760	0.700



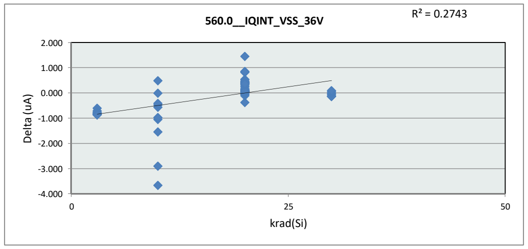
	550.0__IQINT_VDD_36V			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	72	uA		
Min Limit	42	uA		
krad(Si)	3	10	20	30
LL	42.000	42.000	42.000	42.000
Min	52.627	52.289	53.393	52.997
Average	53.879	53.998	54.783	54.170
Max	54.998	55.417	56.101	55.226
UL	72.000	72.000	72.000	72.000



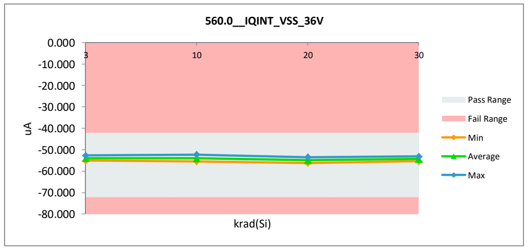
TID LDR Report
TLV1704-SEP

	560.0__IQINT_VSS_36V	
Test Site	MLA	MLA
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	uA	uA
Max Limit	-42	-42
Min Limit	-72	-72

krad(Si)	Serial #	Pre Test LDR	Post test LDR	Delta
3	1	-53.272	-52.659	-0.614
3	2	-54.264	-53.548	-0.716
3	3	-54.198	-53.433	-0.765
3	4	-54.176	-53.341	-0.835
3	5	-54.989	-54.176	-0.813
3	6	-55.031	-54.179	-0.852
3	7	-54.880	-54.017	-0.863
3	8	-54.970	-54.192	-0.778
3	9	-55.858	-55.038	-0.821
3	0	-55.410	-54.532	-0.879
10	1	-55.970	-52.296	-3.674
10	2	-56.181	-53.270	-2.911
10	3	-54.832	-53.279	-1.552
10	4	-54.378	-53.329	-1.049
10	5	-53.771	-54.249	0.478
10	6	-55.233	-54.259	-0.974
10	7	-55.052	-54.475	-0.577
10	8	-55.101	-54.611	-0.490
10	9	-55.446	-55.435	-0.011
10	10	-55.363	-54.939	-0.424
20	11	-55.970	-56.041	0.070
20	12	-56.181	-56.228	0.047
20	13	-54.832	-54.930	0.098
20	14	-54.378	-54.327	-0.051
20	15	-53.771	-53.786	0.015
20	16	-55.233	-55.258	0.025
20	17	-55.052	-55.100	0.048
20	18	-55.101	-55.157	0.056
20	19	-55.446	-55.466	0.021
20	20	-55.363	-55.451	0.088
20	21	-54.913	-55.148	0.236
20	22	-54.917	-55.031	0.114
20	23	-54.902	-54.971	0.069
20	24	-54.637	-54.783	0.146
20	25	-55.222	-55.307	0.085
20	26	-55.189	-55.331	0.142
20	27	-55.313	-54.935	-0.378
20	28	-54.805	-54.691	-0.115
20	29	-54.569	-55.097	0.529
20	30	-54.864	-55.105	0.241
20	31	-54.777	-54.941	0.164
20	32	-54.735	-54.819	0.084
20	33	-54.621	-55.437	0.815
20	34	-55.077	-55.006	-0.070
20	35	-54.681	-54.687	0.007
20	36	-54.944	-54.931	-0.013
20	37	-55.415	-55.412	-0.003
20	38	-55.328	-55.373	0.044
20	39	-55.447	-55.510	0.063
20	40	-55.339	-55.406	0.068
20	41	-54.440	-55.285	0.844
20	42	-53.739	-54.573	0.834
20	43	-53.476	-54.921	1.444
20	44	-54.036	-54.564	0.529
20	45	-54.860	-55.327	0.467
20	46	-53.751	-54.158	0.408
20	47	-55.014	-55.420	0.407
20	48	-55.243	-55.660	0.417
20	49	-54.023	-54.383	0.360
20	50	-53.745	-54.114	0.369
20	51	-53.230	-53.632	0.401
20	52	-53.796	-54.138	0.342
20	53	-53.802	-54.102	0.300
20	54	-53.635	-54.078	0.443
20	55	-53.099	-53.483	0.384
20	56	-53.602	-53.960	0.357
30	1	-53.272	-53.159	-0.113
30	2	-54.264	-54.121	-0.143
30	3	-54.198	-54.055	-0.144
30	4	-54.176	-54.125	-0.052
30	5	-54.989	-54.935	-0.055
30	62	-54.024	-53.889	-0.135
30	63	-55.121	-55.077	-0.043
30	64	-54.068	-54.078	0.011
30	65	-54.197	-54.257	0.060
30	66	-55.303	-55.388	0.084
	Max	-53.099	-52.296	1.444
	Average	-54.691	-54.576	-0.114
	Min	-56.181	-56.228	-3.674
	Std Dev	0.726	0.783	0.729



	560.0__IQINT_VSS_36V			
Test Site	MLA			
Tester	ETS364			
Test Number	EB083902			
Max Limit	-42	uA		
Min Limit	-72	uA		
krad(Si)	3	10	20	30
LL	-72.000	-72.000	-72.000	-72.000
Min	-55.038	-55.435	-56.228	-55.388
Average	-53.911	-54.014	-54.901	-54.308
Max	-52.659	-52.296	-53.483	-53.159
UL	-42.000	-42.000	-42.000	-42.000



Appendix B

SLOK013–November 2018

Total Ionizing Dose HDR Report

This appendix provides the TLV1704-SEP TID HDR report.

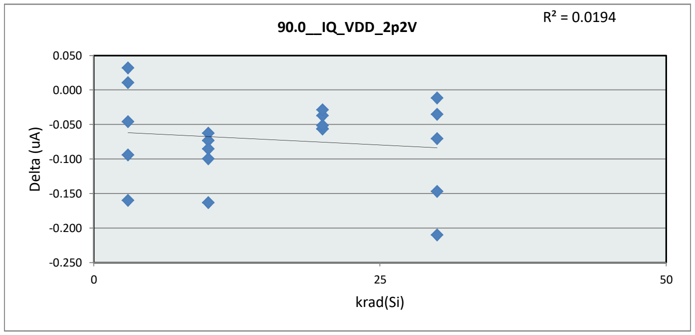
Delta Threshold 10.00%

TID HDR Report
TLV1704-SEP

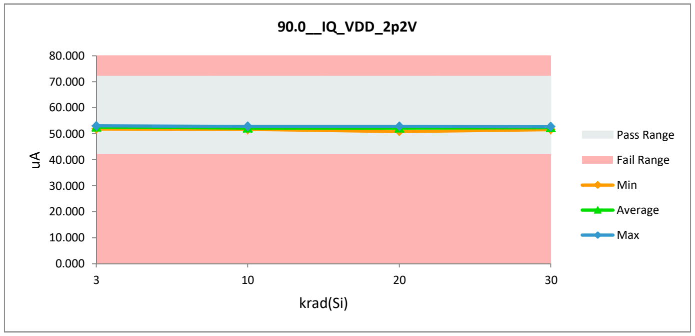
TID HDR Report
TLV1704-SEP

	90.0__IQ_VDD_2p2V		
Test Site	DALLAS	DALLAS	
Tester	ETS364	ETS364	
Test Number	EB083902	EB083902	
Unit	uA	uA	
Max Limit	72	72	
Min Limit	42	42	

krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	52.568	52.661	-0.094
3	2	52.623	52.669	-0.046
3	3	51.879	51.847	0.032
3	4	52.807	52.966	-0.160
3	5	52.748	52.737	0.011
10	6	52.133	52.233	-0.100
10	7	52.377	52.440	-0.063
10	8	51.652	51.725	-0.073
10	9	52.660	52.822	-0.163
10	10	51.521	51.606	-0.085
20	11	52.749	52.804	-0.056
20	12	52.204	52.260	-0.056
20	13	52.274	52.325	-0.051
20	14	52.544	52.581	-0.037
20	15	50.807	50.836	-0.029
30	16	51.581	51.592	-0.011
30	17	52.343	52.489	-0.147
30	18	52.588	52.659	-0.070
30	19	52.370	52.580	-0.210
30	20	52.106	52.141	-0.035
	Max	52.807	52.966	0.032
	Average	52.227	52.299	-0.072
	Min	50.807	50.836	-0.210
	Std Dev	0.515	0.536	0.061



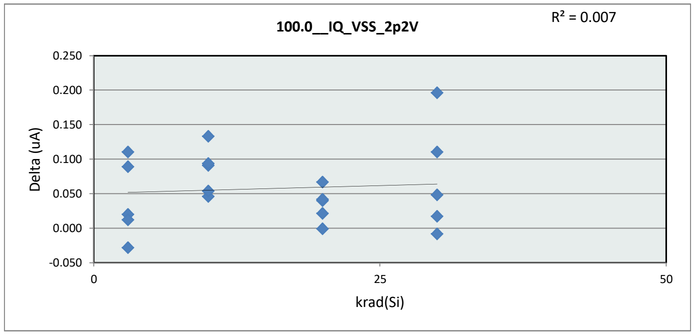
	90.0__IQ_VDD_2p2V			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	72	uA		
Min Limit	42	uA		
krad(Si)	3	10	20	30
LL	42.000	42.000	42.000	42.000
Min	51.847	51.606	50.836	51.592
Average	52.576	52.165	52.161	52.292
Max	52.967	52.822	52.804	52.659
UL	72.000	72.000	72.000	72.000



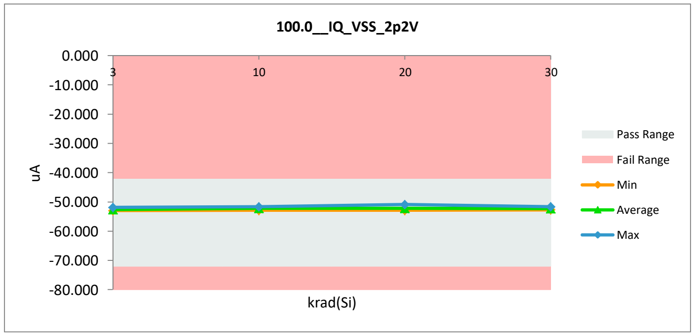
TID HDR Report
TLV1704-SEP

	100.0__IQ_VSS_2p2V	
Test Site	DALLAS	DALLAS
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	uA	uA
Max Limit	-42	-42
Min Limit	-72	-72

krad(Si)	Serial #	re Test HDR Biase	st test HDR.txt Bia	Delta
3	1	-52.631	-52.720	0.089
3	2	-52.695	-52.715	0.020
3	3	-51.913	-51.885	-0.028
3	4	-52.884	-52.994	0.110
3	5	-52.794	-52.806	0.012
10	6	-52.181	-52.272	0.091
10	7	-52.433	-52.479	0.046
10	8	-51.714	-51.767	0.054
10	9	-52.740	-52.873	0.133
10	10	-51.592	-51.686	0.093
20	11	-52.819	-52.858	0.040
20	12	-52.253	-52.320	0.067
20	13	-52.331	-52.373	0.042
20	14	-52.596	-52.617	0.021
20	15	-50.880	-50.879	-0.001
30	16	-51.646	-51.638	-0.008
30	17	-52.422	-52.532	0.110
30	18	-52.646	-52.694	0.048
30	19	-52.440	-52.636	0.196
30	20	-52.165	-52.182	0.017
	Max	-50.880	-50.879	0.196
	Average	-52.289	-52.346	0.058
	Min	-52.884	-52.994	-0.028
	Std Dev	0.515	0.536	0.054

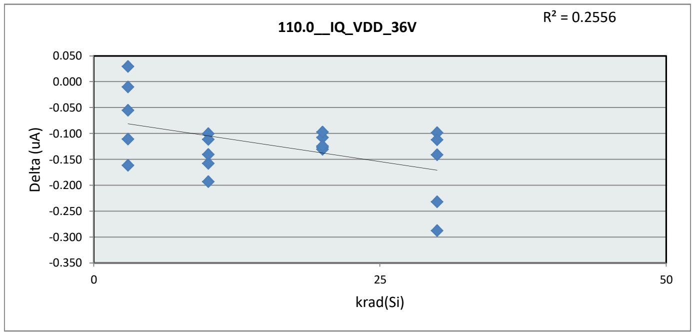


	100.0__IQ_VSS_2p2V			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	-42	uA		
Min Limit	-72	uA		
krad(Si)	3	10	20	30
LL	-72.000	-72.000	-72.000	-72.000
Min	-52.995	-52.873	-52.858	-52.694
Average	-52.624	-52.215	-52.209	-52.336
Max	-51.885	-51.686	-50.879	-51.638
UL	-42.000	-42.000	-42.000	-42.000

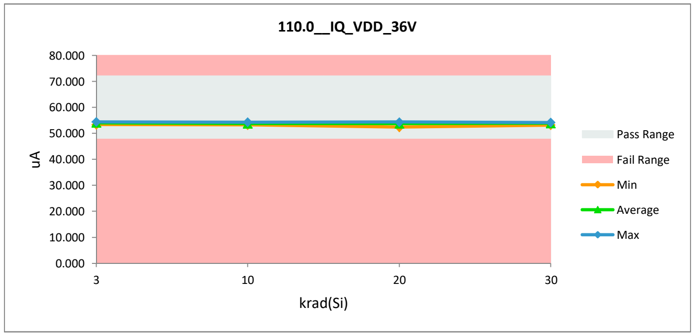


TID HDR Report
TLV1704-SEP

		110.0__IQ_VDD_36V		
Test Site		DALLAS	DALLAS	
Tester		ETS364	ETS364	
Test Number		EB083902	EB083902	
Unit		uA	uA	
Max Limit		72	72	
Min Limit		48	48	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	54.023	54.134	-0.111
3	2	54.131	54.186	-0.055
3	3	53.389	53.359	0.029
3	4	54.268	54.429	-0.162
3	5	54.195	54.205	-0.010
10	6	53.554	53.713	-0.158
10	7	53.864	53.965	-0.100
10	8	53.218	53.330	-0.112
10	9	54.098	54.291	-0.193
10	10	53.080	53.221	-0.141
20	11	54.207	54.333	-0.127
20	12	53.638	53.768	-0.131
20	13	53.669	53.777	-0.108
20	14	54.110	54.235	-0.125
20	15	52.301	52.398	-0.097
30	16	53.091	53.189	-0.098
30	17	53.783	54.015	-0.232
30	18	54.035	54.176	-0.141
30	19	53.791	54.079	-0.287
30	20	53.636	53.749	-0.112
	Max	54.268	54.429	0.029
	Average	53.704	53.828	-0.124
	Min	52.301	52.398	-0.287
	Std Dev	0.495	0.508	0.069

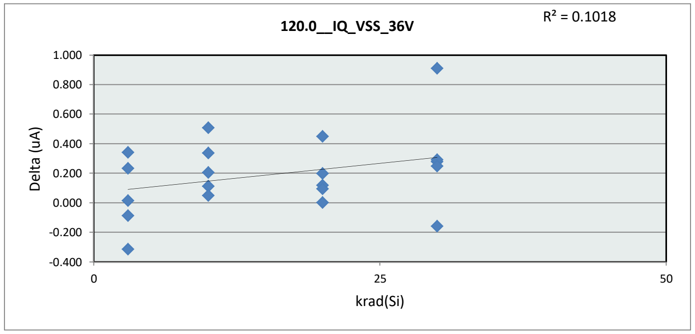


	110.0__IQ_VDD_36V			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	72	uA		
Min Limit	48	uA		
krad(Si)	3	10	20	30
LL	48.000	48.000	48.000	48.000
Min	53.359	53.221	52.398	53.189
Average	54.063	53.704	53.702	53.842
Max	54.429	54.291	54.333	54.176
UL	72.000	72.000	72.000	72.000

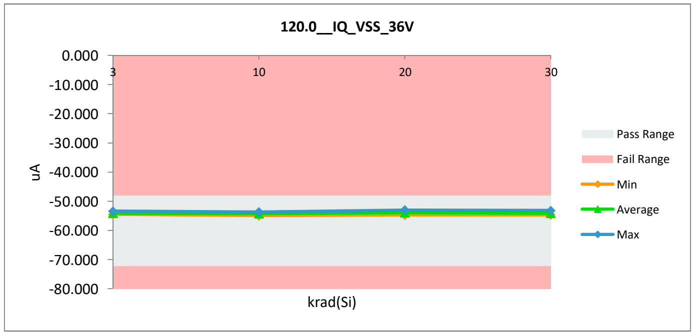


TID HDR Report
TLV1704-SEP

		120.0__IQ_VSS_36V		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	uA	uA	
	Max Limit	-48	-48	
	Min Limit	-72	-72	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	-53.857	-54.199	0.341
3	2	-54.107	-54.340	0.233
3	3	-53.356	-53.370	0.014
3	4	-54.551	-54.465	-0.086
3	5	-54.435	-54.121	-0.313
10	6	-53.445	-53.952	0.507
10	7	-54.417	-54.530	0.113
10	8	-53.595	-53.645	0.050
10	9	-54.605	-54.942	0.337
10	10	-53.619	-53.824	0.205
20	11	-54.483	-54.682	0.200
20	12	-53.504	-53.953	0.449
20	13	-53.651	-53.653	0.002
20	14	-53.983	-54.101	0.118
20	15	-52.895	-52.989	0.094
30	16	-52.909	-53.187	0.278
30	17	-53.663	-54.573	0.910
30	18	-54.369	-54.212	-0.157
30	19	-54.326	-54.617	0.291
30	20	-53.504	-53.753	0.249
	Max	-52.895	-52.989	0.910
	Average	-53.864	-54.055	0.192
	Min	-54.605	-54.942	-0.313
	Std Dev	0.530	0.520	0.263

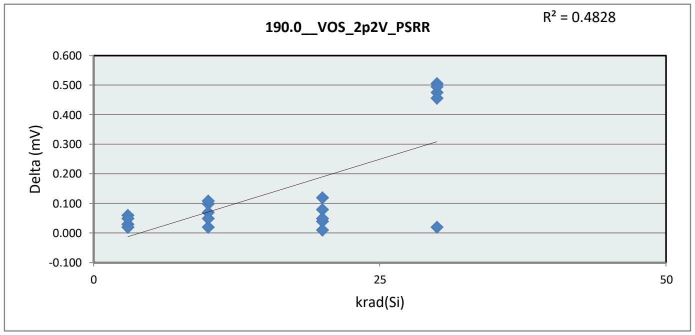


	120.0__IQ_VSS_36V			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	-48	uA		
Min Limit	-72	uA		
krad(Si)	3	10	20	30
LL	-72.000	-72.000	-72.000	-72.000
Min	-54.465	-54.942	-54.682	-54.617
Average	-54.099	-54.179	-53.876	-54.069
Max	-53.370	-53.645	-52.989	-53.187
UL	-48.000	-48.000	-48.000	-48.000

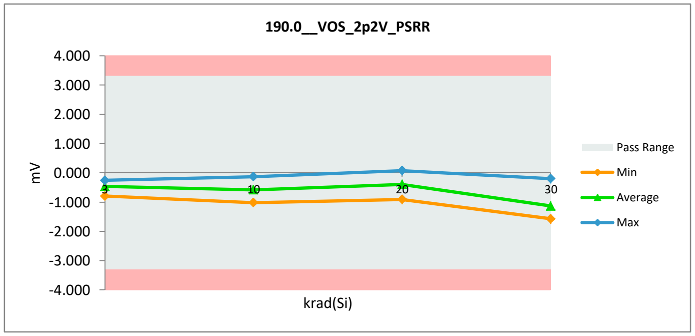


TID HDR Report
TLV1704-SEP

		190.0__VOS_2p2V_PSRR		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	mV	mV	
	Max Limit	3.3	3.3	
	Min Limit	-3.3	-3.3	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	-0.228	-0.257	0.030
3	2	-0.733	-0.792	0.059
3	3	-0.644	-0.693	0.049
3	4	-0.257	-0.277	0.020
3	5	-0.287	-0.307	0.020
10	6	-0.030	-0.129	0.099
10	7	-0.119	-0.188	0.069
10	8	-1.000	-1.020	0.020
10	9	-0.733	-0.842	0.109
10	10	-0.683	-0.733	0.049
20	11	-0.743	-0.782	0.040
20	12	-0.832	-0.911	0.079
20	13	-0.366	-0.376	0.010
20	14	0.129	0.079	0.050
20	15	0.129	0.010	0.119
30	16	-1.000	-1.505	0.505
30	17	-0.178	-0.198	0.020
30	18	-1.099	-1.574	0.475
30	19	-0.980	-1.436	0.455
30	20	-0.455	-0.951	0.495
	Max	0.129	0.079	0.505
	Average	-0.505	-0.644	0.139
	Min	-1.099	-1.574	0.010
	Std Dev	0.389	0.499	0.179

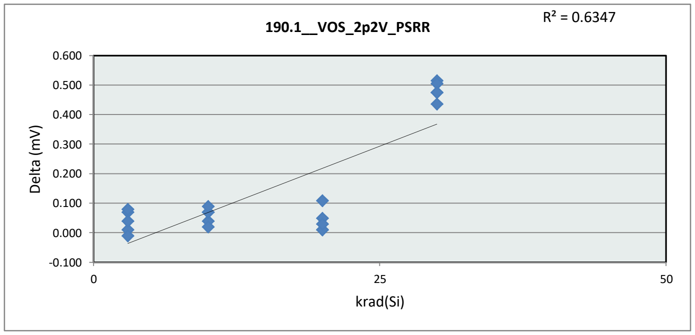


	190.0__VOS_2p2V_PSRR			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	3.3	mV		
Min Limit	-3.3	mV		
krad(Si)	3	10	20	30
LL	-3.300	-3.300	-3.300	-3.300
Min	-0.792	-1.020	-0.911	-1.574
Average	-0.465	-0.582	-0.396	-1.133
Max	-0.257	-0.129	0.079	-0.198
UL	3.300	3.300	3.300	3.300

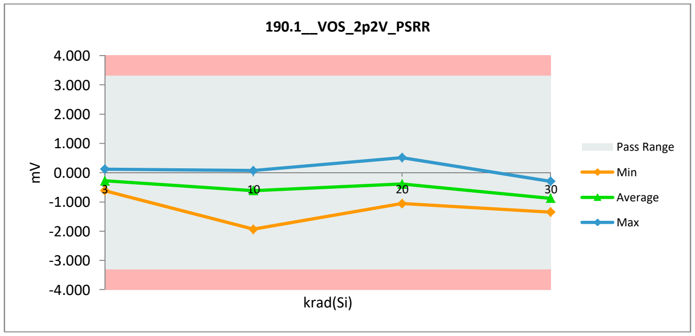


TID HDR Report
TLV1704-SEP

		190.1__VOS_2p2V_PSRR		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	mV	mV	
	Max Limit	3.3	3.3	
	Min Limit	-3.3	-3.3	
krad(Si)	Serial #	re Test HDR Biase	st test HDR.txt Bia	Delta
3	1	-0.218	-0.228	0.010
3	2	-0.545	-0.614	0.069
3	3	-0.198	-0.238	0.040
3	4	-0.436	-0.426	-0.010
3	5	0.198	0.119	0.079
10	6	-0.148	-0.218	0.069
10	7	-1.891	-1.931	0.040
10	8	-0.624	-0.693	0.069
10	9	-0.208	-0.297	0.089
10	10	0.089	0.069	0.020
20	11	-0.604	-0.654	0.050
20	12	-1.049	-1.059	0.010
20	13	0.525	0.515	0.010
20	14	0.356	0.248	0.109
20	15	-0.960	-0.990	0.030
30	16	-0.158	-0.673	0.515
30	17	-0.911	-1.347	0.436
30	18	-0.505	-0.980	0.475
30	19	0.208	-0.297	0.505
30	20	-0.614	-1.089	0.475
	Max	0.525	0.515	0.515
	Average	-0.385	-0.539	0.154
	Min	-1.891	-1.931	-0.010
	Std Dev	0.563	0.588	0.196

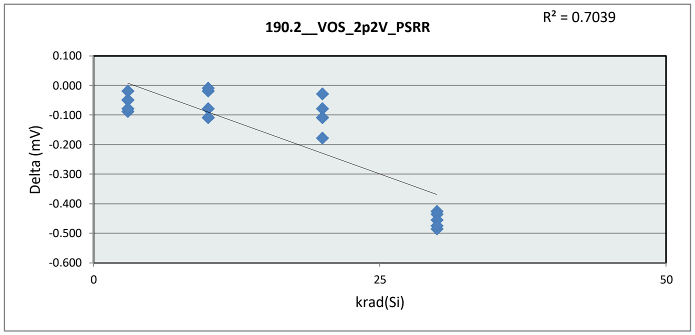


	190.1__VOS_2p2V_PSRR			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	3.3	mV		
Min Limit	-3.3	mV		
krad(Si)	3	10	20	30
LL	-3.300	-3.300	-3.300	-3.300
Min	-0.614	-1.931	-1.059	-1.347
Average	-0.277	-0.614	-0.388	-0.877
Max	0.119	0.069	0.515	-0.297
UL	3.300	3.300	3.300	3.300

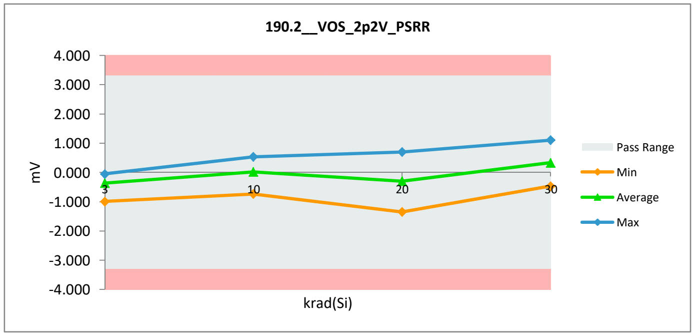


TID HDR Report
TLV1704-SEP

		190.2__VOS_2p2V_PSRR		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	mV	mV	
	Max Limit	3.3	3.3	
	Min Limit	-3.3	-3.3	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	-0.099	-0.049	-0.049
3	2	-0.396	-0.347	-0.049
3	3	-0.406	-0.317	-0.089
3	4	-0.119	-0.099	-0.020
3	5	-1.069	-0.990	-0.079
10	6	-0.752	-0.733	-0.020
10	7	0.426	0.535	-0.109
10	8	0.267	0.376	-0.109
10	9	-0.198	-0.119	-0.079
10	10	0.030	0.040	-0.010
20	11	-0.366	-0.257	-0.109
20	12	-0.564	-0.485	-0.079
20	13	-0.208	-0.099	-0.109
20	14	-1.376	-1.347	-0.030
20	15	0.525	0.703	-0.178
30	16	-0.891	-0.465	-0.426
30	17	0.673	1.109	-0.436
30	18	-0.574	-0.119	-0.455
30	19	0.049	0.535	-0.485
30	20	0.129	0.604	-0.475
	Max	0.673	1.109	-0.010
	Average	-0.246	-0.076	-0.170
	Min	-1.376	-1.347	-0.485
	Std Dev	0.533	0.599	0.174

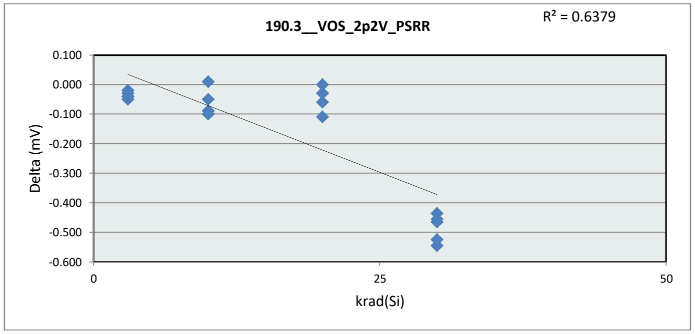


	190.2__VOS_2p2V_PSRR			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	3.3	mV		
Min Limit	-3.3	mV		
krad(Si)	3	10	20	30
LL	-3.300	-3.300	-3.300	-3.300
Min	-0.990	-0.733	-1.347	-0.465
Average	-0.360	0.020	-0.297	0.333
Max	-0.050	0.535	0.703	1.109
UL	3.300	3.300	3.300	3.300

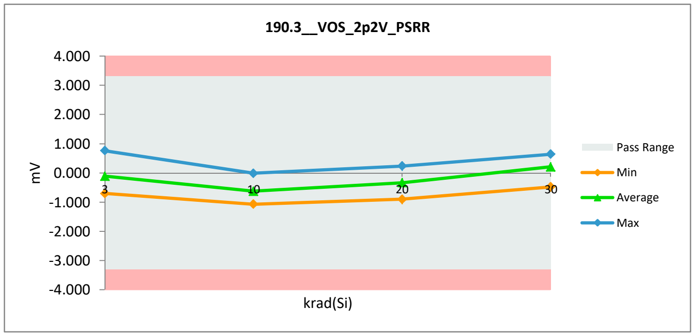


TID HDR Report
TLV1704-SEP

		190.3__VOS_2p2V_PSRR		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	mV	mV	
	Max Limit	3.3	3.3	
	Min Limit	-3.3	-3.3	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	0.010	0.030	-0.020
3	2	-0.139	-0.109	-0.030
3	3	-0.743	-0.703	-0.040
3	4	0.713	0.762	-0.049
3	5	-0.564	-0.525	-0.040
10	6	-0.059	-0.010	-0.049
10	7	-0.584	-0.495	-0.089
10	8	-1.168	-1.069	-0.099
10	9	-0.713	-0.723	0.010
10	10	-0.921	-0.822	-0.099
20	11	0.208	0.238	-0.030
20	12	-0.772	-0.713	-0.059
20	13	-0.020	0.089	-0.109
20	14	-0.931	-0.901	-0.030
20	15	-0.396	-0.396	0.000
30	16	-0.010	0.535	-0.545
30	17	-0.218	0.218	-0.436
30	18	-0.941	-0.475	-0.465
30	19	-0.396	0.129	-0.525
30	20	0.188	0.644	-0.455
	Max	0.713	0.762	0.010
	Average	-0.373	-0.215	-0.158
	Min	-1.168	-1.069	-0.545
	Std Dev	0.485	0.541	0.197

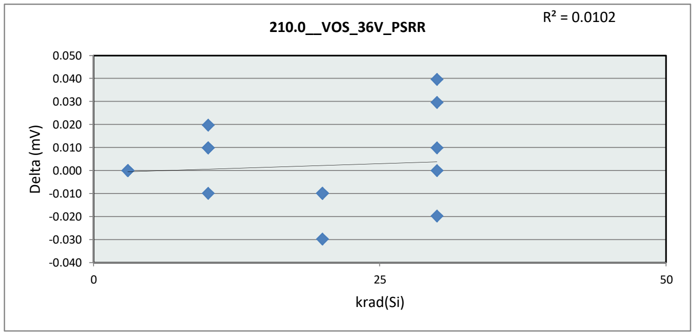


	190.3__VOS_2p2V_PSRR			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	3.3	mV		
Min Limit	-3.3	mV		
krad(Si)	3	10	20	30
LL	-3.300	-3.300	-3.300	-3.300
Min	-0.703	-1.069	-0.901	-0.475
Average	-0.109	-0.624	-0.337	0.210
Max	0.762	-0.010	0.238	0.644
UL	3.300	3.300	3.300	3.300

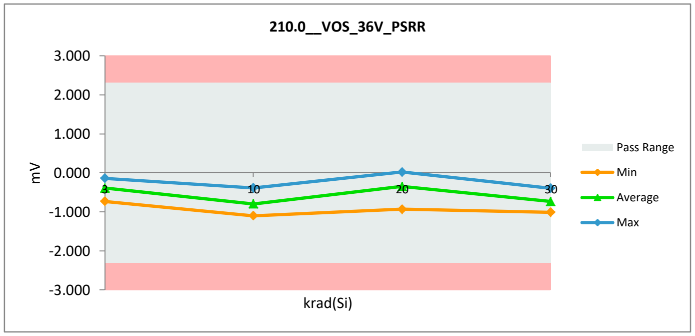


TID HDR Report
TLV1704-SEP

		210.0__VOS_36V_PSRR		
Test Site		DALLAS	DALLAS	
Tester		ETS364	ETS364	
Test Number		EB083902	EB083902	
Unit		mV	mV	
Max Limit		2.3	2.3	
Min Limit		-2.3	-2.3	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	-0.178	-0.178	0.000
3	2	-0.436	-0.436	0.000
3	3	-0.733	-0.733	0.000
3	4	-0.139	-0.139	0.000
3	5	-0.475	-0.475	0.000
10	6	-0.396	-0.386	-0.010
10	7	-1.089	-1.099	0.010
10	8	-0.762	-0.772	0.010
10	9	-0.743	-0.752	0.010
10	10	-0.960	-0.980	0.020
20	11	-0.327	-0.317	-0.010
20	12	-0.941	-0.931	-0.010
20	13	0.010	0.020	-0.010
20	14	-0.257	-0.248	-0.010
20	15	-0.297	-0.267	-0.030
30	16	-0.980	-1.010	0.030
30	17	-0.792	-0.772	-0.020
30	18	-0.980	-0.990	0.010
30	19	-0.515	-0.515	0.000
30	20	-0.356	-0.396	0.040
	Max	0.010	0.020	0.040
	Average	-0.567	-0.569	0.001
	Min	-1.089	-1.099	-0.030
	Std Dev	0.329	0.335	0.016

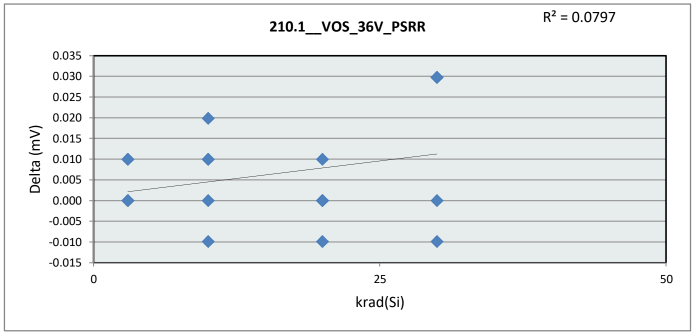


	210.0__VOS_36V_PSRR			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	2.3	mV		
Min Limit	-2.3	mV		
krad(Si)	3	10	20	30
LL	-2.300	-2.300	-2.300	-2.300
Min	-0.733	-1.099	-0.931	-1.010
Average	-0.392	-0.798	-0.349	-0.737
Max	-0.139	-0.386	0.020	-0.396
UL	2.300	2.300	2.300	2.300

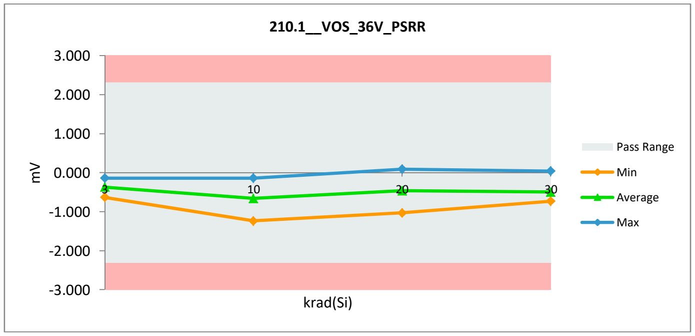


TID HDR Report
TLV1704-SEP

		210.1__VOS_36V_PSRR		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	mV	mV	
	Max Limit	2.3	2.3	
	Min Limit	-2.3	-2.3	
krad(Si)	Serial #	re Test HDR Biase	st test HDR.txt Bia	Delta
3	1	-0.139	-0.139	0.000
3	2	-0.564	-0.564	0.000
3	3	-0.178	-0.188	0.010
3	4	-0.634	-0.634	0.000
3	5	-0.317	-0.327	0.010
10	6	-0.871	-0.881	0.010
10	7	-1.218	-1.238	0.020
10	8	-0.851	-0.861	0.010
10	9	-0.198	-0.188	-0.010
10	10	-0.139	-0.139	0.000
20	11	-0.495	-0.485	-0.010
20	12	-1.030	-1.030	0.000
20	13	0.089	0.089	0.000
20	14	-0.119	-0.119	0.000
20	15	-0.762	-0.772	0.010
30	16	-0.564	-0.564	0.000
30	17	-0.465	-0.495	0.030
30	18	-0.703	-0.733	0.030
30	19	0.030	0.040	-0.010
30	20	-0.703	-0.733	0.030
	Max	0.089	0.089	0.030
	Average	-0.492	-0.498	0.006
	Min	-1.218	-1.238	-0.010
	Std Dev	0.363	0.368	0.013

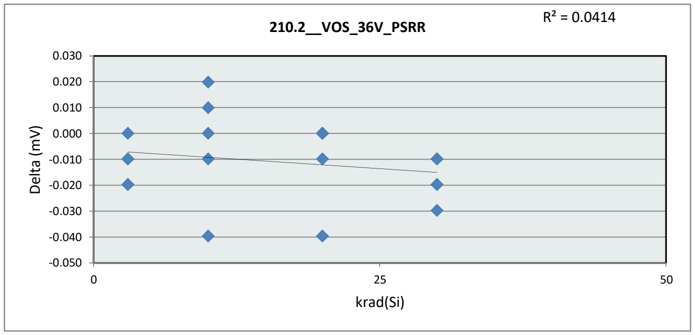


	210.1__VOS_36V_PSRR			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	2.3	mV		
Min Limit	-2.3	mV		
krad(Si)	3	10	20	30
LL	-2.300	-2.300	-2.300	-2.300
Min	-0.634	-1.238	-1.030	-0.733
Average	-0.370	-0.661	-0.463	-0.497
Max	-0.139	-0.139	0.089	0.040
UL	2.300	2.300	2.300	2.300

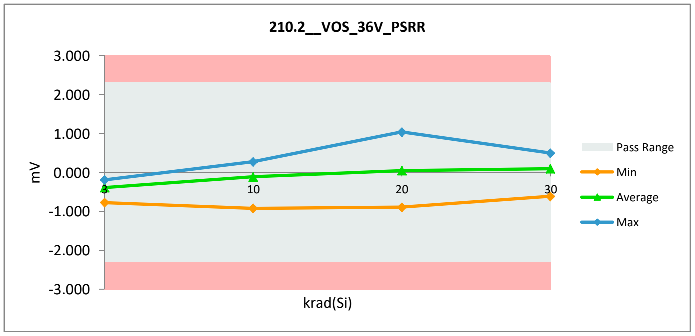


TID HDR Report
TLV1704-SEP

		210.2__VOS_36V_PSRR		
Test Site		DALLAS	DALLAS	
Tester		ETS364	ETS364	
Test Number		EB083902	EB083902	
Unit		mV	mV	
Max Limit		2.3	2.3	
Min Limit		-2.3	-2.3	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	-0.594	-0.574	-0.020
3	2	-0.198	-0.188	-0.010
3	3	-0.218	-0.198	-0.020
3	4	-0.198	-0.188	-0.010
3	5	-0.772	-0.772	0.000
10	6	-0.911	-0.921	0.010
10	7	0.218	0.228	-0.010
10	8	-0.020	0.020	-0.040
10	9	-0.168	-0.168	0.000
10	10	0.297	0.277	0.020
20	11	0.178	0.178	0.000
20	12	0.109	0.109	0.000
20	13	-0.208	-0.198	-0.010
20	14	-0.891	-0.891	0.000
20	15	1.000	1.040	-0.040
30	16	-0.634	-0.614	-0.020
30	17	0.485	0.495	-0.010
30	18	0.010	0.020	-0.010
30	19	0.257	0.287	-0.030
30	20	0.287	0.307	-0.020
	Max	1.000	1.040	0.020
	Average	-0.099	-0.088	-0.011
	Min	-0.911	-0.921	-0.040
	Std Dev	0.489	0.494	0.015

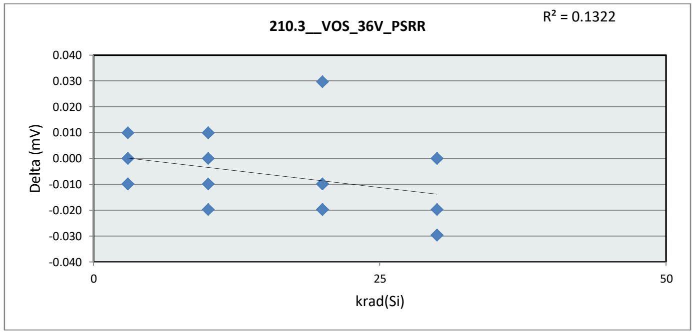


	210.2__VOS_36V_PSRR			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	2.3	mV		
Min Limit	-2.3	mV		
krad(Si)	3	10	20	30
LL	-2.300	-2.300	-2.300	-2.300
Min	-0.772	-0.921	-0.891	-0.614
Average	-0.384	-0.113	0.048	0.099
Max	-0.188	0.277	1.040	0.495
UL	2.300	2.300	2.300	2.300

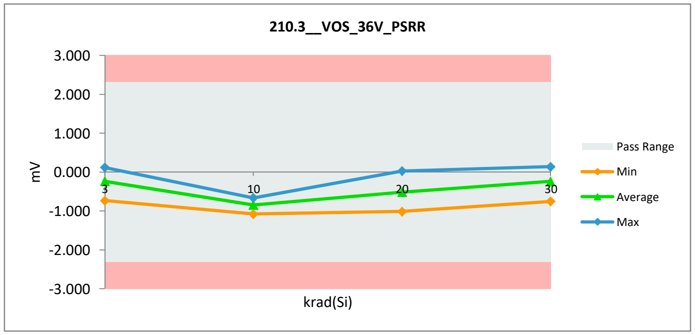


TID HDR Report
TLV1704-SEP

		210.3__VOS_36V_PSRR		
Test Site		DALLAS	DALLAS	
Tester		ETS364	ETS364	
Test Number		EB083902	EB083902	
Unit		mV	mV	
Max Limit		2.3	2.3	
Min Limit		-2.3	-2.3	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	0.129	0.119	0.010
3	2	-0.257	-0.248	-0.010
3	3	-0.743	-0.733	-0.010
3	4	-0.040	-0.040	0.000
3	5	-0.277	-0.277	0.000
10	6	-0.654	-0.663	0.010
10	7	-0.861	-0.871	0.010
10	8	-0.851	-0.842	-0.010
10	9	-0.752	-0.752	0.000
10	10	-1.099	-1.079	-0.020
20	11	-0.337	-0.327	-0.010
20	12	-0.663	-0.693	0.030
20	13	0.010	0.030	-0.020
20	14	-1.030	-1.010	-0.020
20	15	-0.584	-0.574	-0.010
30	16	-0.030	-0.010	-0.020
30	17	-0.307	-0.277	-0.030
30	18	-0.752	-0.752	0.000
30	19	-0.317	-0.287	-0.030
30	20	0.139	0.139	0.000
	Max	0.139	0.139	0.030
	Average	-0.464	-0.457	-0.006
	Min	-1.099	-1.079	-0.030
	Std Dev	0.385	0.386	0.015

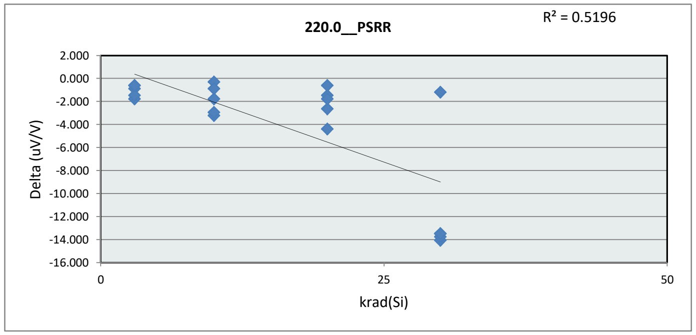


	210.3__VOS_36V_PSRR			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	2.3	mV		
Min Limit	-2.3	mV		
krad(Si)	3	10	20	30
LL	-2.300	-2.300	-2.300	-2.300
Min	-0.733	-1.079	-1.010	-0.753
Average	-0.236	-0.842	-0.515	-0.238
Max	0.119	-0.663	0.030	0.139
UL	2.300	2.300	2.300	2.300

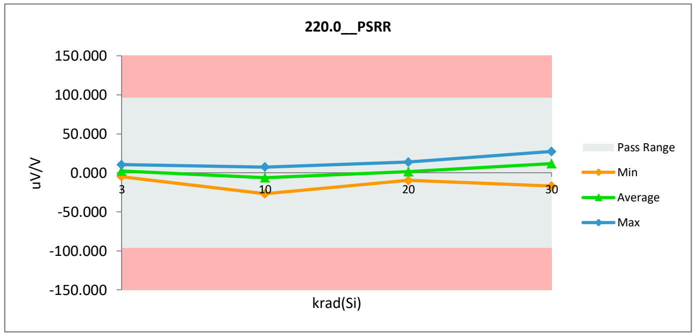


TID HDR Report
TLV1704-SEP

		220.0__PSRR		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	uV/V	uV/V	
	Max Limit	96	96	
	Min Limit	-96	-96	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	1.465	2.343	-0.879
3	2	8.788	10.545	-1.757
3	3	-2.636	-1.172	-1.465
3	4	3.515	4.101	-0.586
3	5	-5.566	-4.980	-0.586
10	6	-10.838	-7.616	-3.222
10	7	-28.707	-26.949	-1.758
10	8	7.030	7.323	-0.293
10	9	-0.293	2.636	-2.929
10	10	-8.202	-7.323	-0.879
20	11	12.303	13.768	-1.465
20	12	-3.222	-0.586	-2.636
20	13	11.131	11.717	-0.586
20	14	-11.424	-9.667	-1.758
20	15	-12.596	-8.202	-4.394
30	16	0.586	14.646	-14.061
30	17	-18.162	-16.990	-1.172
30	18	3.515	17.283	-13.768
30	19	13.768	27.242	-13.475
30	20	2.929	16.404	-13.475
	Max	13.768	27.242	-0.293
	Average	-1.831	2.226	-4.057
	Min	-28.707	-26.949	-14.061
	Std Dev	10.849	13.099	5.047

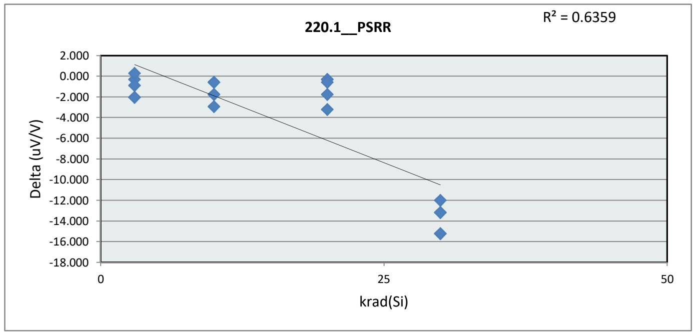


	220.0__PSRR			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	96	uV/V		
Min Limit	-96	uV/V		
krad(Si)	3	10	20	30
LL	-96.000	-96.000	-96.000	-96.000
Min	-4.980	-26.949	-9.667	-16.990
Average	2.168	-6.386	1.406	11.717
Max	10.545	7.323	13.768	27.242
UL	96.000	96.000	96.000	96.000

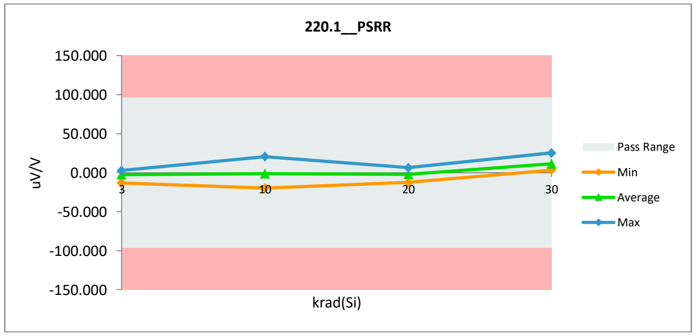


TID HDR Report
TLV1704-SEP

		220.1__PSRR		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	uV/V	uV/V	
	Max Limit	96	96	
	Min Limit	-96	-96	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	2.343	2.636	-0.293
3	2	-0.586	1.465	-2.050
3	3	0.586	1.465	-0.879
3	4	-5.859	-6.152	0.293
3	5	-15.232	-13.182	-2.050
10	6	-21.384	-19.626	-1.758
10	7	19.919	20.505	-0.586
10	8	-6.737	-4.980	-1.758
10	9	0.293	3.222	-2.929
10	10	-6.737	-6.152	-0.586
20	11	3.222	4.980	-1.758
20	12	0.586	0.879	-0.293
20	13	-12.889	-12.596	-0.293
20	14	-14.061	-10.838	-3.222
20	15	5.859	6.444	-0.586
30	16	-12.010	3.222	-15.232
30	17	13.182	25.192	-12.010
30	18	-5.859	7.323	-13.182
30	19	-5.273	9.960	-15.232
30	20	-2.636	10.545	-13.182
	Max	19.919	25.192	0.293
	Average	-3.164	1.216	-4.379
	Min	-21.384	-19.626	-15.232
	Std Dev	9.769	11.060	5.671

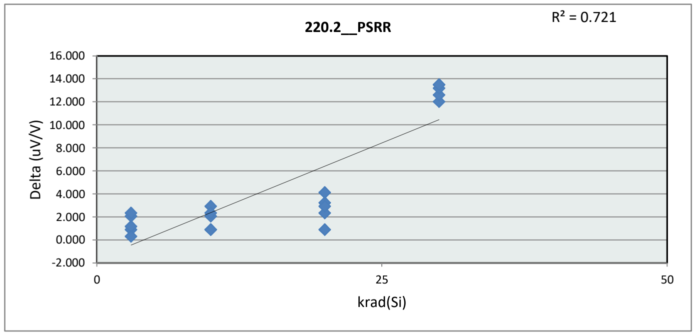


	220.1__PSRR			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	96	uV/V		
Min Limit	-96	uV/V		
krad(Si)	3	10	20	30
LL	-96.000	-96.000	-96.000	-96.000
Min	-13.182	-19.626	-12.596	3.222
Average	-2.754	-1.406	-2.226	11.248
Max	2.636	20.505	6.444	25.192
UL	96.000	96.000	96.000	96.000

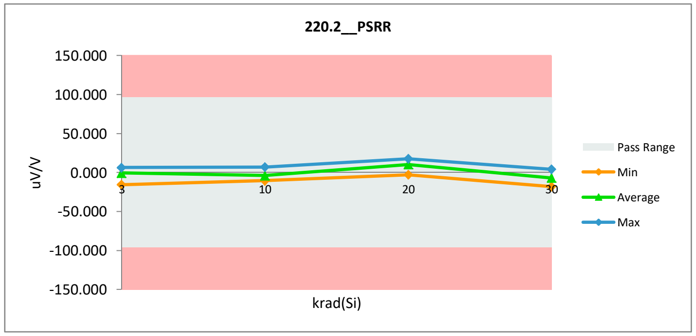


TID HDR Report
TLV1704-SEP

		220.2__PSRR		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	uV/V	uV/V	
	Max Limit	96	96	
	Min Limit	-96	-96	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	-14.646	-15.525	0.879
3	2	5.859	4.687	1.172
3	3	5.566	3.515	2.050
3	4	-2.343	-2.636	0.293
3	5	8.788	6.444	2.344
10	6	-4.687	-5.566	0.879
10	7	-6.152	-9.081	2.929
10	8	-8.495	-10.545	2.050
10	9	0.879	-1.465	2.343
10	10	7.909	7.030	0.879
20	11	16.111	12.889	3.222
20	12	19.919	17.576	2.344
20	13	0.000	-2.929	2.929
20	14	14.354	13.475	0.879
20	15	14.061	9.960	4.101
30	16	7.616	-4.394	12.010
30	17	-5.566	-18.162	12.596
30	18	17.283	4.101	13.182
30	19	6.152	-7.323	13.475
30	20	4.687	-8.788	13.475
	Max	19.919	17.576	13.475
	Average	4.365	-0.337	4.702
	Min	-14.646	-18.162	0.293
	Std Dev	9.415	9.891	4.982



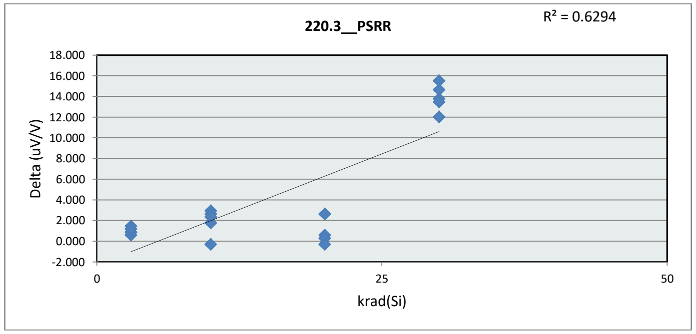
	220.2__PSRR			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	96	uV/V		
Min Limit	-96	uV/V		
krad(Si)	3	10	20	30
LL	-96.000	-96.000	-96.000	-96.000
Min	-15.525	-10.545	-2.929	-18.162
Average	-0.703	-3.925	10.194	-6.913
Max	6.444	7.030	17.576	4.101
UL	96.000	96.000	96.000	96.000



TID HDR Report
TLV1704-SEP

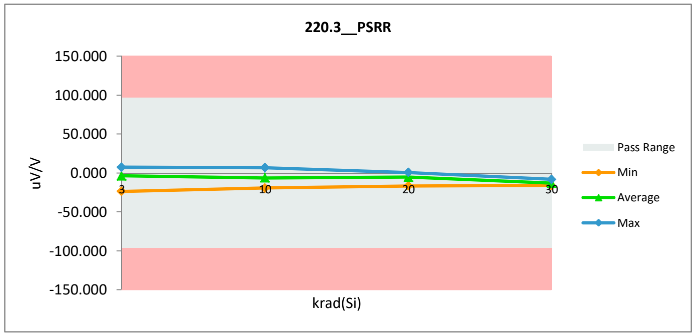
	220.3__PSRR	
Test Site	DALLAS	DALLAS
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	uV/V	uV/V
Max Limit	96	96
Min Limit	-96	-96

krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	3.515	2.636	0.879
3	2	-3.515	-4.101	0.586
3	3	0.000	-0.879	0.879
3	4	-22.263	-23.727	1.465
3	5	8.495	7.323	1.172
10	6	-17.576	-19.333	1.758
10	7	-8.202	-11.131	2.929
10	8	9.374	6.737	2.636
10	9	-1.172	-0.879	-0.293
10	10	-5.273	-7.616	2.343
20	11	-16.111	-16.697	0.586
20	12	3.222	0.586	2.636
20	13	0.879	-1.758	2.636
20	14	-2.929	-3.222	0.293
20	15	-5.566	-5.273	-0.293
30	16	-0.586	-16.111	15.525
30	17	-2.636	-14.646	12.010
30	18	5.566	-8.202	13.768
30	19	2.343	-12.303	14.646
30	20	-1.465	-14.939	13.475
	Max	9.374	7.323	15.525
	Average	-2.695	-7.177	4.482
	Min	-22.263	-23.727	-0.293
	Std Dev	8.261	8.733	5.681



	220.3__PSRR	
Test Site	DALLAS	
Tester	ETS364	
Test Number	EB083902	
Max Limit	96	uV/V
Min Limit	-96	uV/V

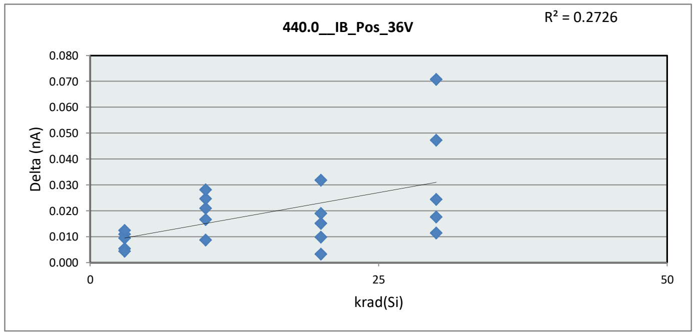
krad(Si)	3	10	20	30
LL	-96.000	-96.000	-96.000	-96.000
Min	-23.727	-19.333	-16.697	-16.111
Average	-3.749	-6.444	-5.273	-13.240
Max	7.323	6.737	0.586	-8.202
UL	96.000	96.000	96.000	96.000



TID HDR Report
TLV1704-SEP

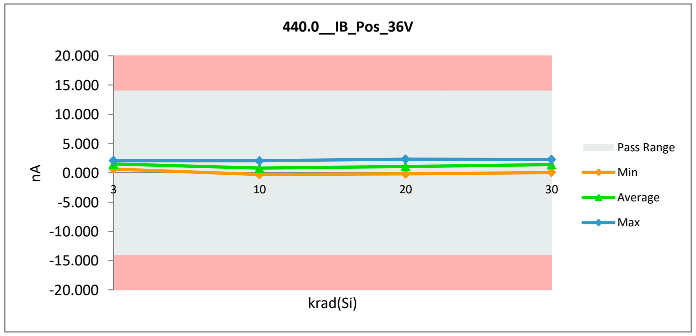
	440.0__IB_Pos_36V	
Test Site	DALLAS	DALLAS
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	nA	nA
Max Limit	14	14
Min Limit	-14	-14

krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	2.088	2.077	0.011
3	2	1.028	1.019	0.009
3	3	0.650	0.645	0.005
3	4	1.818	1.805	0.012
3	5	1.925	1.921	0.004
10	6	1.171	1.162	0.009
10	7	1.312	1.295	0.017
10	8	-0.288	-0.313	0.025
10	9	2.069	2.047	0.021
10	10	-0.141	-0.170	0.028
20	11	2.329	2.326	0.003
20	12	1.385	1.354	0.032
20	13	2.021	2.012	0.010
20	14	0.040	0.021	0.019
20	15	-0.188	-0.203	0.015
30	16	0.075	0.057	0.018
30	17	2.015	1.967	0.047
30	18	1.679	1.655	0.024
30	19	2.295	2.283	0.011
30	20	1.071	1.000	0.071
	Max	2.329	2.326	0.071
	Average	1.218	1.198	0.020
	Min	-0.288	-0.313	0.003
	Std Dev	0.901	0.904	0.016



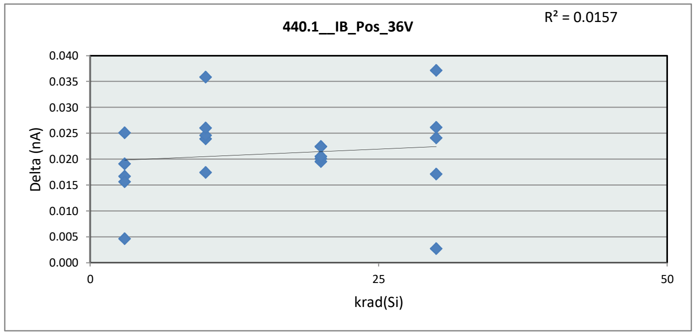
	440.0__IB_Pos_36V	
Test Site	DALLAS	
Tester	ETS364	
Test Number	EB083902	
Max Limit	14	nA
Min Limit	-14	nA

krad(Si)	3	10	20	30
LL	-14.000	-14.000	-14.000	-14.000
Min	0.645	-0.313	-0.203	0.057
Average	1.493	0.804	1.102	1.392
Max	2.077	2.048	2.326	2.283
UL	14.000	14.000	14.000	14.000

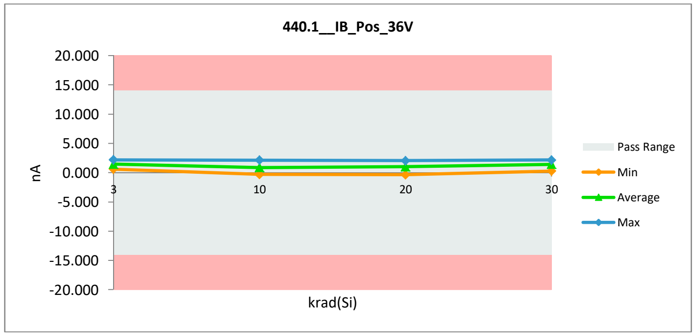


TID HDR Report
TLV1704-SEP

		440.1__IB_Pos_36V		
Test Site		DALLAS	DALLAS	
Tester		ETS364	ETS364	
Test Number		EB083902	EB083902	
Unit		nA	nA	
Max Limit		14	14	
Min Limit		-14	-14	
krad(Si)	Serial #	re Test HDR Biase	st test HDR.txt Bia	Delta
3	1	1.945	1.920	0.025
3	2	1.143	1.127	0.017
3	3	0.610	0.605	0.005
3	4	2.214	2.198	0.016
3	5	1.449	1.429	0.019
10	6	1.362	1.327	0.036
10	7	1.165	1.141	0.024
10	8	-0.266	-0.290	0.025
10	9	2.157	2.139	0.017
10	10	0.144	0.118	0.026
20	11	2.035	2.015	0.020
20	12	1.131	1.109	0.022
20	13	2.087	2.067	0.020
20	14	-0.322	-0.344	0.022
20	15	0.219	0.198	0.020
30	16	0.269	0.266	0.003
30	17	1.922	1.885	0.037
30	18	2.187	2.163	0.024
30	19	1.828	1.802	0.026
30	20	0.981	0.964	0.017
	Max	2.214	2.198	0.037
	Average	1.213	1.192	0.021
	Min	-0.322	-0.344	0.003
	Std Dev	0.851	0.850	0.008

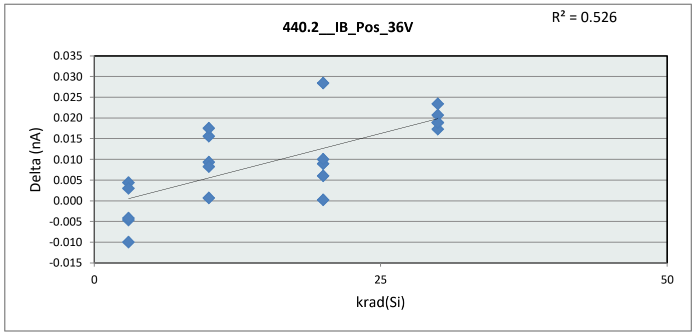


	440.1__IB_Pos_36V			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	14	nA		
Min Limit	-14	nA		
krad(Si)	3	10	20	30
LL	-14.000	-14.000	-14.000	-14.000
Min	0.605	-0.290	-0.344	0.266
Average	1.456	0.887	1.009	1.416
Max	2.198	2.139	2.067	2.163
UL	14.000	14.000	14.000	14.000

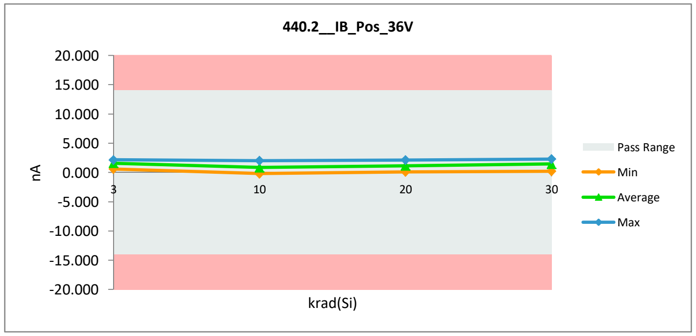


TID HDR Report
TLV1704-SEP

		440.2__IB_Pos_36V		
Test Site		DALLAS	DALLAS	
Tester		ETS364	ETS364	
Test Number		EB083902	EB083902	
Unit		nA	nA	
Max Limit		14	14	
Min Limit		-14	-14	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	2.180	2.175	0.004
3	2	0.950	0.960	-0.010
3	3	0.604	0.601	0.003
3	4	2.039	2.043	-0.005
3	5	2.165	2.169	-0.004
10	6	1.806	1.796	0.009
10	7	0.829	0.813	0.016
10	8	-0.193	-0.194	0.001
10	9	2.029	2.021	0.008
10	10	-0.186	-0.204	0.017
20	11	1.922	1.893	0.028
20	12	1.391	1.383	0.009
20	13	2.133	2.123	0.010
20	14	0.109	0.109	0.000
20	15	0.186	0.180	0.006
30	16	0.223	0.206	0.017
30	17	2.320	2.296	0.023
30	18	1.923	1.904	0.019
30	19	1.791	1.771	0.021
30	20	1.133	1.114	0.019
	Max	2.320	2.296	0.028
	Average	1.268	1.258	0.010
	Min	-0.193	-0.204	-0.010
	Std Dev	0.880	0.878	0.010

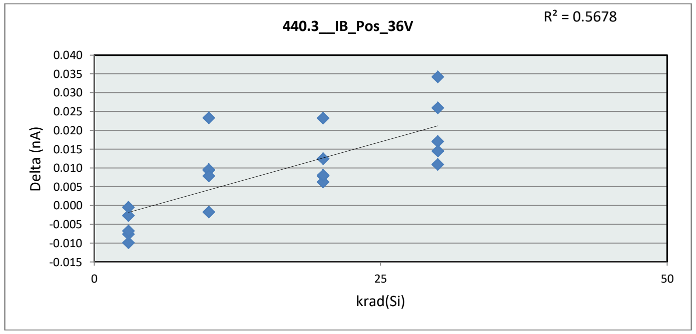


	440.2__IB_Pos_36V			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	14	nA		
Min Limit	-14	nA		
krad(Si)	3	10	20	30
LL	-14.000	-14.000	-14.000	-14.000
Min	0.601	-0.204	0.109	0.206
Average	1.590	0.847	1.138	1.458
Max	2.175	2.021	2.123	2.297
UL	14.000	14.000	14.000	14.000

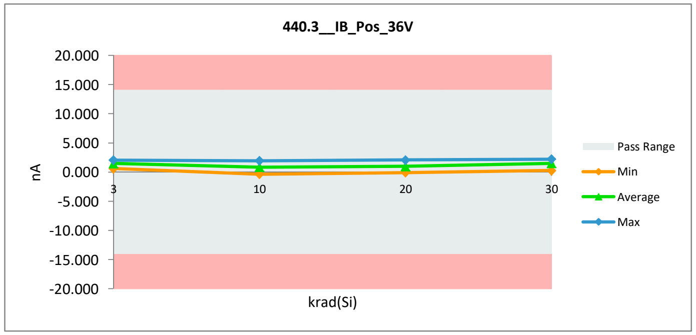


TID HDR Report
TLV1704-SEP

		440.3__IB_Pos_36V		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	nA	nA	
	Max Limit	14	14	
	Min Limit	-14	-14	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	2.044	2.045	-0.001
3	2	0.923	0.933	-0.010
3	3	0.598	0.605	-0.008
3	4	1.720	1.722	-0.003
3	5	2.034	2.041	-0.007
10	6	1.276	1.266	0.009
10	7	1.379	1.381	-0.002
10	8	-0.341	-0.350	0.009
10	9	1.951	1.944	0.008
10	10	0.103	0.080	0.023
20	11	1.930	1.922	0.008
20	12	1.123	1.100	0.023
20	13	2.098	2.085	0.012
20	14	-0.030	-0.037	0.006
20	15	-0.077	-0.085	0.008
30	16	0.296	0.279	0.017
30	17	2.250	2.216	0.034
30	18	1.895	1.881	0.015
30	19	2.047	2.022	0.026
30	20	1.203	1.192	0.011
	Max	2.250	2.216	0.034
	Average	1.221	1.212	0.009
	Min	-0.341	-0.350	-0.010
	Std Dev	0.855	0.855	0.012



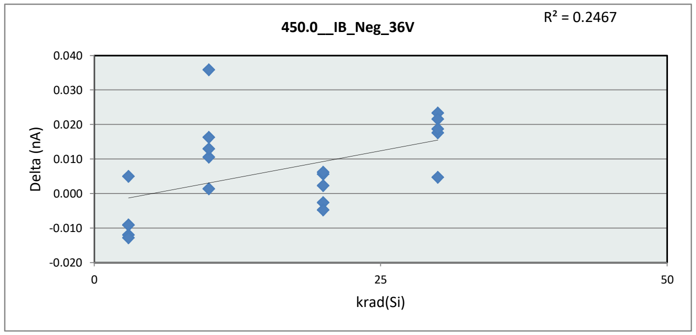
	440.3__IB_Pos_36V			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	14	nA		
Min Limit	-14	nA		
krad(Si)	3	10	20	30
LL	-14.000	-14.000	-14.000	-14.000
Min	0.605	-0.351	-0.085	0.279
Average	1.469	0.864	0.997	1.518
Max	2.045	1.944	2.085	2.216
UL	14.000	14.000	14.000	14.000



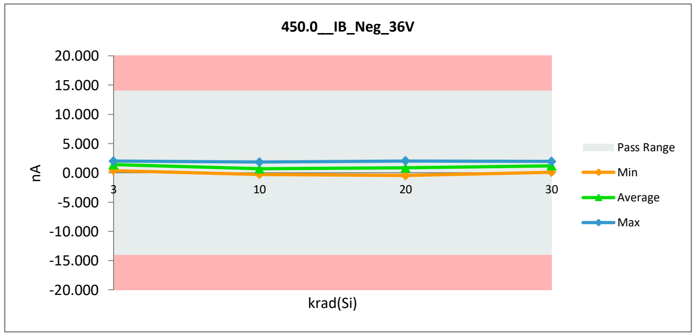
TID HDR Report
TLV1704-SEP

	450.0__IB_Neg_36V	
Test Site	DALLAS	DALLAS
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	nA	nA
Max Limit	14	14
Min Limit	-14	-14

krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	1.805	1.800	0.005
3	2	1.196	1.208	-0.012
3	3	0.383	0.396	-0.013
3	4	1.495	1.504	-0.009
3	5	2.001	2.010	-0.009
10	6	1.189	1.188	0.001
10	7	0.927	0.917	0.011
10	8	-0.248	-0.261	0.013
10	9	1.864	1.828	0.036
10	10	-0.261	-0.277	0.016
20	11	2.044	2.039	0.006
20	12	0.988	0.982	0.006
20	13	1.933	1.931	0.002
20	14	-0.462	-0.459	-0.003
20	15	-0.265	-0.260	-0.005
30	16	0.111	0.107	0.005
30	17	1.922	1.898	0.023
30	18	1.826	1.809	0.018
30	19	1.962	1.940	0.022
30	20	0.250	0.231	0.019
	Max	2.044	2.039	0.036
	Average	1.033	1.026	0.007
	Min	-0.462	-0.459	-0.013
	Std Dev	0.910	0.908	0.013

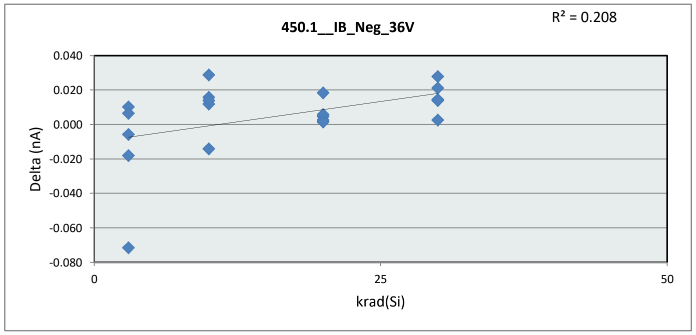


	450.0__IB_Neg_36V			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	14	nA		
Min Limit	-14	nA		
krad(Si)	3	10	20	30
LL	-14.000	-14.000	-14.000	-14.000
Min	0.396	-0.277	-0.459	0.107
Average	1.383	0.679	0.846	1.197
Max	2.010	1.828	2.039	1.940
UL	14.000	14.000	14.000	14.000

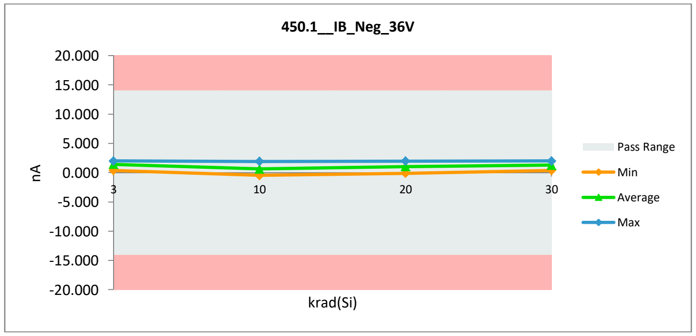


TID HDR Report
TLV1704-SEP

		450.1__IB_Neg_36V		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	nA	nA	
	Max Limit	14	14	
	Min Limit	-14	-14	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	1.867	1.856	0.010
3	2	0.978	0.996	-0.018
3	3	0.315	0.386	-0.072
3	4	1.905	1.898	0.007
3	5	2.001	2.007	-0.006
10	6	1.191	1.162	0.029
10	7	0.923	0.907	0.016
10	8	-0.483	-0.468	-0.014
10	9	1.922	1.910	0.012
10	10	-0.324	-0.338	0.014
20	11	1.970	1.965	0.005
20	12	1.346	1.341	0.006
20	13	1.947	1.928	0.018
20	14	-0.109	-0.112	0.003
20	15	0.051	0.050	0.001
30	16	0.395	0.392	0.003
30	17	1.926	1.911	0.014
30	18	1.711	1.697	0.014
30	19	2.028	2.007	0.021
30	20	0.464	0.436	0.028
	Max	2.028	2.007	0.029
	Average	1.101	1.097	0.005
	Min	-0.483	-0.468	-0.072
	Std Dev	0.884	0.877	0.022

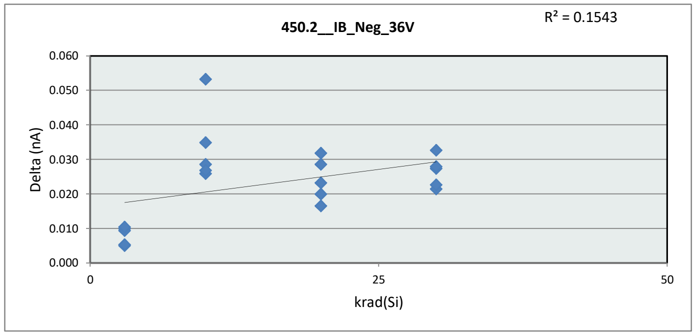


	450.1__IB_Neg_36V			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	14	nA		
Min Limit	-14	nA		
krad(Si)	3	10	20	30
LL	-14.000	-14.000	-14.000	-14.000
Min	0.386	-0.468	-0.112	0.392
Average	1.429	0.635	1.035	1.289
Max	2.007	1.910	1.966	2.007
UL	14.000	14.000	14.000	14.000

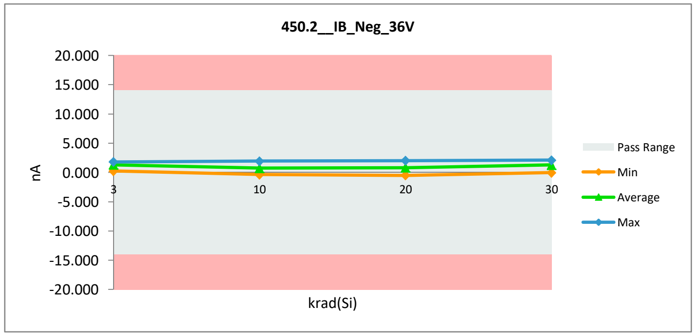


TID HDR Report
TLV1704-SEP

		450.2__IB_Neg_36V		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	nA	nA	
	Max Limit	14	14	
	Min Limit	-14	-14	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	1.641	1.631	0.010
3	2	1.163	1.158	0.005
3	3	0.257	0.248	0.009
3	4	1.699	1.693	0.005
3	5	1.829	1.818	0.010
10	6	1.398	1.372	0.026
10	7	1.046	1.018	0.029
10	8	-0.336	-0.362	0.027
10	9	1.997	1.944	0.053
10	10	-0.255	-0.289	0.035
20	11	2.041	2.024	0.016
20	12	0.959	0.936	0.023
20	13	1.884	1.864	0.020
20	14	-0.466	-0.498	0.032
20	15	-0.147	-0.175	0.029
30	16	-0.013	-0.034	0.021
30	17	2.132	2.105	0.027
30	18	1.788	1.760	0.028
30	19	2.003	1.971	0.033
30	20	0.629	0.607	0.023
	Max	2.132	2.105	0.053
	Average	1.062	1.039	0.023
	Min	-0.466	-0.498	0.005
	Std Dev	0.918	0.919	0.012

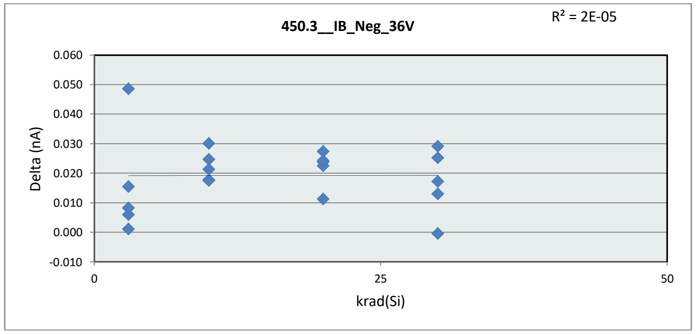


	450.2__IB_Neg_36V			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	14	nA		
Min Limit	-14	nA		
krad(Si)	3	10	20	30
LL	-14.000	-14.000	-14.000	-14.000
Min	0.248	-0.362	-0.498	-0.034
Average	1.310	0.736	0.830	1.282
Max	1.818	1.944	2.024	2.105
UL	14.000	14.000	14.000	14.000

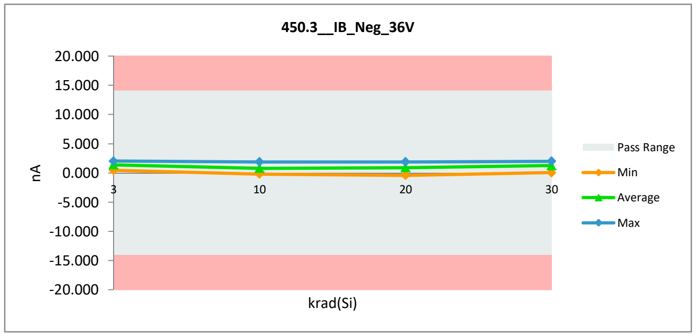


TID HDR Report
TLV1704-SEP

		450.3__IB_Neg_36V		
Test Site		DALLAS	DALLAS	
Tester		ETS364	ETS364	
Test Number		EB083902	EB083902	
Unit		nA	nA	
Max Limit		14	14	
Min Limit		-14	-14	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	2.056	2.041	0.016
3	2	0.856	0.850	0.006
3	3	0.476	0.468	0.008
3	4	1.778	1.777	0.001
3	5	1.962	1.913	0.049
10	6	1.258	1.240	0.018
10	7	1.010	0.992	0.018
10	8	-0.179	-0.204	0.025
10	9	1.933	1.903	0.030
10	10	0.044	0.023	0.021
20	11	1.904	1.893	0.011
20	12	1.286	1.258	0.027
20	13	1.894	1.871	0.023
20	14	-0.381	-0.405	0.024
20	15	-0.116	-0.140	0.024
30	16	0.073	0.060	0.013
30	17	2.035	2.006	0.029
30	18	1.775	1.750	0.025
30	19	1.682	1.665	0.017
30	20	0.814	0.814	0.000
	Max	2.056	2.041	0.049
	Average	1.108	1.089	0.019
	Min	-0.381	-0.405	0.000
	Std Dev	0.853	0.852	0.011



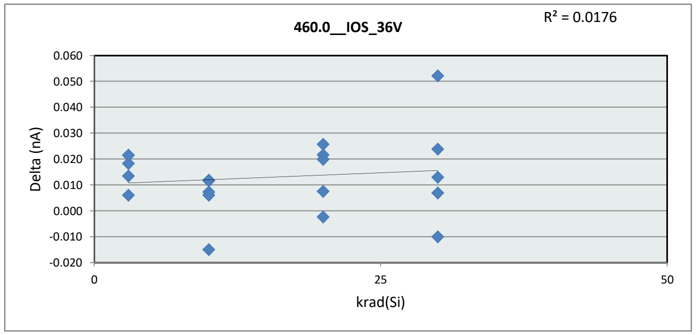
	450.3__IB_Neg_36V			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	14	nA		
Min Limit	-14	nA		
krad(Si)	3	10	20	30
LL	-14.000	-14.000	-14.000	-14.000
Min	0.468	-0.204	-0.405	0.060
Average	1.410	0.791	0.895	1.259
Max	2.041	1.903	1.893	2.006
UL	14.000	14.000	14.000	14.000



TID HDR Report
TLV1704-SEP

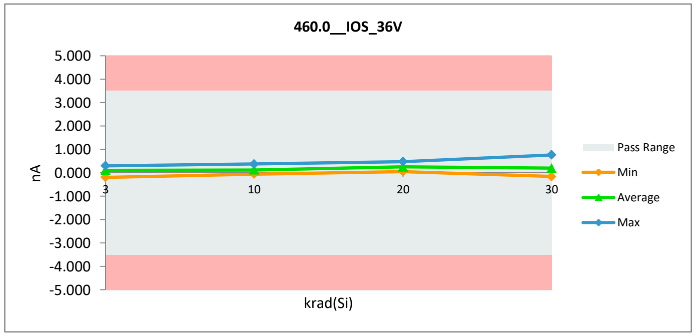
	460.0__IOS_36V	
Test Site	DALLAS	DALLAS
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	nA	nA
Max Limit	3.5	3.5
Min Limit	-3.5	-3.5

krad(Si)	Serial #	re Test HDR Biase	st test HDR.txt Bia	Delta
3	1	0.283	0.277	0.006
3	2	-0.167	-0.189	0.022
3	3	0.267	0.249	0.018
3	4	0.323	0.301	0.021
3	5	-0.075	-0.089	0.013
10	6	-0.019	-0.026	0.007
10	7	0.384	0.378	0.006
10	8	-0.040	-0.052	0.012
10	9	0.204	0.219	-0.015
10	10	0.119	0.108	0.012
20	11	0.285	0.287	-0.002
20	12	0.398	0.372	0.026
20	13	0.088	0.081	0.008
20	14	0.502	0.480	0.022
20	15	0.077	0.057	0.020
30	16	-0.036	-0.049	0.013
30	17	0.093	0.069	0.024
30	18	-0.147	-0.154	0.007
30	19	0.333	0.343	-0.010
30	20	0.821	0.768	0.052
	Max	0.821	0.768	0.052
	Average	0.185	0.172	0.013
	Min	-0.167	-0.189	-0.015
	Std Dev	0.244	0.240	0.014



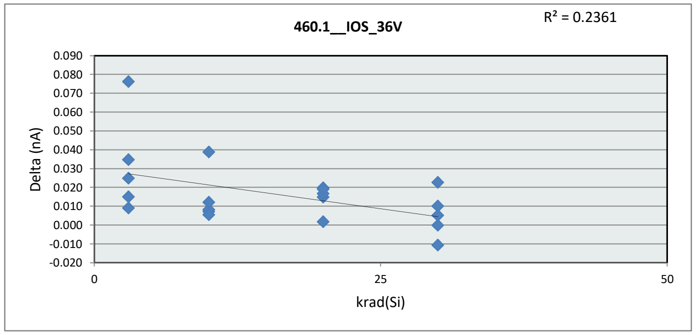
	460.0__IOS_36V	
Test Site	DALLAS	
Tester	ETS364	
Test Number	EB083902	
Max Limit	3.5	nA
Min Limit	-3.5	nA

krad(Si)	3	10	20	30
LL	-3.500	-3.500	-3.500	-3.500
Min	-0.189	-0.052	0.057	-0.154
Average	0.110	0.126	0.256	0.195
Max	0.301	0.378	0.480	0.768
UL	3.500	3.500	3.500	3.500

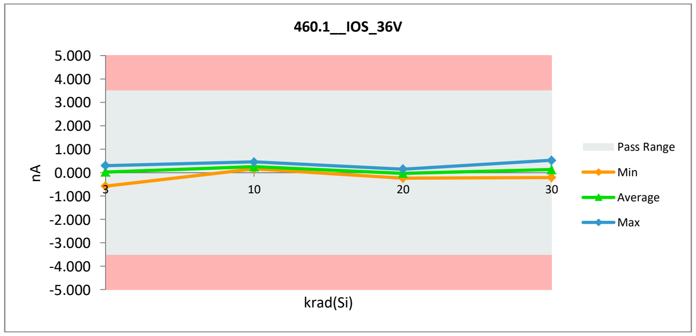


TID HDR Report
TLV1704-SEP

		460.1__IOS_36V		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	nA	nA	
	Max Limit	3.5	3.5	
	Min Limit	-3.5	-3.5	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	0.078	0.063	0.015
3	2	0.166	0.131	0.035
3	3	0.295	0.219	0.076
3	4	0.309	0.300	0.009
3	5	-0.553	-0.577	0.025
10	6	0.172	0.165	0.007
10	7	0.243	0.234	0.008
10	8	0.217	0.178	0.039
10	9	0.235	0.229	0.005
10	10	0.468	0.456	0.012
20	11	0.064	0.050	0.015
20	12	-0.215	-0.232	0.017
20	13	0.140	0.138	0.002
20	14	-0.213	-0.233	0.020
20	15	0.168	0.149	0.019
30	16	-0.126	-0.126	0.000
30	17	-0.004	-0.026	0.023
30	18	0.476	0.466	0.010
30	19	-0.200	-0.205	0.005
30	20	0.518	0.528	-0.011
	Max	0.518	0.528	0.076
	Average	0.112	0.095	0.017
	Min	-0.553	-0.577	-0.011
	Std Dev	0.269	0.271	0.018

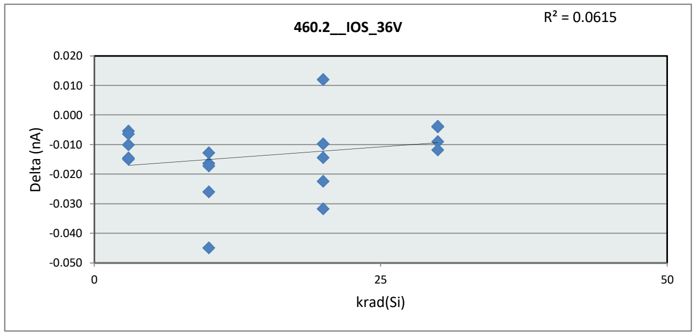


	460.1__IOS_36V			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	3.5	nA		
Min Limit	-3.5	nA		
krad(Si)	3	10	20	30
LL	-3.500	-3.500	-3.500	-3.500
Min	-0.577	0.165	-0.233	-0.205
Average	0.027	0.252	-0.026	0.127
Max	0.300	0.456	0.149	0.528
UL	3.500	3.500	3.500	3.500

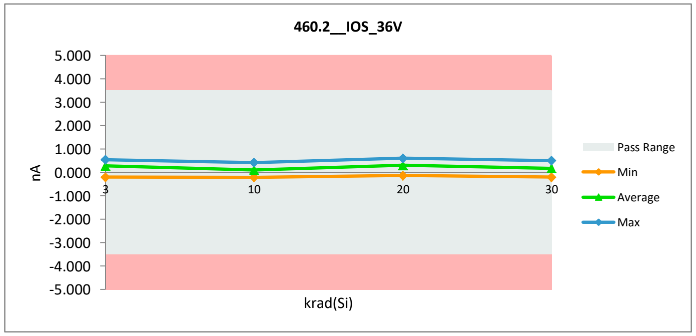


TID HDR Report
TLV1704-SEP

		460.2__IOS_36V		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	nA	nA	
	Max Limit	3.5	3.5	
	Min Limit	-3.5	-3.5	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	0.539	0.544	-0.005
3	2	-0.214	-0.199	-0.015
3	3	0.347	0.354	-0.006
3	4	0.340	0.350	-0.010
3	5	0.336	0.351	-0.015
10	6	0.408	0.424	-0.016
10	7	-0.217	-0.205	-0.013
10	8	0.143	0.169	-0.026
10	9	0.032	0.077	-0.045
10	10	0.068	0.086	-0.017
20	11	-0.119	-0.131	0.012
20	12	0.433	0.447	-0.014
20	13	0.249	0.259	-0.010
20	14	0.575	0.607	-0.032
20	15	0.333	0.356	-0.023
30	16	0.236	0.240	-0.004
30	17	0.188	0.192	-0.004
30	18	0.135	0.144	-0.009
30	19	-0.212	-0.200	-0.012
30	20	0.503	0.507	-0.004
	Max	0.575	0.607	0.012
	Average	0.205	0.219	-0.013
	Min	-0.217	-0.205	-0.045
	Std Dev	0.251	0.252	0.012



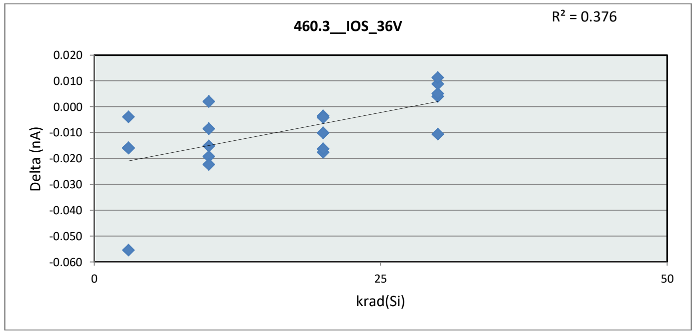
	460.2__IOS_36V			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	3.5	nA		
Min Limit	-3.5	nA		
krad(Si)	3	10	20	30
LL	-3.500	-3.500	-3.500	-3.500
Min	-0.199	-0.205	-0.131	-0.200
Average	0.280	0.110	0.308	0.177
Max	0.544	0.424	0.607	0.507
UL	3.500	3.500	3.500	3.500



TID HDR Report
TLV1704-SEP

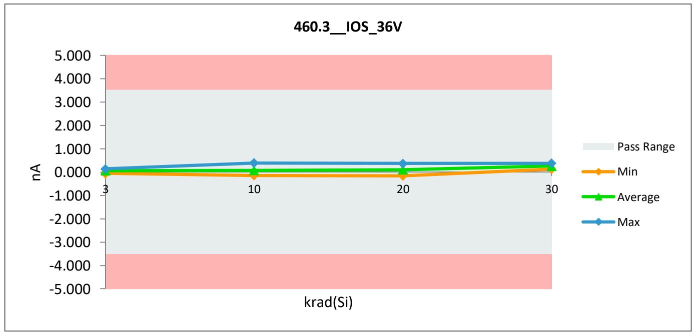
	460.3__IOS_36V	
Test Site	DALLAS	DALLAS
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	nA	nA
Max Limit	3.5	3.5
Min Limit	-3.5	-3.5

krad(Si)	Serial #	re Test HDR Biase	st test HDR.txt Bia	Delta
3	1	-0.013	0.004	-0.016
3	2	0.066	0.082	-0.016
3	3	0.122	0.138	-0.016
3	4	-0.058	-0.055	-0.004
3	5	0.072	0.128	-0.055
10	6	0.018	0.027	-0.008
10	7	0.369	0.389	-0.019
10	8	-0.162	-0.146	-0.015
10	9	0.018	0.041	-0.022
10	10	0.059	0.057	0.002
20	11	0.026	0.029	-0.003
20	12	-0.163	-0.159	-0.004
20	13	0.204	0.214	-0.010
20	14	0.351	0.368	-0.018
20	15	0.040	0.056	-0.016
30	16	0.223	0.219	0.004
30	17	0.215	0.210	0.005
30	18	0.120	0.130	-0.011
30	19	0.366	0.357	0.009
30	20	0.389	0.378	0.011
	Max	0.389	0.389	0.011
	Average	0.113	0.123	-0.010
	Min	-0.163	-0.159	-0.055
	Std Dev	0.167	0.164	0.015



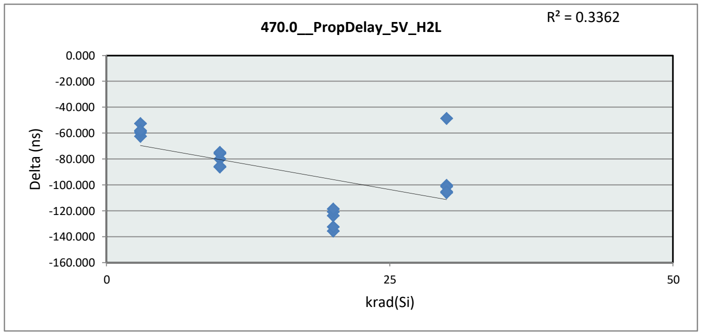
	460.3__IOS_36V	
Test Site	DALLAS	
Tester	ETS364	
Test Number	EB083902	
Max Limit	3.5	nA
Min Limit	-3.5	nA

krad(Si)	3	10	20	30
LL	-3.500	-3.500	-3.500	-3.500
Min	-0.055	-0.146	-0.159	0.130
Average	0.059	0.073	0.102	0.259
Max	0.138	0.389	0.369	0.378
UL	3.500	3.500	3.500	3.500

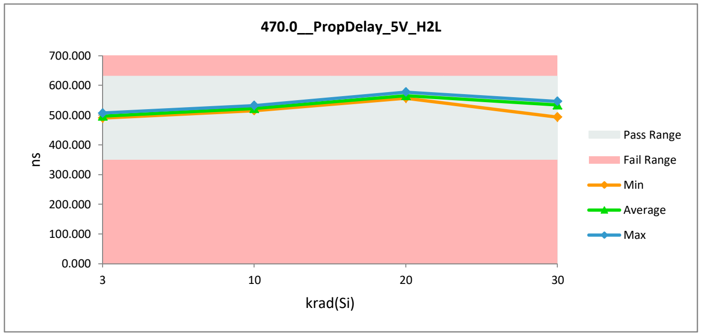


TID HDR Report
TLV1704-SEP

		470.0__PropDelay_5V_H2L		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	ns	ns	
	Max Limit	630	630	
	Min Limit	350	350	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	444.498	506.953	-62.456
3	2	434.041	493.670	-59.629
3	3	438.108	496.523	-58.415
3	4	437.497	490.062	-52.565
3	5	438.298	496.244	-57.945
10	6	440.920	516.591	-75.671
10	7	434.684	514.653	-79.969
10	8	446.133	532.157	-86.024
10	9	442.885	517.541	-74.656
10	10	446.626	532.336	-85.711
20	11	434.421	558.051	-123.630
20	12	436.368	557.035	-120.667
20	13	444.093	562.643	-118.550
20	14	437.018	572.641	-135.622
20	15	444.724	577.204	-132.479
30	16	440.337	546.186	-105.849
30	17	444.548	493.033	-48.485
30	18	443.254	543.423	-100.169
30	19	441.922	543.232	-101.311
30	20	441.146	546.330	-105.184
	Max	446.626	577.204	-48.485
	Average	440.576	529.825	-89.249
	Min	434.041	490.062	-135.622
	Std Dev	4.036	28.253	27.986

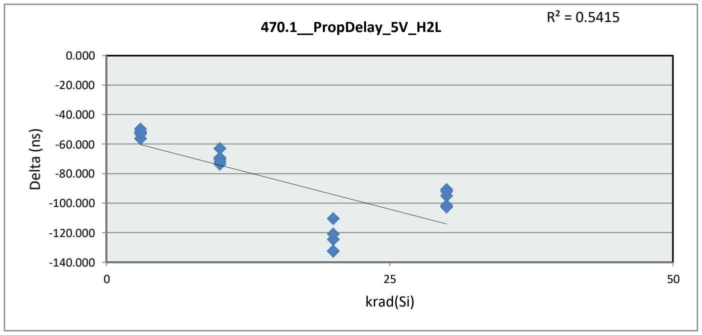


	470.0__PropDelay_5V_H2L			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	630	ns		
Min Limit	350	ns		
krad(Si)	3	10	20	30
LL	350.000	350.000	350.000	350.000
Min	490.062	514.653	557.035	493.033
Average	496.690	522.656	565.515	534.441
Max	506.953	532.336	577.204	546.330
UL	630.000	630.000	630.000	630.000

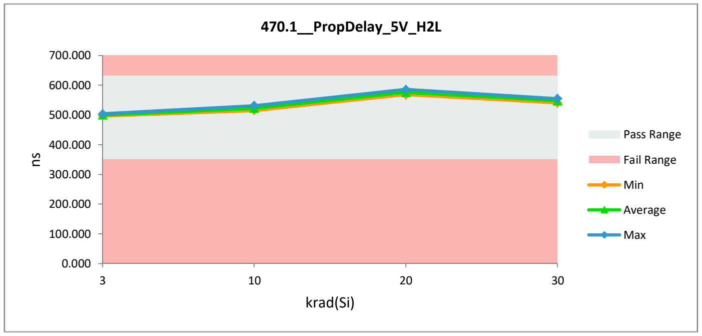


TID HDR Report
TLV1704-SEP

		470.1__PropDelay_5V_H2L		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	ns	ns	
	Max Limit	630	630	
	Min Limit	350	350	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	447.248	503.469	-56.221
3	2	448.787	501.816	-53.028
3	3	448.990	501.581	-52.591
3	4	444.884	496.507	-51.624
3	5	446.861	496.563	-49.701
10	6	453.341	522.445	-69.104
10	7	446.512	516.663	-70.151
10	8	454.994	528.517	-73.523
10	9	451.604	514.638	-63.034
10	10	459.125	530.892	-71.767
20	11	450.208	574.553	-124.345
20	12	451.061	571.833	-120.772
20	13	457.544	567.977	-110.433
20	14	445.401	577.865	-132.464
20	15	453.241	585.498	-132.257
30	16	452.519	553.952	-101.433
30	17	452.995	548.055	-95.060
30	18	450.697	541.279	-90.582
30	19	448.341	540.346	-92.005
30	20	452.104	554.718	-102.614
	Max	459.125	585.498	-49.701
	Average	450.823	536.458	-85.635
	Min	444.884	496.507	-132.464
	Std Dev	3.835	29.450	28.319



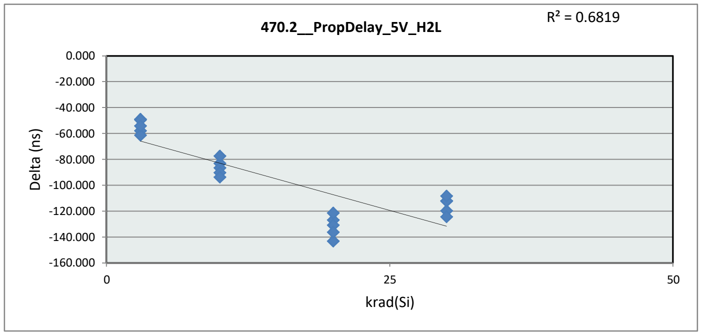
	470.1__PropDelay_5V_H2L			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	630	ns		
Min Limit	350	ns		
krad(Si)	3	10	20	30
LL	350.000	350.000	350.000	350.000
Min	496.507	514.638	567.977	540.346
Average	499.987	522.631	575.545	547.670
Max	503.469	530.892	585.498	554.718
UL	630.000	630.000	630.000	630.000



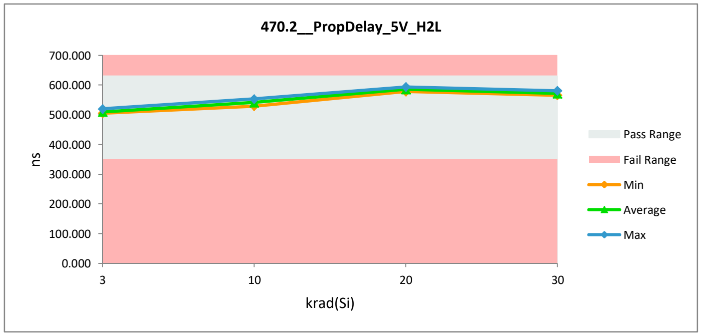
TID HDR Report
TLV1704-SEP

	470.2__PropDelay_5V_H2L	
Test Site	DALLAS	DALLAS
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	ns	ns
Max Limit	630	630
Min Limit	350	350

krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	455.957	504.919	-48.962
3	2	449.543	507.566	-58.023
3	3	458.319	519.649	-61.330
3	4	455.681	505.162	-49.481
3	5	455.424	509.592	-54.168
10	6	455.328	538.519	-83.191
10	7	447.202	533.803	-86.601
10	8	461.993	552.274	-90.281
10	9	451.354	528.824	-77.470
10	10	459.357	553.189	-93.832
20	11	450.819	577.768	-126.948
20	12	452.444	583.288	-130.844
20	13	460.854	582.309	-121.454
20	14	450.360	593.530	-143.170
20	15	454.053	590.479	-136.426
30	16	461.103	580.827	-119.723
30	17	458.352	570.667	-112.316
30	18	455.449	567.453	-112.004
30	19	456.964	565.438	-108.474
30	20	449.591	573.943	-124.352
	Max	461.993	593.530	-48.962
	Average	455.007	551.960	-96.953
	Min	447.202	504.919	-143.170
	Std Dev	4.273	30.889	30.873



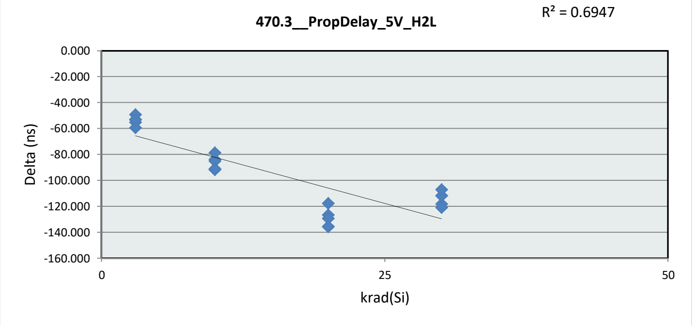
	470.2__PropDelay_5V_H2L			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	630	ns		
Min Limit	350	ns		
krad(Si)	3	10	20	30
LL	350.000	350.000	350.000	350.000
Min	504.919	528.824	577.768	565.438
Average	509.377	541.322	585.475	571.666
Max	519.649	553.189	593.530	580.827
UL	630.000	630.000	630.000	630.000



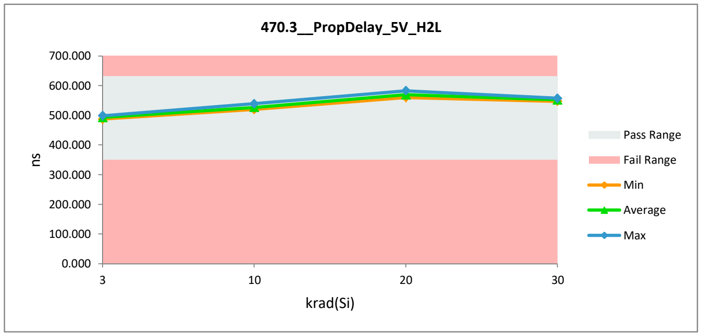
TID HDR Report
TLV1704-SEP

	470.3__PropDelay_5V_H2L	
Test Site	DALLAS	DALLAS
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	ns	ns
Max Limit	630	630
Min Limit	350	350

krad(Si)	Serial #	re Test HDR Biase	st test HDR.txt Bia	Delta
3	1	440.244	493.589	-53.345
3	2	431.557	486.791	-55.234
3	3	438.839	498.252	-59.413
3	4	441.624	491.026	-49.402
3	5	438.400	491.322	-52.922
10	6	435.690	519.612	-83.922
10	7	437.134	522.181	-85.047
10	8	447.228	538.983	-91.755
10	9	441.051	519.675	-78.624
10	10	439.538	530.708	-91.170
20	11	442.139	568.735	-126.596
20	12	437.967	567.478	-129.511
20	13	442.090	559.860	-117.770
20	14	431.954	567.741	-135.787
20	15	447.268	582.733	-135.465
30	16	434.133	552.296	-118.163
30	17	443.777	555.736	-111.959
30	18	435.551	547.338	-111.788
30	19	439.951	547.008	-107.056
30	20	436.354	557.372	-121.017
	Max	447.268	582.733	-49.402
	Average	439.124	534.922	-95.797
	Min	431.557	486.791	-135.787
	Std Dev	4.324	30.425	29.799

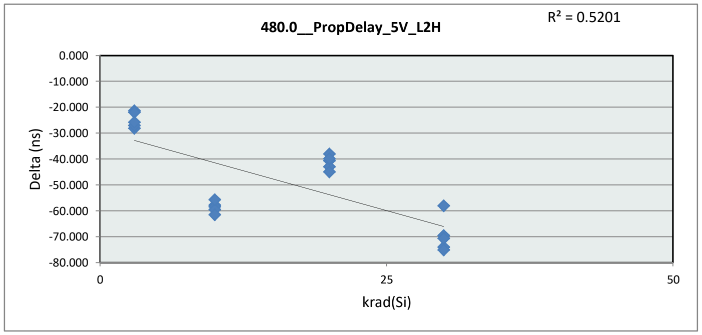


	470.3__PropDelay_5V_H2L			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	630	ns		
Min Limit	350	ns		
krad(Si)	3	10	20	30
LL	350.000	350.000	350.000	350.000
Min	486.791	519.612	559.860	547.008
Average	492.196	526.232	569.309	551.950
Max	498.252	538.983	582.733	557.372
UL	630.000	630.000	630.000	630.000

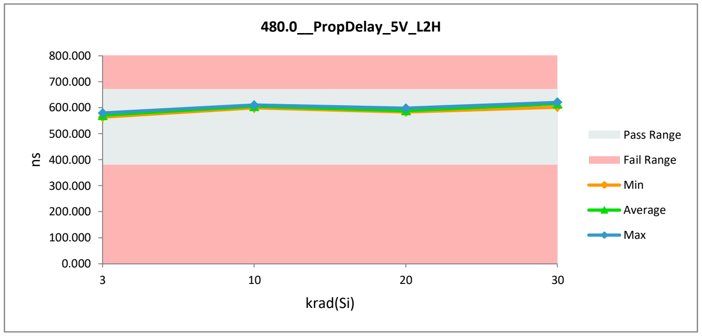


TID HDR Report
TLV1704-SEP

		480.0__PropDelay_5V_L2H		
Test Site		DALLAS	DALLAS	
Tester		ETS364	ETS364	
Test Number		EB083902	EB083902	
Unit		ns	ns	
Max Limit		670	670	
Min Limit		380	380	
krad(Si)	Serial #	re Test HDR Biase	st test HDR.txt Bia	Delta
3	1	547.175	568.435	-21.260
3	2	541.957	570.043	-28.086
3	3	552.370	579.348	-26.978
3	4	541.134	563.067	-21.933
3	5	544.495	570.323	-25.827
10	6	550.331	608.155	-57.825
10	7	544.709	603.123	-58.414
10	8	546.694	606.188	-59.494
10	9	543.282	599.008	-55.727
10	10	548.530	609.991	-61.461
20	11	542.115	582.671	-40.557
20	12	545.517	588.405	-42.888
20	13	549.478	587.505	-38.027
20	14	546.444	586.243	-39.799
20	15	552.835	597.804	-44.969
30	16	546.586	620.570	-73.985
30	17	543.830	601.855	-58.025
30	18	548.889	618.372	-69.483
30	19	545.629	616.251	-70.622
30	20	542.356	617.464	-75.108
	Max	552.835	620.570	-21.260
	Average	546.218	594.741	-48.523
	Min	541.134	563.067	-75.108
	Std Dev	3.396	18.275	17.827

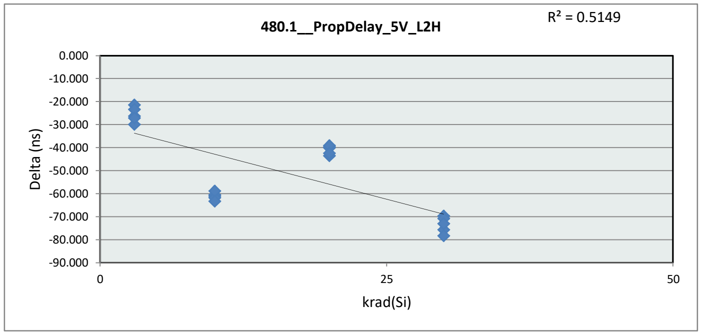


	480.0__PropDelay_5V_L2H			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	670	ns		
Min Limit	380	ns		
krad(Si)	3	10	20	30
LL	380.000	380.000	380.000	380.000
Min	563.067	599.009	582.671	601.855
Average	570.243	605.293	588.526	614.902
Max	579.348	609.991	597.804	620.570
UL	670.000	670.000	670.000	670.000

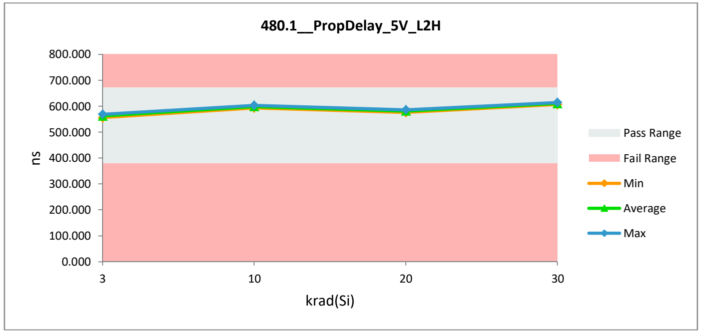


TID HDR Report
TLV1704-SEP

		480.1__PropDelay_5V_L2H		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	ns	ns	
	Max Limit	670	670	
	Min Limit	380	380	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	534.739	556.245	-21.506
3	2	535.803	565.755	-29.952
3	3	542.120	568.534	-26.414
3	4	532.239	555.705	-23.466
3	5	535.703	562.892	-27.190
10	6	538.017	599.155	-61.137
10	7	535.057	595.668	-60.611
10	8	537.651	599.470	-61.819
10	9	534.203	593.079	-58.876
10	10	539.964	603.318	-63.354
20	11	535.955	575.667	-39.712
20	12	538.248	581.848	-43.600
20	13	543.351	583.406	-40.055
20	14	538.756	577.925	-39.170
20	15	543.714	586.219	-42.505
30	16	538.402	614.089	-75.688
30	17	536.278	606.022	-69.745
30	18	537.461	608.244	-70.783
30	19	536.572	609.690	-73.118
30	20	532.477	610.794	-78.317
	Max	543.714	614.089	-21.506
	Average	537.335	587.686	-50.351
	Min	532.239	555.705	-78.317
	Std Dev	3.172	18.987	19.005

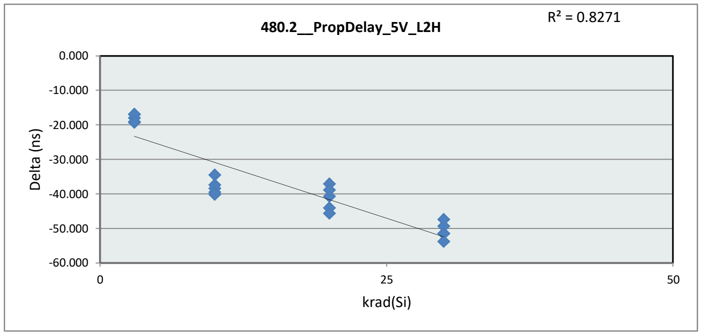


	480.1__PropDelay_5V_L2H			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	670	ns		
Min Limit	380	ns		
krad(Si)	3	10	20	30
LL	380.000	380.000	380.000	380.000
Min	555.705	593.079	575.667	606.022
Average	561.826	598.138	581.013	609.768
Max	568.535	603.318	586.219	614.089
UL	670.000	670.000	670.000	670.000

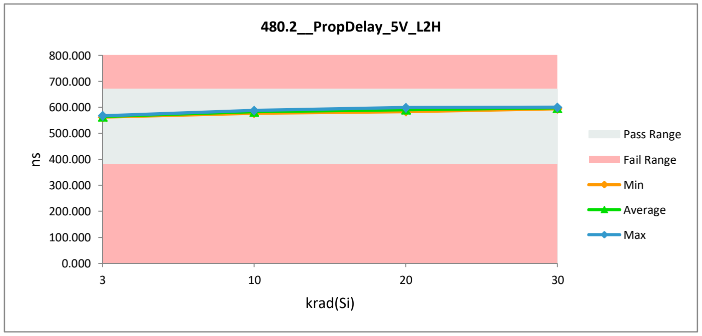


TID HDR Report
TLV1704-SEP

		480.2__PropDelay_5V_L2H		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	ns	ns	
	Max Limit	670	670	
	Min Limit	380	380	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	545.256	563.323	-18.067
3	2	545.864	565.177	-19.313
3	3	550.620	567.536	-16.917
3	4	545.154	562.206	-17.052
3	5	545.523	564.628	-19.104
10	6	548.234	585.606	-37.372
10	7	542.159	580.571	-38.411
10	8	543.324	582.878	-39.554
10	9	543.097	577.614	-34.516
10	10	547.674	587.898	-40.223
20	11	546.623	583.760	-37.138
20	12	548.619	592.715	-44.096
20	13	552.389	593.127	-40.738
20	14	548.340	587.212	-38.873
20	15	553.259	598.927	-45.667
30	16	548.989	598.367	-49.379
30	17	546.846	598.323	-51.477
30	18	548.413	599.931	-51.518
30	19	547.338	594.787	-47.449
30	20	542.936	596.784	-53.848
	Max	553.259	599.931	-16.917
	Average	547.033	584.068	-37.036
	Min	542.159	562.206	-53.848
	Std Dev	3.013	13.203	12.413

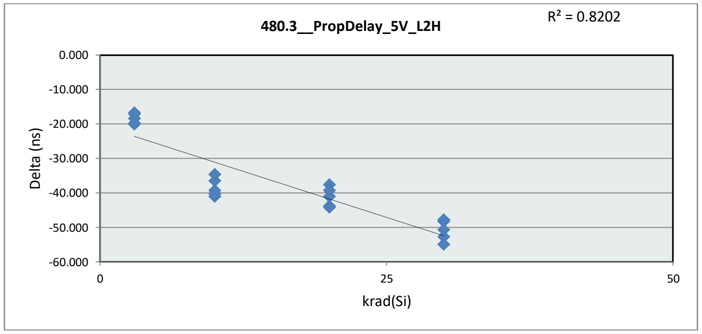


	480.2__PropDelay_5V_L2H			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	670	ns		
Min Limit	380	ns		
krad(Si)	3	10	20	30
LL	380.000	380.000	380.000	380.000
Min	562.206	577.614	583.761	594.787
Average	564.574	582.913	591.148	597.638
Max	567.537	587.898	598.927	599.931
UL	670.000	670.000	670.000	670.000

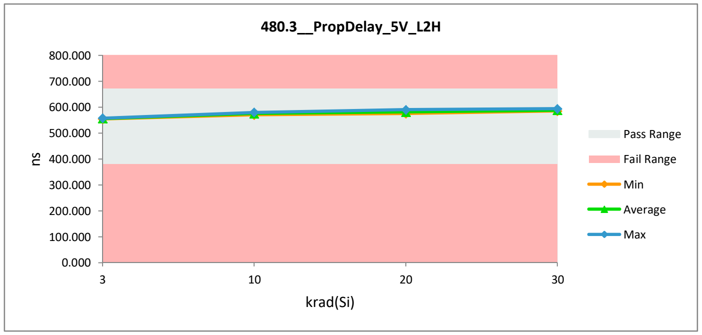


TID HDR Report
TLV1704-SEP

		480.3__PropDelay_5V_L2H		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	ns	ns	
	Max Limit	670	670	
	Min Limit	380	380	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	536.889	555.294	-18.405
3	2	535.933	556.023	-20.090
3	3	540.015	557.080	-17.065
3	4	537.539	554.310	-16.771
3	5	535.887	555.709	-19.823
10	6	538.177	574.648	-36.471
10	7	538.409	577.685	-39.276
10	8	538.363	579.383	-41.020
10	9	535.307	569.936	-34.629
10	10	534.442	574.728	-40.286
20	11	537.484	575.051	-37.567
20	12	537.163	580.921	-43.758
20	13	542.952	583.963	-41.011
20	14	538.215	577.469	-39.254
20	15	545.433	589.618	-44.185
30	16	538.329	586.533	-48.203
30	17	540.936	593.644	-52.708
30	18	536.100	586.753	-50.653
30	19	537.251	585.049	-47.798
30	20	534.067	588.947	-54.881
	Max	545.433	593.644	-16.771
	Average	537.945	575.137	-37.193
	Min	534.067	554.310	-54.881
	Std Dev	2.749	12.919	12.321

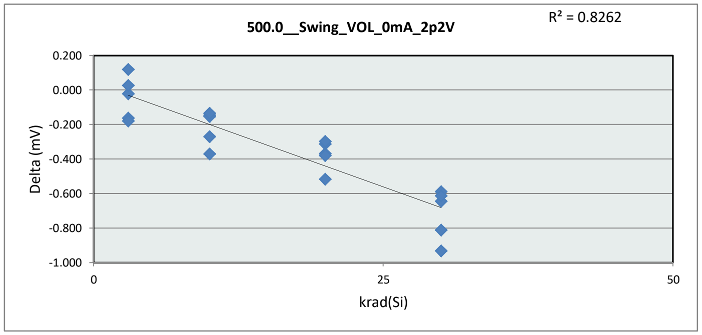


	480.3__PropDelay_5V_L2H			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	670	ns		
Min Limit	380	ns		
krad(Si)	3	10	20	30
LL	380.000	380.000	380.000	380.000
Min	554.310	569.936	575.051	585.050
Average	555.683	575.276	581.405	588.185
Max	557.080	579.383	589.618	593.644
UL	670.000	670.000	670.000	670.000

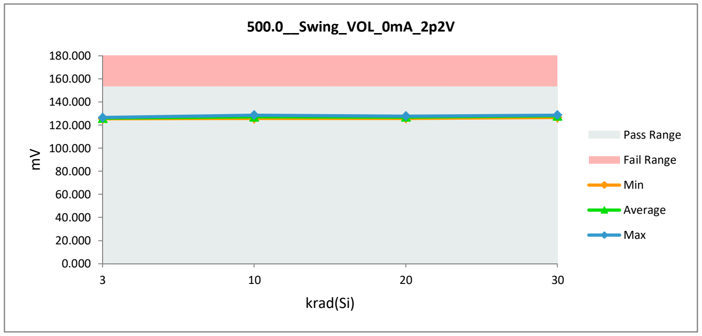


TID HDR Report
TLV1704-SEP

		500.0__Swing_VOL_0mA_2p2V		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	mV	mV	
	Max Limit	153	153	
	Min Limit	0.1	0.1	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	126.173	126.335	-0.162
3	2	125.505	125.526	-0.021
3	3	125.433	125.313	0.119
3	4	126.215	126.394	-0.178
3	5	125.835	125.807	0.028
10	6	125.436	125.582	-0.146
10	7	125.557	125.710	-0.153
10	8	128.368	128.501	-0.134
10	9	126.809	127.179	-0.371
10	10	127.705	127.975	-0.270
20	11	126.405	126.717	-0.313
20	12	125.200	125.717	-0.517
20	13	126.247	126.614	-0.368
20	14	126.982	127.361	-0.379
20	15	127.393	127.691	-0.298
30	16	127.875	128.464	-0.589
30	17	127.369	128.180	-0.812
30	18	125.787	126.432	-0.645
30	19	126.609	127.541	-0.932
30	20	127.547	128.160	-0.613
	Max	128.368	128.501	0.119
	Average	126.522	126.860	-0.338
	Min	125.200	125.313	-0.932
	Std Dev	0.942	1.070	0.278

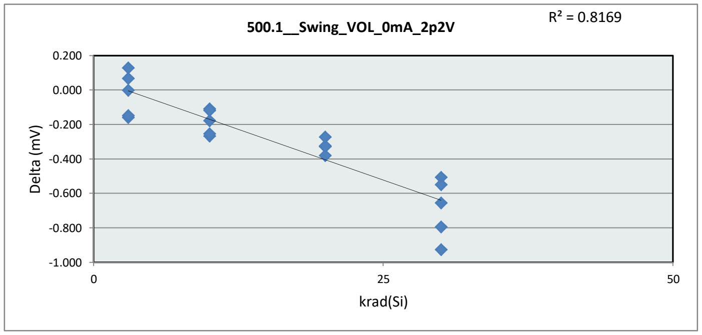


	500.0__Swing_VOL_0mA_2p2			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	153	mV		
Min Limit	0.1	mV		
krad(Si)	3	10	20	30
LL	0.100	0.100	0.100	0.100
Min	125.313	125.582	125.717	126.432
Average	125.875	126.990	126.820	127.755
Max	126.394	128.501	127.691	128.464
UL	153.000	153.000	153.000	153.000

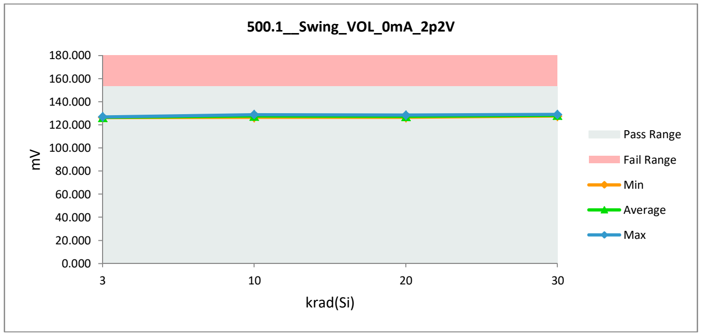


TID HDR Report
TLV1704-SEP

		500.1__Swing_VOL_0mA_2p2V		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	mV	mV	
	Max Limit	153	153	
	Min Limit	0.1	0.1	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	126.094	126.254	-0.160
3	2	126.322	126.323	-0.001
3	3	126.414	126.285	0.128
3	4	126.706	126.855	-0.149
3	5	126.747	126.679	0.067
10	6	126.260	126.370	-0.110
10	7	126.561	126.738	-0.177
10	8	128.049	128.168	-0.119
10	9	127.451	127.718	-0.267
10	10	128.592	128.846	-0.254
20	11	126.849	127.177	-0.328
20	12	125.997	126.377	-0.380
20	13	126.662	126.989	-0.327
20	14	127.007	127.331	-0.325
20	15	128.080	128.352	-0.272
30	16	128.181	128.687	-0.506
30	17	127.467	128.262	-0.794
30	18	126.832	127.488	-0.656
30	19	126.950	127.876	-0.926
30	20	128.307	128.856	-0.550
	Max	128.592	128.856	0.128
	Average	127.076	127.382	-0.305
	Min	125.997	126.254	-0.926
	Std Dev	0.791	0.910	0.273

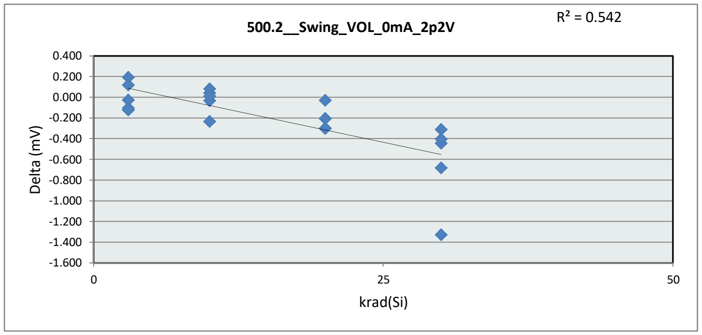


	500.1__Swing_VOL_0mA_2p2			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	153	mV		
Min Limit	0.1	mV		
krad(Si)	3	10	20	30
LL	0.100	0.100	0.100	0.100
Min	126.254	126.370	126.377	127.488
Average	126.479	127.568	127.245	128.234
Max	126.855	128.846	128.352	128.856
UL	153.000	153.000	153.000	153.000

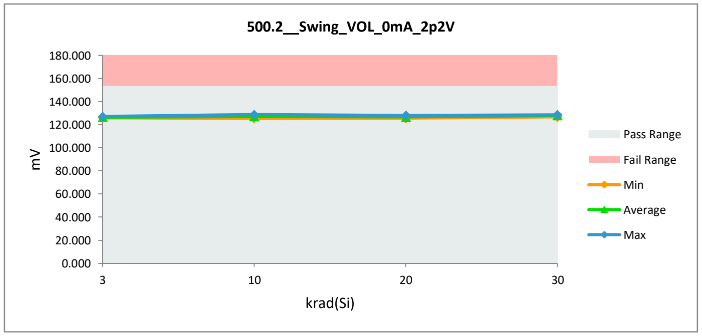


TID HDR Report
TLV1704-SEP

		500.2__Swing_VOL_0mA_2p2V		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	mV	mV	
	Max Limit	153	153	
	Min Limit	0.1	0.1	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	126.890	126.995	-0.105
3	2	125.982	126.011	-0.028
3	3	126.540	126.350	0.190
3	4	126.859	126.982	-0.123
3	5	126.738	126.620	0.117
10	6	125.499	125.459	0.040
10	7	126.513	126.549	-0.036
10	8	128.774	128.695	0.080
10	9	126.738	126.973	-0.235
10	10	128.283	128.275	0.008
20	11	125.883	126.187	-0.304
20	12	125.406	125.614	-0.208
20	13	126.731	126.938	-0.206
20	14	126.825	127.125	-0.300
20	15	127.981	128.013	-0.032
30	16	128.110	128.554	-0.445
30	17	127.677	128.359	-0.682
30	18	126.265	126.671	-0.406
30	19	126.589	127.918	-1.329
30	20	127.659	127.970	-0.311
	Max	128.774	128.695	0.190
	Average	126.897	127.113	-0.216
	Min	125.406	125.459	-1.329
	Std Dev	0.923	0.977	0.338

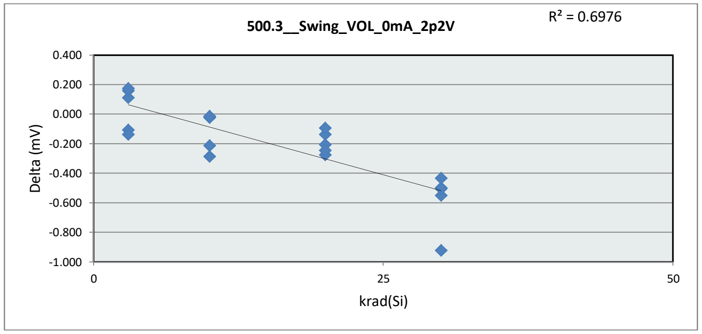


	500.2__Swing_VOL_0mA_2p2			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	153	mV		
Min Limit	0.1	mV		
krad(Si)	3	10	20	30
LL	0.100	0.100	0.100	0.100
Min	126.011	125.459	125.614	126.671
Average	126.592	127.190	126.775	127.894
Max	126.996	128.695	128.013	128.554
UL	153.000	153.000	153.000	153.000

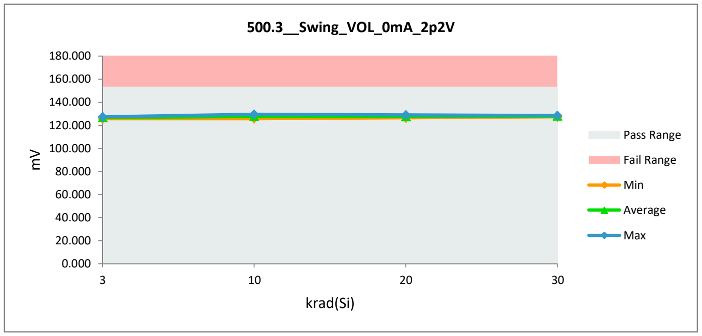


TID HDR Report
TLV1704-SEP

		500.3__Swing_VOL_0mA_2p2V		
Test Site		DALLAS	DALLAS	
Tester		ETS364	ETS364	
Test Number		EB083902	EB083902	
Unit		mV	mV	
Max Limit		153	153	
Min Limit		0.1	0.1	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	126.803	126.909	-0.107
3	2	125.672	125.560	0.112
3	3	127.337	127.179	0.159
3	4	126.765	126.904	-0.138
3	5	126.896	126.722	0.174
10	6	125.581	125.603	-0.022
10	7	126.277	126.299	-0.022
10	8	128.879	128.894	-0.014
10	9	127.640	127.853	-0.213
10	10	129.053	129.340	-0.287
20	11	127.429	127.705	-0.277
20	12	126.150	126.357	-0.206
20	13	126.289	126.427	-0.138
20	14	127.415	127.660	-0.245
20	15	128.736	128.830	-0.094
30	16	127.805	128.304	-0.499
30	17	127.152	127.703	-0.551
30	18	126.628	127.133	-0.505
30	19	127.004	127.927	-0.923
30	20	127.700	128.134	-0.434
	Max	129.053	129.340	0.174
	Average	127.161	127.372	-0.212
	Min	125.581	125.560	-0.923
	Std Dev	0.975	1.052	0.270

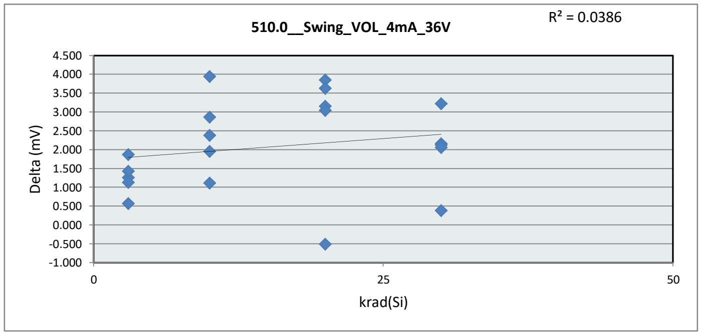


	500.3__Swing_VOL_0mA_2p2			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	153	mV		
Min Limit	0.1	mV		
krad(Si)	3	10	20	30
LL	0.100	0.100	0.100	0.100
Min	125.560	125.603	126.357	127.133
Average	126.655	127.598	127.396	127.840
Max	127.179	129.340	128.830	128.304
UL	153.000	153.000	153.000	153.000

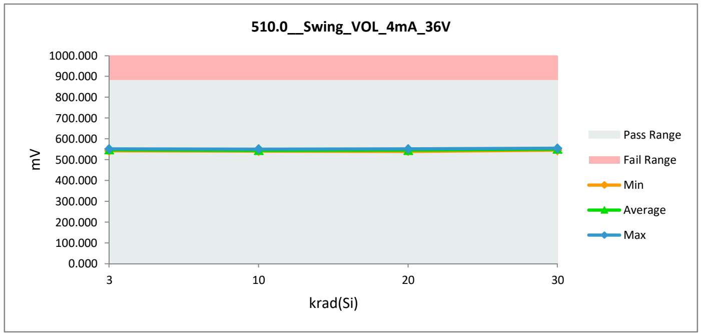


TID HDR Report
TLV1704-SEP

		510.0__Swing_VOL_4mA_36V		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	mV	mV	
	Max Limit	880	880	
	Min Limit	0.1	0.1	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	552.801	551.539	1.262
3	2	546.185	544.753	1.432
3	3	543.956	542.086	1.870
3	4	547.346	546.777	0.569
3	5	552.669	551.540	1.129
10	6	547.528	543.587	3.941
10	7	545.582	543.625	1.957
10	8	544.029	541.167	2.862
10	9	553.238	550.857	2.381
10	10	546.010	544.892	1.118
20	11	551.004	547.153	3.851
20	12	544.122	544.627	-0.505
20	13	554.758	551.609	3.149
20	14	543.253	540.209	3.043
20	15	544.741	541.108	3.633
30	16	547.367	545.208	2.159
30	17	556.625	554.501	2.125
30	18	552.297	550.241	2.055
30	19	550.185	549.801	0.385
30	20	558.045	554.823	3.222
	Max	558.045	554.823	3.941
	Average	549.087	547.005	2.082
	Min	543.253	540.209	-0.505
	Std Dev	4.567	4.551	1.212

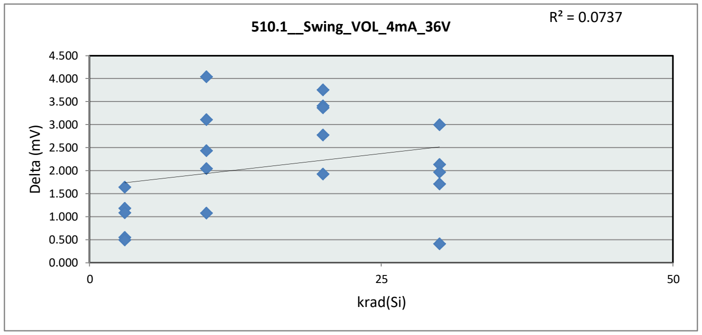


	510.0__Swing_VOL_4mA_36V			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	880	mV		
Min Limit	0.1	mV		
krad(Si)	3	10	20	30
LL	0.100	0.100	0.100	0.100
Min	542.086	541.168	540.210	545.208
Average	547.339	544.826	544.941	550.915
Max	551.540	550.857	551.609	554.823
UL	880.000	880.000	880.000	880.000

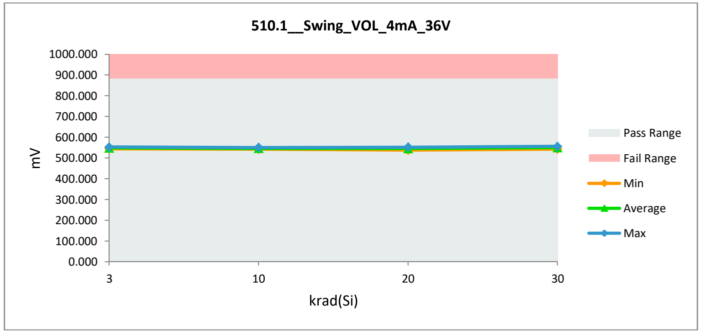


TID HDR Report
TLV1704-SEP

		510.1__Swing_VOL_4mA_36V		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	mV	mV	
	Max Limit	880	880	
	Min Limit	0.1	0.1	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	554.234	553.051	1.183
3	2	546.474	544.834	1.640
3	3	546.488	545.944	0.545
3	4	547.117	546.624	0.493
3	5	551.252	550.166	1.086
10	6	550.072	546.033	4.039
10	7	547.811	545.770	2.042
10	8	545.715	542.612	3.103
10	9	552.989	550.558	2.431
10	10	546.812	545.732	1.079
20	11	553.691	549.937	3.754
20	12	545.673	543.746	1.927
20	13	555.312	552.539	2.774
20	14	541.049	537.646	3.403
20	15	544.447	541.082	3.365
30	16	545.718	542.720	2.997
30	17	553.316	551.186	2.130
30	18	550.482	548.775	1.707
30	19	551.640	551.229	0.411
30	20	558.300	556.335	1.965
	Max	558.300	556.335	4.039
	Average	549.430	547.326	2.104
	Min	541.049	537.646	0.411
	Std Dev	4.359	4.605	1.109

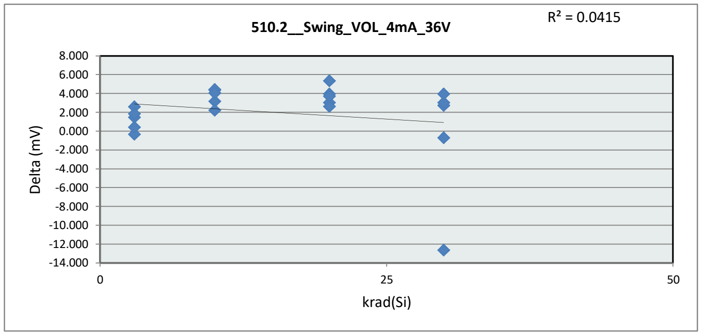


	510.1__Swing_VOL_4mA_36V			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	880	mV		
Min Limit	0.1	mV		
krad(Si)	3	10	20	30
LL	0.100	0.100	0.100	0.100
Min	544.834	542.612	537.646	542.720
Average	548.124	546.141	544.990	550.049
Max	553.051	550.558	552.539	556.335
UL	880.000	880.000	880.000	880.000

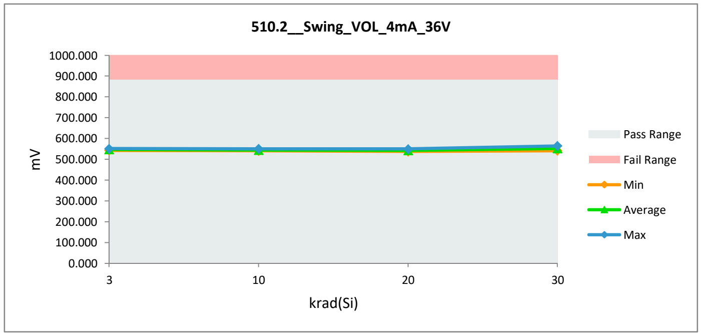


TID HDR Report
TLV1704-SEP

		510.2__Swing_VOL_4mA_36V		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	mV	mV	
	Max Limit	880	880	
	Min Limit	0.1	0.1	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	551.993	550.543	1.450
3	2	544.449	544.803	-0.354
3	3	545.268	542.686	2.582
3	4	548.495	548.087	0.408
3	5	553.239	551.422	1.817
10	6	548.220	543.871	4.349
10	7	545.442	542.293	3.149
10	8	545.152	540.740	4.412
10	9	552.844	550.622	2.222
10	10	548.913	544.856	4.057
20	11	551.484	548.450	3.034
20	12	545.429	541.473	3.956
20	13	553.364	549.661	3.703
20	14	540.432	537.812	2.621
20	15	544.684	539.360	5.324
30	16	544.301	541.593	2.708
30	17	555.352	556.069	-0.716
30	18	550.273	547.260	3.013
30	19	552.055	564.711	-12.656
30	20	555.345	551.399	3.947
	Max	555.352	564.711	5.324
	Average	548.837	546.886	1.951
	Min	540.432	537.812	-12.656
	Std Dev	4.278	6.376	3.786

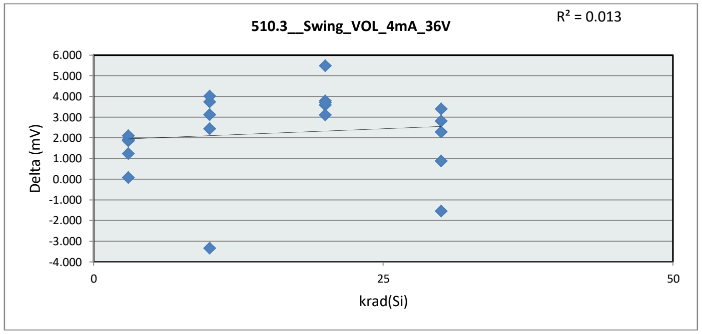


	510.2__Swing_VOL_4mA_36V			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	880	mV		
Min Limit	0.1	mV		
krad(Si)	3	10	20	30
LL	0.100	0.100	0.100	0.100
Min	542.686	540.740	537.812	541.593
Average	547.508	544.476	543.351	552.206
Max	551.422	550.622	549.662	564.711
UL	880.000	880.000	880.000	880.000

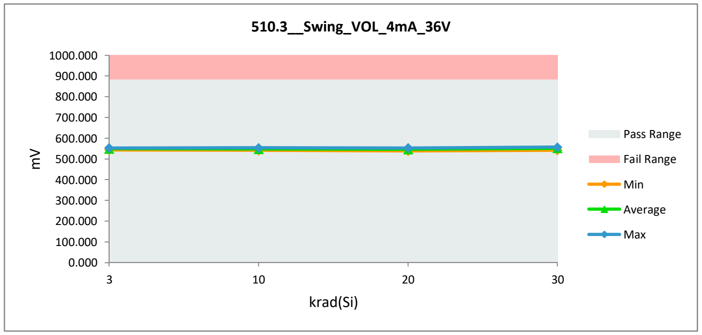


TID HDR Report
TLV1704-SEP

		510.3__Swing_VOL_4mA_36V		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	mV	mV	
	Max Limit	880	880	
	Min Limit	0.1	0.1	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	554.254	553.025	1.229
3	2	547.224	545.374	1.851
3	3	545.792	543.884	1.908
3	4	551.507	551.427	0.080
3	5	554.361	552.255	2.106
10	6	549.968	546.234	3.734
10	7	547.827	544.704	3.123
10	8	545.463	541.447	4.016
10	9	556.330	553.886	2.444
10	10	548.408	551.748	-3.340
20	11	556.603	553.016	3.588
20	12	548.654	544.870	3.784
20	13	555.276	551.575	3.701
20	14	541.346	538.247	3.099
20	15	548.261	542.781	5.480
30	16	544.843	542.026	2.817
30	17	555.691	553.400	2.291
30	18	554.302	553.422	0.881
30	19	554.984	556.537	-1.554
30	20	557.471	554.078	3.393
	Max	557.471	556.537	5.480
	Average	550.928	548.697	2.232
	Min	541.346	538.247	-3.340
	Std Dev	4.728	5.375	2.036

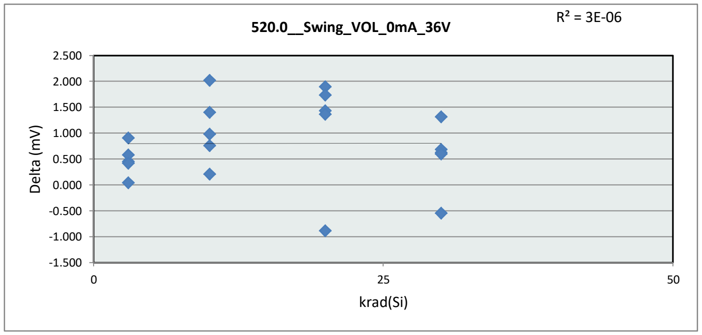


	510.3__Swing_VOL_4mA_36V			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	880	mV		
Min Limit	0.1	mV		
krad(Si)	3	10	20	30
LL	0.100	0.100	0.100	0.100
Min	543.884	541.447	538.247	542.026
Average	549.193	547.604	546.098	551.893
Max	553.025	553.886	553.016	556.537
UL	880.000	880.000	880.000	880.000

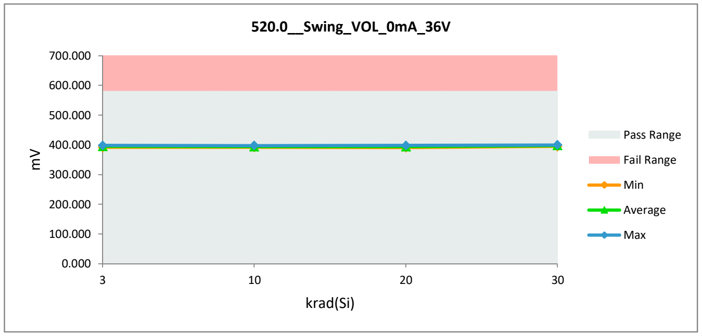


TID HDR Report
TLV1704-SEP

		520.0__Swing_VOL_0mA_36V		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	mV	mV	
	Max Limit	580	580	
	Min Limit	0.1	0.1	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	398.059	397.606	0.453
3	2	393.129	392.545	0.584
3	3	392.355	391.447	0.909
3	4	394.214	394.168	0.045
3	5	397.847	397.426	0.421
10	6	394.418	392.400	2.018
10	7	393.248	392.488	0.760
10	8	393.438	392.034	1.404
10	9	398.509	397.528	0.981
10	10	394.330	394.120	0.210
20	11	396.613	394.714	1.899
20	12	392.248	393.132	-0.884
20	13	399.302	397.867	1.435
20	14	392.017	390.653	1.364
20	15	393.038	391.299	1.739
30	16	395.164	394.475	0.689
30	17	400.302	399.679	0.623
30	18	397.252	396.650	0.603
30	19	396.414	396.956	-0.542
30	20	400.405	399.089	1.316
	Max	400.405	399.679	2.018
	Average	395.615	394.814	0.801
	Min	392.017	390.653	-0.884
	Std Dev	2.767	2.811	0.758

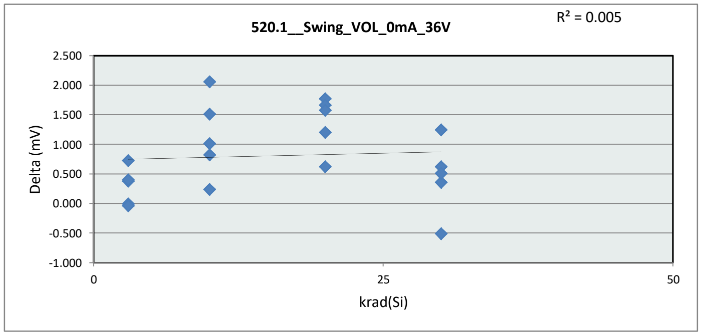


	520.0__Swing_VOL_0mA_36V			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	580	mV		
Min Limit	0.1	mV		
krad(Si)	3	10	20	30
LL	0.100	0.100	0.100	0.100
Min	391.447	392.034	390.653	394.475
Average	394.638	393.714	393.533	397.370
Max	397.606	397.528	397.867	399.679
UL	580.000	580.000	580.000	580.000

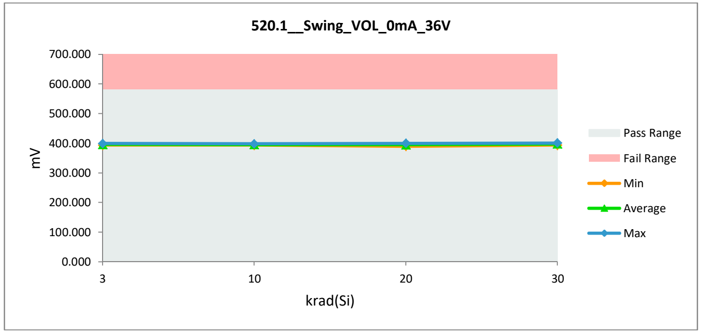


TID HDR Report
TLV1704-SEP

		520.1__Swing_VOL_0mA_36V		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	mV	mV	
	Max Limit	580	580	
	Min Limit	0.1	0.1	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	399.223	398.840	0.382
3	2	394.518	393.794	0.724
3	3	394.852	394.856	-0.005
3	4	395.099	395.136	-0.038
3	5	397.633	397.228	0.404
10	6	396.968	394.910	2.058
10	7	395.406	394.584	0.822
10	8	394.990	393.479	1.511
10	9	399.145	398.129	1.015
10	10	395.472	395.231	0.241
20	11	399.062	397.288	1.773
20	12	394.439	393.817	0.622
20	13	400.527	399.324	1.203
20	14	391.447	389.783	1.664
20	15	393.667	392.089	1.578
30	16	394.654	393.409	1.246
30	17	398.647	398.022	0.625
30	18	396.896	396.540	0.356
30	19	397.709	398.219	-0.510
30	20	401.321	400.814	0.508
	Max	401.321	400.814	2.058
	Average	396.584	395.775	0.809
	Min	391.447	389.783	-0.510
	Std Dev	2.538	2.722	0.682

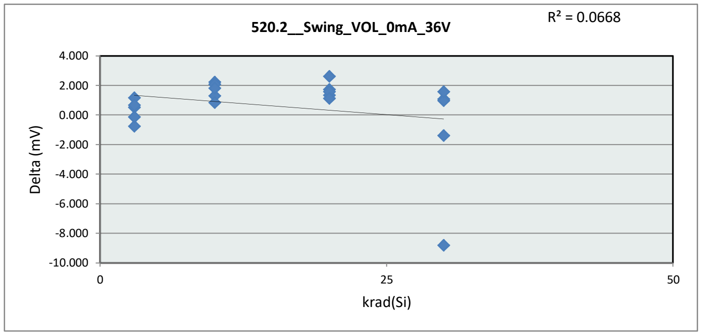


	520.1__Swing_VOL_0mA_36V			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	580	mV		
Min Limit	0.1	mV		
krad(Si)	3	10	20	30
LL	0.100	0.100	0.100	0.100
Min	393.794	393.480	389.783	393.409
Average	395.971	395.267	394.460	397.401
Max	398.840	398.130	399.324	400.814
UL	580.000	580.000	580.000	580.000

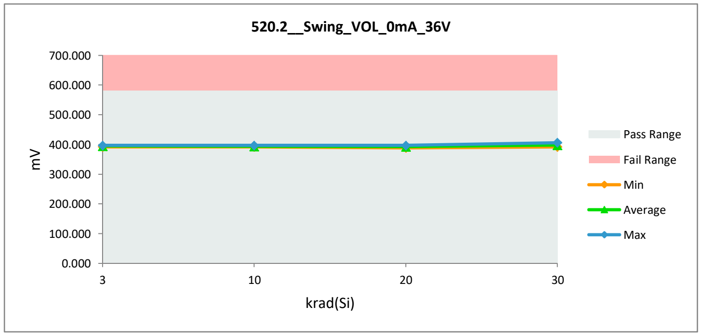


TID HDR Report
TLV1704-SEP

		520.2__Swing_VOL_0mA_36V		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	mV	mV	
	Max Limit	580	580	
	Min Limit	0.1	0.1	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	396.931	396.426	0.505
3	2	392.037	392.802	-0.765
3	3	393.211	392.044	1.167
3	4	395.008	395.155	-0.146
3	5	397.539	396.877	0.662
10	6	394.485	392.279	2.206
10	7	393.195	391.904	1.291
10	8	393.815	391.740	2.074
10	9	397.721	396.888	0.834
10	10	395.963	394.164	1.799
20	11	396.259	394.924	1.335
20	12	392.493	390.767	1.727
20	13	398.184	396.618	1.566
20	14	390.036	388.934	1.102
20	15	392.638	390.032	2.605
30	16	392.779	391.699	1.080
30	17	399.109	400.512	-1.402
30	18	395.581	394.610	0.971
30	19	396.946	405.752	-8.806
30	20	398.158	396.594	1.564
	Max	399.109	405.752	2.605
	Average	395.104	394.536	0.569
	Min	390.036	388.934	-8.806
	Std Dev	2.506	3.895	2.409



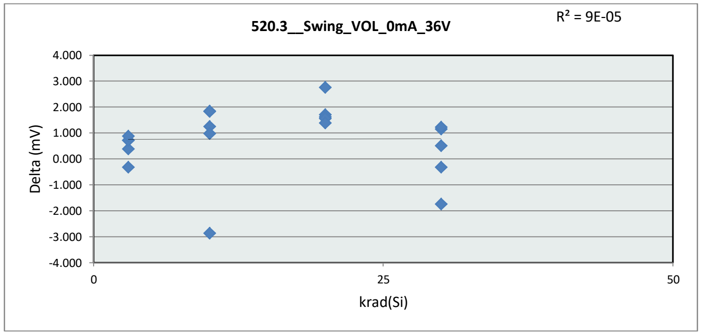
	520.2__Swing_VOL_0mA_36V			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	580	mV		
Min Limit	0.1	mV		
krad(Si)	3	10	20	30
LL	0.100	0.100	0.100	0.100
Min	392.044	391.740	388.934	391.699
Average	394.661	393.395	392.255	397.833
Max	396.877	396.888	396.618	405.752
UL	580.000	580.000	580.000	580.000



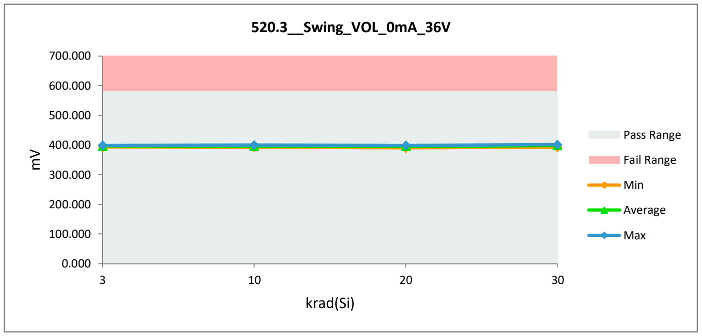
TID HDR Report
TLV1704-SEP

	520.3__Swing_VOL_0mA_36V	
Test Site	DALLAS	DALLAS
Tester	ETS364	ETS364
Test Number	EB083902	EB083902
Unit	mV	mV
Max Limit	580	580
Min Limit	0.1	0.1

krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	398.693	398.303	0.390
3	2	394.172	393.454	0.718
3	3	394.031	393.315	0.717
3	4	397.076	397.401	-0.325
3	5	398.797	397.915	0.882
10	6	395.549	393.706	1.843
10	7	394.604	393.357	1.247
10	8	394.096	392.262	1.834
10	9	400.727	399.753	0.974
10	10	396.072	398.933	-2.861
20	11	400.122	398.410	1.713
20	12	395.052	393.431	1.621
20	13	399.549	397.990	1.560
20	14	391.053	389.662	1.391
20	15	395.705	392.942	2.763
30	16	393.318	392.165	1.153
30	17	399.259	398.746	0.512
30	18	398.378	398.701	-0.323
30	19	398.931	400.673	-1.741
30	20	400.118	398.888	1.230
	Max	400.727	400.673	2.763
	Average	396.765	396.000	0.765
	Min	391.053	389.662	-2.861
	Std Dev	2.752	3.237	1.290

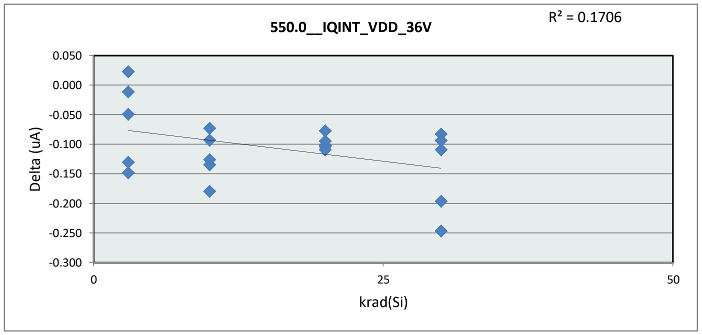


	520.3__Swing_VOL_0mA_36V			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	580	mV		
Min Limit	0.1	mV		
krad(Si)	3	10	20	30
LL	0.100	0.100	0.100	0.100
Min	393.315	392.262	389.662	392.165
Average	396.078	395.602	394.487	397.835
Max	398.303	399.753	398.410	400.673
UL	580.000	580.000	580.000	580.000

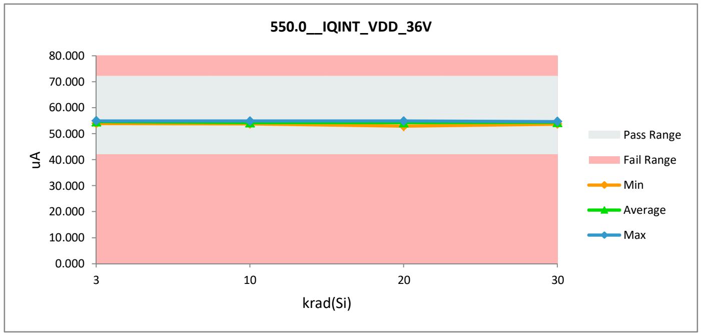


TID HDR Report
TLV1704-SEP

		550.0__IQINT_VDD_36V		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	uA	uA	
	Max Limit	72	72	
	Min Limit	42	42	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	54.525	54.673	-0.148
3	2	54.618	54.667	-0.049
3	3	53.935	53.913	0.023
3	4	54.795	54.925	-0.130
3	5	54.689	54.701	-0.012
10	6	54.056	54.182	-0.126
10	7	54.368	54.461	-0.093
10	8	53.740	53.813	-0.073
10	9	54.636	54.815	-0.179
10	10	53.600	53.735	-0.135
20	11	54.714	54.817	-0.104
20	12	54.145	54.247	-0.102
20	13	54.201	54.279	-0.078
20	14	54.633	54.742	-0.109
20	15	52.789	52.884	-0.095
30	16	53.604	53.687	-0.083
30	17	54.282	54.478	-0.196
30	18	54.548	54.657	-0.109
30	19	54.299	54.545	-0.246
30	20	54.144	54.237	-0.093
	Max	54.795	54.925	0.023
	Average	54.216	54.323	-0.107
	Min	52.789	52.884	-0.246
	Std Dev	0.497	0.508	0.060

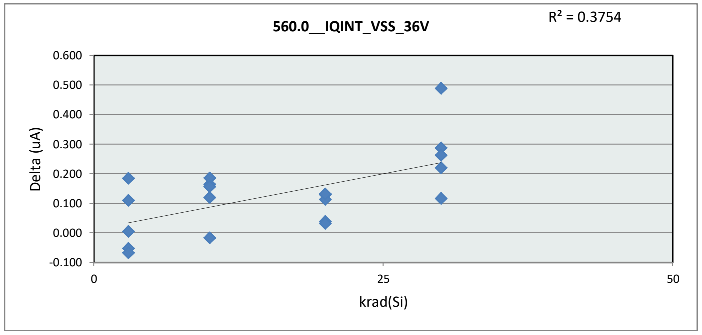


	550.0__IQINT_VDD_36V			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	72	uA		
Min Limit	42	uA		
krad(Si)	3	10	20	30
LL	42.000	42.000	42.000	42.000
Min	53.913	53.735	52.884	53.687
Average	54.576	54.201	54.194	54.321
Max	54.925	54.815	54.817	54.657
UL	72.000	72.000	72.000	72.000

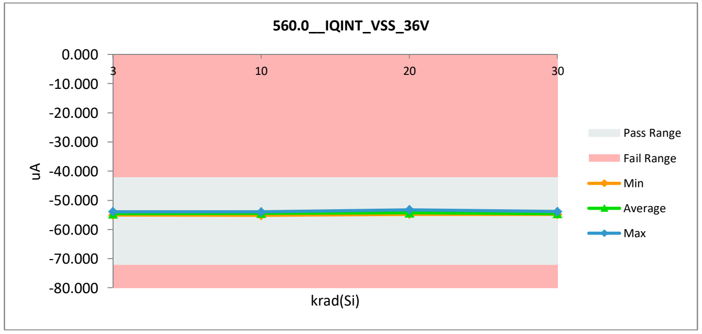


TID HDR Report
TLV1704-SEP

		560.0__IQINT_VSS_36V		
	Test Site	DALLAS	DALLAS	
	Tester	ETS364	ETS364	
	Test Number	EB083902	EB083902	
	Unit	uA	uA	
	Max Limit	-42	-42	
	Min Limit	-72	-72	
krad(Si)	Serial #	re Test HDR Biase	t test HDR.txt Bia	Delta
3	1	-54.690	-54.637	-0.053
3	2	-54.656	-54.766	0.109
3	3	-53.977	-53.909	-0.068
3	4	-54.869	-55.053	0.184
3	5	-54.768	-54.773	0.005
10	6	-54.104	-54.223	0.119
10	7	-54.615	-54.778	0.163
10	8	-53.985	-53.968	-0.017
10	9	-54.975	-55.160	0.185
10	10	-53.905	-54.061	0.156
20	11	-54.753	-54.792	0.038
20	12	-54.181	-54.310	0.129
20	13	-54.215	-54.246	0.031
20	14	-54.602	-54.715	0.113
20	15	-53.140	-53.271	0.131
30	16	-53.569	-53.856	0.287
30	17	-54.289	-54.777	0.488
30	18	-54.570	-54.790	0.220
30	19	-54.594	-54.856	0.262
30	20	-54.382	-54.498	0.116
	Max	-53.140	-53.271	0.488
	Average	-54.342	-54.472	0.130
	Min	-54.975	-55.160	-0.068
	Std Dev	0.465	0.477	0.129



	560.0__IQINT_VSS_36V			
Test Site	DALLAS			
Tester	ETS364			
Test Number	EB083902			
Max Limit	-42	uA		
Min Limit	-72	uA		
krad(Si)	3	10	20	30
LL	-72.000	-72.000	-72.000	-72.000
Min	-55.053	-55.160	-54.792	-54.856
Average	-54.628	-54.438	-54.267	-54.555
Max	-53.909	-53.968	-53.271	-53.856
UL	-42.000	-42.000	-42.000	-42.000



IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATA SHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES “AS IS” AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI’s products are provided subject to TI’s Terms of Sale or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI’s provision of these resources does not expand or otherwise alter TI’s applicable warranties or warranty disclaimers for TI products.

TI objects to and rejects any additional or different terms you may have proposed.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265
Copyright © 2025, Texas Instruments Incorporated